S71GS256/128N based MCPs

Stacked Multi-Chip Product (MCP)
256/128 Megabit (16/8M x 16-bit) CMOS 3.0 Volt V_{CC} and 1.8 V V_{IO} MirrorBit™ Uniform Sector Page-mode Flash Memory with 64/32 Megabit (4/2M x 16-bit) 1.8V pSRAM

Data Sheet

ADVANCE INFORMATION

Distinctive Characteristics

MCP Features

- **Power supply voltage**
  - — Flash Memory
    V_{CC}: 2.7V to 3.1V
    V_{IO}: 1.65V to 1.95V
  - — pSRAM
    V_{CC}: 1.7 V to 1.95 V

High Performance

- **110 ns access time**
- **30 ns page read times**
- **Packages:**
  - — 8.0x11.6x1.2 mm FBGA (TLA084)
- **Operating Temperature**
  - — -25°C to +85°C (Wireless)

General Description

The S71GS Series is a product line of stacked Multi-chip Product (MCP) packages and consists of

- One S29GL Flash memory die with 1.8 V V_{IO}
- one 1.8 V pSRAM (Note)

Note: *Burst mode features of the pSRAM in the S71GS family of MCPs is not available. This MCP uses the page mode operation which utilizes the page mode Flash and page mode feature-set of the pSRAM.*

Publication Number S71GS256/128N_00 **Revision** A **Amendment** 0 **Issue Date** December 17, 2004

Product Selector Guide

Part Number		S7IGS256NC0	
Speed/Voltage Option	Full Voltage Range V_{CC} = 2.7 V to 3.1 V (Flash) V_{IO} = 1.65 V to 1.95 V (Flash) V_{CC} = 1.7 V to 1.95 V (pSRAM)	Flash	pSRAM
Max. Access Time (ns)		110	70
Max. CE# Access Time (ns)		110	70
Max. Page Access Time (tpacc)		30	25
Max. OE# Access Time (ns)		30	25

Part Number		S7IGS128NB0	
Speed/Voltage Option	Full Voltage Range V_{CC} = 2.7 V to 3.1 V (Flash) V_{IO} = 1.65 V to 1.95 V (Flash) V_{CC} = 1.7 V to 1.95 V (pSRAM)	Flash	pSRAM
Max. Access Time (ns)		110	70
Max. CE# Access Time (ns)		110	70
Max. Page Access Time (tpacc)		30	25
Max. OE# Access Time (ns)		30	25

S71GS256/128N based MCPs

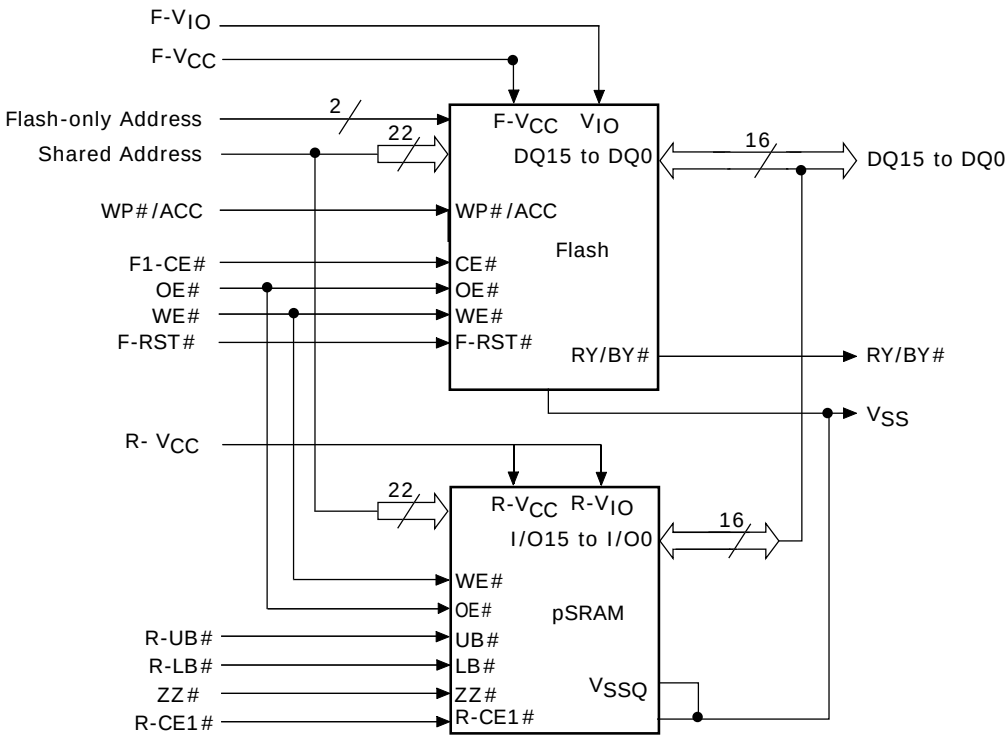
S29GLxxxN MirrorBit™ Flash Family

CellularRAM Type 2

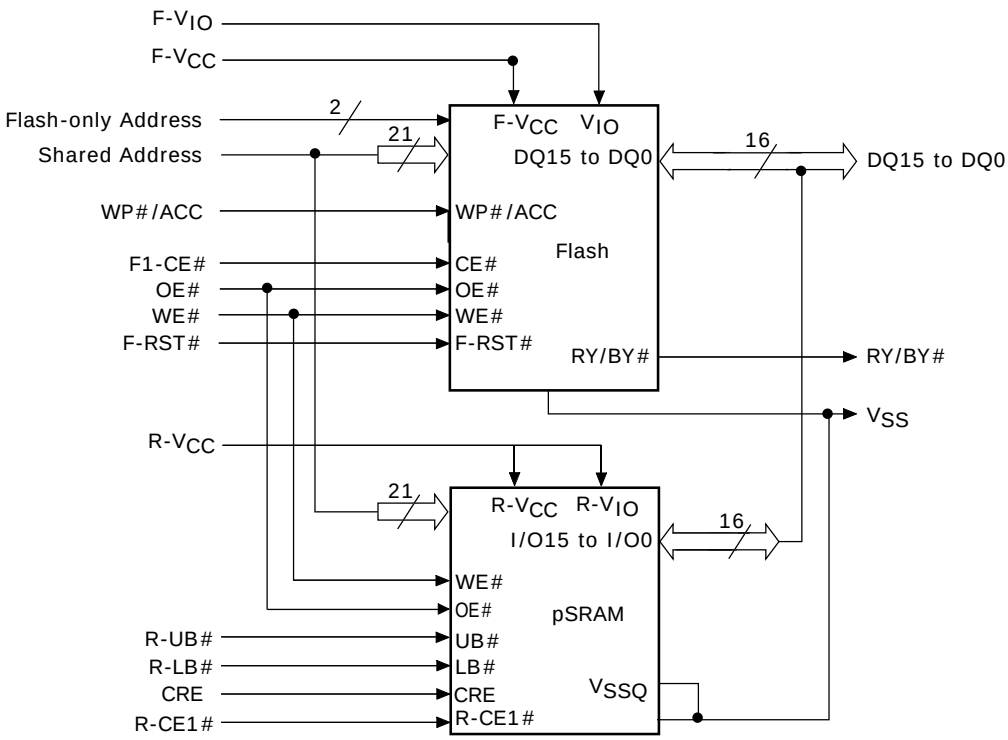
Revision Summary

MCP Block Diagrams

(256 Mb Flash + 64 Mb pSRAM)



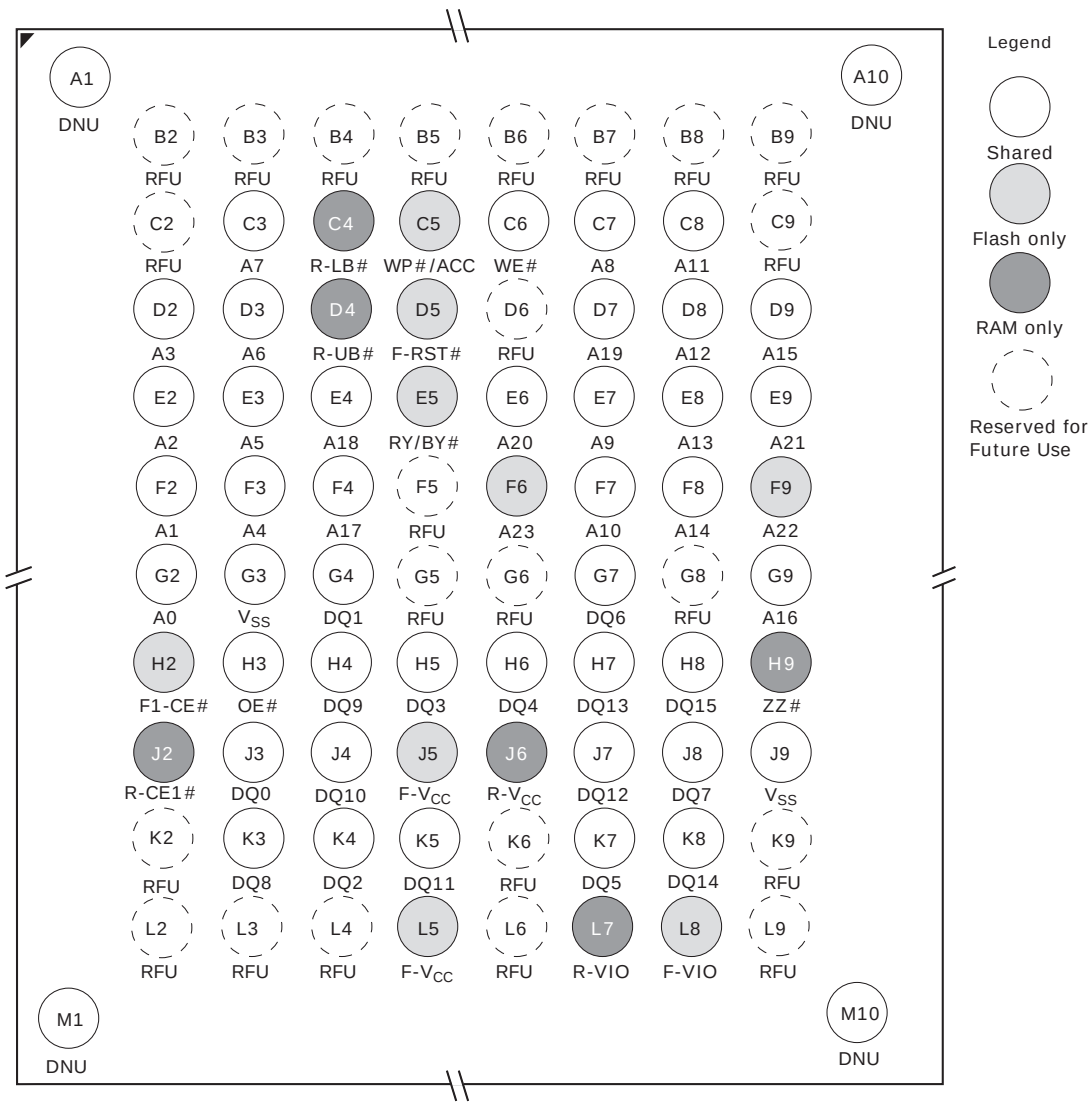
(I28 Mb Flash + 32 Mb pSRAM)



Connection Diagrams

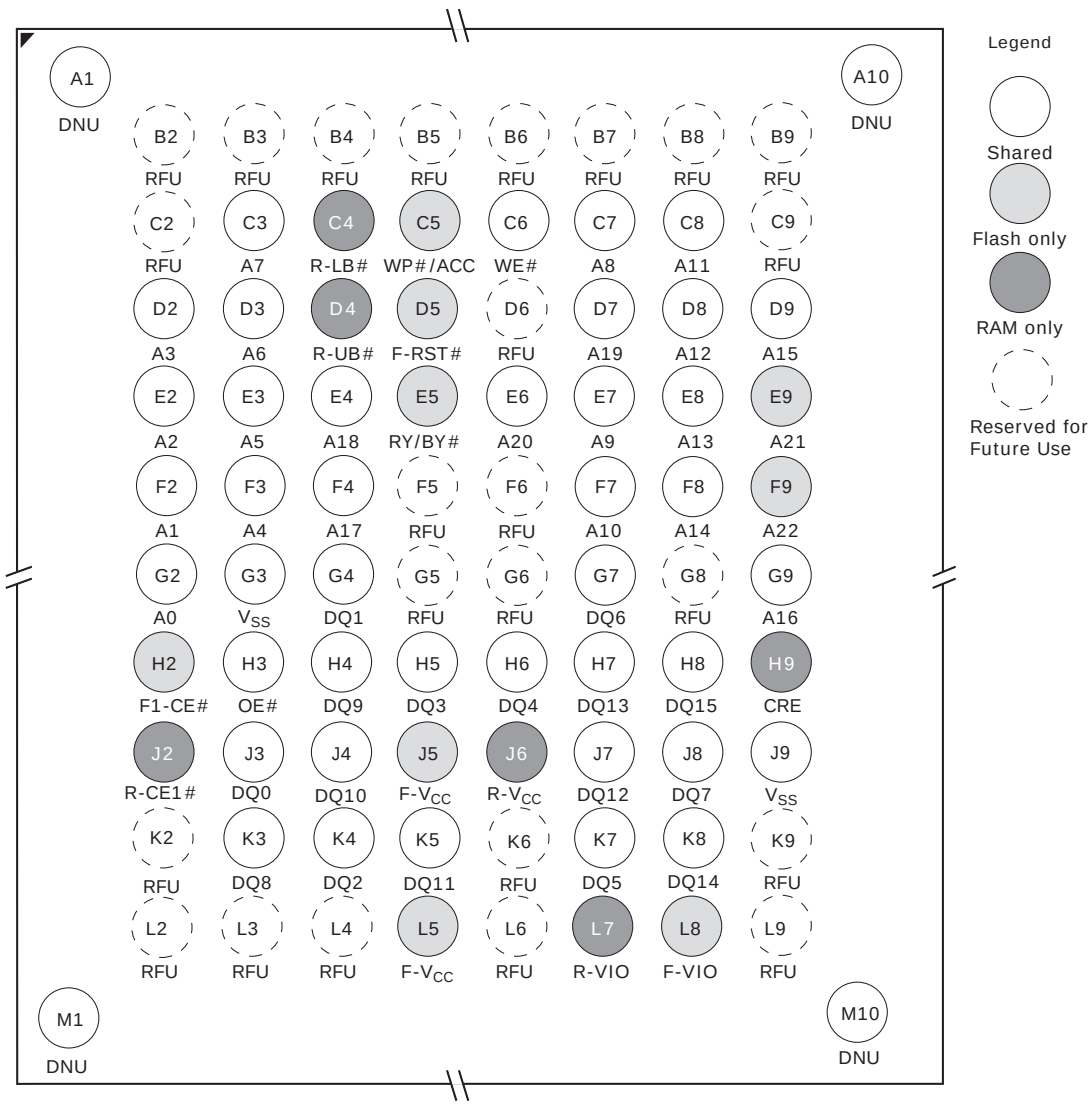
256 Mb Flash + 64 Mb pSRAM Pinout

84-ball Fine-Pitch Ball Grid Array
256 Mb Flash + 64 Mb pSRAM
Pinout
(Top View, Balls Facing Down)



128 Mb Flash + 32 Mb pSRAM Pinout

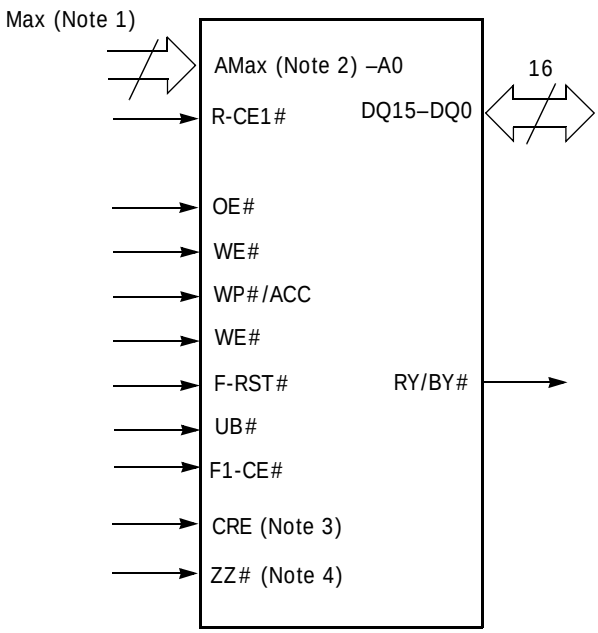
84-ball Fine-Pitch Ball Grid Array
128 Mb Flash + 32 Mb pSRAM
Pinout
(Top View, Balls Facing Down)



Input/Output Descriptions

A23-A0	=	24 Address inputs (256 Mb)
A22-A0	=	23 Address inputs (128 Mb)
DQ15-DQ0	=	Data input/output
OE#	=	Output Enable input. Asynchronous relative to CLK for the Burst mode.
WE#	=	Write Enable input.
V_{SS}	=	Ground
NC	=	No Connect; not connected internally
F-RST#	=	Hardware reset input. Low = device resets and returns to reading array data
WP#/ACC	=	Hardware write protect input / programming acceleration input.
R-CE1#	=	Chip-enable input for pSRAM.
ZZ#	=	pSRAM Sleep mode
CRE	=	Configuration Register Enable. CRE is used only for power savings, but does not enable burst operations.
F1-CE#	=	Chip-enable input for Flash 1.
F-V_{CC}	=	Flash 3.0 Volt-only single power supply.
R-V_{CC}	=	pSRAM Power Supply.
R-UB#	=	Upper Byte Control (pSRAM).
R-LB#	=	Lower Byte Control (pSRAM).
RFU	=	Reserved for future use.
RY/BY#	=	Ready/Busy output.
F-V_{IO}	=	Flash Input/Output Buffer Power Supply
R-V_{IO}	=	pSRAM Input/Output Buffer Power Supply

Logic Symbol

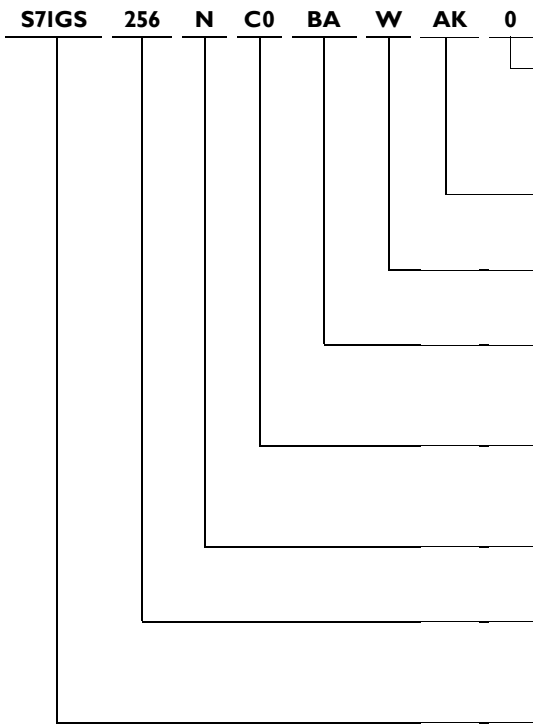


Notes:

1. *Max = 24 [256 Mb Flash], 23 [128 Mb Flash].*
2. *AMax = A23 [256 Mb Flash], A22 [128 Mb Flash].*
3. *CRE is available only in Synchronous pSRAM.*
4. *ZZ# is available only in Asynchronous pSRAM.*

Ordering Information

The order number (Valid Combination) is formed by the following:



PACKING TYPE
0 = Tray
2 = 7” Tape and Reel
3 = 13” Tape and Reel

PACKAGE MODIFIER / MODEL NUMBER
See Valid Combinations table

TEMPERATURE RANGE
W = Wireless (-25°C to +85°C)

PACKAGE TYPE
BA = Very Thin Fine-pitch BGA Lead (Pb)-free compliant package
BF = Very Thin Fine-pitch BGA Lead (Pb)-free package

pSRAM DENSITY
C0 = 64 Mb pSRAM
B0 = 32 Mb pSRAM

PROCESS TECHNOLOGY
N = 110 nm, MirrorBit™ Technology

FLASH DENSITY
256 = 256 Mb
128 = 128 Mb

PRODUCT FAMILY
S71GS Multi-chip Product (MCP)
3.0 Volt-only V_{CC} and 1.8 V V_{IO} Uniform Sector Page Mode Flash Memory with 1.8 Volt pSRAM

S71GS256NC0 Valid Combinations				Flash Initial/Page Speed (ns)	Address Sector Protection	(p)SRAM Supplier	(p)SRAM Type/ Access Time (ns)	Package Type	Package Marking
Base Ordering Part Number	Package & Temperature	Package Modifier/ Model Number	Packing Type						
S71GS256NC0	BAW	AK	0, 2, 3 (Note 1)	110/30	Lowest Add	CellRam 2A (Note 3)	70 / 25	8mmx11.6mm 84-ball Lead (Pb)-free Compliant	(Note 2)
		AP			Highest Add				
S71GS256NC0	BFW	AK			Lowest Add			8mmx11.6mm 84-ball Lead (Pb)-free	
		AP			Highest Add				

Notes:
1. *Type 0 is standard. Specify other options as required.*
2. *BGA package marking omits leading “S” and packing type designator from ordering part number.*
3. *For specifications, refer to the CellularRam 2A module.*

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult your local sales office to confirm availability of specific valid combinations and to check on newly released combinations.

S71GS128NB0 Valid Combinations									
Base Ordering Part Number	Package & Temperature	Package Modifier/ Model Number	Packing Type	Flash Initial/Page Speed (ns)	Address Sector Protection	(p)SRAM Supplier	(p)SRAM Type/ Access Time (ns)	Package Type	Package Marking
S71GS128NB0	BAW	AK	0, 2, 3 (Note 1)	110/30	Lowest Add	CellRam 2 (Note 3)	70 / 25	8mmx11.6mm 84-ball Lead (Pb)-free Compliant	(Note 2)
		AP			Highest Add				
S71GS128NB0	BFW	AK			Lowest Add			8mmx11.6mm 84-ball Lead (Pb)-free	
		AP			Highest Add				

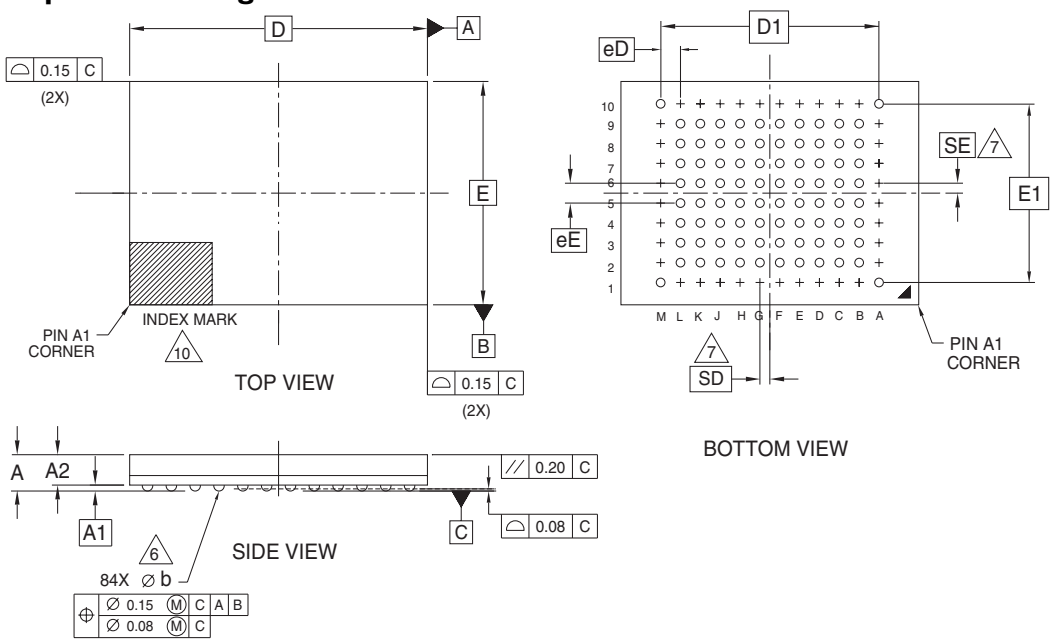
Notes:
1. *Type 0 is standard. Specify other options as required.*
2. *BGA package marking omits leading "S" and packing type designator from ordering part number.*
3. *For specifications, refer to the CellularRam 2 module.*

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult your local sales office to confirm availability of specific valid combinations and to check on newly released combinations.

Physical Dimensions

TLA084—84-ball Fine-Pitch Ball Grid Array (FBGA) 8.0 x 11.6 x1.2 mm MCP Compatible Package



PACKAGE	TLA 084			
JEDEC	N/A			
D x E	11.60 mm x 8.00 mm PACKAGE			
SYMBOL	MIN	NOM	MAX	NOTE
A	---	---	1.20	PROFILE
A1	0.17	---	---	BALL HEIGHT
A2	0.81	---	0.97	BODY THICKNESS
D	11.60 BSC.			BODY SIZE
E	8.00 BSC.			BODY SIZE
D1	8.80 BSC.			MATRIX FOOTPRINT
E1	7.20 BSC.			MATRIX FOOTPRINT
MD	12			MATRIX SIZE D DIRECTION
ME	10			MATRIX SIZE E DIRECTION
n	84			BALL COUNT
Ø b	0.35	0.40	0.45	BALL DIAMETER
eE	0.80 BSC.			BALL PITCH
eD	0.80 BSC			BALL PITCH
SD / SE	0.40 BSC.			SOLDER BALL PLACEMENT
	A2,A3,A4,A5,A6,A7,A8,A9 B1,B10,C1,C10,D1,D10, E1,E10,F1,F10,G1,G10, H1,H10,J1,J10,K1,K10,L1,L10, M2,M3,M4,M5,M6,M7,M8,M9			DEPOPULATED SOLDER BALLS

NOTES:

1. DIMENSIONING AND TOLERANCING METHODS PER ASME Y14.5M-1994.
2. ALL DIMENSIONS ARE IN MILLIMETERS.
3. BALL POSITION DESIGNATION PER JESD 95-1, SPP-010.
4. e REPRESENTS THE SOLDER BALL GRID PITCH.
5. SYMBOL "MD" IS THE BALL MATRIX SIZE IN THE "D" DIRECTION.

   SYMBOL "ME" IS THE BALL MATRIX SIZE IN THE "E" DIRECTION.

   n IS THE NUMBER OF POPULTED SOLDER BALL POSITIONS FOR MATRIX SIZE MD X ME.

6. DIMENSION "b" IS MEASURED AT THE MAXIMUM BALL DIAMETER IN A PLANE PARALLEL TO DATUM C.
7. SD AND SE ARE MEASURED WITH RESPECT TO DATUMS A AND B AND DEFINE THE POSITION OF THE CENTER SOLDER BALL IN THE OUTER ROW.

   WHEN THERE IS AN ODD NUMBER OF SOLDER BALLS IN THE OUTER ROW SD OR SE = 0.000.

   WHEN THERE IS AN EVEN NUMBER OF SOLDER BALLS IN THE OUTER ROW, SD OR SE = e/2

8. "+" INDICATES THE THEORETICAL CENTER OF DEPOPULATED BALLS.
9. N/A
10. A1 CORNER TO BE IDENTIFIED BY CHAMFER, LASER OR INK MARK, METALLIZED MARK INDENTATION OR OTHER MEANS.

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S29GLxxxN MirrorBit™ Flash Family

S29GL512N, S29GL256N, S29GL128N
512 Megabit, 256 Megabit, and 128 Megabit, 3.0 Volt-only Page Mode Flash Memory featuring 110 nm MirrorBit process technology

Data Sheet

ADVANCE INFORMATION

Distinctive Characteristics

Architectural Advantages

- **Single power supply operation**
  - 3 volt read, erase, and program operations
- **Enhanced VersatileI/O™ control**
  - All input levels (address, control, and DQ input levels) and outputs are determined by voltage on V_{IO} input. V_{IO} range is 1.65 to V_{CC}
- **Manufactured on 110 nm MirrorBit process technology**
- **Secured Silicon Sector region**
  - 128-word/256-byte sector for permanent, secure identification through an 8-word/16-byte random Electronic Serial Number, accessible through a command sequence
  - May be programmed and locked at the factory or by the customer
- **Flexible sector architecture**
  - S29GL512N: Five hundred twelve 64 Kword (128 Kbyte) sectors
  - S29GL256N: Two hundred fifty-six 64 Kword (128 Kbyte) sectors
  - S29GL128N: One hundred twenty-eight 64 Kword (128 Kbyte) sectors
- **Compatibility with JEDEC standards**
  - Provides pinout and software compatibility for single-power supply flash, and superior inadvertent write protection
- **100,000 erase cycles per sector typical**
- **20-year data retention typical**

Performance Characteristics

- **High performance**
  - 90 ns access time (S29GL128N, S29GL256N, S29GL512N)
  - 8-word/16-byte page read buffer
  - 25 ns page read times
  - 16-word/32-byte write buffer reduces overall programming time for multiple-word updates
- **Low power consumption (typical values at 3.0 V, 5 MHz)**
  - 25 mA typical active read current;
  - 50 mA typical erase/program current
  - 1 µA typical standby mode current

Software & Hardware Features

- **Software features**
  - Program Suspend & Resume: read other sectors before programming operation is completed
  - Erase Suspend & Resume: read/program other sectors before an erase operation is completed
  - Data# polling & toggle bits provide status
  - Unlock Bypass Program command reduces overall multiple-word programming time
  - CFI (Common Flash Interface) compliant: allows host system to identify and accommodate multiple flash devices
- **Hardware features**
  - Advanced Sector Protection
  - WP#/ACC input accelerates programming time (when high voltage is applied) for greater throughput during system production. Protects first or last sector regardless of sector protection settings
  - Hardware reset input (RESET#) resets device
  - Ready/Busy# output (RY/BY#) detects program or erase cycle completion

Publication Number S29GLxxxN_MCP **Revision** A **Amendment** 1 **Issue Date** December 15, 2004

General Description

The S29GL512/256/128N family of devices are 3.0V single power flash memory manufactured using 110 nm MirrorBit technology. The S29GL512N is a 512 Mbit, organized as 33,554,432 words or 67,108,864 bytes. The S29GL256N is a 256 Mbit, organized as 16,777,216 words or 33,554,432 bytes. The S29GL128N is a 128 Mbit, organized as 8,388,608 words or 16,777,216 bytes. The device can be programmed either in the host system or in standard EPROM programmers.

Access times as fast as 90 ns (S29GL128N, S29GL256N, S29GL512N) are available. Note that each access time has a specific operating voltage range (V_{CC}) and an I/O voltage range (V_{IO}), as specified in the "Product Selector Guide" section. The devices are offered in a 56-pin TSOP or 64-ball Fortified BGA package. Each device has separate chip enable (CE#), write enable (WE#) and output enable (OE#) controls.

Each device requires only a **single 3.0 volt power supply** for both read and write functions. In addition to a V_{CC} input, a high-voltage **accelerated program (**WP#/**ACC)** input provides shorter programming times through increased current. This feature is intended to facilitate factory throughput during system production, but may also be used in the field if desired.

The devices are entirely command set compatible with the **JEDEC single-power-supply Flash standard**. Commands are written to the device using standard microprocessor write timing. Write cycles also internally latch addresses and data needed for the programming and erase operations.

The **sector erase architecture** allows memory sectors to be erased and reprogrammed without affecting the data contents of other sectors. The device is fully erased when shipped from the factory.

Device programming and erasure are initiated through command sequences. Once a program or erase operation has begun, the host system need only poll the DQ7 (Data# Polling) or DQ6 (toggle) **status bits** or monitor the **Ready/Busy# (RY/BY#)** output to determine whether the operation is complete. To facilitate programming, an **Unlock Bypass** mode reduces command sequence overhead by requiring only two write cycles to program data instead of four.

The **Enhanced VersatileI/O™** (V_{IO}) control allows the host system to set the voltage levels that the device generates and tolerates on all input levels (address, chip control, and DQ input levels) to the same voltage level that is asserted on the V_{IO} pin. This allows the device to operate in a 1.8 V or 3 V system environment as required.

Hardware data protection measures include a low V_{CC} detector that automatically inhibits write operations during power transitions. **Persistent Sector Protection** provides in-system, command-enabled protection of any combination of sectors using a single power supply at V_{CC}. **Password Sector Protection** prevents unauthorized write and erase operations in any combination of sectors through a user-defined 64-bit password.

The **Erase Suspend/Erase Resume** feature allows the host system to pause an erase operation in a given sector to read or program any other sector and then complete the erase operation. The **Program Suspend/Program Resume** feature enables the host system to pause a program operation in a given sector to read any other sector and then complete the program operation.

The **hardware RESET# pin** terminates any operation in progress and resets the device, after which it is then ready for a new operation. The RESET# pin may be

tied to the system reset circuitry. A system reset would thus also reset the device, enabling the host system to read boot-up firmware from the Flash memory device.

The device reduces power consumption in the **standby mode** when it detects specific voltage levels on CE# and RESET#, or when addresses have been stable for a specified period of time.

The **Secured Silicon Sector** provides a 128-word/256-byte area for code or data that can be permanently protected. Once this sector is protected, no further changes within the sector can occur.

The **Write Protect (WP#/ACC)** feature protects the first or last sector by asserting a logic low on the WP# pin.

MirrorBit flash technology combines years of Flash memory manufacturing experience to produce the highest levels of quality, reliability and cost effectiveness. The device electrically erases all bits within a sector simultaneously via hot-hole assisted erase. The data is programmed using hot electron injection.

Product Selector Guide

S29GL5I2N

Part Number			S29GL512N			
Speed Option	V_{CC} = 2.7–3.6 V	V_{IO} = 2.7–3.6 V		**10**	**11**	
		V_{IO} = 1.65–1.95 V				**11**
	V_{CC} = 3.0-3.6V	V_{IO} = 3.0-3.6V	**90**			
Max. Access Time (ns)			90	100	110	110
Max. CE# Access Time (ns)			90	100	110	110
Max. Page access time (ns)			25	25	25	30
Max. OE# Access Time (ns)			25	25	25	30

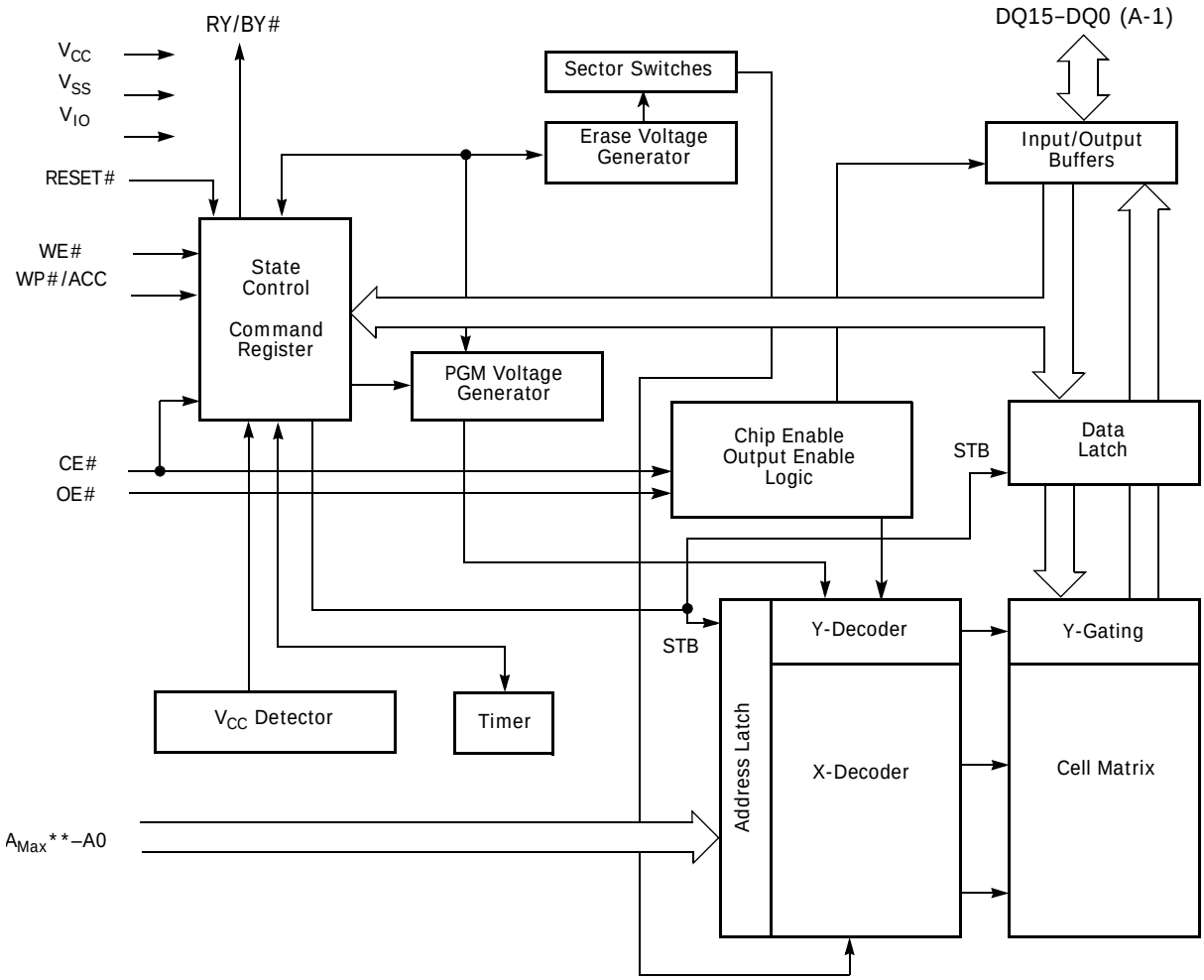
S29GL256N

Part Number		S29GL256N				
Speed Option	V_{CC} = 2.7–3.6 V	V_{IO} = 2.7–3.6 V		**10**	**11**	
		V_{IO} = 1.65–1.95 V				**11**
	V_{CC} = Regulated (3.0-3.6V)	V_{IO} = Regulated (3.0-3.6V)	**90**			
Max. Access Time (ns)			90	100	110	110
Max. CE# Access Time (ns)			90	100	110	110
Max. Page access time (ns)			25	25	25	30
Max. OE# Access Time (ns)			25	25	25	30

S29GLI28N

Part Number		S29GL128N				
Speed Option	V_{CC} = 2.7–3.6 V	V_{IO} = 2.7–3.6 V		**10**	**11**	
		V_{IO} = 1.65–1.95 V				**11**
	V_{CC} = Regulated (3.0-3.6V)	V_{IO} = Regulated (3.0-3.6V)	**90**			
Max. Access Time (ns)			90	100	110	110
Max. CE# Access Time (ns)			90	100	110	110
Max. Page access time (ns)			25	25	25	30
Max. OE# Access Time (ns)			25	25	25	30

Block Diagram



Notes:

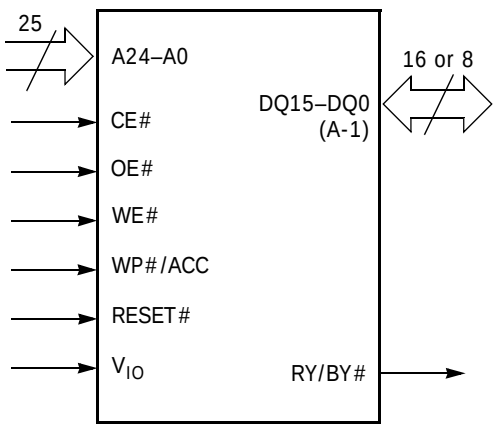
1. *A_{Max} GL512N = A24, A_{Max} GL256N = A23, A_{Max} GL128N = A22*

Pin Description

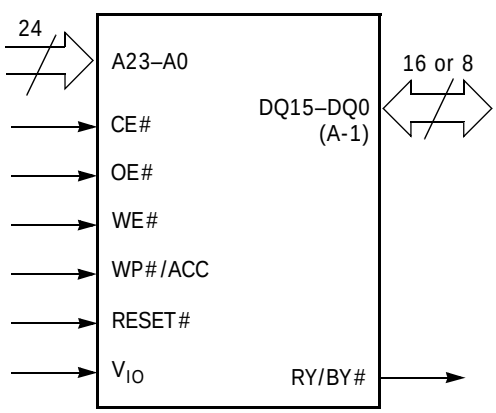
A24–A0	=	25 Address inputs (512 Mb)
A23–A0	=	24 Address inputs (256 Mb)
A22–A0	=	23 Address inputs (128 Mb)
DQ14–DQ0	=	15 Data inputs/outputs
DQ15/A-1	=	DQ15 (Data input/output, word mode), A-1 (LSB Address input
CE#	=	Chip Enable input
OE#	=	Output Enable input
WE#	=	Write Enable input
WP#/ACC	=	Hardware Write Protect input; Acceleration input
RESET#	=	Hardware Reset Pin input
RY/BY#	=	Ready/Busy output
V_{CC}	=	3.0 volt-only single power supply (see Product Selector Guide for speed options and voltage supply tolerances)
V_{IO}	=	Output Buffer power
V_{SS}	=	Device Ground
NC	=	Pin Not Connected Internally

Logic Symbol

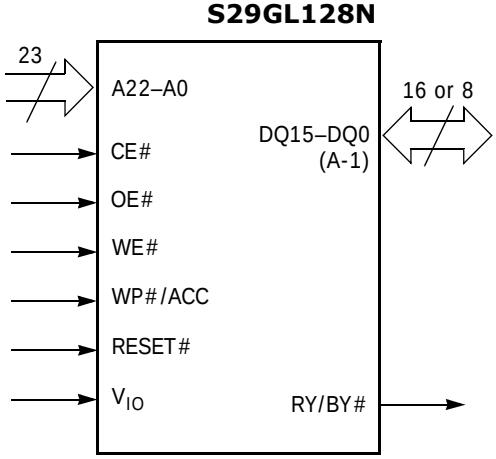
S29GL512N



S29GL256N



S29GL128N



Device Bus Operations

This section describes the requirements and use of the device bus operations, which are initiated through the internal command register. The command register itself does not occupy any addressable memory location. The register is a latch used to store the commands, along with the address and data information needed to execute the command. The contents of the register serve as inputs to the internal state machine. The state machine outputs dictate the function of the device. Table 1 lists the device bus operations, the inputs and control levels they require, and the resulting output. The following subsections describe each of these operations in further detail.

Table I. Device Bus Operations

Operation	CE#	OE#	WE#	RESET#	WP#/ ACC	Addresses (Note 1)	DQ0–DQ15
Read	L	L	H	H	X	A_{IN}	D_{OUT}
Write (Program/Erase)	L	H	L	H	Note 2	A_{IN}	(Note 3)
Accelerated Program	L	H	L	H	V_{HH}	A_{IN}	(Note 3)
Standby	V_{CC} ± 0.3 V	X	X	V_{CC} ± 0.3 V	H	X	High-Z
Output Disable	L	H	H	H	X	X	High-Z
Reset	X	X	X	L	X	X	High-Z

Legend: *L = Logic Low = V_{IL}, H = Logic High = V_{IH}, V_{ID} = 11.5–12.5 V, V_{HH} = 11.5–12.5V, X = Don't Care, SA = Sector Address, A_{IN} = Address In, D_{IN} = Data In, D_{OUT} = Data Out*

Notes:

1. *Addresses are AMax:A0 in word mode. Sector addresses are A_{Max}:A16 in both modes.*
2. *If WP# = V_{IL}, the first or last sector group remains protected. If WP# = V_{IH}, the first or last sector will be protected or unprotected as determined by the method described in "Write Protect (WP#)". All sectors are unprotected when shipped from the factory (The Secured Silicon Sector may be factory protected depending on version ordered.)*
3. *D_{IN} or D_{OUT} as required by command sequence, data polling, or sector protect algorithm (see Figure 2, Figure 4, and Figure 5).*

VersatileIO™ (V_{IO}) Control

The **VersatileIO**™ (V_{IO}) control allows the host system to set the voltage levels that the device generates and tolerates on CE# and DQ I/Os to the same voltage level that is asserted on V_{IO}. See Ordering Information for V_{IO} options on this device.

For example, a $V_{I/O}$ of 1.65 V to 3.6 V allows for I/O at the 1.8 or 3 volt levels, driving and receiving signals to and from other 1.8-V or 3-V devices on the same data bus.

Requirements for Reading Array Data

To read array data from the outputs, the system must drive the CE# and OE# pins to V_{IL}. CE# is the power control and selects the device. OE# is the output control and gates array data to the output pins. WE# should remain at V_{IH}.

The internal state machine is set for reading array data upon device power-up, or after a hardware reset. This ensures that no spurious alteration of the memory

content occurs during the power transition. No command is necessary in this mode to obtain array data. Standard microprocessor read cycles that assert valid addresses on the device address inputs produce valid data on the device data outputs. The device remains enabled for read access until the command register contents are altered.

See "Reading Array Data" on page 66 for more information. Refer to the AC Read-Only Operations table for timing specifications and to Figure 11 for the timing diagram. Refer to the DC Characteristics table for the active current specification on reading array data.

Page Mode Read

The device is capable of fast page mode read and is compatible with the page mode Mask ROM read operation. This mode provides faster read access speed for random locations within a page. The page size of the device is 8 words/16 bytes. The appropriate page is selected by the higher address bits A(max)–A3. Address bits A2–A0 determine the specific word within a page. This is an asynchronous operation; the microprocessor supplies the specific word location.

The random or initial page access is equal to t_{ACC} or t_{CE} and subsequent page read accesses (as long as the locations specified by the microprocessor falls within that page) is equivalent to t_{PACC}. When CE# is de-asserted and reasserted for a subsequent access, the access time is t_{ACC} or t_{CE}. Fast page mode accesses are obtained by keeping the "read-page addresses" constant and changing the "intra-read page" addresses.

Writing Commands/Command Sequences

To write a command or command sequence (which includes programming data to the device and erasing sectors of memory), the system must drive WE# and CE# to V_{IL}, and OE# to V_{IH}.

The device features an **Unlock Bypass** mode to facilitate faster programming. Once the device enters the Unlock Bypass mode, only two write cycles are required to program a word or byte, instead of four. The "Word Program Command Sequence" section has details on programming data to the device using both standard and Unlock Bypass command sequences.

An erase operation can erase one sector, multiple sectors, or the entire device. Table 2, Table 4, and Table 5 indicate the address space that each sector occupies.

Refer to the DC Characteristics table for the active current specification for the write mode. The AC Characteristics section contains timing specification tables and timing diagrams for write operations.

Write Buffer

Write Buffer Programming allows the system write to a maximum of 16 words/32 bytes in one programming operation. This results in faster effective programming time than the standard programming algorithms. See "Write Buffer" for more information.

Accelerated Program Operation

The device offers accelerated program operations through the ACC function. This is one of two functions provided by the WP#/ACC pin. This function is primarily intended to allow faster manufacturing throughput at the factory.

If the system asserts V_{HH} on this pin, the device automatically enters the aforementioned Unlock Bypass mode, temporarily unprotects any protected sector groups, and uses the higher voltage on the pin to reduce the time required for program operations. The system would use a two-cycle program command sequence as required by the Unlock Bypass mode. Removing V_{HH} from the WP#/ACC pin returns the device to normal operation. *Note that the WP#/ACC pin must not be at V_{HH} for operations other than accelerated programming, or device damage may result. WP# has an internal pullup; when unconnected, WP# is at V_{IH}.*

Autoselect Functions

If the system writes the autoselect command sequence, the device enters the autoselect mode. The system can then read autoselect codes from the internal register (which is separate from the memory array) on DQ7–DQ0. Standard read cycle timings apply in this mode. Refer to the "Autoselect Mode" section on page 52 and "Autoselect Command Sequence" section on page 66 sections for more information.

Standby Mode

When the system is not reading or writing to the device, it can place the device in the standby mode. In this mode, current consumption is greatly reduced, and the outputs are placed in the high impedance state, independent of the OE# input.

The device enters the CMOS standby mode when the CE# and RESET# pins are both held at $V_{IO} \pm 0.3$ V. (Note that this is a more restricted voltage range than V_{IH}.) If CE# and RESET# are held at V_{IH}, but not within $V_{IO} \pm 0.3$ V, the device will be in the standby mode, but the standby current will be greater. The device requires standard access time (t_{CE}) for read access when the device is in either of these standby modes, before it is ready to read data.

If the device is deselected during erasure or programming, the device draws active current until the operation is completed.

Refer to the "DC Characteristics" section on page 90 for the standby current specification.

Automatic Sleep Mode

The automatic sleep mode minimizes Flash device energy consumption. The device automatically enables this mode when addresses remain stable for t_{ACC} + 30 ns. The automatic sleep mode is independent of the CE#, WE#, and OE# control signals. Standard address access timings provide new data when addresses are changed. While in sleep mode, output data is latched and always available to the system. Refer to the "DC Characteristics" section on page 90 for the automatic sleep mode current specification.

RESET#: Hardware Reset Pin

The RESET# pin provides a hardware method of resetting the device to reading array data. When the RESET# pin is driven low for at least a period of t_{RP}, the device immediately terminates any operation in progress, tristates all output pins, and ignores all read/write commands for the duration of the RESET# pulse. The device also resets the internal state machine to reading array data. The operation that was interrupted should be reinitiated once the device is ready to accept another command sequence, to ensure data integrity.

Current is reduced for the duration of the RESET# pulse. When RESET# is held at V_{SS}±0.3 V, the device draws CMOS standby current (I_{CC5}). If RESET# is held at V_{IL} but not within V_{SS}±0.3 V, the standby current will be greater.

The RESET# pin may be tied to the system reset circuitry. A system reset would thus also reset the Flash memory, enabling the system to read the boot-up firmware from the Flash memory.

Refer to the AC Characteristics tables for RESET# parameters and to Figure 13 for the timing diagram.

Output Disable Mode

When the OE# input is at V_{IH}, output from the device is disabled. The output pins are placed in the high impedance state.

Table 2. Sector Address Table–S29GL5I2N

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA0	0	0	0	0	0	0	0	0	0	128/64	0000000–000FFFF
SA1	0	0	0	0	0	0	0	0	1	128/64	0010000–001FFFF
SA2	0	0	0	0	0	0	0	1	0	128/64	0020000–002FFFF
SA3	0	0	0	0	0	0	0	1	1	128/64	0030000–003FFFF
SA4	0	0	0	0	0	0	1	0	0	128/64	0040000–004FFFF
SA5	0	0	0	0	0	0	1	0	1	128/64	0050000–005FFFF
SA6	0	0	0	0	0	0	1	1	0	128/64	0060000–006FFFF
SA7	0	0	0	0	0	0	1	1	1	128/64	0070000–007FFFF
SA8	0	0	0	0	0	1	0	0	0	128/64	0080000–008FFFF
SA9	0	0	0	0	0	1	0	0	1	128/64	0090000–009FFFF
SA10	0	0	0	0	0	1	0	1	0	128/64	00A0000–00AFFFF
SA11	0	0	0	0	0	1	0	1	1	128/64	00B0000–00BFFFF
SA12	0	0	0	0	0	1	1	0	0	128/64	00C0000–00CFFFF
SA13	0	0	0	0	0	1	1	0	1	128/64	00D0000–00DFFFF
SA14	0	0	0	0	0	1	1	1	0	128/64	00E0000–00EFFFF
SA15	0	0	0	0	0	1	1	1	1	128/64	00F0000–00FFFFF
SA16	0	0	0	0	1	0	0	0	0	128/64	0100000–010FFFF
SA17	0	0	0	0	1	0	0	0	1	128/64	0110000–011FFFF
SA18	0	0	0	0	1	0	0	1	0	128/64	0120000–012FFFF
SA19	0	0	0	0	1	0	0	1	1	128/64	0130000–013FFFF
SA20	0	0	0	0	1	0	1	0	0	128/64	0140000–014FFFF
SA21	0	0	0	0	1	0	1	0	1	128/64	0150000–015FFFF
SA22	0	0	0	0	1	0	1	1	0	128/64	0160000–016FFFF
SA23	0	0	0	0	1	0	1	1	1	128/64	0170000–017FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA24	0	0	0	0	1	1	0	0	0	128/64	0180000–018FFFF
SA25	0	0	0	0	1	1	0	0	1	128/64	0190000–019FFFF
SA26	0	0	0	0	1	1	0	1	0	128/64	01A0000–01AFFFF
SA27	0	0	0	0	1	1	0	1	1	128/64	01B0000–01BFFFF
SA28	0	0	0	0	1	1	1	0	0	128/64	01C0000–01CFFFF
SA29	0	0	0	0	1	1	1	0	1	128/64	01D0000–01DFFFF
SA30	0	0	0	0	1	1	1	1	0	128/64	01E0000–01EFFFF
SA31	0	0	0	0	1	1	1	1	1	128/64	01F0000–01FFFFF
SA32	0	0	0	1	0	0	0	0	0	128/64	0200000–020FFFF
SA33	0	0	0	1	0	0	0	0	1	128/64	0210000–021FFFF
SA34	0	0	0	1	0	0	0	1	0	128/64	0220000–022FFFF
SA35	0	0	0	1	0	0	0	1	1	128/64	0230000–023FFFF
SA36	0	0	0	1	0	0	1	0	0	128/64	0240000–024FFFF
SA37	0	0	0	1	0	0	1	0	1	128/64	0250000–025FFFF
SA38	0	0	0	1	0	0	1	1	0	128/64	0260000–026FFFF
SA39	0	0	0	1	0	0	1	1	1	128/64	0270000–027FFFF
SA40	0	0	0	1	0	1	0	0	0	128/64	0280000–028FFFF
SA41	0	0	0	1	0	1	0	0	1	128/64	0290000–029FFFF
SA42	0	0	0	1	0	1	0	1	0	128/64	02A0000–02AFFFF
SA43	0	0	0	1	0	1	0	1	1	128/64	02B0000–02BFFFF
SA44	0	0	0	1	0	1	1	0	0	128/64	02C0000–02CFFFF
SA45	0	0	0	1	0	1	1	0	1	128/64	02D0000–02DFFFF
SA46	0	0	0	1	0	1	1	1	0	128/64	02E0000–02EFFFF
SA47	0	0	0	1	0	1	1	1	1	128/64	02F0000–02FFFFF
SA48	0	0	0	1	1	0	0	0	0	128/64	0300000–030FFFF
SA49	0	0	0	1	1	0	0	0	1	128/64	0310000–031FFFF
SA50	0	0	0	1	1	0	0	1	0	128/64	0320000–032FFFF
SA51	0	0	0	1	1	0	0	1	1	128/64	0330000–033FFFF
SA52	0	0	0	1	1	0	1	0	0	128/64	0340000–034FFFF
SA53	0	0	0	1	1	0	1	0	1	128/64	0350000–035FFFF
SA54	0	0	0	1	1	0	1	1	0	128/64	0360000–036FFFF
SA55	0	0	0	1	1	0	1	1	1	128/64	0370000–037FFFF
SA56	0	0	0	1	1	1	0	0	0	128/64	0380000–038FFFF
SA57	0	0	0	1	1	1	0	0	1	128/64	0390000–039FFFF
SA58	0	0	0	1	1	1	0	1	0	128/64	03A0000–03AFFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA59	0	0	0	1	1	1	0	1	1	128/64	03B0000–03BFFFF
SA60	0	0	0	1	1	1	1	0	0	128/64	03C0000–03CFFFF
SA61	0	0	0	1	1	1	1	0	1	128/64	03D0000–03DFFFF
SA62	0	0	0	1	1	1	1	1	0	128/64	03E0000–03EFFFF
SA63	0	0	0	1	1	1	1	1	1	128/64	03F0000–03FFFFF
SA64	0	0	1	0	0	0	0	0	0	128/64	0400000–040FFFF
SA65	0	0	1	0	0	0	0	0	1	128/64	0410000–041FFFF
SA66	0	0	1	0	0	0	0	1	0	128/64	0420000–042FFFF
SA67	0	0	1	0	0	0	0	1	1	128/64	0430000–043FFFF
SA68	0	0	1	0	0	0	1	0	0	128/64	0440000–044FFFF
SA69	0	0	1	0	0	0	1	0	1	128/64	0450000–045FFFF
SA70	0	0	1	0	0	0	1	1	0	128/64	0460000–046FFFF
SA71	0	0	1	0	0	0	1	1	1	128/64	0470000–047FFFF
SA72	0	0	1	0	0	1	0	0	0	128/64	0480000–048FFFF
SA73	0	0	1	0	0	1	0	0	1	128/64	0490000–049FFFF
SA74	0	0	1	0	0	1	0	1	0	128/64	04A0000–04AFFFF
SA75	0	0	1	0	0	1	0	1	1	128/64	04B0000–04BFFFF
SA76	0	0	1	0	0	1	1	0	0	128/64	04C0000–04CFFFF
SA77	0	0	1	0	0	1	1	0	1	128/64	04D0000–04DFFFF
SA78	0	0	1	0	0	1	1	1	0	128/64	04E0000–04EFFFF
SA79	0	0	1	0	0	1	1	1	1	128/64	04F0000–04FFFFF
SA80	0	0	1	0	1	0	0	0	0	128/64	0500000–050FFFF
SA81	0	0	1	0	1	0	0	0	1	128/64	0510000–051FFFF
SA82	0	0	1	0	1	0	0	1	0	128/64	0520000–052FFFF
SA83	0	0	1	0	1	0	0	1	1	128/64	0530000–053FFFF
SA84	0	0	1	0	1	0	1	0	0	128/64	0540000–054FFFF
SA85	0	0	1	0	1	0	1	0	1	128/64	0550000–055FFFF
SA86	0	0	1	0	1	0	1	1	0	128/64	0560000–056FFFF
SA87	0	0	1	0	1	0	1	1	1	128/64	0570000–057FFFF
SA88	0	0	1	0	1	1	0	0	0	128/64	0580000–058FFFF
SA89	0	0	1	0	1	1	0	0	1	128/64	0590000–059FFFF
SA90	0	0	1	0	1	1	0	1	0	128/64	05A0000–05AFFFF
SA91	0	0	1	0	1	1	0	1	1	128/64	05B0000–05BFFFF
SA92	0	0	1	0	1	1	1	0	0	128/64	05C0000–05CFFFF
SA93	0	0	1	0	1	1	1	0	1	128/64	05D0000–05DFFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA94	0	0	1	0	1	1	1	1	0	128/64	05E0000–05EFFFF
SA95	0	0	1	0	1	1	1	1	1	128/64	05F0000–05FFFFF
SA96	0	0	1	1	0	0	0	0	0	128/64	0600000–060FFFF
SA97	0	0	1	1	0	0	0	0	1	128/64	0610000–061FFFF
SA98	0	0	1	1	0	0	0	1	0	128/64	0620000–062FFFF
SA99	0	0	1	1	0	0	0	1	1	128/64	0630000–063FFFF
SA100	0	0	1	1	0	0	1	0	0	128/64	0640000–064FFFF
SA101	0	0	1	1	0	0	1	0	1	128/64	0650000–065FFFF
SA102	0	0	1	1	0	0	1	1	0	128/64	0660000–066FFFF
SA103	0	0	1	1	0	0	1	1	1	128/64	0670000–067FFFF
SA104	0	0	1	1	0	1	0	0	0	128/64	0680000–068FFFF
SA105	0	0	1	1	0	1	0	0	1	128/64	0690000–069FFFF
SA106	0	0	1	1	0	1	0	1	0	128/64	06A0000–06AFFFF
SA107	0	0	1	1	0	1	0	1	1	128/64	06B0000–06BFFFF
SA108	0	0	1	1	0	1	1	0	0	128/64	06C0000–06CFFFF
SA109	0	0	1	1	0	1	1	0	1	128/64	06D0000–06DFFFF
SA110	0	0	1	1	0	1	1	1	0	128/64	06E0000–06EFFFF
SA111	0	0	1	1	0	1	1	1	1	128/64	06F0000–06FFFFF
SA112	0	0	1	1	1	0	0	0	0	128/64	0700000–070FFFF
SA113	0	0	1	1	1	0	0	0	1	128/64	0710000–071FFFF
SA114	0	0	1	1	1	0	0	1	0	128/64	0720000–072FFFF
SA115	0	0	1	1	1	0	0	1	1	128/64	0730000–073FFFF
SA116	0	0	1	1	1	0	1	0	0	128/64	0740000–074FFFF
SA117	0	0	1	1	1	0	1	0	1	128/64	0750000–075FFFF
SA118	0	0	1	1	1	0	1	1	0	128/64	0760000–076FFFF
SA119	0	0	1	1	1	0	1	1	1	128/64	0770000–077FFFF
SA120	0	0	1	1	1	1	0	0	0	128/64	0780000–078FFFF
SA121	0	0	1	1	1	1	0	0	1	128/64	0790000–079FFFF
SA122	0	0	1	1	1	1	0	1	0	128/64	07A0000–07AFFFF
SA123	0	0	1	1	1	1	0	1	1	128/64	07B0000–07BFFFF
SA124	0	0	1	1	1	1	1	0	0	128/64	07C0000–07CFFFF
SA125	0	0	1	1	1	1	1	0	1	128/64	07D0000–07DFFFF
SA126	0	0	1	1	1	1	1	1	0	128/64	07E0000–07EFFFF
SA127	0	0	1	1	1	1	1	1	1	128/64	07F0000–07FFFFF
SA128	0	1	0	0	0	0	0	0	0	128/64	0800000–080FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA129	0	1	0	0	0	0	0	0	1	128/64	0810000–081FFFF
SA130	0	1	0	0	0	0	0	1	0	128/64	0820000–082FFFF
SA131	0	1	0	0	0	0	0	1	1	128/64	0830000–083FFFF
SA132	0	1	0	0	0	0	1	0	0	128/64	0840000–084FFFF
SA133	0	1	0	0	0	0	1	0	1	128/64	0850000–085FFFF
SA134	0	1	0	0	0	0	1	1	0	128/64	0860000–086FFFF
SA135	0	1	0	0	0	0	1	1	1	128/64	0870000–087FFFF
SA136	0	1	0	0	0	1	0	0	0	128/64	0880000–088FFFF
SA137	0	1	0	0	0	1	0	0	1	128/64	0890000–089FFFF
SA138	0	1	0	0	0	1	0	1	0	128/64	08A0000–08AFFFF
SA139	0	1	0	0	0	1	0	1	1	128/64	08B0000–08BFFFF
SA140	0	1	0	0	0	1	1	0	0	128/64	08C0000–08CFFFF
SA141	0	1	0	0	0	1	1	0	1	128/64	08D0000–08DFFFF
SA142	0	1	0	0	0	1	1	1	0	128/64	08E0000–08EFFFF
SA143	0	1	0	0	0	1	1	1	1	128/64	08F0000–08FFFFF
SA144	0	1	0	0	1	0	0	0	0	128/64	0900000–090FFFF
SA145	0	1	0	0	1	0	0	0	1	128/64	0910000–091FFFF
SA146	0	1	0	0	1	0	0	1	0	128/64	0920000–092FFFF
SA147	0	1	0	0	1	0	0	1	1	128/64	0930000–093FFFF
SA148	0	1	0	0	1	0	1	0	0	128/64	0940000–094FFFF
SA149	0	1	0	0	1	0	1	0	1	128/64	0950000–095FFFF
SA150	0	1	0	0	1	0	1	1	0	128/64	0960000–096FFFF
SA151	0	1	0	0	1	0	1	1	1	128/64	0970000–097FFFF
SA152	0	1	0	0	1	1	0	0	0	128/64	0980000–098FFFF
SA153	0	1	0	0	1	1	0	0	1	128/64	0990000–099FFFF
SA154	0	1	0	0	1	1	0	1	0	128/64	09A0000–09AFFFF
SA155	0	1	0	0	1	1	0	1	1	128/64	09B0000–09BFFFF
SA156	0	1	0	0	1	1	1	0	0	128/64	09C0000–09CFFFF
SA157	0	1	0	0	1	1	1	0	1	128/64	09D0000–09DFFFF
SA158	0	1	0	0	1	1	1	1	0	128/64	09E0000–09EFFFF
SA159	0	1	0	0	1	1	1	1	1	128/64	09F0000–09FFFFF
SA160	0	1	0	1	0	0	0	0	0	128/64	0A00000–0A0FFFF
SA161	0	1	0	1	0	0	0	0	1	128/64	0A10000–0A1FFFF
SA162	0	1	0	1	0	0	0	1	0	128/64	0A20000–0A2FFFF
SA163	0	1	0	1	0	0	0	1	1	128/64	0A30000–0A3FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA164	0	1	0	1	0	0	1	0	0	128/64	0A40000–0A4FFFF
SA165	0	1	0	1	0	0	1	0	1	128/64	0A50000–0A5FFFF
SA166	0	1	0	1	0	0	1	1	0	128/64	0A60000–0A6FFFF
SA167	0	1	0	1	0	0	1	1	1	128/64	0A70000–0A7FFFF
SA168	0	1	0	1	0	1	0	0	0	128/64	0A80000–0A8FFFF
SA169	0	1	0	1	0	1	0	0	1	128/64	0A90000–0A9FFFF
SA170	0	1	0	1	0	1	0	1	0	128/64	0AA0000–0AAFFFF
SA171	0	1	0	1	0	1	0	1	1	128/64	0AB0000–0ABFFFF
SA172	0	1	0	1	0	1	1	0	0	128/64	0AC0000–0ACFFFF
SA173	0	1	0	1	0	1	1	0	1	128/64	0AD0000–0ADFFFF
SA174	0	1	0	1	0	1	1	1	0	128/64	0AE0000–0AEFFFF
SA175	0	1	0	1	0	1	1	1	1	128/64	0AF0000–0AFFFFF
SA176	0	1	0	1	1	0	0	0	0	128/64	0B00000–0B0FFFF
SA177	0	1	0	1	1	0	0	0	1	128/64	0B10000–0B1FFFF
SA178	0	1	0	1	1	0	0	1	0	128/64	0B20000–0B2FFFF
SA179	0	1	0	1	1	0	0	1	1	128/64	0B30000–0B3FFFF
SA180	0	1	0	1	1	0	1	0	0	128/64	0B40000–0B4FFFF
SA181	0	1	0	1	1	0	1	0	1	128/64	0B50000–0B5FFFF
SA182	0	1	0	1	1	0	1	1	0	128/64	0B60000–0B6FFFF
SA183	0	1	0	1	1	0	1	1	1	128/64	0B70000–0B7FFFF
SA184	0	1	0	1	1	1	0	0	0	128/64	0B80000–0B8FFFF
SA185	0	1	0	1	1	1	0	0	1	128/64	0B90000–0B9FFFF
SA186	0	1	0	1	1	1	0	1	0	128/64	0BA0000–0BAFFFF
SA187	0	1	0	1	1	1	0	1	1	128/64	0BB0000–0BBFFFF
SA188	0	1	0	1	1	1	1	0	0	128/64	0BC0000–0BCFFFF
SA189	0	1	0	1	1	1	1	0	1	128/64	0BD0000–0BDFFFF
SA190	0	1	0	1	1	1	1	1	0	128/64	0BE0000–0BEFFFF
SA191	0	1	0	1	1	1	1	1	1	128/64	0BF0000–0BFFFFF
SA192	0	1	1	0	0	0	0	0	0	128/64	0C00000–0C0FFFF
SA193	0	1	1	0	0	0	0	0	1	128/64	0C10000–0C1FFFF
SA194	0	1	1	0	0	0	0	1	0	128/64	0C20000–0C2FFFF
SA195	0	1	1	0	0	0	0	1	1	128/64	0C30000–0C3FFFF
SA196	0	1	1	0	0	0	1	0	0	128/64	0C40000–0C4FFFF
SA197	0	1	1	0	0	0	1	0	1	128/64	0C50000–0C5FFFF
SA198	0	1	1	0	0	0	1	1	0	128/64	0C60000–0C6FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA199	0	1	1	0	0	0	1	1	1	128/64	0C70000–0C7FFFF
SA200	0	1	1	0	0	1	0	0	0	128/64	0C80000–0C8FFFF
SA201	0	1	1	0	0	1	0	0	1	128/64	0C90000–0C9FFFF
SA202	0	1	1	0	0	1	0	1	0	128/64	0CA0000–0CAFFFF
SA203	0	1	1	0	0	1	0	1	1	128/64	0CB0000–0CBFFFF
SA204	0	1	1	0	0	1	1	0	0	128/64	0CC0000–0CCFFFF
SA205	0	1	1	0	0	1	1	0	1	128/64	0CD0000–0CDFFFF
SA206	0	1	1	0	0	1	1	1	0	128/64	0CE0000–0CEFFFF
SA207	0	1	1	0	0	1	1	1	1	128/64	0CF0000–0CFFFFF
SA208	0	1	1	0	1	0	0	0	0	128/64	0D00000–0D0FFFF
SA209	0	1	1	0	1	0	0	0	1	128/64	0D10000–0D1FFFF
SA210	0	1	1	0	1	0	0	1	0	128/64	0D20000–0D2FFFF
SA211	0	1	1	0	1	0	0	1	1	128/64	0D30000–0D3FFFF
SA212	0	1	1	0	1	0	1	0	0	128/64	0D40000–0D4FFFF
SA213	0	1	1	0	1	0	1	0	1	128/64	0D50000–0D5FFFF
SA214	0	1	1	0	1	0	1	1	0	128/64	0D60000–0D6FFFF
SA215	0	1	1	0	1	0	1	1	1	128/64	0D70000–0D7FFFF
SA216	0	1	1	0	1	1	0	0	0	128/64	0D80000–0D8FFFF
SA217	0	1	1	0	1	1	0	0	1	128/64	0D90000–0D9FFFF
SA218	0	1	1	0	1	1	0	1	0	128/64	0DA0000–0DAFFFF
SA219	0	1	1	0	1	1	0	1	1	128/64	0DB0000–0DBFFFF
SA220	0	1	1	0	1	1	1	0	0	128/64	0DC0000–0DCFFFF
SA221	0	1	1	0	1	1	1	0	1	128/64	0DD0000–0DDFFFF
SA222	0	1	1	0	1	1	1	1	0	128/64	0DE0000–0DEFFFF
SA223	0	1	1	0	1	1	1	1	1	128/64	0DF0000–0DFFFFF
SA224	0	1	1	1	0	0	0	0	0	128/64	0E00000–0E0FFFF
SA225	0	1	1	1	0	0	0	0	1	128/64	0E10000–0E1FFFF
SA226	0	1	1	1	0	0	0	1	0	128/64	0E20000–0E2FFFF
SA227	0	1	1	1	0	0	0	1	1	128/64	0E30000–0E3FFFF
SA228	0	1	1	1	0	0	1	0	0	128/64	0E40000–0E4FFFF
SA229	0	1	1	1	0	0	1	0	1	128/64	0E50000–0E5FFFF
SA230	0	1	1	1	0	0	1	1	0	128/64	0E60000–0E6FFFF
SA231	0	1	1	1	0	0	1	1	1	128/64	0E70000–0E7FFFF
SA232	0	1	1	1	0	1	0	0	0	128/64	0E80000–0E8FFFF
SA233	0	1	1	1	0	1	0	0	1	128/64	0E90000–0E9FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA234	0	1	1	1	0	1	0	1	0	128/64	0EA0000–0EAFFFF
SA235	0	1	1	1	0	1	0	1	1	128/64	0EB0000–0EBFFFF
SA236	0	1	1	1	0	1	1	0	0	128/64	0EC0000–0ECFFFF
SA237	0	1	1	1	0	1	1	0	1	128/64	0ED0000–0EDFFFF
SA238	0	1	1	1	0	1	1	1	0	128/64	0EE0000–0EEFFFF
SA239	0	1	1	1	0	1	1	1	1	128/64	0EF0000–0EFFFFF
SA240	0	1	1	1	1	0	0	0	0	128/64	0F00000–0F0FFFF
SA241	0	1	1	1	1	0	0	0	1	128/64	0F10000–0F1FFFF
SA242	0	1	1	1	1	0	0	1	0	128/64	0F20000–0F2FFFF
SA243	0	1	1	1	1	0	0	1	1	128/64	0F30000–0F3FFFF
SA244	0	1	1	1	1	0	1	0	0	128/64	0F40000–0F4FFFF
SA245	0	1	1	1	1	0	1	0	1	128/64	0F50000–0F5FFFF
SA246	0	1	1	1	1	0	1	1	0	128/64	0F60000–0F6FFFF
SA247	0	1	1	1	1	0	1	1	1	128/64	0F70000–0F7FFFF
SA248	0	1	1	1	1	1	0	0	0	128/64	0F80000–0F8FFFF
SA249	0	1	1	1	1	1	0	0	1	128/64	0F90000–0F9FFFF
SA250	0	1	1	1	1	1	0	1	0	128/64	0FA0000–0FAFFFF
SA251	0	1	1	1	1	1	0	1	1	128/64	0FB0000–0FBFFFF
SA252	0	1	1	1	1	1	1	0	0	128/64	0FC0000–0FCFFFF
SA253	0	1	1	1	1	1	1	0	1	128/64	0FD0000–0FDFFFF
SA254	0	1	1	1	1	1	1	1	0	128/64	0FE0000–0FEFFFF
SA255	0	1	1	1	1	1	1	1	1	128/64	0FF0000–0FFFFFF
SA256	1	0	0	0	0	0	0	0	0	128/64	1000000–100FFFF
SA257	1	0	0	0	0	0	0	0	1	128/64	1010000–101FFFF
SA258	1	0	0	0	0	0	0	1	0	128/64	1020000–102FFFF
SA259	1	0	0	0	0	0	0	1	1	128/64	1030000–103FFFF
SA260	1	0	0	0	0	0	1	0	0	128/64	1040000–104FFFF
SA261	1	0	0	0	0	0	1	0	1	128/64	1050000–105FFFF
SA262	1	0	0	0	0	0	1	1	0	128/64	1060000–106FFFF
SA263	1	0	0	0	0	0	1	1	1	128/64	1070000–107FFFF
SA264	1	0	0	0	0	1	0	0	0	128/64	1080000–108FFFF
SA265	1	0	0	0	0	1	0	0	1	128/64	1090000–109FFFF
SA266	1	0	0	0	0	1	0	1	0	128/64	10A0000–10AFFFF
SA267	1	0	0	0	0	1	0	1	1	128/64	10B0000–10BFFFF
SA268	1	0	0	0	0	1	1	0	0	128/64	10C0000–10CFFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA269	1	0	0	0	0	1	1	0	1	128/64	10D0000–10DFFFF
SA270	1	0	0	0	0	1	1	1	0	128/64	10E0000–10EFFFF
SA271	1	0	0	0	0	1	1	1	1	128/64	10F0000–10FFFFF
SA272	1	0	0	0	1	0	0	0	0	128/64	1100000–110FFFF
SA273	1	0	0	0	1	0	0	0	1	128/64	1110000–111FFFF
SA274	1	0	0	0	1	0	0	1	0	128/64	1120000–112FFFF
SA275	1	0	0	0	1	0	0	1	1	128/64	1130000–113FFFF
SA276	1	0	0	0	1	0	1	0	0	128/64	1140000–114FFFF
SA277	1	0	0	0	1	0	1	0	1	128/64	1150000–115FFFF
SA278	1	0	0	0	1	0	1	1	0	128/64	1160000–116FFFF
SA279	1	0	0	0	1	0	1	1	1	128/64	1170000–117FFFF
SA280	1	0	0	0	1	1	0	0	0	128/64	1180000–118FFFF
SA281	1	0	0	0	1	1	0	0	1	128/64	1190000–119FFFF
SA282	1	0	0	0	1	1	0	1	0	128/64	11A0000–11AFFFF
SA283	1	0	0	0	1	1	0	1	1	128/64	11B0000–11BFFFF
SA284	1	0	0	0	1	1	1	0	0	128/64	11C0000–11CFFFF
SA285	1	0	0	0	1	1	1	0	1	128/64	11D0000–11DFFFF
SA286	1	0	0	0	1	1	1	1	0	128/64	11E0000–11EFFFF
SA287	1	0	0	0	1	1	1	1	1	128/64	11F0000–11FFFFF
SA288	1	0	0	1	0	0	0	0	0	128/64	1200000–120FFFF
SA289	1	0	0	1	0	0	0	0	1	128/64	1210000–121FFFF
SA290	1	0	0	1	0	0	0	1	0	128/64	1220000–122FFFF
SA291	1	0	0	1	0	0	0	1	1	128/64	1230000–123FFFF
SA292	1	0	0	1	0	0	1	0	0	128/64	1240000–124FFFF
SA293	1	0	0	1	0	0	1	0	1	128/64	1250000–125FFFF
SA294	1	0	0	1	0	0	1	1	0	128/64	1260000–126FFFF
SA295	1	0	0	1	0	0	1	1	1	128/64	1270000–127FFFF
SA296	1	0	0	1	0	1	0	0	0	128/64	1280000–128FFFF
SA297	1	0	0	1	0	1	0	0	1	128/64	1290000–129FFFF
SA298	1	0	0	1	0	1	0	1	0	128/64	12A0000–12AFFFF
SA299	1	0	0	1	0	1	0	1	1	128/64	12B0000–12BFFFF
SA300	1	0	0	1	0	1	1	0	0	128/64	12C0000–12CFFFF
SA301	1	0	0	1	0	1	1	0	1	128/64	12D0000–12DFFFF
SA302	1	0	0	1	0	1	1	1	0	128/64	12E0000–12EFFFF
SA303	1	0	0	1	0	1	1	1	1	128/64	12F0000–12FFFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA304	1	0	0	1	1	0	0	0	0	128/64	1300000–130FFFF
SA305	1	0	0	1	1	0	0	0	1	128/64	1310000–131FFFF
SA306	1	0	0	1	1	0	0	1	0	128/64	1320000–132FFFF
SA307	1	0	0	1	1	0	0	1	1	128/64	1330000–133FFFF
SA308	1	0	0	1	1	0	1	0	0	128/64	1340000–134FFFF
SA309	1	0	0	1	1	0	1	0	1	128/64	1350000–135FFFF
SA310	1	0	0	1	1	0	1	1	0	128/64	1360000–136FFFF
SA311	1	0	0	1	1	0	1	1	1	128/64	1370000–137FFFF
SA312	1	0	0	1	1	1	0	0	0	128/64	1380000–138FFFF
SA313	1	0	0	1	1	1	0	0	1	128/64	1390000–139FFFF
SA314	1	0	0	1	1	1	0	1	0	128/64	13A0000–13AFFFF
SA315	1	0	0	1	1	1	0	1	1	128/64	13B0000–13BFFFF
SA316	1	0	0	1	1	1	1	0	0	128/64	13C0000–13CFFFF
SA317	1	0	0	1	1	1	1	0	1	128/64	13D0000–13DFFFF
SA318	1	0	0	1	1	1	1	1	0	128/64	13E0000–13EFFFF
SA319	1	0	0	1	1	1	1	1	1	128/64	13F0000–13FFFFF
SA320	1	0	1	0	0	0	0	0	0	128/64	1400000–140FFFF
SA321	1	0	1	0	0	0	0	0	1	128/64	1410000–141FFFF
SA322	1	0	1	0	0	0	0	1	0	128/64	1420000–142FFFF
SA323	1	0	1	0	0	0	0	1	1	128/64	1430000–143FFFF
SA324	1	0	1	0	0	0	1	0	0	128/64	1440000–144FFFF
SA325	1	0	1	0	0	0	1	0	1	128/64	1450000–145FFFF
SA326	1	0	1	0	0	0	1	1	0	128/64	1460000–146FFFF
SA327	1	0	1	0	0	0	1	1	1	128/64	1470000–147FFFF
SA328	1	0	1	0	0	1	0	0	0	128/64	1480000–148FFFF
SA329	1	0	1	0	0	1	0	0	1	128/64	1490000–149FFFF
SA330	1	0	1	0	0	1	0	1	0	128/64	14A0000–14AFFFF
SA331	1	0	1	0	0	1	0	1	1	128/64	14B0000–14BFFFF
SA332	1	0	1	0	0	1	1	0	0	128/64	14C0000–14CFFFF
SA333	1	0	1	0	0	1	1	0	1	128/64	14D0000–14DFFFF
SA334	1	0	1	0	0	1	1	1	0	128/64	14E0000–14EFFFF
SA335	1	0	1	0	0	1	1	1	1	128/64	14F0000–14FFFFF
SA336	1	0	1	0	1	0	0	0	0	128/64	1500000–150FFFF
SA337	1	0	1	0	1	0	0	0	1	128/64	1510000–151FFFF
SA338	1	0	1	0	1	0	0	1	0	128/64	1520000–152FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA339	1	0	1	0	1	0	0	1	1	128/64	1530000–153FFFF
SA340	1	0	1	0	1	0	1	0	0	128/64	1540000–154FFFF
SA341	1	0	1	0	1	0	1	0	1	128/64	1550000–155FFFF
SA342	1	0	1	0	1	0	1	1	0	128/64	1560000–156FFFF
SA343	1	0	1	0	1	0	1	1	1	128/64	1570000–157FFFF
SA344	1	0	1	0	1	1	0	0	0	128/64	1580000–158FFFF
SA345	1	0	1	0	1	1	0	0	1	128/64	1590000–159FFFF
SA346	1	0	1	0	1	1	0	1	0	128/64	15A0000–15AFFFF
SA347	1	0	1	0	1	1	0	1	1	128/64	15B0000–15BFFFF
SA348	1	0	1	0	1	1	1	0	0	128/64	15C0000–15CFFFF
SA349	1	0	1	0	1	1	1	0	1	128/64	15D0000–15DFFFF
SA350	1	0	1	0	1	1	1	1	0	128/64	15E0000–15EFFFF
SA351	1	0	1	0	1	1	1	1	1	128/64	15F0000–15FFFFF
SA352	1	0	1	1	0	0	0	0	0	128/64	1600000–160FFFF
SA353	1	0	1	1	0	0	0	0	1	128/64	1610000–161FFFF
SA354	1	0	1	1	0	0	0	1	0	128/64	1620000–162FFFF
SA355	1	0	1	1	0	0	0	1	1	128/64	1630000–163FFFF
SA356	1	0	1	1	0	0	1	0	0	128/64	1640000–164FFFF
SA357	1	0	1	1	0	0	1	0	1	128/64	1650000–165FFFF
SA358	1	0	1	1	0	0	1	1	0	128/64	1660000–166FFFF
SA359	1	0	1	1	0	0	1	1	1	128/64	1670000–167FFFF
SA360	1	0	1	1	0	1	0	0	0	128/64	1680000–168FFFF
SA361	1	0	1	1	0	1	0	0	1	128/64	1690000–169FFFF
SA362	1	0	1	1	0	1	0	1	0	128/64	16A0000–16AFFFF
SA363	1	0	1	1	0	1	0	1	1	128/64	16B0000–16BFFFF
SA364	1	0	1	1	0	1	1	0	0	128/64	16C0000–16CFFFF
SA365	1	0	1	1	0	1	1	0	1	128/64	16D0000–16DFFFF
SA366	1	0	1	1	0	1	1	1	0	128/64	16E0000–16EFFFF
SA367	1	0	1	1	0	1	1	1	1	128/64	16F0000–16FFFFF
SA368	1	0	1	1	1	0	0	0	0	128/64	1700000–170FFFF
SA369	1	0	1	1	1	0	0	0	1	128/64	1710000–171FFFF
SA370	1	0	1	1	1	0	0	1	0	128/64	1720000–172FFFF
SA371	1	0	1	1	1	0	0	1	1	128/64	1730000–173FFFF
SA372	1	0	1	1	1	0	1	0	0	128/64	1740000–174FFFF
SA373	1	0	1	1	1	0	1	0	1	128/64	1750000–175FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA374	1	0	1	1	1	0	1	1	0	128/64	1760000–176FFFF
SA375	1	0	1	1	1	0	1	1	1	128/64	1770000–177FFFF
SA376	1	0	1	1	1	1	0	0	0	128/64	1780000–178FFFF
SA377	1	0	1	1	1	1	0	0	1	128/64	1790000–179FFFF
SA378	1	0	1	1	1	1	0	1	0	128/64	17A0000–17AFFFF
SA379	1	0	1	1	1	1	0	1	1	128/64	17B0000–17BFFFF
SA380	1	0	1	1	1	1	1	0	0	128/64	17C0000–17CFFFF
SA381	1	0	1	1	1	1	1	0	1	128/64	17D0000–17DFFFF
SA382	1	0	1	1	1	1	1	1	0	128/64	17E0000–17EFFFF
SA383	1	0	1	1	1	1	1	1	1	128/64	17F0000–17FFFFF
SA384	1	1	0	0	0	0	0	0	0	128/64	1800000–180FFFF
SA385	1	1	0	0	0	0	0	0	1	128/64	1810000–181FFFF
SA386	1	1	0	0	0	0	0	1	0	128/64	1820000–182FFFF
SA387	1	1	0	0	0	0	0	1	1	128/64	1830000–183FFFF
SA388	1	1	0	0	0	0	1	0	0	128/64	1840000–184FFFF
SA389	1	1	0	0	0	0	1	0	1	128/64	1850000–185FFFF
SA390	1	1	0	0	0	0	1	1	0	128/64	1860000–186FFFF
SA391	1	1	0	0	0	0	1	1	1	128/64	1870000–187FFFF
SA392	1	1	0	0	0	1	0	0	0	128/64	1880000–188FFFF
SA393	1	1	0	0	0	1	0	0	1	128/64	1890000–189FFFF
SA394	1	1	0	0	0	1	0	1	0	128/64	18A0000–18AFFFF
SA395	1	1	0	0	0	1	0	1	1	128/64	18B0000–18BFFFF
SA396	1	1	0	0	0	1	1	0	0	128/64	18C0000–18CFFFF
SA397	1	1	0	0	0	1	1	0	1	128/64	18D0000–18DFFFF
SA398	1	1	0	0	0	1	1	1	0	128/64	18E0000–18EFFFF
SA399	1	1	0	0	0	1	1	1	1	128/64	18F0000–18FFFFF
SA400	1	1	0	0	1	0	0	0	0	128/64	1900000–190FFFF
SA401	1	1	0	0	1	0	0	0	1	128/64	1910000–191FFFF
SA402	1	1	0	0	1	0	0	1	0	128/64	1920000–192FFFF
SA403	1	1	0	0	1	0	0	1	1	128/64	1930000–193FFFF
SA404	1	1	0	0	1	0	1	0	0	128/64	1940000–194FFFF
SA405	1	1	0	0	1	0	1	0	1	128/64	1950000–195FFFF
SA406	1	1	0	0	1	0	1	1	0	128/64	1960000–196FFFF
SA407	1	1	0	0	1	0	1	1	1	128/64	1970000–197FFFF
SA408	1	1	0	0	1	1	0	0	0	128/64	1980000–198FFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA409	1	1	0	0	1	1	0	0	1	128/64	1990000–199FFFF
SA410	1	1	0	0	1	1	0	1	0	128/64	19A0000–19AFFFF
SA411	1	1	0	0	1	1	0	1	1	128/64	19B0000–19BFFFF
SA412	1	1	0	0	1	1	1	0	0	128/64	19C0000–19CFFFF
SA413	1	1	0	0	1	1	1	0	1	128/64	19D0000–19DFFFF
SA414	1	1	0	0	1	1	1	1	0	128/64	19E0000–19EFFFF
SA415	1	1	0	0	1	1	1	1	1	128/64	19F0000–19FFFFF
SA416	1	1	0	1	0	0	0	0	0	128/64	1A00000–1A0FFFF
SA417	1	1	0	1	0	0	0	0	1	128/64	1A10000–1A1FFFF
SA418	1	1	0	1	0	0	0	1	0	128/64	1A20000–1A2FFFF
SA419	1	1	0	1	0	0	0	1	1	128/64	1A30000–1A3FFFF
SA420	1	1	0	1	0	0	1	0	0	128/64	1A40000–1A4FFFF
SA421	1	1	0	1	0	0	1	0	1	128/64	1A50000–1A5FFFF
SA422	1	1	0	1	0	0	1	1	0	128/64	1A60000–1A6FFFF
SA423	1	1	0	1	0	0	1	1	1	128/64	1A70000–1A7FFFF
SA424	1	1	0	1	0	1	0	0	0	128/64	1A80000–1A8FFFF
SA425	1	1	0	1	0	1	0	0	1	128/64	1A90000–1A9FFFF
SA426	1	1	0	1	0	1	0	1	0	128/64	1AA0000–1AAFFFF
SA427	1	1	0	1	0	1	0	1	1	128/64	1AB0000–1ABFFFF
SA428	1	1	0	1	0	1	1	0	0	128/64	1AC0000–1ACFFFF
SA429	1	1	0	1	0	1	1	0	1	128/64	1AD0000–1ADFFFF
SA430	1	1	0	1	0	1	1	1	0	128/64	1AE0000–1AEFFFF
SA431	1	1	0	1	0	1	1	1	1	128/64	1AF0000–1AFFFFF
SA432	1	1	0	1	1	0	0	0	0	128/64	1B00000–1B0FFFF
SA433	1	1	0	1	1	0	0	0	1	128/64	1B10000–1B1FFFF
SA434	1	1	0	1	1	0	0	1	0	128/64	1B20000–1B2FFFF
SA435	1	1	0	1	1	0	0	1	1	128/64	1B30000–1B3FFFF
SA436	1	1	0	1	1	0	1	0	0	128/64	1B40000–1B4FFFF
SA437	1	1	0	1	1	0	1	0	1	128/64	1B50000–1B5FFFF
SA438	1	1	0	1	1	0	1	1	0	128/64	1B60000–1B6FFFF
SA439	1	1	0	1	1	0	1	1	1	128/64	1B70000–1B7FFFF
SA440	1	1	0	1	1	1	0	0	0	128/64	1B80000–1B8FFFF
SA441	1	1	0	1	1	1	0	0	1	128/64	1B90000–1B9FFFF
SA442	1	1	0	1	1	1	0	1	0	128/64	1BA0000–1BAFFFF
SA443	1	1	0	1	1	1	0	1	1	128/64	1BB0000–1BBFFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA444	1	1	0	1	1	1	1	0	0	128/64	1BC0000–1BCFFFF
SA445	1	1	0	1	1	1	1	0	1	128/64	1BD0000–1BDFFFF
SA446	1	1	0	1	1	1	1	1	0	128/64	1BE0000–1BEFFFF
SA447	1	1	0	1	1	1	1	1	1	128/64	1BF0000–1BFFFFF
SA448	1	1	1	0	0	0	0	0	0	128/64	1C00000–1C0FFFF
SA449	1	1	1	0	0	0	0	0	1	128/64	1C10000–1C1FFFF
SA450	1	1	1	0	0	0	0	1	0	128/64	1C20000–1C2FFFF
SA451	1	1	1	0	0	0	0	1	1	128/64	1C30000–1C3FFFF
SA452	1	1	1	0	0	0	1	0	0	128/64	1C40000–1C4FFFF
SA453	1	1	1	0	0	0	1	0	1	128/64	1C50000–1C5FFFF
SA454	1	1	1	0	0	0	1	1	0	128/64	1C60000–1C6FFFF
SA455	1	1	1	0	0	0	1	1	1	128/64	1C70000–1C7FFFF
SA456	1	1	1	0	0	1	0	0	0	128/64	1C80000–1C8FFFF
SA457	1	1	1	0	0	1	0	0	1	128/64	1C90000–1C9FFFF
SA458	1	1	1	0	0	1	0	1	0	128/64	1CA0000–1CAFFFF
SA459	1	1	1	0	0	1	0	1	1	128/64	1CB0000–1CBFFFF
SA460	1	1	1	0	0	1	1	0	0	128/64	1CC0000–1CCFFFF
SA461	1	1	1	0	0	1	1	0	1	128/64	1CD0000–1CDFFFF
SA462	1	1	1	0	0	1	1	1	0	128/64	1CE0000–1CEFFFF
SA463	1	1	1	0	0	1	1	1	1	128/64	1CF0000–1CFFFFF
SA464	1	1	1	0	1	0	0	0	0	128/64	1D00000–1D0FFFF
SA465	1	1	1	0	1	0	0	0	1	128/64	1D10000–1D1FFFF
SA466	1	1	1	0	1	0	0	1	0	128/64	1D20000–1D2FFFF
SA467	1	1	1	0	1	0	0	1	1	128/64	1D30000–1D3FFFF
SA468	1	1	1	0	1	0	1	0	0	128/64	1D40000–1D4FFFF
SA469	1	1	1	0	1	0	1	0	1	128/64	1D50000–1D5FFFF
SA470	1	1	1	0	1	0	1	1	0	128/64	1D60000–1D6FFFF
SA471	1	1	1	0	1	0	1	1	1	128/64	1D70000–1D7FFFF
SA472	1	1	1	0	1	1	0	0	0	128/64	1D80000–1D8FFFF
SA473	1	1	1	0	1	1	0	0	1	128/64	1D90000–1D9FFFF
SA474	1	1	1	0	1	1	0	1	0	128/64	1DA0000–1DAFFFF
SA475	1	1	1	0	1	1	0	1	1	128/64	1DB0000–1DBFFFF
SA476	1	1	1	0	1	1	1	0	0	128/64	1DC0000–1DCFFFF
SA477	1	1	1	0	1	1	1	0	1	128/64	1DD0000–1DDFFFF
SA478	1	1	1	0	1	1	1	1	0	128/64	1DE0000–1DEFFFF

Table 2. Sector Address Table–S29GL5I2N (Continued)

Sector	A24–A16									Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA479	1	1	1	0	1	1	1	1	1	128/64	1DF0000–1DFFFFF
SA480	1	1	1	1	0	0	0	0	0	128/64	1E00000–1E0FFFF
SA481	1	1	1	1	0	0	0	0	1	128/64	1E10000–1E1FFFF
SA482	1	1	1	1	0	0	0	1	0	128/64	1E20000–1E2FFFF
SA483	1	1	1	1	0	0	0	1	1	128/64	1E30000–1E3FFFF
SA484	1	1	1	1	0	0	1	0	0	128/64	1E40000–1E4FFFF
SA485	1	1	1	1	0	0	1	0	1	128/64	1E50000–1E5FFFF
SA486	1	1	1	1	0	0	1	1	0	128/64	1E60000–1E6FFFF
SA487	1	1	1	1	0	0	1	1	1	128/64	1E70000–1E7FFFF
SA488	1	1	1	1	0	1	0	0	0	128/64	1E80000–1E8FFFF
SA489	1	1	1	1	0	1	0	0	1	128/64	1E90000–1E9FFFF
SA490	1	1	1	1	0	1	0	1	0	128/64	1EA0000–1EAFFFF
SA491	1	1	1	1	0	1	0	1	1	128/64	1EB0000–1EBFFFF
SA492	1	1	1	1	0	1	1	0	0	128/64	1EC0000–1ECFFFF
SA493	1	1	1	1	0	1	1	0	1	128/64	1ED0000–1EDFFFF
SA494	1	1	1	1	0	1	1	1	0	128/64	1EE0000–1EEFFFF
SA495	1	1	1	1	0	1	1	1	1	128/64	1EF0000–1EFFFFF
SA496	1	1	1	1	1	0	0	0	0	128/64	1F00000–1F0FFFF
SA497	1	1	1	1	1	0	0	0	1	128/64	1F10000–1F1FFFF
SA498	1	1	1	1	1	0	0	1	0	128/64	1F20000–1F2FFFF
SA499	1	1	1	1	1	0	0	1	1	128/64	1F30000–1F3FFFF
SA500	1	1	1	1	1	0	1	0	0	128/64	1F40000–1F4FFFF
SA501	1	1	1	1	1	0	1	0	1	128/64	1F50000–1F5FFFF
SA502	1	1	1	1	1	0	1	1	0	128/64	1F60000–1F6FFFF
SA503	1	1	1	1	1	0	1	1	1	128/64	1F70000–1F7FFFF
SA504	1	1	1	1	1	1	0	0	0	128/64	1F80000–1F8FFFF
SA505	1	1	1	1	1	1	0	0	1	128/64	1F90000–1F9FFFF
SA506	1	1	1	1	1	1	0	1	0	128/64	1FA0000–1FAFFFF
SA507	1	1	1	1	1	1	0	1	1	128/64	1FB0000–1FBFFFF
SA508	1	1	1	1	1	1	1	0	0	128/64	1FC0000–1FCFFFF
SA509	1	1	1	1	1	1	1	0	1	128/64	1FD0000–1FDFFFF
SA510	1	1	1	1	1	1	1	1	0	128/64	1FE0000–1FEFFFF
SA511	1	1	1	1	1	1	1	1	1	128/64	1FF0000–1FFFFFF

Table 3. Sector Address Table–S29GL256N

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA0	0	0	0	0	0	0	0	0	128/64	0000000–000FFFF
SA1	0	0	0	0	0	0	0	1	128/64	0010000–001FFFF
SA2	0	0	0	0	0	0	1	0	128/64	0020000–002FFFF
SA3	0	0	0	0	0	0	1	1	128/64	0030000–003FFFF
SA4	0	0	0	0	0	1	0	0	128/64	0040000–004FFFF
SA5	0	0	0	0	0	1	0	1	128/64	0050000–005FFFF
SA6	0	0	0	0	0	1	1	0	128/64	0060000–006FFFF
SA7	0	0	0	0	0	1	1	1	128/64	0070000–007FFFF
SA8	0	0	0	0	1	0	0	0	128/64	0080000–008FFFF
SA9	0	0	0	0	1	0	0	1	128/64	0090000–009FFFF
SA10	0	0	0	0	1	0	1	0	128/64	00A0000–00AFFFF
SA11	0	0	0	0	1	0	1	1	128/64	00B0000–00BFFFF
SA12	0	0	0	0	1	1	0	0	128/64	00C0000–00CFFFF
SA13	0	0	0	0	1	1	0	1	128/64	00D0000–00DFFFF
SA14	0	0	0	0	1	1	1	0	128/64	00E0000–00EFFFF
SA15	0	0	0	0	1	1	1	1	128/64	00F0000–00FFFFF
SA16	0	0	0	1	0	0	0	0	128/64	0100000–010FFFF
SA17	0	0	0	1	0	0	0	1	128/64	0110000–011FFFF
SA18	0	0	0	1	0	0	1	0	128/64	0120000–012FFFF
SA19	0	0	0	1	0	0	1	1	128/64	0130000–013FFFF
SA20	0	0	0	1	0	1	0	0	128/64	0140000–014FFFF
SA21	0	0	0	1	0	1	0	1	128/64	0150000–015FFFF
SA22	0	0	0	1	0	1	1	0	128/64	0160000–016FFFF
SA23	0	0	0	1	0	1	1	1	128/64	0170000–017FFFF
SA24	0	0	0	1	1	0	0	0	128/64	0180000–018FFFF
SA25	0	0	0	1	1	0	0	1	128/64	0190000–019FFFF
SA26	0	0	0	1	1	0	1	0	128/64	01A0000–01AFFFF
SA27	0	0	0	1	1	0	1	1	128/64	01B0000–01BFFFF
SA28	0	0	0	1	1	1	0	0	128/64	01C0000–01CFFFF
SA29	0	0	0	1	1	1	0	1	128/64	01D0000–01DFFFF
SA30	0	0	0	1	1	1	1	0	128/64	01E0000–01EFFFF
SA31	0	0	0	1	1	1	1	1	128/64	01F0000–01FFFFF
SA32	0	0	1	0	0	0	0	0	128/64	0200000–020FFFF
SA33	0	0	1	0	0	0	0	1	128/64	0210000–021FFFF

Table 3. Sector Address Table–S29GL256N (Continued)

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA34	0	0	1	0	0	0	1	0	128/64	0220000–022FFFF
SA35	0	0	1	0	0	0	1	1	128/64	0230000–023FFFF
SA36	0	0	1	0	0	1	0	0	128/64	0240000–024FFFF
SA37	0	0	1	0	0	1	0	1	128/64	0250000–025FFFF
SA38	0	0	1	0	0	1	1	0	128/64	0260000–026FFFF
SA39	0	0	1	0	0	1	1	1	128/64	0270000–027FFFF
SA40	0	0	1	0	1	0	0	0	128/64	0280000–028FFFF
SA41	0	0	1	0	1	0	0	1	128/64	0290000–029FFFF
SA42	0	0	1	0	1	0	1	0	128/64	02A0000–02AFFFF
SA43	0	0	1	0	1	0	1	1	128/64	02B0000–02BFFFF
SA44	0	0	1	0	1	1	0	0	128/64	02C0000–02CFFFF
SA45	0	0	1	0	1	1	0	1	128/64	02D0000–02DFFFF
SA46	0	0	1	0	1	1	1	0	128/64	02E0000–02EFFFF
SA47	0	0	1	0	1	1	1	1	128/64	02F0000–02FFFFF
SA48	0	0	1	1	0	0	0	0	128/64	0300000–030FFFF
SA49	0	0	1	1	0	0	0	1	128/64	0310000–031FFFF
SA50	0	0	1	1	0	0	1	0	128/64	0320000–032FFFF
SA51	0	0	1	1	0	0	1	1	128/64	0330000–033FFFF
SA52	0	0	1	1	0	1	0	0	128/64	0340000–034FFFF
SA53	0	0	1	1	0	1	0	1	128/64	0350000–035FFFF
SA54	0	0	1	1	0	1	1	0	128/64	0360000–036FFFF
SA55	0	0	1	1	0	1	1	1	128/64	0370000–037FFFF
SA56	0	0	1	1	1	0	0	0	128/64	0380000–038FFFF
SA57	0	0	1	1	1	0	0	1	128/64	0390000–039FFFF
SA58	0	0	1	1	1	0	1	0	128/64	03A0000–03AFFFF
SA59	0	0	1	1	1	0	1	1	128/64	03B0000–03BFFFF
SA60	0	0	1	1	1	1	0	0	128/64	03C0000–03CFFFF
SA61	0	0	1	1	1	1	0	1	128/64	03D0000–03DFFFF
SA62	0	0	1	1	1	1	1	0	128/64	03E0000–03EFFFF
SA63	0	0	1	1	1	1	1	1	128/64	03F0000–03FFFFF
SA64	0	1	0	0	0	0	0	0	128/64	0400000–040FFFF
SA65	0	1	0	0	0	0	0	1	128/64	0410000–041FFFF
SA66	0	1	0	0	0	0	1	0	128/64	0420000–042FFFF
SA67	0	1	0	0	0	0	1	1	128/64	0430000–043FFFF
SA68	0	1	0	0	0	1	0	0	128/64	0440000–044FFFF

Table 3. Sector Address Table–S29GL256N (Continued)

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA69	0	1	0	0	0	1	0	1	128/64	0450000–045FFFF
SA70	0	1	0	0	0	1	1	0	128/64	0460000–046FFFF
SA71	0	1	0	0	0	1	1	1	128/64	0470000–047FFFF
SA72	0	1	0	0	1	0	0	0	128/64	0480000–048FFFF
SA73	0	1	0	0	1	0	0	1	128/64	0490000–049FFFF
SA74	0	1	0	0	1	0	1	0	128/64	04A0000–04AFFFF
SA75	0	1	0	0	1	0	1	1	128/64	04B0000–04BFFFF
SA76	0	1	0	0	1	1	0	0	128/64	04C0000–04CFFFF
SA77	0	1	0	0	1	1	0	1	128/64	04D0000–04DFFFF
SA78	0	1	0	0	1	1	1	0	128/64	04E0000–04EFFFF
SA79	0	1	0	0	1	1	1	1	128/64	04F0000–04FFFFF
SA80	0	1	0	1	0	0	0	0	128/64	0500000–050FFFF
SA81	0	1	0	1	0	0	0	1	128/64	0510000–051FFFF
SA82	0	1	0	1	0	0	1	0	128/64	0520000–052FFFF
SA83	0	1	0	1	0	0	1	1	128/64	0530000–053FFFF
SA84	0	1	0	1	0	1	0	0	128/64	0540000–054FFFF
SA85	0	1	0	1	0	1	0	1	128/64	0550000–055FFFF
SA86	0	1	0	1	0	1	1	0	128/64	0560000–056FFFF
SA87	0	1	0	1	0	1	1	1	128/64	0570000–057FFFF
SA88	0	1	0	1	1	0	0	0	128/64	0580000–058FFFF
SA89	0	1	0	1	1	0	0	1	128/64	0590000–059FFFF
SA90	0	1	0	1	1	0	1	0	128/64	05A0000–05AFFFF
SA91	0	1	0	1	1	0	1	1	128/64	05B0000–05BFFFF
SA92	0	1	0	1	1	1	0	0	128/64	05C0000–05CFFFF
SA93	0	1	0	1	1	1	0	1	128/64	05D0000–05DFFFF
SA94	0	1	0	1	1	1	1	0	128/64	05E0000–05EFFFF
SA95	0	1	0	1	1	1	1	1	128/64	05F0000–05FFFFF
SA96	0	1	1	0	0	0	0	0	128/64	0600000–060FFFF
SA97	0	1	1	0	0	0	0	1	128/64	0610000–061FFFF
SA98	0	1	1	0	0	0	1	0	128/64	0620000–062FFFF
SA99	0	1	1	0	0	0	1	1	128/64	0630000–063FFFF
SA100	0	1	1	0	0	1	0	0	128/64	0640000–064FFFF
SA101	0	1	1	0	0	1	0	1	128/64	0650000–065FFFF
SA102	0	1	1	0	0	1	1	0	128/64	0660000–066FFFF
SA103	0	1	1	0	0	1	1	1	128/64	0670000–067FFFF

Table 3. Sector Address Table–S29GL256N (Continued)

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA104	0	1	1	0	1	0	0	0	128/64	0680000–068FFFF
SA105	0	1	1	0	1	0	0	1	128/64	0690000–069FFFF
SA106	0	1	1	0	1	0	1	0	128/64	06A0000–06AFFFF
SA107	0	1	1	0	1	0	1	1	128/64	06B0000–06BFFFF
SA108	0	1	1	0	1	1	0	0	128/64	06C0000–06CFFFF
SA109	0	1	1	0	1	1	0	1	128/64	06D0000–06DFFFF
SA110	0	1	1	0	1	1	1	0	128/64	06E0000–06EFFFF
SA111	0	1	1	0	1	1	1	1	128/64	06F0000–06FFFFF
SA112	0	1	1	1	0	0	0	0	128/64	0700000–070FFFF
SA113	0	1	1	1	0	0	0	1	128/64	0710000–071FFFF
SA114	0	1	1	1	0	0	1	0	128/64	0720000–072FFFF
SA115	0	1	1	1	0	0	1	1	128/64	0730000–073FFFF
SA116	0	1	1	1	0	1	0	0	128/64	0740000–074FFFF
SA117	0	1	1	1	0	1	0	1	128/64	0750000–075FFFF
SA118	0	1	1	1	0	1	1	0	128/64	0760000–076FFFF
SA119	0	1	1	1	0	1	1	1	128/64	0770000–077FFFF
SA120	0	1	1	1	1	0	0	0	128/64	0780000–078FFFF
SA121	0	1	1	1	1	0	0	1	128/64	0790000–079FFFF
SA122	0	1	1	1	1	0	1	0	128/64	07A0000–07AFFFF
SA123	0	1	1	1	1	0	1	1	128/64	07B0000–07BFFFF
SA124	0	1	1	1	1	1	0	0	128/64	07C0000–07CFFFF
SA125	0	1	1	1	1	1	0	1	128/64	07D0000–07DFFFF
SA126	0	1	1	1	1	1	1	0	128/64	07E0000–07EFFFF
SA127	0	1	1	1	1	1	1	1	128/64	07F0000–07FFFFF
SA128	1	0	0	0	0	0	0	0	128/64	0800000–080FFFF
SA129	1	0	0	0	0	0	0	1	128/64	0810000–081FFFF
SA130	1	0	0	0	0	0	1	0	128/64	0820000–082FFFF
SA131	1	0	0	0	0	0	1	1	128/64	0830000–083FFFF
SA132	1	0	0	0	0	1	0	0	128/64	0840000–084FFFF
SA133	1	0	0	0	0	1	0	1	128/64	0850000–085FFFF
SA134	1	0	0	0	0	1	1	0	128/64	0860000–086FFFF
SA135	1	0	0	0	0	1	1	1	128/64	0870000–087FFFF
SA136	1	0	0	0	1	0	0	0	128/64	0880000–088FFFF
SA137	1	0	0	0	1	0	0	1	128/64	0890000–089FFFF
SA138	1	0	0	0	1	0	1	0	128/64	08A0000–08AFFFF

Table 3. Sector Address Table–S29GL256N (Continued)

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA139	1	0	0	0	1	0	1	1	128/64	08B0000–08BFFFF
SA140	1	0	0	0	1	1	0	0	128/64	08C0000–08CFFFF
SA141	1	0	0	0	1	1	0	1	128/64	08D0000–08DFFFF
SA142	1	0	0	0	1	1	1	0	128/64	08E0000–08EFFFF
SA143	1	0	0	0	1	1	1	1	128/64	08F0000–08FFFFF
SA144	1	0	0	1	0	0	0	0	128/64	0900000–090FFFF
SA145	1	0	0	1	0	0	0	1	128/64	0910000–091FFFF
SA146	1	0	0	1	0	0	1	0	128/64	0920000–092FFFF
SA147	1	0	0	1	0	0	1	1	128/64	0930000–093FFFF
SA148	1	0	0	1	0	1	0	0	128/64	0940000–094FFFF
SA149	1	0	0	1	0	1	0	1	128/64	0950000–095FFFF
SA150	1	0	0	1	0	1	1	0	128/64	0960000–096FFFF
SA151	1	0	0	1	0	1	1	1	128/64	0970000–097FFFF
SA152	1	0	0	1	1	0	0	0	128/64	0980000–098FFFF
SA153	1	0	0	1	1	0	0	1	128/64	0990000–099FFFF
SA154	1	0	0	1	1	0	1	0	128/64	09A0000–09AFFFF
SA155	1	0	0	1	1	0	1	1	128/64	09B0000–09BFFFF
SA156	1	0	0	1	1	1	0	0	128/64	09C0000–09CFFFF
SA157	1	0	0	1	1	1	0	1	128/64	09D0000–09DFFFF
SA158	1	0	0	1	1	1	1	0	128/64	09E0000–09EFFFF
SA159	1	0	0	1	1	1	1	1	128/64	09F0000–09FFFFF
SA160	1	0	1	0	0	0	0	0	128/64	0A00000–0A0FFFF
SA161	1	0	1	0	0	0	0	1	128/64	0A10000–0A1FFFF
SA162	1	0	1	0	0	0	1	0	128/64	0A20000–0A2FFFF
SA163	1	0	1	0	0	0	1	1	128/64	0A30000–0A3FFFF
SA164	1	0	1	0	0	1	0	0	128/64	0A40000–0A4FFFF
SA165	1	0	1	0	0	1	0	1	128/64	0A50000–0A5FFFF
SA166	1	0	1	0	0	1	1	0	128/64	0A60000–0A6FFFF
SA167	1	0	1	0	0	1	1	1	128/64	0A70000–0A7FFFF
SA168	1	0	1	0	1	0	0	0	128/64	0A80000–0A8FFFF
SA169	1	0	1	0	1	0	0	1	128/64	0A90000–0A9FFFF
SA170	1	0	1	0	1	0	1	0	128/64	0AA0000–0AAFFFF
SA171	1	0	1	0	1	0	1	1	128/64	0AB0000–0ABFFFF
SA172	1	0	1	0	1	1	0	0	128/64	0AC0000–0ACFFFF
SA173	1	0	1	0	1	1	0	1	128/64	0AD0000–0ADFFFF

Table 3. Sector Address Table–S29GL256N (Continued)

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA174	1	0	1	0	1	1	1	0	128/64	0AE0000–0AEFFFF
SA175	1	0	1	0	1	1	1	1	128/64	0AF0000–0AFFFFF
SA176	1	0	1	1	0	0	0	0	128/64	0B00000–0B0FFFF
SA177	1	0	1	1	0	0	0	1	128/64	0B10000–0B1FFFF
SA178	1	0	1	1	0	0	1	0	128/64	0B20000–0B2FFFF
SA179	1	0	1	1	0	0	1	1	128/64	0B30000–0B3FFFF
SA180	1	0	1	1	0	1	0	0	128/64	0B40000–0B4FFFF
SA181	1	0	1	1	0	1	0	1	128/64	0B50000–0B5FFFF
SA182	1	0	1	1	0	1	1	0	128/64	0B60000–0B6FFFF
SA183	1	0	1	1	0	1	1	1	128/64	0B70000–0B7FFFF
SA184	1	0	1	1	1	0	0	0	128/64	0B80000–0B8FFFF
SA185	1	0	1	1	1	0	0	1	128/64	0B90000–0B9FFFF
SA186	1	0	1	1	1	0	1	0	128/64	0BA0000–0BAFFFF
SA187	1	0	1	1	1	0	1	1	128/64	0BB0000–0BBFFFF
SA188	1	0	1	1	1	1	0	0	128/64	0BC0000–0BCFFFF
SA189	1	0	1	1	1	1	0	1	128/64	0BD0000–0BDFFFF
SA190	1	0	1	1	1	1	1	0	128/64	0BE0000–0BEFFFF
SA191	1	0	1	1	1	1	1	1	128/64	0BF0000–0BFFFFF
SA192	1	1	0	0	0	0	0	0	128/64	0C00000–0C0FFFF
SA193	1	1	0	0	0	0	0	1	128/64	0C10000–0C1FFFF
SA194	1	1	0	0	0	0	1	0	128/64	0C20000–0C2FFFF
SA195	1	1	0	0	0	0	1	1	128/64	0C30000–0C3FFFF
SA196	1	1	0	0	0	1	0	0	128/64	0C40000–0C4FFFF
SA197	1	1	0	0	0	1	0	1	128/64	0C50000–0C5FFFF
SA198	1	1	0	0	0	1	1	0	128/64	0C60000–0C6FFFF
SA199	1	1	0	0	0	1	1	1	128/64	0C70000–0C7FFFF
SA200	1	1	0	0	1	0	0	0	128/64	0C80000–0C8FFFF
SA201	1	1	0	0	1	0	0	1	128/64	0C90000–0C9FFFF
SA202	1	1	0	0	1	0	1	0	128/64	0CA0000–0CAFFFF
SA203	1	1	0	0	1	0	1	1	128/64	0CB0000–0CBFFFF
SA204	1	1	0	0	1	1	0	0	128/64	0CC0000–0CCFFFF
SA205	1	1	0	0	1	1	0	1	128/64	0CD0000–0CDFFFF
SA206	1	1	0	0	1	1	1	0	128/64	0CE0000–0CEFFFF
SA207	1	1	0	0	1	1	1	1	128/64	0CF0000–0CFFFFF
SA208	1	1	0	1	0	0	0	0	128/64	0D00000–0D0FFFF

Table 3. Sector Address Table–S29GL256N (Continued)

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA209	1	1	0	1	0	0	0	1	128/64	0D10000–0D1FFFF
SA210	1	1	0	1	0	0	1	0	128/64	0D20000–0D2FFFF
SA211	1	1	0	1	0	0	1	1	128/64	0D30000–0D3FFFF
SA212	1	1	0	1	0	1	0	0	128/64	0D40000–0D4FFFF
SA213	1	1	0	1	0	1	0	1	128/64	0D50000–0D5FFFF
SA214	1	1	0	1	0	1	1	0	128/64	0D60000–0D6FFFF
SA215	1	1	0	1	0	1	1	1	128/64	0D70000–0D7FFFF
SA216	1	1	0	1	1	0	0	0	128/64	0D80000–0D8FFFF
SA217	1	1	0	1	1	0	0	1	128/64	0D90000–0D9FFFF
SA218	1	1	0	1	1	0	1	0	128/64	0DA0000–0DAFFFF
SA219	1	1	0	1	1	0	1	1	128/64	0DB0000–0DBFFFF
SA220	1	1	0	1	1	1	0	0	128/64	0DC0000–0DCFFFF
SA221	1	1	0	1	1	1	0	1	128/64	0DD0000–0DDFFFF
SA222	1	1	0	1	1	1	1	0	128/64	0DE0000–0DEFFFF
SA223	1	1	0	1	1	1	1	1	128/64	0DF0000–0DFFFFF
SA224	1	1	1	0	0	0	0	0	128/64	0E00000–0E0FFFF
SA225	1	1	1	0	0	0	0	1	128/64	0E10000–0E1FFFF
SA226	1	1	1	0	0	0	1	0	128/64	0E20000–0E2FFFF
SA227	1	1	1	0	0	0	1	1	128/64	0E30000–0E3FFFF
SA228	1	1	1	0	0	1	0	0	128/64	0E40000–0E4FFFF
SA229	1	1	1	0	0	1	0	1	128/64	0E50000–0E5FFFF
SA230	1	1	1	0	0	1	1	0	128/64	0E60000–0E6FFFF
SA231	1	1	1	0	0	1	1	1	128/64	0E70000–0E7FFFF
SA232	1	1	1	0	1	0	0	0	128/64	0E80000–0E8FFFF
SA233	1	1	1	0	1	0	0	1	128/64	0E90000–0E9FFFF
SA234	1	1	1	0	1	0	1	0	128/64	0EA0000–0EAFFFF
SA235	1	1	1	0	1	0	1	1	128/64	0EB0000–0EBFFFF
SA236	1	1	1	0	1	1	0	0	128/64	0EC0000–0ECFFFF
SA237	1	1	1	0	1	1	0	1	128/64	0ED0000–0EDFFFF
SA238	1	1	1	0	1	1	1	0	128/64	0EE0000–0EEFFFF
SA239	1	1	1	0	1	1	1	1	128/64	0EF0000–0EFFFFF
SA240	1	1	1	1	0	0	0	0	128/64	0F00000–0F0FFFF
SA241	1	1	1	1	0	0	0	1	128/64	0F10000–0F1FFFF
SA242	1	1	1	1	0	0	1	0	128/64	0F20000–0F2FFFF
SA243	1	1	1	1	0	0	1	1	128/64	0F30000–0F3FFFF

Table 3. Sector Address Table–S29GL256N (Continued)

Sector	A23–A16								Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA244	1	1	1	1	0	1	0	0	128/64	0F40000–0F4FFFF
SA245	1	1	1	1	0	1	0	1	128/64	0F50000–0F5FFFF
SA246	1	1	1	1	0	1	1	0	128/64	0F60000–0F6FFFF
SA247	1	1	1	1	0	1	1	1	128/64	0F70000–0F7FFFF
SA248	1	1	1	1	1	0	0	0	128/64	0F80000–0F8FFFF
SA249	1	1	1	1	1	0	0	1	128/64	0F90000–0F9FFFF
SA250	1	1	1	1	1	0	1	0	128/64	0FA0000–0FAFFFF
SA251	1	1	1	1	1	0	1	1	128/64	0FB0000–0FBFFFF
SA252	1	1	1	1	1	1	0	0	128/64	0FC0000–0FCFFFF
SA253	1	1	1	1	1	1	0	1	128/64	0FD0000–0FDFFFF
SA254	1	1	1	1	1	1	1	0	128/64	0FE0000–0FEFFFF
SA255	1	1	1	1	1	1	1	1	128/64	0FF0000–0FFFFFF

Table 4. Sector Address Table–S29GLI28N

Sector	A22–A16						Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA0	0	0	0	0	0	0	128/64	0000000–000FFFF
SA1	0	0	0	0	0	1	128/64	0010000–001FFFF
SA2	0	0	0	0	1	0	128/64	0020000–002FFFF
SA3	0	0	0	0	1	1	128/64	0030000–003FFFF
SA4	0	0	0	1	0	0	128/64	0040000–004FFFF
SA5	0	0	0	1	0	1	128/64	0050000–005FFFF
SA6	0	0	0	1	1	0	128/64	0060000–006FFFF
SA7	0	0	0	1	1	1	128/64	0070000–007FFFF
SA8	0	0	1	0	0	0	128/64	0080000–008FFFF
SA9	0	0	1	0	0	1	128/64	0090000–009FFFF
SA10	0	0	1	0	1	0	128/64	00A0000–00AFFFF
SA11	0	0	1	0	1	1	128/64	00B0000–00BFFFF
SA12	0	0	1	1	0	0	128/64	00C0000–00CFFFF
SA13	0	0	1	1	0	1	128/64	00D0000–00DFFFF
SA14	0	0	1	1	1	0	128/64	00E0000–00EFFFF
SA15	0	0	1	1	1	1	128/64	00F0000–00FFFFF
SA16	0	1	0	0	0	0	128/64	0100000–010FFFF
SA17	0	1	0	0	0	1	128/64	0110000–011FFFF

Table 4. Sector Address Table–S29GLI28N (Continued)

Sector	A22–A16						Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA18	0	1	0	0	1	0	128/64	0120000–012FFFF
SA19	0	1	0	0	1	1	128/64	0130000–013FFFF
SA20	0	1	0	1	0	0	128/64	0140000–014FFFF
SA21	0	1	0	1	0	1	128/64	0150000–015FFFF
SA22	0	1	0	1	1	0	128/64	0160000–016FFFF
SA23	0	1	0	1	1	1	128/64	0170000–017FFFF
SA24	0	1	1	0	0	0	128/64	0180000–018FFFF
SA25	0	1	1	0	0	1	128/64	0190000–019FFFF
SA26	0	1	1	0	1	0	128/64	01A0000–01AFFFF
SA27	0	1	1	0	1	1	128/64	01B0000–01BFFFF
SA28	0	1	1	1	0	0	128/64	01C0000–01CFFFF
SA29	0	1	1	1	0	1	128/64	01D0000–01DFFFF
SA30	0	1	1	1	1	0	128/64	01E0000–01EFFFF
SA31	0	1	1	1	1	1	128/64	01F0000–01FFFFF
SA32	1	0	0	0	0	0	128/64	0200000–020FFFF
SA33	1	0	0	0	0	1	128/64	0210000–021FFFF
SA34	1	0	0	0	1	0	128/64	0220000–022FFFF
SA35	1	0	0	0	1	1	128/64	0230000–023FFFF
SA36	1	0	0	1	0	0	128/64	0240000–024FFFF
SA37	1	0	0	1	0	1	128/64	0250000–025FFFF
SA38	1	0	0	1	1	0	128/64	0260000–026FFFF
SA39	1	0	0	1	1	1	128/64	0270000–027FFFF
SA40	1	0	1	0	0	0	128/64	0280000–028FFFF
SA41	1	0	1	0	0	1	128/64	0290000–029FFFF
SA42	1	0	1	0	1	0	128/64	02A0000–02AFFFF
SA43	1	0	1	0	1	1	128/64	02B0000–02BFFFF
SA44	1	0	1	1	0	0	128/64	02C0000–02CFFFF
SA45	1	0	1	1	0	1	128/64	02D0000–02DFFFF
SA46	1	0	1	1	1	0	128/64	02E0000–02EFFFF
SA47	1	0	1	1	1	1	128/64	02F0000–02FFFFF
SA48	1	1	0	0	0	0	128/64	0300000–030FFFF
SA49	1	1	0	0	0	1	128/64	0310000–031FFFF
SA50	1	1	0	0	1	0	128/64	0320000–032FFFF
SA51	1	1	0	0	1	1	128/64	0330000–033FFFF
SA52	1	1	0	1	0	0	128/64	0340000–034FFFF

Table 4. Sector Address Table–S29GLI28N (Continued)

Sector	A22–A16						Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA53	1	1	0	1	0	1	128/64	0350000–035FFFF
SA54	1	1	0	1	1	0	128/64	0360000–036FFFF
SA55	1	1	0	1	1	1	128/64	0370000–037FFFF
SA56	1	1	1	0	0	0	128/64	0380000–038FFFF
SA57	1	1	1	0	0	1	128/64	0390000–039FFFF
SA58	1	1	1	0	1	0	128/64	03A0000–03AFFFF
SA59	1	1	1	0	1	1	128/64	03B0000–03BFFFF
SA60	1	1	1	1	0	0	128/64	03C0000–03CFFFF
SA61	1	1	1	1	0	1	128/64	03D0000–03DFFFF
SA62	1	1	1	1	1	0	128/64	03E0000–03EFFFF
SA63	1	1	1	1	1	1	128/64	03F0000–03FFFFF
SA64	0	0	0	0	0	0	128/64	0400000–040FFFF
SA65	0	0	0	0	0	1	128/64	0410000–041FFFF
SA66	0	0	0	0	1	0	128/64	0420000–042FFFF
SA67	0	0	0	0	1	1	128/64	0430000–043FFFF
SA68	0	0	0	1	0	0	128/64	0440000–044FFFF
SA69	0	0	0	1	0	1	128/64	0450000–045FFFF
SA70	0	0	0	1	1	0	128/64	0460000–046FFFF
SA71	0	0	0	1	1	1	128/64	0470000–047FFFF
SA72	0	0	1	0	0	0	128/64	0480000–048FFFF
SA73	0	0	1	0	0	1	128/64	0490000–049FFFF
SA74	0	0	1	0	1	0	128/64	04A0000–04AFFFF
SA75	0	0	1	0	1	1	128/64	04B0000–04BFFFF
SA76	0	0	1	1	0	0	128/64	04C0000–04CFFFF
SA77	0	0	1	1	0	1	128/64	04D0000–04DFFFF
SA78	0	0	1	1	1	0	128/64	04E0000–04EFFFF
SA79	0	0	1	1	1	1	128/64	04F0000–04FFFFF
SA80	0	1	0	0	0	0	128/64	0500000–050FFFF
SA81	0	1	0	0	0	1	128/64	0510000–051FFFF
SA82	0	1	0	0	1	0	128/64	0520000–052FFFF
SA83	0	1	0	0	1	1	128/64	0530000–053FFFF
SA84	0	1	0	1	0	0	128/64	0540000–054FFFF
SA85	0	1	0	1	0	1	128/64	0550000–055FFFF
SA86	0	1	0	1	1	0	128/64	0560000–056FFFF
SA87	0	1	0	1	1	1	128/64	0570000–057FFFF

Table 4. Sector Address Table–S29GLI28N (Continued)

Sector	A22–A16						Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA88	0	1	1	0	0	0	128/64	0580000–058FFFF
SA89	0	1	1	0	0	1	128/64	0590000–059FFFF
SA90	0	1	1	0	1	0	128/64	05A0000–05AFFFF
SA91	0	1	1	0	1	1	128/64	05B0000–05BFFFF
SA92	0	1	1	1	0	0	128/64	05C0000–05CFFFF
SA93	0	1	1	1	0	1	128/64	05D0000–05DFFFF
SA94	0	1	1	1	1	0	128/64	05E0000–05EFFFF
SA95	0	1	1	1	1	1	128/64	05F0000–05FFFFF
SA96	1	0	0	0	0	0	128/64	0600000–060FFFF
SA97	1	0	0	0	0	1	128/64	0610000–061FFFF
SA98	1	0	0	0	1	0	128/64	0620000–062FFFF
SA99	1	0	0	0	1	1	128/64	0630000–063FFFF
SA100	1	0	0	1	0	0	128/64	0640000–064FFFF
SA101	1	0	0	1	0	1	128/64	0650000–065FFFF
SA102	1	0	0	1	1	0	128/64	0660000–066FFFF
SA103	1	0	0	1	1	1	128/64	0670000–067FFFF
SA104	1	0	1	0	0	0	128/64	0680000–068FFFF
SA105	1	0	1	0	0	1	128/64	0690000–069FFFF
SA106	1	0	1	0	1	0	128/64	06A0000–06AFFFF
SA107	1	0	1	0	1	1	128/64	06B0000–06BFFFF
SA108	1	0	1	1	0	0	128/64	06C0000–06CFFFF
SA109	1	0	1	1	0	1	128/64	06D0000–06DFFFF
SA110	1	0	1	1	1	0	128/64	06E0000–06EFFFF
SA111	1	0	1	1	1	1	128/64	06F0000–06FFFFF
SA112	1	1	0	0	0	0	128/64	0700000–070FFFF
SA113	1	1	0	0	0	1	128/64	0710000–071FFFF
SA114	1	1	0	0	1	0	128/64	0720000–072FFFF
SA115	1	1	0	0	1	1	128/64	0730000–073FFFF
SA116	1	1	0	1	0	0	128/64	0740000–074FFFF
SA117	1	1	0	1	0	1	128/64	0750000–075FFFF
SA118	1	1	0	1	1	0	128/64	0760000–076FFFF
SA119	1	1	0	1	1	1	128/64	0770000–077FFFF
SA120	1	1	1	0	0	0	128/64	0780000–078FFFF
SA121	1	1	1	0	0	1	128/64	0790000–079FFFF
SA122	1	1	1	0	1	0	128/64	07A0000–07AFFFF

Table 4. Sector Address Table–S29GLI28N (Continued)

Sector	A22–A16						Sector Size (Kbytes/ Kwords)	Address Range (in hexadecimal)
SA123	1	1	1	0	1	1	128/64	07B0000–07BFFFF
SA124	1	1	1	1	0	0	128/64	07C0000–07CFFFF
SA125	1	1	1	1	0	1	128/64	07D0000–07DFFFF
SA126	1	1	1	1	1	0	128/64	07E0000–07EFFFF
SA127	1	1	1	1	1	1	128/64	07F0000–07FFFFF

Autoselect Mode

The autoselect mode provides manufacturer and device identification, and sector group protection verification, through identifier codes output on DQ7–DQ0. This mode is primarily intended for programming equipment to automatically match a device to be programmed with its corresponding programming algorithm. However, the autoselect codes can also be accessed in-system through the command register.

When using programming equipment, the autoselect mode requires VID on address pin A9. Address pins A6, A3, A2, A1, and A0 must be as shown in Table 5. In addition, when verifying sector protection, the sector address must appear on the appropriate highest order address bits (see Table 2). Table 5 shows the remaining address bits that are don't care. When all necessary bits have been set as required, the programming equipment may then read the corresponding identifier code on DQ7–DQ0.

To access the autoselect codes in-system, the host system can issue the autoselect command via the command register, as shown in Table 12. This method does not require V_{ID}. Refer to the Autoselect Command Sequence section for more information.

Table 5. Autoselect Codes, (High Voltage Method)

Description		CE#	OE#	WE #	A22 to A15	A14 to A10	A9	A8 to A7	A6	A5 to A4	A3 to A2	A1	A0	DQ8 to DQ15	DQ7 to DQ0
Manufacturer ID: Spansion Product		L	L	H	X	X	V_{ID}	X	L	X	L	L	L	00	01h
Device ID S29GL512N	Cycle 1	L	L	H	X	X	V_{ID}	X	L	X	L	L	H	22	7Eh
	Cycle 2										H	H	L	22	23h
	Cycle 3										H	H	H	22	01h
Device ID S29GL256N	Cycle 1	L	L	H	X	X	V_{ID}	X	L	X	L	L	H	22	7Eh
	Cycle 2										H	H	L	22	22h
	Cycle 3										H	H	H	22	01h
Device ID S29GL128N	Cycle 1	L	L	H	X	X	V_{ID}	X	L	X	L	L	H	22	7Eh
	Cycle 2										H	H	L	22	21h
	Cycle 3										H	H	H	22	01h
Sector Group Protection Verification		L	L	H	SA	X	V_{ID}	X	L	X	L	H	L	X	01h (protected), 00h (unprotected)
Secured Silicon Sector Indicator Bit (DQ7), WP# protects highest address sector		L	L	H	X	X	V_{ID}	X	L	X	L	H	H	X	98h (factory locked), 18h (not factory locked)
Secured Silicon Sector Indicator Bit (DQ7), WP# protects lowest address sector		L	L	H	X	X	V_{ID}	X	L	X	L	H	H	X	88h (factory locked), 08h (not factory locked)

Legend: *L = Logic Low = V_{IL}, H = Logic High = V_{IH}, SA = Sector Address, X = Don't care.*

Sector Protection

The device features several levels of sector protection, which can disable both the program and erase operations in certain sectors or sector groups:

Persistent Sector Protection

A command sector protection method that replaces the old 12 V controlled protection method.

Password Sector Protection

A highly sophisticated protection method that requires a password before changes to certain sectors or sector groups are permitted

WP# Hardware Protection

A write protect pin that can prevent program or erase operations in the outermost sectors.

The WP# Hardware Protection feature is always available, independent of the software managed protection method chosen.

Selecting a Sector Protection Mode

All parts default to operate in the Persistent Sector Protection mode. The customer must then choose if the Persistent or Password Protection method is most desirable. There are two one-time programmable non-volatile bits that define which sector protection method will be used. If the customer decides to continue

using the Persistent Sector Protection method, they must set the **Persistent Sector Protection Mode Locking Bit**. This will permanently set the part to operate only using Persistent Sector Protection. If the customer decides to use the password method, they must set the **Password Mode Locking Bit**. This will permanently set the part to operate only using password sector protection.

It is important to remember that setting either the **Persistent Sector Protection Mode Locking Bit** or the **Password Mode Locking Bit** permanently selects the protection mode. It is not possible to switch between the two methods once a locking bit has been set. **It is important that one mode is explicitly selected when the device is first programmed, rather than relying on the default mode alone.** This is so that it is not possible for a system program or virus to later set the Password Mode Locking Bit, which would cause an unexpected shift from the default Persistent Sector Protection Mode into the Password Protection Mode.

The device is shipped with all sectors unprotected. The factory offers the option of programming and protecting sectors at the factory prior to shipping the device through the ExpressFlash™ Service. Contact your sales representative for details.

It is possible to determine whether a sector is protected or unprotected. See "Autoselect Command Sequence" section on page 66 for details.

Advanced Sector Protection

Advanced Sector Protection features several levels of sector protection, which can disable both the program and erase operations in certain sectors.

Persistent Sector Protection is a method that replaces the old 12V controlled protection method.

Password Sector Protection is a highly sophisticated protection method that requires a password before changes to certain sectors are permitted.

Lock Register

The Lock Register consists of 3 bits (DQ2, DQ1, and DQ0). These DQ2, DQ1, DQ0 bits of the Lock Register are programmable by the user. Users are not allowed to program both DQ2 and DQ1 bits of the Lock Register to the 00 state. If the user tries to program DQ2 and DQ1 bits of the Lock Register to the 00 state, the device will abort the Lock Register back to the default 11 state. The programming time of the Lock Register is same as the typical word programming time without utilizing the Write Buffer of the device. During a Lock Register programming sequence execution, the DQ6 Toggle Bit I will toggle until the programming of the Lock Register has completed to indicate programming status. All Lock Register bits are readable to allow users to verify Lock Register statuses.

The Customer Secured Silicon Sector Protection Bit is DQ0, Persistent Protection Mode Lock Bit is DQ1, and Password Protection Mode Lock Bit is DQ2 are accessible by all users. Each of these bits are non-volatile. DQ15-DQ3 are reserved and must be 1's when the user tries to program the DQ2, DQ1, and DQ0 bits of the Lock Register. The user is not required to program DQ2, DQ1 and DQ0 bits of the Lock Register at the same time. This allows users to lock the Secured Silicon Sector and then set the device either permanently into Password Protection Mode or Persistent Protection Mode and then lock the Secured Silicon Sector at separate instances and time frames.

- Secured Silicon Sector Protection allows the user to lock the Secured Silicon Sector area

- Persistent Protection Mode Lock Bit allows the user to set the device permanently to operate in the Persistent Protection Mode
- Password Protection Mode Lock Bit allows the user to set the device permanently to operate in the Password Protection Mode

Table 6. Lock Register

DQ15-3	DQ2	DQ1	DQ0
Don't Care	Password Protection Mode Lock Bit	Persistent Protection Mode Lock Bit	Secured Silicon Sector Protection Bit

Persistent Sector Protection

The Persistent Sector Protection method replaces the old 12 V controlled protection method while at the same time enhancing flexibility by providing three different sector protection states:

- **Dynamically Locked**-The sector is protected and can be changed by a simple command
- **Persistently Locked**-A sector is protected and cannot be changed
- **Unlocked**-The sector is unprotected and can be changed by a simple command

In order to achieve these states, three types of "bits" are going to be used:

Dynamic Protection Bit (DYB)

A volatile protection bit is assigned for each sector. After power-up or hardware reset, the contents of all DYB bits are in the "unprotected state". Each DYB is individually modifiable through the DYB Set Command and DYB Clear Command. When the parts are first shipped, all of the Persistent Protect Bits (PPB) are cleared into the unprotected state. The DYB bits and PPB Lock bit are defaulted to power up in the cleared state or unprotected state - meaning the all PPB bits are changeable.

The Protection State for each sector is determined by the logical OR of the PPB and the DYB related to that sector. For the sectors that have the PPB bits cleared, the DYB bits control whether or not the sector is protected or unprotected. By issuing the DYB Set and DYB Clear command sequences, the DYB bits will be protected or unprotected, thus placing each sector in the protected or unprotected state. These are the so-called Dynamic Locked or Unlocked states. They are called dynamic states because it is very easy to switch back and forth between the protected and un-protected conditions. This allows software to easily protect sectors against inadvertent changes yet does not prevent the easy removal of protection when changes are needed.

The DYB bits maybe set or cleared as often as needed. The PPB bits allow for a more static, and difficult to change, level of protection. The PPB bits retain their state across power cycles because they are Non-Volatile. Individual PPB bits are set with a program command but must all be cleared as a group through an erase command.

The PPB Lock Bit adds an additional level of protection. Once all PPB bits are programmed to the desired settings, the PPB Lock Bit may be set to the "freeze state". Setting the PPB Lock Bit to the "freeze state" disables all program and erase commands to the Non-Volatile PPB bits. In effect, the PPB Lock Bit locks the PPB bits into their current state. The only way to clear the PPB Lock Bit to the

"unfreeze state" is to go through a power cycle, or hardware reset. The Software Reset command will not clear the PPB Lock Bit to the "unfreeze state". System boot code can determine if any changes to the PPB bits are needed e.g. to allow new system code to be downloaded. If no changes are needed then the boot code can set the PPB Lock Bit to disable any further changes to the PPB bits during system operation.

The WP# write protect pin adds a final level of hardware protection. When this pin is low it is not possible to change the contents of the WP# protected sectors. These sectors generally hold system boot code. So, the WP# pin can prevent any changes to the boot code that could override the choices made while setting up sector protection during system initialization.

It is possible to have sectors that have been persistently locked, and sectors that are left in the dynamic state. The sectors in the dynamic state are all unprotected. If there is a need to protect some of them, a simple DYB Set command sequence is all that is necessary. The DYB Set and DYB Clear commands for the dynamic sectors switch the DYB bits to signify protected and unprotected, respectively. If there is a need to change the status of the persistently locked sectors, a few more steps are required. First, the PPB Lock Bit must be disabled to the "unfreeze state" by either putting the device through a power-cycle, or hardware reset. The PPB bits can then be changed to reflect the desired settings. Setting the PPB Lock Bit once again to the "freeze state" will lock the PPB bits, and the device operates normally again.

Note: to achieve the best protection, it's recommended to execute the PPB Lock Bit Set command early in the boot code, and protect the boot code by holding WP# = V_{IL}.

Persistent Protection Bit (PPB)

A single Persistent (non-volatile) Protection Bit is assigned to each sector. If a PPB is programmed to the protected state through the "PPB Program" command, that sector will be protected from program or erase operations will be read-only. If a PPB requires erasure, all of the sector PPB bits must first be erased in parallel through the "All PPB Erase" command. The "All PPB Erase" command will preprogrammed all PPB bits prior to PPB erasing. All PPB bits erase in parallel, unlike programming where individual PPB bits are programmable. The PPB bits have the same endurance as the flash memory.

Programming the PPB bit requires the typical word programming time without utilizing the Write Buffer. During a PPB bit programming and A11 PPB bit erasing sequence execution, the DQ6 Toggle Bit I will toggle until the programming of the PPB bit or erasing of all PPB bits has completed to indicate programming and erasing status. Erasing all of the PPB bits at once requires typical sector erase time. During the erasing of all PPB bits, the DQ3 Sector Erase Timer bit will output a 1 to indicate the erasure of all PPB bits are in progress. When the erasure of all PPB bits has completed, the DQ3 Sector Erase Timer bit will output a 0 to indicate that all PPB bits have been erased. Reading the PPB Status bit requires the initial access time of the device.

Persistent Protection Bit Lock (PPB Lock Bit)

A global volatile bit. When set to the "freeze state", the PPB bits cannot be changed. When cleared to the "unfreeze state", the PPB bits are changeable. There is only one PPB Lock Bit per device. The PPB Lock Bit is cleared to the "un-

freeze state" after power-up or hardware reset. There is no command sequence to unlock or "unfreeze" the PPB Lock Bit.

Configuring the PPB Lock Bit to the freeze state requires approximately 100ns. Reading the PPB Lock Status bit requires the initial access time of the device.

Table 7. Sector Protection Schemes

Protection States			Sector State
DYB Bit	PPB Bit	PPB Lock Bit	
Unprotect	Unprotect	Unfreeze	Unprotected – PPB and DYB are changeable
Unprotect	Unprotect	Freeze	Unprotected – PPB not changeable, DYB is changeable
Unprotect	Protect	Unfreeze	Protected – PPB and DYB are changeable
Unprotect	Protect	Freeze	Protected – PPB not changeable, DYB is changeable
Protect	Unprotect	Unfreeze	Protected – PPB and DYB are changeable
Protect	Unprotect	Freeze	Protected – PPB not changeable, DYB is changeable
Protect	Protect	Unfreeze	Protected – PPB and DYB are changeable
Protect	Protect	Freeze	Protected – PPB not changeable, DYB is changeable

Table 7 contains all possible combinations of the DYB bit, PPB bit, and PPB Lock Bit relating to the status of the sector. In summary, if the PPB bit is set, and the PPB Lock Bit is set, the sector is protected and the protection cannot be removed until the next power cycle or hardware reset clears the PPB Lock Bit to "unfreeze state". If the PPB bit is cleared, the sector can be dynamically locked or unlocked. The DYB bit then controls whether or not the sector is protected or unprotected. If the user attempts to program or erase a protected sector, the device ignores the command and returns to read mode. A program command to a protected sector enables status polling for approximately 1 µs before the device returns to read mode without having modified the contents of the protected sector. An erase command to a protected sector enables status polling for approximately 50 µs after which the device returns to read mode without having erased the protected sector. The programming of the DYB bit, PPB bit, and PPB Lock Bit for a given sector can be verified by writing a DYB Status Read, PPB Status Read, and PPB Lock Status Read commands to the device.

The Autoselect Sector Protection Verification outputs the OR function of the DYB bit and PPB bit per sector basis. When the OR function of the DYB bit and PPB bit is a 1, the sector is either protected by DYB or PPB or both. When the OR function of the DYB bit and PPB bit is a 0, the sector is unprotected through both the DYB and PPB.

Persistent Protection Mode Lock Bit

Like the Password Protection Mode Lock Bit, a Persistent Protection Mode Lock Bit exists to guarantee that the device remain in software sector protection. Once programmed, the Persistent Protection Mode Lock Bit prevents programming of the Password Protection Mode Lock Bit. This guarantees that a hacker could not place the device in Password Protection Mode. The Password Protection Mode Lock Bit resides in the "Lock Register".

Password Sector Protection

The Password Sector Protection method allows an even higher level of security than the Persistent Sector Protection method. There are two main differences between the Persistent Sector Protection and the Password Sector Protection methods:

- When the device is first powered on, or comes out of a reset cycle, the PPB Lock Bit is set to the locked state, or the freeze state, rather than cleared to the unlocked state, or the unfreeze state.
- The only means to clear and unfreeze the PPB Lock Bit is by writing a unique 64-bit Password to the device.

The Password Sector Protection method is otherwise identical to the Persistent Sector Protection method.

A 64-bit password is the only additional tool utilized in this method.

The password is stored in a one-time programmable (OTP) region outside of the flash memory. Once the Password Protection Mode Lock Bit is set, the password is permanently set with no means to read, program, or erase it. The password is used to clear and unfreeze the PPB Lock Bit. The Password Unlock command must be written to the flash, along with a password. The flash device internally compares the given password with the pre-programmed password. If they match, the PPB Lock Bit is cleared to the “unfreezed state”, and the PPB bits can be altered. If they do not match, the flash device does nothing. There is a built-in 2 µs delay for each “password check” after the valid 64-bit password has been entered for the PPB Lock Bit to be cleared to the “unfreezed state”. This delay is intended to thwart any efforts to run a program that tries all possible combinations in order to crack the password.

Password and Password Protection Mode Lock Bit

In order to select the Password Sector Protection method, the customer must first program the password. The factory recommends that the password be somehow correlated to the unique Electronic Serial Number (ESN) of the particular flash device. Each ESN is different for every flash device; therefore each password should be different for every flash device. While programming in the password region, the customer may perform Password Read operations. Once the desired password is programmed in, the customer must then set the Password Protection Mode Lock Bit. This operation achieves two objectives:

1. It permanently sets the device to operate using the Password Protection Mode. It is not possible to reverse this function.
2. It also disables all further commands to the password region. All program, and read operations are ignored.

Both of these objectives are important, and if not carefully considered, may lead to unrecoverable errors. The user must be sure that the Password Sector Protection method is desired when programming the Password Protection Mode Lock Bit. More importantly, the user must be sure that the password is correct when the Password Protection Mode Lock Bit is programmed. Due to the fact that read operations are disabled, there is no means to read what the password is afterwards. If the password is lost after programming the Password Protection Mode Lock Bit, there will be no way to clear and unfreeze the PPB Lock Bit. The Password Protection Mode Lock Bit, once programmed, prevents reading the 64-bit password on the DQ bus and further password programming. The Password Protection Mode Lock Bit is not erasable. Once Password Protection Mode Lock Bit is

programmed, the Persistent Protection Mode Lock Bit is disabled from programming, guaranteeing that no changes to the protection scheme are allowed.

64-bit Password

The 64-bit Password is located in its own memory space and is accessible through the use of the Password Program and Password Read commands. The password function works in conjunction with the Password Protection Mode Lock Bit, which when programmed, prevents the Password Read command from reading the contents of the password on the pins of the device.

Persistent Protection Bit Lock (PPB Lock Bit)

A global volatile bit. The PPB Lock Bit is a volatile bit that reflects the state of the Password Protection Mode Lock Bit after power-up reset. If the Password Protection Mode Lock Bit is also programmed after programming the Password, the Password Unlock command must be issued to clear and unfreeze the PPB Lock Bit after a hardware reset (RESET# asserted) or a power-up reset. Successful execution of the Password Unlock command clears and unfreezes the PPB Lock Bit, allowing for sector PPB bits to be modified. Without issuing the Password Unlock command, while asserting RESET#, taking the device through a power-on reset, or issuing the PPB Lock Bit Set command sets the PPB Lock Bit to a the “freeze state”.

If the Password Protection Mode Lock Bit is not programmed, the device defaults to Persistent Protection Mode. In the Persistent Protection Mode, the PPB Lock Bit is cleared to the “unfreeze state” after power-up or hardware reset. The PPB Lock Bit is set to the “freeze state” by issuing the PPB Lock Bit Set command. Once set to the “freeze state” the only means for clearing the PPB Lock Bit to the “unfreeze state” is by issuing a hardware or power-up reset. The Password Unlock command is ignored in Persistent Protection Mode.

Reading the PPB Lock Bit requires a 200ns access time.

Secured Silicon Sector Flash Memory Region

The Secured Silicon Sector feature provides a Flash memory region that enables permanent part identification through an Electronic Serial Number (ESN). The Secured Silicon Sector is 256 bytes in length, and uses a Secured Silicon Sector Indicator Bit (DQ7) to indicate whether or not the Secured Silicon Sector is locked when shipped from the factory. This bit is permanently set at the factory and cannot be changed, which prevents cloning of a factory locked part. This ensures the security of the ESN once the product is shipped to the field.

The factory offers the device with the Secured Silicon Sector either customer lockable (standard shipping option) or factory locked (contact an AMD sales representative for ordering information). The customer-lockable version is shipped with the Secured Silicon Sector unprotected, allowing customers to program the sector after receiving the device. The customer-lockable version also has the Secured Silicon Sector Indicator Bit permanently set to a “0.” The factory-locked version is always protected when shipped from the factory, and has the Secured Silicon Sector Indicator Bit permanently set to a “1.” Thus, the Secured Silicon Sector Indicator Bit prevents customer-lockable devices from being used to replace devices that are factory locked. *Note that the ACC function and unlock bypass modes are not available when the Secured Silicon Sector is enabled.*

The Secured Silicon sector address space in this device is allocated as follows:

Secured Silicon Sector Address Range	Customer Lockable	ESN Factory Locked	ExpressFlash Factory Locked
000000h–000007h	Determined by customer	ESN	ESN or determined by customer
000008h–00007Fh		Unavailable	Determined by customer

The system accesses the Secured Silicon Sector through a command sequence (see “Write Protect (WP#)”). After the system has written the Enter Secured Silicon Sector command sequence, it may read the Secured Silicon Sector by using the addresses normally occupied by the first sector (SA0). This mode of operation continues until the system issues the Exit Secured Silicon Sector command sequence, or until power is removed from the device. On power-up, or following a hardware reset, the device reverts to sending commands to sector SA0.

Customer Lockable: Secured Silicon Sector NOT Programmed or Protected At the Factory

Unless otherwise specified, the device is shipped such that the customer may program and protect the 256-byte Secured Silicon sector.

The system may program the Secured Silicon Sector using the write-buffer, accelerated and/or unlock bypass methods, in addition to the standard programming command sequence. See “Command Definitions” .

Programming and protecting the Secured Silicon Sector must be used with caution since, once protected, there is no procedure available for unprotecting the Secured Silicon Sector area and none of the bits in the Secured Silicon Sector memory space can be modified in any way.

The Secured Silicon Sector area can be protected using one of the following procedures:

- Write the three-cycle Enter Secured Silicon Sector Region command sequence, and then follow the in-system sector protect algorithm, except that *RESET# may be at either V_{IH} or V_{ID}*. This allows in-system protection of the Secured Silicon Sector without raising any device pin to a high voltage. Note that this method is only applicable to the Secured Silicon Sector.
- To verify the protect/unprotect status of the Secured Silicon Sector, follow the algorithm.

Once the Secured Silicon Sector is programmed, locked and verified, the system must write the Exit Secured Silicon Sector Region command sequence to return to reading and writing within the remainder of the array.

Factory Locked: Secured Silicon Sector Programmed and Protected At the Factory

In devices with an ESN, the Secured Silicon Sector is protected when the device is shipped from the factory. The Secured Silicon Sector cannot be modified in any way. An ESN Factory Locked device has an 16-byte random ESN at addresses 000000h–000007h. Please contact your sales representative for details on ordering ESN Factory Locked devices.

Customers may opt to have their code programmed by the factory through the ExpressFlash service (Express Flash Factory Locked). The devices are then shipped from the factory with the Secured Silicon Sector permanently locked. Contact your sales representative for details on using the ExpressFlash service.

Write Protect (WP#)

The Write Protect function provides a hardware method of protecting the first or last sector group without using V_{ID}. Write Protect is one of two functions provided by the WP#/ACC input.

If the system asserts V_{IL} on the WP#/ACC pin, the device disables program and erase functions in the first or last sector group independently of whether those sector groups were protected or unprotected using the method described in"Advanced Sector Protection" section on page 54. Note that if WP#/ACC is at V_{IL} when the device is in the standby mode, the maximum input load current is increased. See the table in "DC Characteristics" section on page 90.

If the system asserts V_{IH} on the WP#/ACC pin, the device reverts to whether the first or last sector was previously set to be protected or unprotected using the method described in "Sector Group Protection and Unprotection". *Note that WP# has an internal pullup; when unconnected, WP# is at V_{IH}.*

Hardware Data Protection

The command sequence requirement of unlock cycles for programming or erasing provides data protection against inadvertent writes (refer to Table 12 for command definitions). In addition, the following hardware data protection measures prevent accidental erasure or programming, which might otherwise be caused by spurious system level signals during V_{CC} power-up and power-down transitions, or from system noise.

Low V_{CC} Write Inhibit

When V_{CC} is less than V_{LKO}, the device does not accept any write cycles. This protects data during V_{CC} power-up and power-down. The command register and all internal program/erase circuits are disabled, and the device resets to the read mode. Subsequent writes are ignored until V_{CC} is greater than V_{LKO}. The system must provide the proper signals to the control pins to prevent unintentional writes when V_{CC} is greater than V_{LKO}.

Write Pulse "Glitch" Protection

Noise pulses of less than 5 ns (typical) on OE#, CE# or WE# do not initiate a write cycle.

Logical Inhibit

Write cycles are inhibited by holding any one of OE# = V_{IL}, CE# = V_{IH} or WE# = V_{IH}. To initiate a write cycle, CE# and WE# must be a logical zero while OE# is a logical one.

Power-Up Write Inhibit

If WE# = CE# = V_{IL} and OE# = V_{IH} during power up, the device does not accept commands on the rising edge of WE#. The internal state machine is automatically reset to the read mode on power-up.

Common Flash Memory Interface (CFI)

The Common Flash Interface (CFI) specification outlines device and host system software interrogation handshake, which allows specific vendor-specified software algorithms to be used for entire families of devices. Software support can

then be device-independent, JEDEC ID-independent, and forward- and backward-compatible for the specified flash device families. Flash vendors can standardize their existing interfaces for long-term compatibility.

This device enters the CFI Query mode when the system writes the CFI Query command, 98h, to address 55h, any time the device is ready to read array data. The system can read CFI information at the addresses given in Tables 8-11. To terminate reading CFI data, the system must write the reset command.

The system can also write the CFI query command when the device is in the autoselect mode. The device enters the CFI query mode, and the system can read CFI data at the addresses given in Tables 8–11. The system must write the reset command to return the device to reading array data.

For further information, please refer to the CFI Specification and CFI Publication 100, available via the World Wide Web at http://www.amd.com/flash/cfi. Alternatively, contact your sales representative for copies of these documents.

Table 8. CFI Query Identification String

Addresses (x16)	Data	Description
10h 11h 12h	0051h 0052h 0059h	Query Unique ASCII string “QRY”
13h 14h	0002h 0000h	Primary OEM Command Set
15h 16h	0040h 0000h	Address for Primary Extended Table
17h 18h	0000h 0000h	Alternate OEM Command Set (00h = none exists)
19h 1Ah	0000h 0000h	Address for Alternate OEM Extended Table (00h = none exists)

Table 9. System Interface String

Addresses (x16)	Data	Description
1Bh	0027h	V_{CC} Min. (write/erase) D7–D4: volt, D3–D0: 100 millivolt
1Ch	0036h	V_{CC} Max. (write/erase) D7–D4: volt, D3–D0: 100 millivolt
1Dh	0000h	V_{PP} Min. voltage (00h = no V_{PP} pin present)
1Eh	0000h	V_{PP} Max. voltage (00h = no V_{PP} pin present)
1Fh	0007h	Typical timeout per single byte/word write 2^N µs
20h	0007h	Typical timeout for Min. size buffer write 2^N µs (00h = not supported)
21h	000Ah	Typical timeout per individual block erase 2^N ms
22h	0000h	Typical timeout for full chip erase 2^N ms (00h = not supported)
23h	0001h	Max. timeout for byte/word write 2^N times typical
24h	0005h	Max. timeout for buffer write 2^N times typical
25h	0004h	Max. timeout per individual block erase 2^N times typical
26h	0000h	Max. timeout for full chip erase 2^N times typical (00h = not supported)

Table 10. Device Geometry Definition

Addresses (x16)	Data	Description
27h	001Ah 0019h 0018h	Device Size = 2^N byte 1A = 512 Mb, 19 = 256 Mb, 18 = 128 Mb
28h 29h	0002h 0000h	Flash Device Interface description (refer to CFI publication 100)
2Ah 2Bh	0005h 0000h	Max. number of byte in multi-byte write = 2^N (00h = not supported)
2Ch	0001h	Number of Erase Block Regions within device (01h = uniform device, 02h = boot device)
2Dh 2Eh 2Fh 30h	00xxh 000xh 0000h 000xh	Erase Block Region 1 Information (refer to the CFI specification or CFI publication 100) 00FFh, 001h, 0000h, 0002h = 512 Mb 00FFh, 0000h, 0000h, 0002h = 256 Mb 007Fh, 0000h, 0000h, 0002h = 128 Mb
31h 32h 33h 34h	0000h 0000h 0000h 0000h	Erase Block Region 2 Information (refer to CFI publication 100)
35h 36h 37h 38h	0000h 0000h 0000h 0000h	Erase Block Region 3 Information (refer to CFI publication 100)
39h 3Ah 3Bh 3Ch	0000h 0000h 0000h 0000h	Erase Block Region 4 Information (refer to CFI publication 100)

Table II. Primary Vendor-Specific Extended Query

Addresses (x16)	Data	Description
40h 41h 42h	0050h 0052h 0049h	Query-unique ASCII string “PRI”
43h	0031h	Major version number, ASCII
44h	0033h	Minor version number, ASCII
45h	0010h	Address Sensitive Unlock (Bits 1-0) 0 = Required, 1 = Not Required Process Technology (Bits 7-2) 0100b = 110 nm MirrorBit
46h	0002h	Erase Suspend 0 = Not Supported, 1 = To Read Only, 2 = To Read & Write
47h	0001h	Sector Protect 0 = Not Supported, X = Number of sectors in per group
48h	0000h	Sector Temporary Unprotect 00 = Not Supported, 01 = Supported
49h	0008h	Sector Protect/Unprotect scheme 0008h = Advanced Sector Protection
4Ah	0000h	Simultaneous Operation 00 = Not Supported, X = Number of Sectors in Bank
4Bh	0000h	Burst Mode Type 00 = Not Supported, 01 = Supported
4Ch	0002h	Page Mode Type 00 = Not Supported, 01 = 4 Word Page, 02 = 8 Word Page
4Dh	00B5h	ACC (Acceleration) Supply Minimum 00h = Not Supported, D7-D4: Volt, D3-D0: 100 mV
4Eh	00C5h	ACC (Acceleration) Supply Maximum 00h = Not Supported, D7-D4: Volt, D3-D0: 100 mV
4Fh	00xxh	WP# Protection 04h = Uniform sectors bottom WP# protect, 05h = Uniform sectors top WP# protect
50h	0001h	Program Suspend 00h = Not Supported, 01h = Supported

Command Definitions

Writing specific address and data commands or sequences into the command register initiates device operations. Table 12 defines the valid register command sequences. *Writing incorrect address and data values or writing them in the improper sequence may place the device in an unknown state.* A reset command is then required to return the device to reading array data.

All addresses are latched on the falling edge of WE# or CE#, whichever happens later. All data is latched on the rising edge of WE# or CE#, whichever happens first. Refer to the AC Characteristics section for timing diagrams.

Reading Array Data

The device is automatically set to reading array data after device power-up. No commands are required to retrieve data. The device is ready to read array data after completing an Embedded Program or Embedded Erase algorithm.

After the device accepts an Erase Suspend command, the device enters the erase-suspend-read mode, after which the system can read data from any non-erase-suspended sector. After completing a programming operation in the Erase Suspend mode, the system may once again read array data with the same exception. See the Erase Suspend/Erase Resume Commands section for more information.

The system *must* issue the reset command to return the device to the read (or erase-suspend-read) mode if DQ5 goes high during an active program or erase operation, or if the device is in the autoselect mode. See the next section, Reset Command, for more information.

See also Requirements for Reading Array Data in the Device Bus Operations section for more information. The Read-Only Operations–"AC Characteristics" section provides the read parameters, and Figure 11 shows the timing diagram.

Reset Command

Writing the reset command resets the device to the read or erase-suspend-read mode. Address bits are don't cares for this command.

The reset command may be written between the sequence cycles in an erase command sequence before erasing begins. This resets the device to the read mode. Once erasure begins, however, the device ignores reset commands until the operation is complete.

The reset command may be written between the sequence cycles in a program command sequence before programming begins. This resets the device to the read mode. If the program command sequence is written while the device is in the Erase Suspend mode, writing the reset command returns the device to the erase-suspend-read mode. Once programming begins, however, the device ignores reset commands until the operation is complete.

The reset command may be written between the sequence cycles in an autoselect command sequence. Once in the autoselect mode, the reset command must be written to return to the read mode. If the device entered the autoselect mode while in the Erase Suspend mode, writing the reset command returns the device to the erase-suspend-read mode.

If DQ5 goes high during a program or erase operation, writing the reset command returns the device to the read mode (or erase-suspend-read mode if the device was in Erase Suspend).

Note that if DQ1 goes high during a Write Buffer Programming operation, the system must write the Write-to-Buffer-Abort Reset command sequence to reset the device for the next operation.

Autoselect Command Sequence

The autoselect command sequence allows the host system to access the manufacturer and device codes, and determine whether or not a sector is protected. Table 12 shows the address and data requirements. This method is an alternative to that shown in Table 5, which is intended for PROM programmers and requires V_{ID} on address pin A9. The autoselect command sequence may be written to an

address that is either in the read or erase-suspend-read mode. The autoselect command may not be written while the device is actively programming or erasing.

The autoselect command sequence is initiated by first writing two unlock cycles. This is followed by a third write cycle that contains the autoselect command. The device then enters the autoselect mode. The system may read at any address any number of times without initiating another autoselect command sequence:

- A read cycle at address XX00h returns the manufacturer code.
- Three read cycles at addresses 01h, 0Eh, and 0Fh return the device code.
- A read cycle to an address containing a sector address (SA), and the address 02h on A7–A0 in word mode returns 01h if the sector is protected, or 00h if it is unprotected.

The system must write the reset command to return to the read mode (or erase-suspend-read mode if the device was previously in Erase Suspend).

Enter Secured Silicon Sector/Exit Secured Silicon Sector Command Sequence

The Secured Silicon Sector region provides a secured data area containing an 8-word/16-byte random Electronic Serial Number (ESN). The system can access the Secured Silicon Sector region by issuing the three-cycle Enter Secured Silicon Sector command sequence. The device continues to access the Secured Silicon Sector region until the system issues the four-cycle Exit Secured Silicon Sector command sequence. The Exit Secured Silicon Sector command sequence returns the device to normal operation. Table 12 shows the address and data requirements for both command sequences. See also “Secured Silicon Sector Flash Memory Region” for further information. *Note that the ACC function and unlock bypass modes are not available when the Secured Silicon Sector is enabled.*

Word Program Command Sequence

Programming is a four-bus-cycle operation. The program command sequence is initiated by writing two unlock write cycles, followed by the program set-up command. The program address and data are written next, which in turn initiate the Embedded Program algorithm. The system is *not* required to provide further controls or timings. The device automatically provides internally generated program pulses and verifies the programmed cell margin. Table 12 shows the address and data requirements for the word program command sequence.

When the Embedded Program algorithm is complete, the device then returns to the read mode and addresses are no longer latched. The system can determine the status of the program operation by using DQ7 or DQ6. Refer to the Write Operation Status section for information on these status bits.

Any commands written to the device during the Embedded Program Algorithm are ignored. ***Note that the Secured Silicon Sector, autoselect, and CFI functions are unavailable when a program operation is in progress.*** Note that a **hardware reset** immediately terminates the program operation. The program command sequence should be reinitiated once the device has returned to the read mode, to ensure data integrity.

Programming is allowed in any sequence of address locations and across sector boundaries. Programming to the same word address multiple times without intervening erases (incremental bit programming) requires a modified programming method. For such application requirements, please contact your

local Spansion representative. Word programming is supported for backward compatibility with existing Flash driver software and for occasional writing of individual words. Use of Write Buffer Programming is strongly recommended for general programming use when more than a few words are to be programmed. The effective word programming time using Write Buffer Programming is much shorter than the single word programming time. **Any word cannot be programmed from "0" back to a "1."** Attempting to do so may cause the device to set DQ5 = 1, or cause the DQ7 and DQ6 status bits to indicate the operation was successful. However, a succeeding read will show that the data is still "0." Only erase operations can convert a "0" to a "1."

Unlock Bypass Command Sequence

The unlock bypass feature allows the system to program words to the device faster than using the standard program command sequence. The unlock bypass command sequence is initiated by first writing two unlock cycles. This is followed by a third write cycle containing the unlock bypass command, 20h. The device then enters the unlock bypass mode. A two-cycle unlock bypass program command sequence is all that is required to program in this mode. The first cycle in this sequence contains the unlock bypass program command, A0h; the second cycle contains the program address and data. Additional data is programmed in the same manner. This mode dispenses with the initial two unlock cycles required in the standard program command sequence, resulting in faster total programming time. Table 12 shows the requirements for the command sequence.

During the unlock bypass mode, only the Unlock Bypass Program and Unlock Bypass Reset commands are valid. To exit the unlock bypass mode, the system must issue the two-cycle unlock bypass reset command sequence. (See Table 12).

Write Buffer Programming

Write Buffer Programming allows the system write to a maximum of 16 words/32 bytes in one programming operation. This results in faster effective programming time than the standard programming algorithms. The Write Buffer Programming command sequence is initiated by first writing two unlock cycles. This is followed by a third write cycle containing the Write Buffer Load command written at the Sector Address in which programming will occur. The fourth cycle writes the sector address and the number of word locations, minus one, to be programmed. For example, if the system will program 6 unique address locations, then 05h should be written to the device. This tells the device how many write buffer addresses will be loaded with data and therefore when to expect the Program Buffer to Flash command. The number of locations to program cannot exceed the size of the write buffer or the operation will abort.

The fifth cycle writes the first address location and data to be programmed. The write-buffer-page is selected by address bits A_{MAX}–A_4. All subsequent address/data pairs must fall within the selected-write-buffer-page. The system then writes the remaining address/data pairs into the write buffer. Write buffer locations may be loaded in any order.

The write-buffer-page address must be the same for all address/data pairs loaded into the write buffer. (This means Write Buffer Programming cannot be performed across multiple write-buffer pages. This also means that Write Buffer Programming cannot be performed across multiple sectors. If the system attempts to load programming data outside of the selected write-buffer page, the operation will abort.)

Note that if a Write Buffer address location is loaded multiple times, the address/data pair counter will be decremented for every data load operation. The host system must therefore account for loading a write-buffer location more than once. The counter decrements for each data load operation, not for each unique write-buffer-address location. Note also that if an address location is loaded more than once into the buffer, the final data loaded for that address will be programmed.

Once the specified number of write buffer locations have been loaded, the system must then write the Program Buffer to Flash command at the sector address. Any other address and data combination aborts the Write Buffer Programming operation. The device then begins programming. Data polling should be used while monitoring the last address location loaded into the write buffer. DQ7, DQ6, DQ5, and DQ1 should be monitored to determine the device status during Write Buffer Programming.

The write-buffer programming operation can be suspended using the standard program suspend/resume commands. Upon successful completion of the Write Buffer Programming operation, the device is ready to execute the next command.

The Write Buffer Programming Sequence can be aborted in the following ways:

- Load a value that is greater than the page buffer size during the Number of Locations to Program step.
- Write to an address in a sector different than the one specified during the Write-Buffer-Load command.
- Write an Address/Data pair to a different write-buffer-page than the one selected by the Starting Address during the write buffer data loading stage of the operation.
- Write data other than the Confirm Command after the specified number of data load cycles.

The abort condition is indicated by DQ1 = 1, DQ7 = DATA# (for the last address location loaded), DQ6 = toggle, and DQ5=0. A Write-to-Buffer-Abort Reset command sequence must be written to reset the device for the next operation. Note that the full 3-cycle Write-to-Buffer-Abort Reset command sequence is required when using Write-Buffer-Programming features in Unlock Bypass mode.

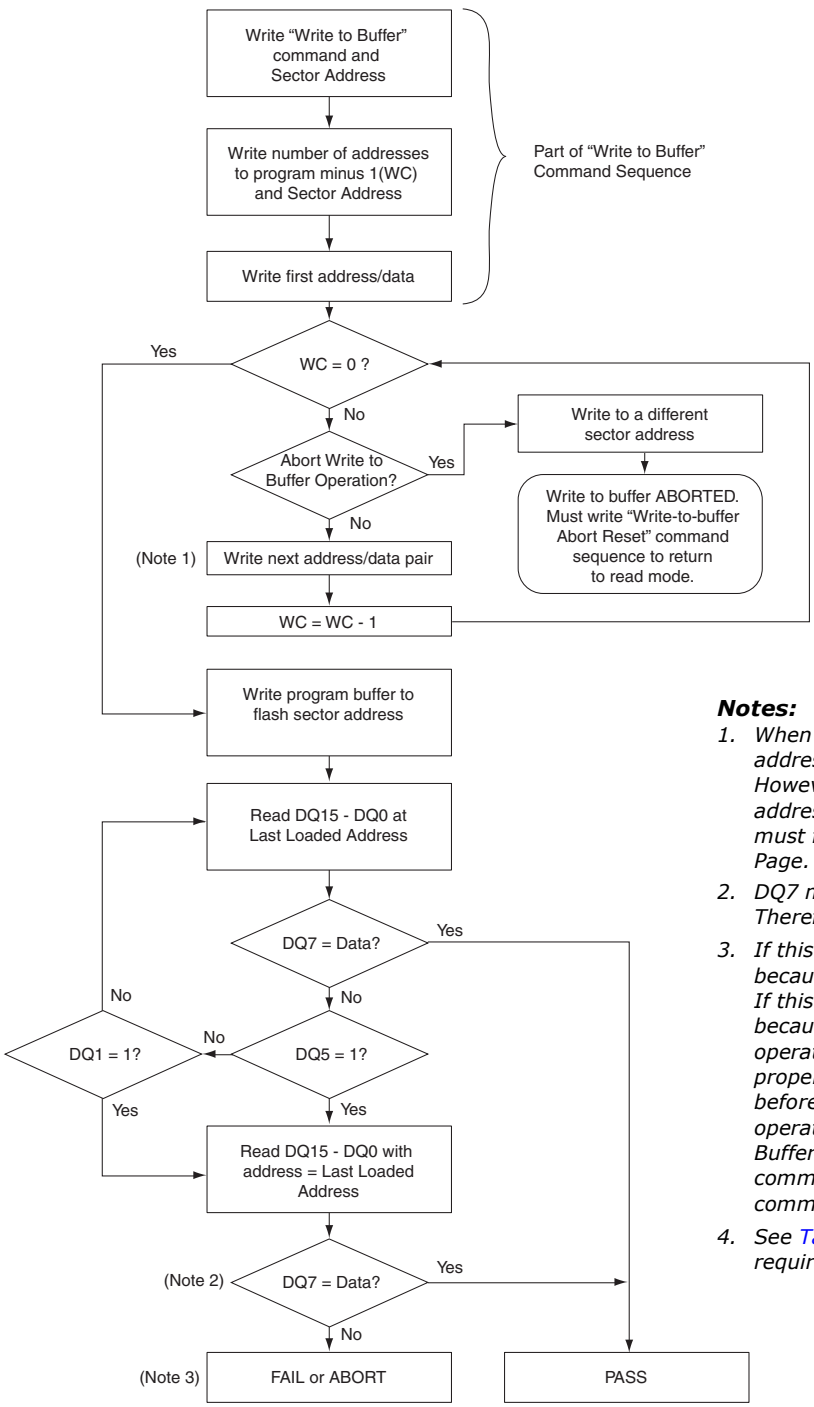
Write buffer programming is allowed in any sequence. Note that the Secured Silicon sector, autoselect, and CFI functions are unavailable when a program operation is in progress. This flash device is capable of handling multiple write buffer programming operations on the same write buffer address range without intervening erases. For applications requiring incremental bit programming, a modified programming method is required, please contact your local Spansion representative. **Any bit in a write buffer address range cannot be programmed from "0" back to a "1."** Attempting to do so may cause the device to set DQ5 = 1, or cause the DQ7 and DQ6 status bits to indicate the operation was successful. However, a succeeding read will show that the data is still "0." Only erase operations can convert a "0" to a "1."

Accelerated Program

The device offers accelerated program operations through the WP#/ACC pin. When the system asserts V_{HH} on the WP#/ACC pin, the device automatically enters the Unlock Bypass mode. The system may then write the two-cycle Unlock Bypass program command sequence. The device uses the higher voltage on the WP#/ACC pin to accelerate the operation. *Note that the* WP#/*ACC pin must not*

be at V_{HH} for operations other than accelerated programming, or device damage may result. WP# has an internal pullup; when unconnected, WP# is at V_{IH}.

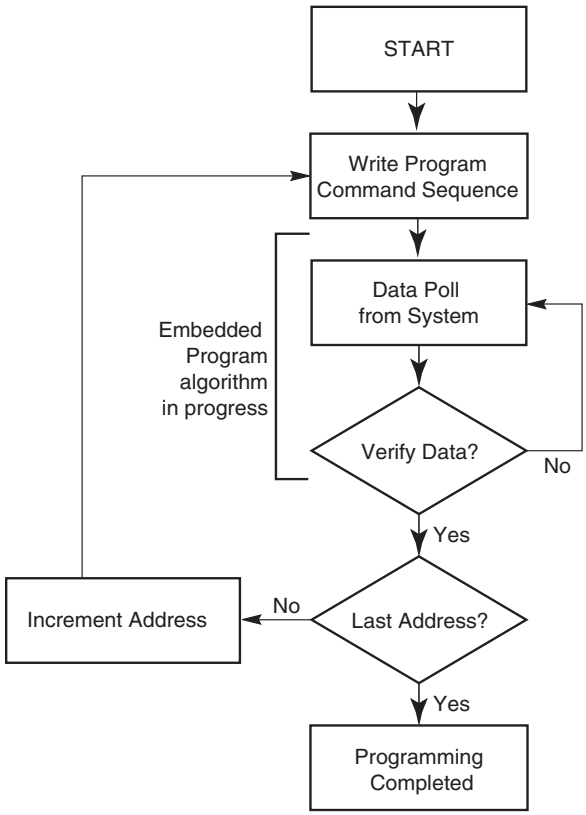
Figure 2 illustrates the algorithm for the program operation. Refer to the Erase and Program Operations–"AC Characteristics" section for parameters, and Figure 14 for timing diagrams.



Notes:

1. *When Sector Address is specified, any address in the selected sector is acceptable. However, when loading Write-Buffer address locations with data, all addresses must fall within the selected Write-Buffer Page.*
2. *DQ7 may change simultaneously with DQ5. Therefore, DQ7 should be verified.*
3. *If this flowchart location was reached because DQ5= "1", then the device FAILED. If this flowchart location was reached because DQ1= "1", then the Write to Buffer operation was ABORTED. In either case, the proper reset command must be written before the device can begin another operation. If DQ1=1, write the Write-Buffer-Programming-Abort-Reset command. if DQ5=1, write the Reset command.*
4. *See Table 12 for command sequences required for write buffer programming.*

Figure I. Write Buffer Programming Operation



Note: *See Table 12 for program command sequence.*

Figure 2. Program Operation

Program Suspend/Program Resume Command Sequence

The Program Suspend command allows the system to interrupt a programming operation or a Write to Buffer programming operation so that data can be read from any non-suspended sector. When the Program Suspend command is written during a programming process, the device halts the program operation within 15 µs maximum (5µs typical) and updates the status bits. Addresses are not required when writing the Program Suspend command.

After the programming operation has been suspended, the system can read array data from any non-suspended sector. The Program Suspend command may also be issued during a programming operation while an erase is suspended. In this case, data may be read from any addresses not in Erase Suspend or Program Suspend. If a read is needed from the Secured Silicon Sector area (One-time Program area), then user must use the proper command sequences to enter and exit this region. *Note that the Secured Silicon Sector autoselect, and CFI functions are unavailable when program operation is in progress.*

The system may also write the autoselect command sequence when the device is in the Program Suspend mode. The system can read as many autoselect codes as required. When the device exits the autoselect mode, the device reverts to the Program Suspend mode, and is ready for another valid operation. See Autoselect Command Sequence for more information.

After the Program Resume command is written, the device reverts to programming. The system can determine the status of the program operation using the DQ7 or DQ6 status bits, just as in the standard program operation. See Write Operation Status for more information.

The system must write the Program Resume command (address bits are don't care) to exit the Program Suspend mode and continue the programming operation. Further writes of the Resume command are ignored. Another Program Suspend command can be written after the device has resume programming.

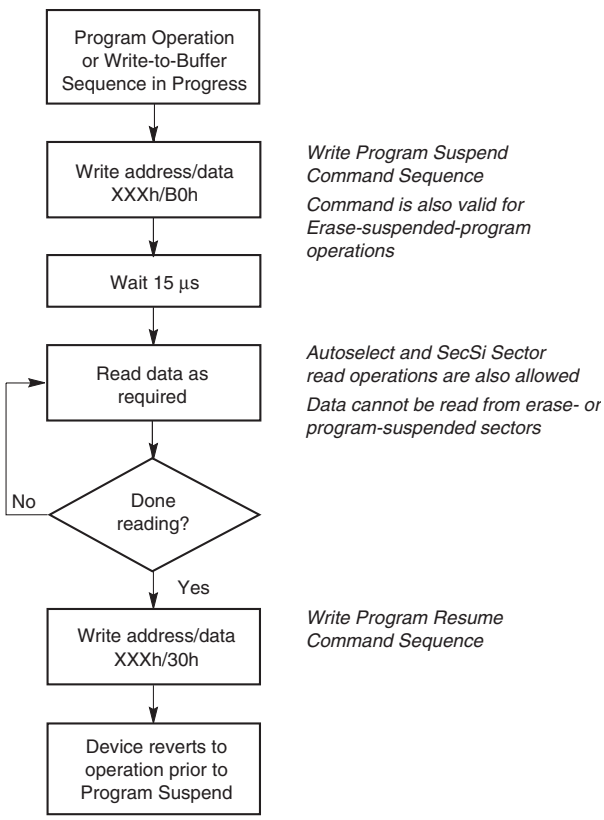


Figure 3. Program Suspend/Program Resume

Chip Erase Command Sequence

Chip erase is a six bus cycle operation. The chip erase command sequence is initiated by writing two unlock cycles, followed by a set-up command. Two additional unlock write cycles are then followed by the chip erase command, which in turn invokes the Embedded Erase algorithm. The device does *not* require the system to preprogram prior to erase. The Embedded Erase algorithm automatically preprograms and verifies the entire memory for an all zero data pattern prior to electrical erase. The system is not required to provide any controls or timings during these operations. Table 12 shows the address and data requirements for the chip erase command sequence.

When the Embedded Erase algorithm is complete, the device returns to the read mode and addresses are no longer latched. The system can determine the status of the erase operation by using DQ7, DQ6, or DQ2. Refer to the Write Operation Status section for information on these status bits.

Any commands written during the chip erase operation are ignored, including erase suspend commands. However, note that a **hardware reset** immediately terminates the erase operation. If that occurs, the chip erase command sequence should be reinitiated once the device has returned to reading array data, to ensure data integrity.

Figure 4 illustrates the algorithm for the erase operation. ***Note that the Secured Silicon Sector, autoselect, and CFI functions are unavailable when an erase operation in is progress.*** Refer to the "Erase And Programming Performance" section on page 102 in the AC Characteristics section for parameters, and Figure 16 section for timing diagrams.

Sector Erase Command Sequence

Sector erase is a six bus cycle operation. The sector erase command sequence is initiated by writing two unlock cycles, followed by a set-up command. Two additional unlock cycles are written, and are then followed by the address of the sector to be erased, and the sector erase command. Table 12 shows the address and data requirements for the sector erase command sequence.

The device does *not* require the system to preprogram prior to erase. The Embedded Erase algorithm automatically programs and verifies the entire memory for an all zero data pattern prior to electrical erase. The system is not required to provide any controls or timings during these operations.

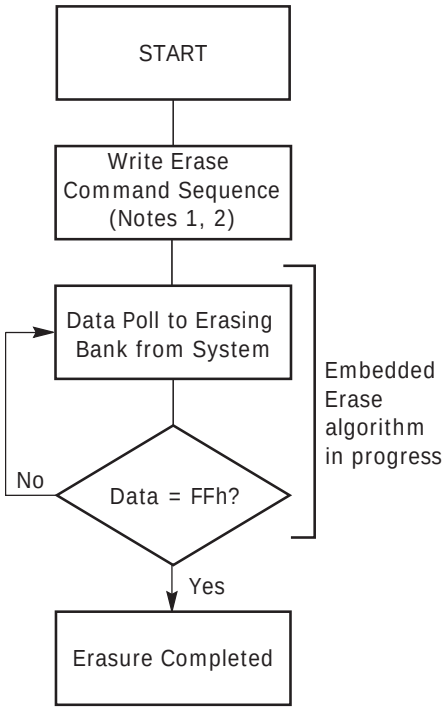
After the command sequence is written, a sector erase time-out of 50 µs occurs. During the time-out period, additional sector addresses and sector erase commands may be written. Loading the sector erase buffer may be done in any sequence, and the number of sectors may be from one sector to all sectors. The time between these additional cycles must be less than 50 µs, otherwise erasure may begin. Any sector erase address and command following the exceeded time-out may or may not be accepted. It is recommended that processor interrupts be disabled during this time to ensure all commands are accepted. The interrupts can be re-enabled after the last Sector Erase command is written. **Any command other than Sector Erase or Erase Suspend during the time-out period resets the device to the read mode.** ***Note that the Secured Silicon Sector, autoselect, and CFI functions are unavailable when an erase operation in is progress.*** The system must rewrite the command sequence and any additional addresses and commands.

The system can monitor DQ3 to determine if the sector erase timer has timed out (See the section on DQ3: Sector Erase Timer.). The time-out begins from the rising edge of the final WE# pulse in the command sequence.

When the Embedded Erase algorithm is complete, the device returns to reading array data and addresses are no longer latched. The system can determine the status of the erase operation by reading DQ7, DQ6, or DQ2 in the erasing sector. Refer to the Write Operation Status section for information on these status bits.

Once the sector erase operation has begun, only the Erase Suspend command is valid. All other commands are ignored. However, note that a **hardware reset** immediately terminates the erase operation. If that occurs, the sector erase command sequence should be reinitiated once the device has returned to reading array data, to ensure data integrity.

Figure 4 illustrates the algorithm for the erase operation. Refer to the Erase and Program Operations table in the AC Characteristics section for parameters, and Figure 16 section for timing diagrams.



Notes:

1. *See Table 12 for program command sequence.*
2. *See the section on DQ3 for information on the sector erase timer.*

Figure 4. Erase Operation

Erase Suspend/Erase Resume Commands

The Erase Suspend command, B0h, allows the system to interrupt a sector erase operation and then read data from, or program data to, any sector not selected for erasure. This command is valid only during the sector erase operation, including the 50 µs time-out period during the sector erase command sequence. The Erase Suspend command is ignored if written during the chip erase operation or Embedded Program algorithm.

When the Erase Suspend command is written during the sector erase operation, the device requires a typical of 5 µs (maximum of 20 µs) to suspend the erase operation. However, when the Erase Suspend command is written during the sector erase time-out, the device immediately terminates the time-out period and suspends the erase operation.

After the erase operation has been suspended, the device enters the erase-suspend-read mode. The system can read data from or program data to any sector not selected for erasure. (The device “erase suspends” all sectors selected for erasure.) Reading at any address within erase-suspended sectors produces status information on DQ7–DQ0. The system can use DQ7, or DQ6 and DQ2 together, to determine if a sector is actively erasing or is erase-suspended. Refer to the Write Operation Status section for information on these status bits.

After an erase-suspended program operation is complete, the device returns to the erase-suspend-read mode. The system can determine the status of the pro-

gram operation using the DQ7 or DQ6 status bits, just as in the standard word program operation. Refer to the Write Operation Status section for more information.

In the erase-suspend-read mode, the system can also issue the autoselect command sequence. Refer to the "Autoselect Mode" section and "Autoselect Command Sequence" section on page 66 sections for details.

To resume the sector erase operation, the system must write the Erase Resume command. The address of the erase-suspended sector is required when writing this command. Further writes of the Resume command are ignored. Another Erase Suspend command can be written after the chip has resumed erasing. It is important to allow an interval of at least 5 ms between Erase Resume and Erase Suspend.

Lock Register Command Set Definitions

The Lock Register Command Set permits the user to one-time program the Secured Silicon Sector Protection Bit, Persistent Protection Mode Lock Bit, and Password Protection Mode Lock Bit. The Lock Register bits are all readable after an initial access delay.

The **Lock Register Command Set Entry** command sequence must be issued prior to any of the following commands listed, to enable proper command execution.

Note that issuing the **Lock Register Command Set Entry** command **disables reads and writes for the flash memory**.

- Lock Register Program Command
- Lock Register Read Command

The **Lock Register Command Set Exit** command must be issued after the execution of the commands to reset the device to read mode. Otherwise the device will hang. If this happens, the flash device must be reset. Please refer to RESET# for more information. It is important to note that the device will be in either Persistent Protection mode or Password Protection mode depending on the mode selected prior to the device hang.

For either the Secured Silicon Sector to be locked, or the device to be permanently set to the Persistent Protection Mode or the Password Protection Mode, the associated Lock Register bits must be programmed. **Note that the Persistent Protection Mode Lock Bit and Password Protection Mode Lock Bit can never be programmed together at the same time. If so, the Lock Register Program operation will abort**.

The Lock Register Command Set Exit command must be initiated to re-enable reads and writes to the main memory.

Password Protection Command Set Definitions

The Password Protection Command Set permits the user to program the 64-bit password, verify the programming of the 64-bit password, and then later unlock the device by issuing the valid 64-bit password.

The **Password Protection Command Set Entry** command sequence must be issued prior to any of the commands listed following to enable proper command execution.

Note that issuing the **Password Protection Command Set Entry** command **disabled reads and writes the main memory.**

- **Password Program Command**
- **Password Read Command**
- **Password Unlock Command**

The Password Program command permits programming the password that is used as part of the hardware protection scheme. The actual password is 64-bits long. There is no special addressing order required for programming the password. **The password is programmed in 8-bit or 16-bit portions. Each portion requires a Password Program Command.**

Once the Password is written and verified, the Password Protection Mode Lock Bit in the "Lock Register" must be programmed in order to prevent verification. The Password Program command is only capable of programming "0"s. Programming a "1" after a cell is programmed as a "0" results in a time-out by the Embedded Program Algorithm™ with the cell remaining as a "0". The password is all F's when shipped from the factory. All 64-bit password combinations are valid as a password.

The Password Read command is used to verify the Password. The Password is verifiable only when the Password Protection Mode Lock Bit in the "Lock Register" is not programmed. If the Password Protection Mode Lock Bit in the "Lock Register" is programmed and the user attempts to read the Password, the device will always drive all F's onto the DQ databus.

The lower two address bits (A1–A0) for word mode and (A1–A-1) for by byte mode are valid during the Password Read, Password Program, and Password Unlock commands. **Writing a "1" to any other address bits (A_{MAX}-A2) will abort the Password Read and Password Program commands.**

The Password Unlock command is used to clear the PPB Lock Bit to the "unfreeze state" so that the PPB bits can be modified. The exact password must be entered in order for the unlocking function to occur. **This 64-bit Password Unlock command sequence will take at least 2 µs to process each time to prevent a hacker from running through the all 64-bit combinations in an attempt to correctly match the password. If another password unlock is issued before the 64-bit password check execution window is completed, the command will be ignored. If the wrong address or data is given during password unlock command cycle, the device may enter the write-to-buffer abort state. In order to exit the write-to-abort state, the write-to-buffer-abort-reset command must be given. Otherwise the device will hang.**

The Password Unlock function is accomplished by writing Password Unlock command and data to the device to perform the clearing of the PPB Lock Bit to the "unfreeze state". The password is 64 bits long. A1 and A0 are used for matching. Writing the Password Unlock command does not need to be address order specific. An example sequence is starting with the lower address A1-A0=00, followed by A1-A0=01, A1-A0=10, and A1-A0=11 if the device is configured to operate in word mode.

Approximately 2 µs is required for unlocking the device after the valid 64-bit password is given to the device. It is the responsibility of the microprocessor to keep track of the entering the portions of the 64-bit password with the Password Unlock command, the order, and when to read the PPB Lock bit to confirm successful password unlock. In order to re-lock the device into the Password Protection Mode, the PPB Lock Bit Set command can be re-issued.

The **Password Protection Command Set Exit** command must be issued after the execution of the commands listed previously to reset the device to read mode. Otherwise the device will hang.
Note that issuing the **Password Protection Command Set Exit command re-enables reads and writes for the main memory.**

Non-Volatile Sector Protection Command Set Definitions

The Non-Volatile Sector Protection Command Set permits the user to program the Persistent Protection Bits (PPB bits), erase all of the Persistent Protection Bits (PPB bits), and read the logic state of the Persistent Protection Bits (PPB bits).

The **Non-Volatile Sector Protection Command Set Entry** command sequence must be issued prior to any of the commands listed following to enable proper command execution.

Note that issuing the **Non-Volatile Sector Protection Command Set Entry** command **disables reads and writes for the main memory**.

- PPB Program Command

The PPB Program command is used to program, or set, a given PPB bit. Each PPB bit is individually programmed (but is bulk erased with the other PPB bits). The specific sector address (A24-A16 for S29GL512N, A23-A16 for S29GL256N, A22-A16 for S29GL128N) is written at the same time as the program command. If the PPB Lock Bit is set to the “freeze state”, the PPB Program command will not execute and the command will time-out without programming the PPB bit.

- All PPB Erase Command

The All PPB Erase command is used to erase all PPB bits in bulk. There is no means for individually erasing a specific PPB bit. Unlike the PPB program, no specific sector address is required. However, when the All PPB Erase command is issued, all Sector PPB bits are erased in parallel. If the PPB Lock Bit is set to “freeze state”, the ALL PPB Erase command will not execute and the command will time-out without erasing the PPB bits.

The device will preprogram all PPB bits prior to erasing when issuing the All PPB Erase command. Also note that the total number of PPB program/erase cycles has the same endurance as the flash memory array.

- PPB Status Read Command

The programming state of the PPB for a given sector can be verified by writing a PPB Status Read Command to the device. This requires an initial access time latency.

The **Non-Volatile Sector Protection Command Set Exit** command must be issued after the execution of the commands listed previously to reset the device to read mode.

Note that issuing the **Non-Volatile Sector Protection Command Set Exit** command **re-enables reads and writes for the main memory**.

Global Volatile Sector Protection Freeze Command Set

The Global Volatile Sector Protection Freeze Command Set permits the user to set the PPB Lock Bit and reading the logic state of the PPB Lock Bit.

The **Global Volatile Sector Protection Freeze Command Set Entry** command sequence must be issued prior to any of the commands listed following to enable proper command execution.

Reads and writes from the main memory are not allowed.

- PPB Lock Bit Set Command

The PPB Lock Bit Set command is used to set the PPB Lock Bit to the “freeze state” if it is cleared either at reset or if the Password Unlock command was successfully executed. There is no PPB Lock Bit Clear command. Once the PPB Lock Bit is set to the “freeze state”, it cannot be cleared unless the device is taken through a power-on clear (for Persistent Protection Mode) or the Password Unlock command is executed (for Password Protection Mode). If the Password Protection Mode Lock Bit is programmed, the PPB Lock Bit status is reflected as set to the “freeze state”, even after a power-on reset cycle.

- PPB Lock Bit Status Read Command

The programming state of the PPB Lock Bit can be verified by executing a PPB Lock Bit Status Read command to the device.

The **Global Volatile Sector Protection Freeze Command Set Exit** command must be issued after the execution of the commands listed previously to reset the device to read mode.

Volatile Sector Protection Command Set

The Volatile Sector Protection Command Set permits the user to set the Dynamic Protection Bit (DYB) to the “protected state”, clear the Dynamic Protection Bit (DYB) to the “unprotected state”, and read the logic state of the Dynamic Protection Bit (DYB).

The **Volatile Sector Protection Command Set Entry** command sequence must be issued prior to any of the commands listed following to enable proper command execution.

Note that issuing the **Volatile Sector Protection Command Set Entry** command **disables reads and writes from main memory**.

- DYB Set Command
- DYB Clear Command

The DYB Set and DYB Clear commands are used to protect or unprotect a DYB for a given sector. The high order address bits are issued at the same time as the code 00h or 01h on DQ7-DQ0. All other DQ data bus pins are ignored during the data write cycle. The DYB bits are modifiable at any time, regardless of the state of the PPB bit or PPB Lock Bit. The DYB bits are cleared to the “unprotected state” at power-up or hardware reset.

—DYB Status Read Command

The programming state of the DYB bit for a given sector can be verified by writing a DYB Status Read command to the device. This requires an initial access delay.

The **Volatile Sector Protection Command Set Exit** command must be issued after the execution of the commands listed previously to reset the device to read mode.

Note that issuing the **Volatile Sector Protection Command Set Exit command re-enables reads and writes to the main memory**.

Secured Silicon Sector Entry Command

The Secured Silicon Sector Entry command allows the following commands to be executed

- Read from Secured Silicon Sector
- Program to Secured Silicon Sector

Once the Secured Silicon Sector Entry Command is issued, the Secured Silicon Sector Exit command has to be issued to exit Secured Silicon Sector Mode.

Secured Silicon Sector Exit Command

The Secured Silicon Sector Exit command may be issued to exit the Secured Silicon Sector Mode.

Command Definitions

Table 12. S29GL512N, S29GL256N, S29GL128N Command Definitions, x16

Command (Notes)		Cycles	Bus Cycles (Notes 2–5)											
			First		Second		Third		Fourth		Fifth		Sixth	
			Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data
Read (6)		1	RA	RD										
Reset (7)		1	XXX	F0										
Autoselect (Note 8)	Manufacturer ID	4	555	AA	2AA	55	555	90	X00	01				
	Device ID	4	555	AA	2AA	55	555	90	X01	227E	X0E	Note 17	X0F	Note 17
	Sector Protect Verify	4	555	AA	2AA	55	555	90	(SA) X02	XX00				
										XX01				
	Secure Device Verify (9)	4	555	AA	2AA	55	555	90	X03	Note 10				
CFI Query (11)		1	55	98										
Program		4	555	AA	2AA	55	555	A0	PA	PD				
Write to Buffer		3	555	AA	2AA	55	SA	25	SA	WC	PA	PD	WBL	PD
Program Buffer to Flash (confirm)		1	SA	29										
Write-to-Buffer-Abort Reset (16)		3	555	AA	2AA	55	555	F0						
Unlock Bypass		3	555	AA	2AA	55	555	20						
Unlock Bypass Program (12)		2	XXX	A0	PA	PD								
Unlock Bypass Sector Erase (12)		2	XXX	80	SA	30								
Unlock Bypass Chip Erase (12)		2	XXX	80	XXX	10								
Unlock Bypass Reset (13)		2	XXX	90	XXX	00								
Chip Erase		6	555	AA	2AA	55	555	80	555	AA	2AA	55	555	10
Sector Erase		6	555	AA	2AA	55	555	80	555	AA	2AA	55	SA	30
Erase Suspend/Program Suspend (14)		1	XXX	B0										
Erase Resume/Program Resume (15)		1	XXX	30										
Sector Command Definitions														
Secured Silicon SEctor	Secured Silicon Sector Entry	3	555	AA	2AA	55	555	88						
	Secured Silicon Sector Exit (18)	4	555	AA	2AA	55	555	90	XX	00				
Lock Register Command Set Definitions														
Lock Register	Lock Register Command Set Entry	3	555	AA	2AA	55	555	40						
	Lock Register Bits Program (22)	2	XXX	A0	XXX	Data								
	Lock Register Bits Read (22)	1	00	Data										
	Lock Register Command Set Exit (18, 23)	2	XXX	90	XXX	00								
Password Protection Command Set Definitions														

Command (Notes)		Cycles	Bus Cycles (Notes 2–5)											
			First		Second		Third		Fourth		Fifth		Sixth	
			Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data	Addr	Data
Password	Password Protection Command Set Entry	3	555	AA	2AA	55	555	60						
	Password Program (20)	2	XXX	A0	PWA x	PWD x								
	Password Read (19)	4	XXX	PWD 0	01	PWD 1	02	PWD 2	03	PWD 3				
	Password Unlock (19)	7	00	25	00	03	00	PWD 0	01	PWD 1	02	PWD 2	03	PWD 3
			00	29										
	Password Protection Command Set Exit (18, 23)	2	XXX	90	XXX	00								
Non-Volatile Sector Protection Command Set Definitions														
PPB	Nonvolatile Sector Protection Command Set Entry	3	555	AA	2AA	55	555	C0						
	PPB Program (24, 25)	2	XXX	A0	SA	00								
	All PPB Erase	2	XXX	80	00	30								
	PPB Status Read (25)	1	SA	RD (0)										
	Non-Volatile Sector Protection Command Set Exit (18)	2	XXX	90	XXX	00								
Global Non-Volatile Sector Protection Freeze Command Set Definitions														
PPB Lock Bit	Global Non-Volatile Sector Protection Freeze Command Set Entry	3	555	AA	2AA	55	555	50						
	PPB Lock Bit Set (25)	2	XXX	A0	XXX	00								
	PPB Lock Status Read (25)	1	XXX	RD (0)										
	Global Non-Volatile Sector Protection Freeze Command Set Exit (18)	2	XXX	90	XXX	00								
Volatile Sector Protection Command Set Definitions														
DYB	Volatile Sector Protection Command Set Entry	3	555	AA	2AA	55	555	E0						
	DYB Set (24, 25)	2	XXX	A0	SA	00								
	DYB Clear (25)	2	XXX	A0	SA	01								
	DYB Status Read (25)	1	SA	RD (0)										
	Volatile Sector Protection Command Set Exit (18)	2	XXX	90	XXX	00								

Legend:

X = Don't care

RA = Address of the memory to be read.

RD = Data read from location RA during read operation.

PA = Address of the memory location to be programmed. Addresses latch on the falling edge of the WE# or CE# pulse, whichever happens later.

PD = Data to be programmed at location PA. Data latches on the rising edge of the WE# or CE# pulse, whichever happens first.

SA = Address of the sector to be verified (in autoselect mode) or erased. Address bits A_{max}–A16 uniquely select any sector.

WBL = Write Buffer Location. The address must be within the same write buffer page as PA.

WC = Word Count is the number of write buffer locations to load minus 1.

PWD = Password

PWD_x = Password word0, word1, word2, and word3.

DATA = Lock Register Contents: PD(0) = Secured Silicon Sector Protection Bit, PD(1) = Persistent Protection Mode Lock Bit, PD(2) = Password Protection Mode Lock Bit.

Notes:

1. *See Table 1 for description of bus operations.*
2. *All values are in hexadecimal.*
3. *Except for the read cycle, and the 4th, 5th, and 6th cycle of the autoselect command sequence, all bus cycles are write cycles.*
4. *Data bits DQ15-DQ8 are don't cares for unlock and command cycles.*
5. *Address bits A_{MAX}:A16 are don't cares for unlock and command cycles, unless SA or PA required. (A_{MAX} is the Highest Address pin.).*
6. *No unlock or command cycles required when reading array data.*
7. *The Reset command is required to return to reading array data when device is in the autoselect mode, or if DQ5 goes high (while the device is providing status data).*
8. *The fourth, fifth, and sixth cycle of the autoselect command sequence is a read cycle.*
9. *The data is 00h for an unprotected sector and 01h for a protected sector. See "Autoselect Command Sequence" for more information. This is same as PPB Status Read except that the protect and unprotect statuses are inverted here.*
10. *The data value for DQ7 is "1" for a serialized and protected OTP region and "0" for an unserialized and unprotected Secured Silicon Sector region. See "Secured Silicon Sector Flash Memory Region" for more information. For S29GLxxxNH: XX18h/18h = Not Factory Locked. XX98h/98h = Factory Locked. For S29GLxxxNL: XX08h/08h = Not Factory Locked. XX88h/88h = Factory Locked.*
11. *Command is valid when device is ready to read array data or when device is in autoselect mode.*
12. *The Unlock-Bypass command is required prior to the Unlock-Bypass-Program command.*
13. *The Unlock-Bypass-Reset command is required to return to reading array data when the device is in the unlock bypass mode.*
14. *The system may read and program/program suspend in non-erasing sectors, or enter the autoselect mode, when in the Erase Suspend mode. The Erase Suspend command is valid only during a sector erase operation.*
15. *The Erase Resume/Program Resume command is valid only during the Erase Suspend/Program Suspend modes.*
16. *Issue this command sequence to return to READ mode after detecting device is in a Write-to-Buffer-Abort state. NOTE: the full command sequence is required if resetting out of ABORT while using Unlock Bypass Mode.*
17. *S29GL512NH/L = 2223h/23h, 2201h/01h; S29GL256NH/L = 2222h/22h, 2201h/01h; S29GL128NH/L = 2221h/21h, 2201h/01h.*
18. *The Exit command returns the device to reading the array.*
19. *Note that the password portion can be entered or read in any order as long as the entire 64-bit password is entered or read.*
20. *For PWDx, only one portion of the password can be programmed per each "A0" command.*
21. *The All PPB Erase command embeds programming of all PPB bits before erasure.*
22. *All Lock Register bits are one-time programmable. Note that the program state = "0" and the erase state = "1". Also note that of both the Persistent Protection Mode Lock Bit and the Password Protection Mode Lock Bit cannot be programmed at the same time or the Lock Register Bits Program operation will abort and return the device to read mode. Lock Register bits that are reserved for future use will default to "1's". The Lock Register is shipped out as "FFFF's" before Lock Register Bit program execution.*
23. *If any of the Entry command was initiated, an Exit command must be issued to reset the device into read mode. Otherwise the device will hang.*
24. *If ACC = V_{HH}, sector protection will match when ACC = V_{IH}*
25. *Protected State = "00h", Unprotected State = "01h".*

Write Operation Status

The device provides several bits to determine the status of a program or erase operation: DQ2, DQ3, DQ5, DQ6, and DQ7. Table 13 and the following subsections describe the function of these bits. DQ7 and DQ6 each offer a method for determining whether a program or erase operation is complete or in progress. The device also provides a hardware-based output signal, RY/BY#, to determine whether an Embedded Program or Erase operation is in progress or has been completed.

Note that all Write Operation Status DQ bits are valid only after 4 µs delay.

DQ7: Data# Polling

The Data# Polling bit, DQ7, indicates to the host system whether an Embedded Program or Erase algorithm is in progress or completed, or whether the device is in Erase Suspend. Data# Polling is valid after the rising edge of the final WE# pulse in the command sequence.

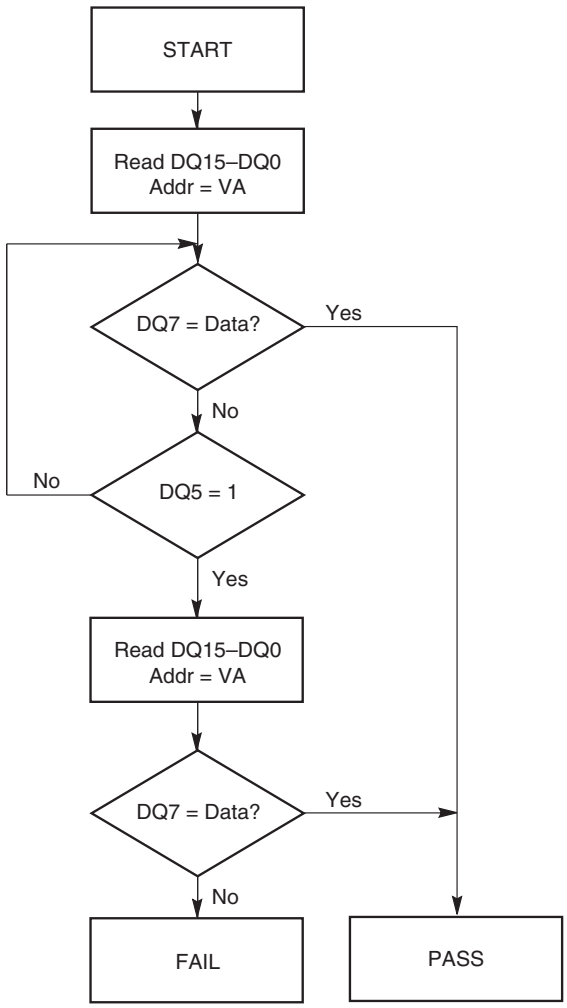
During the Embedded Program algorithm, the device outputs on DQ7 the complement of the datum programmed to DQ7. This DQ7 status also applies to programming during Erase Suspend. When the Embedded Program algorithm is complete, the device outputs the datum programmed to DQ7. The system must provide the program address to read valid status information on DQ7. If a program address falls within a protected sector, Data# Polling on DQ7 is active for approximately 1 µs, then the device returns to the read mode.

During the Embedded Erase algorithm, Data# Polling produces a “0” on DQ7. When the Embedded Erase algorithm is complete, or if the device enters the Erase Suspend mode, Data# Polling produces a “1” on DQ7. The system must provide an address within any of the sectors selected for erasure to read valid status information on DQ7.

After an erase command sequence is written, if all sectors selected for erasing are protected, Data# Polling on DQ7 is active for approximately 100 µs, then the device returns to the read mode. If not all selected sectors are protected, the Embedded Erase algorithm erases the unprotected sectors, and ignores the selected sectors that are protected. However, if the system reads DQ7 at an address within a protected sector, the status may not be valid.

Just prior to the completion of an Embedded Program or Erase operation, DQ7 may change asynchronously with DQ0–DQ6 while Output Enable (OE#) is asserted low. That is, the device may change from providing status information to valid data on DQ7. Depending on when the system samples the DQ7 output, it may read the status or valid data. Even if the device has completed the program or erase operation and DQ7 has valid data, the data outputs on DQ0–DQ6 may be still invalid. Valid data on DQ0–DQ7 will appear on successive read cycles.

Table 13 shows the outputs for Data# Polling on DQ7. Figure 5 shows the Data# Polling algorithm. Figure 17 in the AC Characteristics section shows the Data# Polling timing diagram.



Notes:

1. *VA = Valid address for programming. During a sector erase operation, a valid address is any sector address within the sector being erased. During chip erase, a valid address is any non-protected sector address.*
2. *DQ7 should be rechecked even if DQ5 = "1" because DQ7 may change simultaneously with DQ5.*

Figure 5. Data# Polling Algorithm

RY/BY#: Ready/Busy#

The RY/BY# is a dedicated, open-drain output pin which indicates whether an Embedded Algorithm is in progress or complete. The RY/BY# status is valid after the rising edge of the final WE# pulse in the command sequence. Since RY/BY# is an open-drain output, several RY/BY# pins can be tied together in parallel with a pull-up resistor to V_{CC}.

If the output is low (Busy), the device is actively erasing or programming. (This includes programming in the Erase Suspend mode.) If the output is high (Ready), the device is in the read mode, the standby mode, or in the erase-suspend-read mode. Table 13 shows the outputs for RY/BY#.

DQ6: Toggle Bit I

Toggle Bit I on DQ6 indicates whether an Embedded Program or Erase algorithm is in progress or complete, or whether the device has entered the Erase Suspend mode. Toggle Bit I may be read at any address, and is valid after the rising edge of the final WE# pulse in the command sequence (prior to the program or erase operation), and during the sector erase time-out.

During an Embedded Program or Erase algorithm operation, successive read cycles to any address cause DQ6 to toggle. The system may use either OE# or CE# to control the read cycles. When the operation is complete, DQ6 stops toggling.

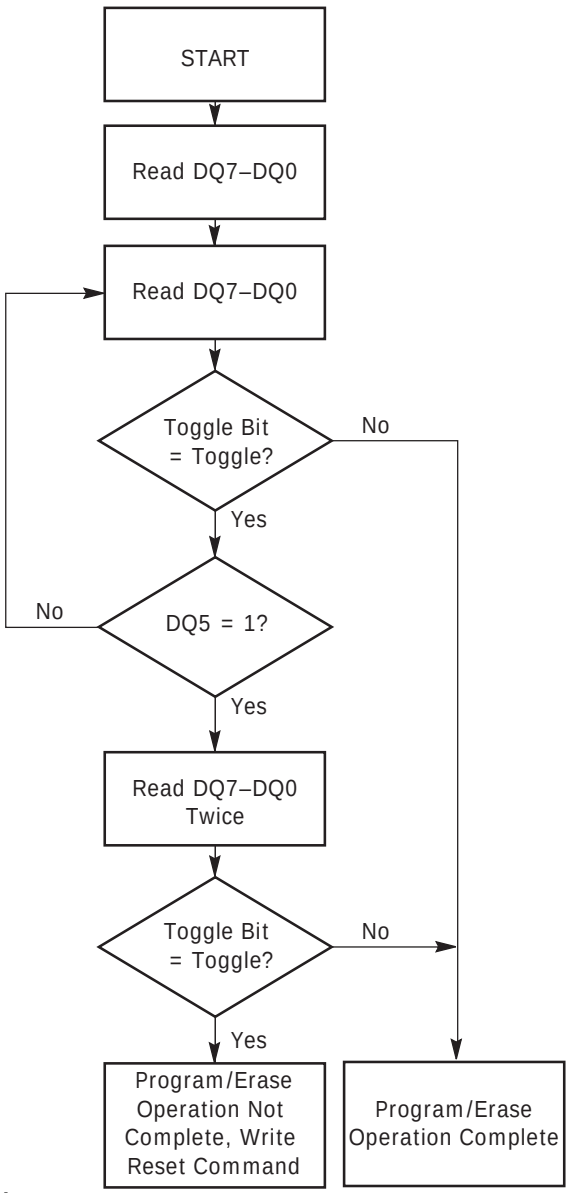
After an erase command sequence is written, if all sectors selected for erasing are protected, DQ6 toggles for approximately 100 µs, then returns to reading array data. If not all selected sectors are protected, the Embedded Erase algorithm erases the unprotected sectors, and ignores the selected sectors that are protected.

The system can use DQ6 and DQ2 together to determine whether a sector is actively erasing or is erase-suspended. When the device is actively erasing (that is, the Embedded Erase algorithm is in progress), DQ6 toggles. When the device enters the Erase Suspend mode, DQ6 stops toggling. However, the system must also use DQ2 to determine which sectors are erasing or erase-suspended. Alternatively, the system can use DQ7 (see the subsection on DQ7: Data# Polling).

If a program address falls within a protected sector, DQ6 toggles for approximately 1 µs after the program command sequence is written, then returns to reading array data.

DQ6 also toggles during the erase-suspend-program mode, and stops toggling once the Embedded Program algorithm is complete.

Table 13 shows the outputs for Toggle Bit I on DQ6. Figure 6 shows the toggle bit algorithm. Figure 18 in the “AC Characteristics” section shows the toggle bit timing diagrams. Figure 19 shows the differences between DQ2 and DQ6 in graphical form. See also the subsection on DQ2: Toggle Bit II.



Note:
The system should recheck the toggle bit even if DQ5 = "1" because the toggle bit may stop toggling as DQ5 changes to "1." See the subsections on DQ6 and DQ2 for more information.

Figure 6. Toggle Bit Algorithm

DQ2: Toggle Bit II

The "Toggle Bit II" on DQ2, when used with DQ6, indicates whether a particular sector is actively erasing (that is, the Embedded Erase algorithm is in progress), or whether that sector is erase-suspended. Toggle Bit II is valid after the rising edge of the final WE# pulse in the command sequence.

DQ2 toggles when the system reads at addresses within those sectors that have been selected for erasure. (The system may use either OE# or CE# to control the

read cycles.) But DQ2 cannot distinguish whether the sector is actively erasing or is erase-suspended. DQ6, by comparison, indicates whether the device is actively erasing, or is in Erase Suspend, but cannot distinguish which sectors are selected for erasure. Thus, both status bits are required for sector and mode information. Refer to Table 13 to compare outputs for DQ2 and DQ6.

Figure 6 shows the toggle bit algorithm in flowchart form, and the section "DQ2: Toggle Bit II" explains the algorithm. See also the RY/BY#: Ready/Busy# subsection. Figure 18 shows the toggle bit timing diagram. Figure 19 shows the differences between DQ2 and DQ6 in graphical form.

Reading Toggle Bits DQ6/DQ2

Refer to Figure 6 and Figure 19 for the following discussion. Whenever the system initially begins reading toggle bit status, it must read DQ7–DQ0 at least twice in a row to determine whether a toggle bit is toggling. Typically, the system would note and store the value of the toggle bit after the first read. After the second read, the system would compare the new value of the toggle bit with the first. If the toggle bit is not toggling, the device has completed the program or erase operation. The system can read array data on DQ7–DQ0 on the following read cycle.

However, if after the initial two read cycles, the system determines that the toggle bit is still toggling, the system also should note whether the value of DQ5 is high (see the section on DQ5). If it is, the system should then determine again whether the toggle bit is toggling, since the toggle bit may have stopped toggling just as DQ5 went high. If the toggle bit is no longer toggling, the device has successfully completed the program or erase operation. If it is still toggling, the device did not completed the operation successfully, and the system must write the reset command to return to reading array data.

The remaining scenario is that the system initially determines that the toggle bit is toggling and DQ5 has not gone high. The system may continue to monitor the toggle bit and DQ5 through successive read cycles, determining the status as described in the previous paragraph. Alternatively, it may choose to perform other system tasks. In this case, the system must start at the beginning of the algorithm when it returns to determine the status of the operation (top of Figure 6).

DQ5: Exceeded Timing Limits

DQ5 indicates whether the program, erase, or write-to-buffer time has exceeded a specified internal pulse count limit. Under these conditions DQ5 produces a "1," indicating that the program or erase cycle was not successfully completed.

The device may output a "1" on DQ5 if the system tries to program a "1" to a location that was previously programmed to "0." **Only an erase operation can change a "0" back to a "1."** Under this condition, the device halts the operation, and when the timing limit has been exceeded, DQ5 produces a "1."

In all these cases, the system must write the reset command to return the device to the reading the array (or to erase-suspend-read if the device was previously in the erase-suspend-program mode).

DQ3: Sector Erase Timer

After writing a sector erase command sequence, the system may read DQ3 to determine whether or not erasure has begun. (The sector erase timer does not apply to the chip erase command.) If additional sectors are selected for erasure,

the entire time-out also applies after each additional sector erase command. When the time-out period is complete, DQ3 switches from a “0” to a “1.” If the time between additional sector erase commands from the system can be assumed to be less than 50 µs, the system need not monitor DQ3. See also the Sector Erase Command Sequence section.

After the sector erase command is written, the system should read the status of DQ7 (Data# Polling) or DQ6 (Toggle Bit I) to ensure that the device has accepted the command sequence, and then read DQ3. If DQ3 is “1,” the Embedded Erase algorithm has begun; all further commands (except Erase Suspend) are ignored until the erase operation is complete. If DQ3 is “0,” the device will accept additional sector erase commands. To ensure the command has been accepted, the system software should check the status of DQ3 prior to and following each subsequent sector erase command. If DQ3 is high on the second status check, the last command might not have been accepted.

Table 13 shows the status of DQ3 relative to the other status bits.

DQI: Write-to-Buffer Abort

DQ1 indicates whether a Write-to-Buffer operation was aborted. Under these conditions DQ1 produces a “1”. The system must issue the Write-to-Buffer-Abort-Reset command sequence to return the device to reading array data. See Write Buffer section for more details.

Table I3. Write Operation Status

Status			DQ7 (Note 2)	DQ6	DQ5 (Note 1)	DQ3	DQ2 (Note 2)	DQ1	RY/BY#
Standard Mode	Embedded Program Algorithm		DQ7#	Toggle	0	N/A	No toggle	0	0
	Embedded Erase Algorithm		0	Toggle	0	1	Toggle	N/A	0
Program Suspend Mode	Program-Suspend Read	Program-Suspended Sector	Invalid (not allowed)						1
		Non-Program Suspended Sector	Data						1
Erase Suspend Mode	Erase-Suspend Read	Erase-Suspended Sector	1	No toggle	0	N/A	Toggle	N/A	1
		Non-Erase Suspended Sector	Data						1
	Erase-Suspend-Program (Embedded Program)		DQ7#	Toggle	0	N/A	N/A	N/A	0
Write-to-Buffer	Busy (Note 3)		DQ7#	Toggle	0	N/A	N/A	0	0
	Abort (Note 4)		DQ7#	Toggle	0	N/A	N/A	1	0

Notes:

1. *DQ5 switches to ‘1’ when an Embedded Program, Embedded Erase, or Write-to-Buffer operation has exceeded the maximum timing limits. Refer to the section on DQ5 for more information.*
2. *DQ7 and DQ2 require a valid address when reading status information. Refer to the appropriate subsection for further details.*
3. *The Data# Polling algorithm should be used to monitor the last loaded write-buffer address location.*
4. *DQ1 switches to ‘1’ when the device has aborted the write-to-buffer operation.*

Absolute Maximum Ratings

A9, OE#, and ACC (Note 5) . . . . . –0.5 V to +12.5 V

All other pins . . . . . –0.5 V to V_{CC} + 0.5V

5. *Minimum DC input voltage on pins A9, OE#, and ACC is*

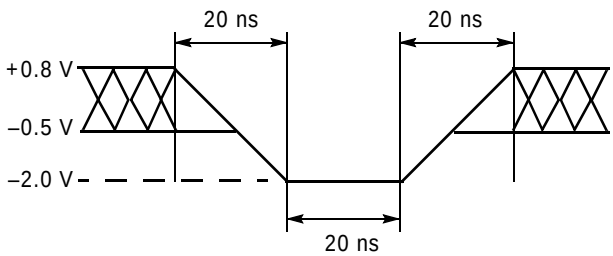


Figure 7.

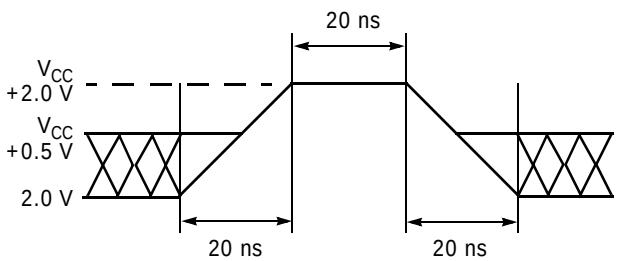


Figure 8. Maximum Positive Overshoot Waveform

Operating Ranges

Notes:

1. *Operating ranges define those limits between which the functionality of the device is guaranteed.*
2. *See "Product Selector Guide" section on page 19.*

DC Characteristics

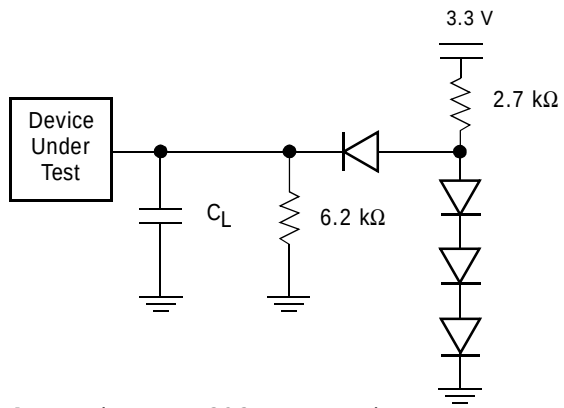
CMOS Compatible-S29GLI28N, S29GL256N, S29GL5I2N

Parameter Symbol	Parameter Description (Notes)	Test Conditions	Min	Typ	Max	Unit
I_{LI}	Input Load Current (1)	$V_{IN} = V_{SS}$ to V_{CC}, $V_{CC} = V_{CC\ max}$			WP/ACC: ±2.0	µA
					Others: ±1.0	
I_{LIT}	A9 Input Load Current	$V_{CC} = V_{CC\ max}$; A9 = 12.5 V			35	µA
I_{LO}	Output Leakage Current	$V_{OUT} = V_{SS}$ to V_{CC}, $V_{CC} = V_{CC\ max}$			±1.0	µA
I_{CC1}	V_{CC} Active Read Current (1)	CE# = V_{IL}, OE# = V_{IH}, $V_{CC} = V_{CCmax}$, *f* = 5 MHz		30	50	mA
		CE# = V_{IL}, OE# = V_{IH}, $V_{CC} = V_{CCmax}$, f = 10 MHz		60	90	
I_{CC2}	V_{CC} Intra-Page Read Current (1)	CE# = V_{IL}, OE# = V_{IH}, $V_{CC} = V_{CCmax}$ f = 10 MHz		1	10	mA
		CE# = V_{IL}, OE# = V_{IH}, $V_{CC} = V_{CCmax}$, f=33 MHz		5	20	
I_{CC3}	V_{CC} Active Erase/Program Current (2, 3)	CE# = V_{IL}, OE# = V_{IH}, $V_{CC} = V_{CCmax}$		50	80	mA
I_{CC4}	V_{CC} Standby Current	CE#, RESET# = V_{SS} ± 0.3 V, OE# = V_{IH}, $V_{CC} = V_{CCmax}$ $V_{IL} = V_{SS}$ + 0.3 V/-0.1V		1	5	mA
I_{CC5}	V_{CC} Reset Current	$V_{CC} = V_{CCmax}$; $V_{IL} = V_{SS}$ + 0.3 V/-0.1V, RESET# = V_{SS} ± 0.3 V		1	5	µA
I_{CC6}	Automatic Sleep Mode (4)	$V_{CC} = V_{CCmax}$ $V_{IH} = V_{CC}$ ± 0.3 V, $V_{IL} = V_{SS}$ + 0.3 V/-0.1V, WP#/A_{CC} = V_{IH}		1	5	µA
I_{ACC}	ACC Accelerated Program Current	CE# = V_{IL}, OE# = V_{IH}, $V_{CC} = V_{CCmax}$, WP#/ACC = V_{IH}	WP#/ACC pin	10	20	mA
			V_{CC} pin	50	80	
V_{IL}	Input Low Voltage (5)		–0.1		0.3 x V_{IO}	V
V_{IH}	Input High Voltage (5)		0.7 x V_{IO}		V_{IO} + 0.3	V
V_{HH}	Voltage for ACC Erase/Program Acceleration	V_{CC} = 2.7 –3.6 V	11.5		12.5	V
V_{ID}	Voltage for Autoselect and Temporary Sector Unprotect	V_{CC} = 2.7 –3.6 V	11.5		12.5	V
V_{OL}	Output Low Voltage (5)	I_{OL} = 100 µA			0.15 x V_{IO}	V
V_{OH}	Output High Voltage (5)	I_{OH} = -100 µA	0.85 x V_{IO}			V
V_{LKO}	Low V_{CC} Lock-Out Voltage (3)		2.3		2.5	V

Notes:

1. *The I_{CC} current listed is typically less than 2 mA/MHz, with OE# at V_{IH}.*
2. *I_{CC} active while Embedded Erase or Embedded Program or Write Buffer Programming is in progress.*
3. *Not 100% tested.*
4. *Automatic sleep mode enables the lower power mode when addresses remain stable tor t_{ACC} + 30 ns.*
5. *V_{IO} = 1.65–1.95 V or 2.7–3.6 V*
6. *V_{CC} = 3 V and V_{IO} = 3V or 1.8V. When V_{IO} is at 1.8V, I/O pins cannot operate at 3V.*

Test Conditions



Note: *Diodes are IN3064 or equivalent.*

Figure 9. Test Setup

Table 14. Test Specifications

Test Condition	All Speeds	Unit
Output Load	1 TTL gate	
Output Load Capacitance, C_L (including jig capacitance)	30	pF
Input Rise and Fall Times	5	ns
Input Pulse Levels	0.0–V_{IO}	V
Input timing measurement reference levels (See Note)	0.5V_{IO}	V
Output timing measurement reference levels	0.5 V_{IO}	V

Note: *If $V_{IO} < V_{CC}$, the reference level is 0.5 V_{IO}.*

Key to Switching Waveforms

Waveform	Inputs	Outputs
	Steady	
	Changing from H to L	
	Changing from L to H	
	Don't Care, Any Change Permitted	Changing, State Unknown
	Does Not Apply	Center Line is High Impedance State (High Z)

Note: *If $V_{IO} < V_{CC}$, the input measurement reference level is 0.5 V_{IO}.*

Figure 10. Input Waveforms and Measurement Levels

AC Characteristics

Read-Only Operations–S29GL128N, S29GL256N, S29GL512N

Parameter		Description		Test Setup		Speed Options				Unit
JEDEC	Std.					90	100	110	110	
t_{AVAV}	t_{RC}	Read Cycle Time		$V_{IO} = V_{CC} = 3$ V	Min	90	100	110		ns
				$V_{IO} = 1.8$ V, $V_{CC} = 3$ V					110	
t_{AVQV}	t_{ACC}	Address to Output Delay (Note 2)		$V_{IO} = V_{CC} = 3$ V	Max	90	100	110		ns
				$V_{IO} = 1.8$ V, $V_{CC} = 3$ V					110	
t_{ELQV}	t_{CE}	Chip Enable to Output Delay (Note 3)		$V_{IO} = V_{CC} = 3$ V	Max	90	100	110		ns
				$V_{IO} = 1.8$ V, $V_{CC} = 3$ V					110	
	t_{PACC}	Page Access Time			Max	25	25	25	30	ns
t_{GLQV}	t_{OE}	Output Enable to Output Delay			Max	25	25	35	35	ns
t_{EHQZ}	t_{DF}	Chip Enable to Output High Z (Note 1)			Max	20				ns
t_{GHQZ}	t_{DF}	Output Enable to Output High Z (Note 1)			Max	20				ns
t_{AXQX}	t_{OH}	Output Hold Time From Addresses, CE# or OE#, Whichever Occurs First			Min	0				ns
	t_{OEH}	Output Enable Hold Time (Note 1)	Read		Min	0				ns
			Toggle and Data# Polling		Min	10				ns
	t_{CEH}	Chip Enable Hold Time	Read		Min	35				ns

Notes:

1. *Not 100% tested.*
2. *CE#, OE# = V_{IL}*
3. *OE# = V_{IL}*
4. *See Figure 9 and Table 14 for test specifications.*
5. *Unless otherwise indicated, AC specifications for 90 ns, 100 ns, and 110 ns speed options are tested with $V_{IO} = V_{CC} = 3$ V. AC specifications for 110 ns speed options are tested with $V_{IO} = 1.8$ V and $V_{CC} = 3.0$ V.*

AC Characteristics

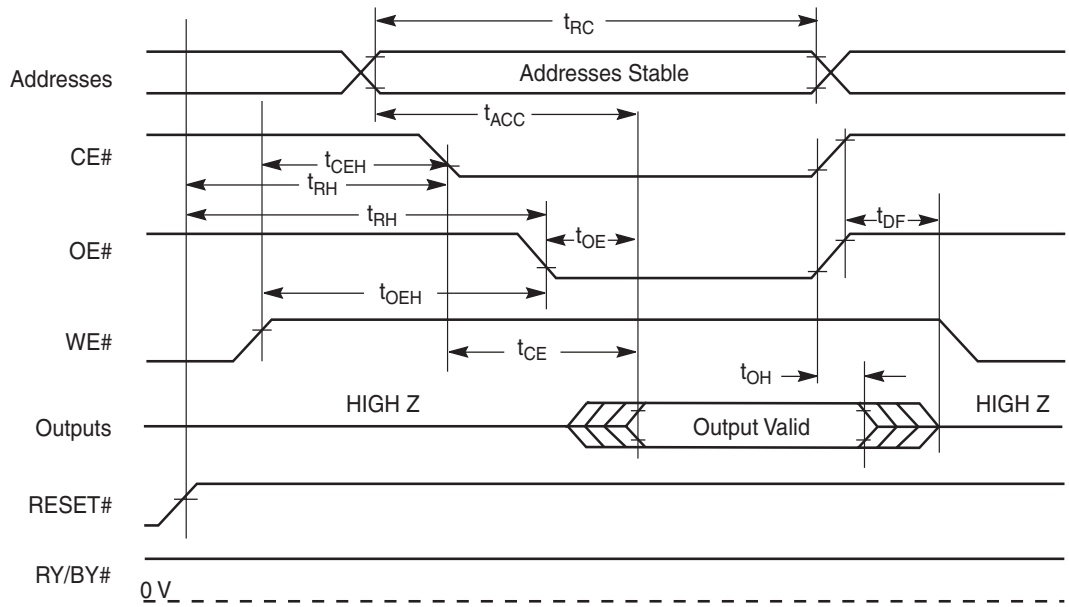
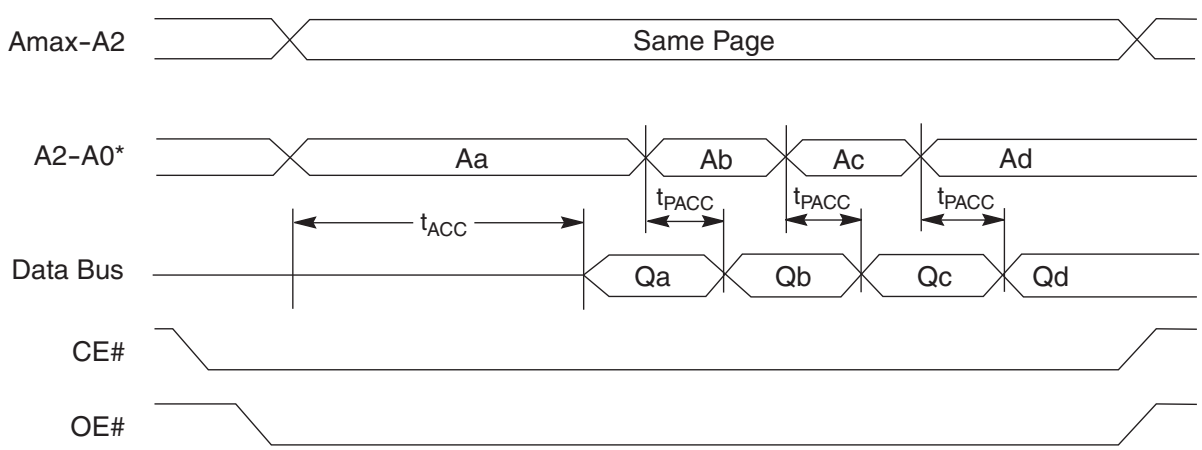


Figure 11. Read Operation Timings



Notes:
1. Figure shows word mode.

Figure 12. Page Read Timings

AC Characteristics

Hardware Reset (RESET#)

Parameter		Description		Speed (Note 2)	Unit
JEDEC	Std.				
	t_{Ready}	RESET# Pin Low (During Embedded Algorithms) to Read Mode (See Note)	Max	20	ns
	t_{Ready}	RESET# Pin Low (NOT During Embedded Algorithms) to Read Mode (See Note)	Max	500	ns
	t_{RP}	RESET# Pulse Width	Min	500	ns
	t_{RH}	Reset High Time Before Read (See Note)	Min	50	ns
	t_{RPD}	RESET# Low to Standby Mode	Min	20	µs
	t_{RB}	RY/BY# Recovery Time	Min	0	ns

Notes:

1. *Not 100% tested. If ramp rate is equal to or faster than 1V/100µs with a falling edge of the RESET# pin initiated, the RESET# pin needs to be held low only for 100µs for power-up.*
2. *Next generation devices may have different reset speeds.*

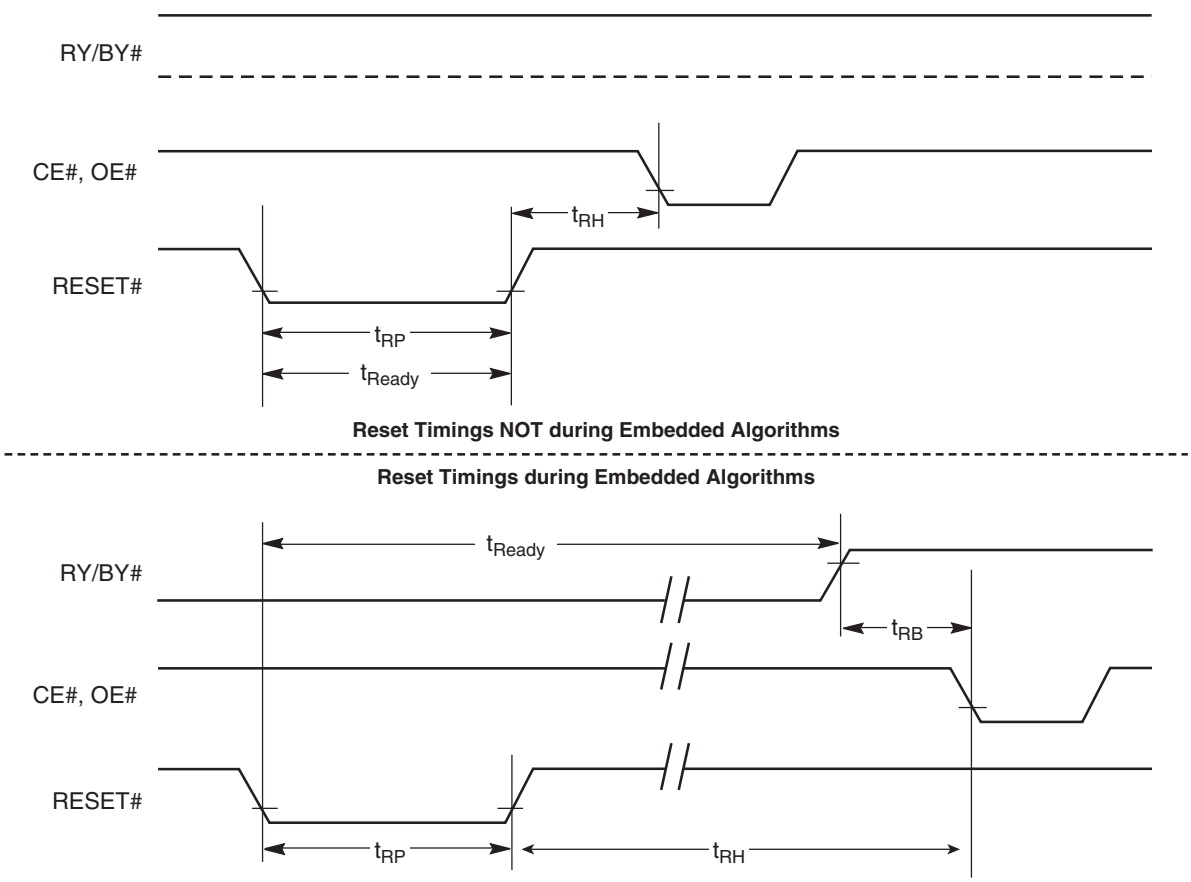


Figure 13. Reset Timings

AC Characteristics

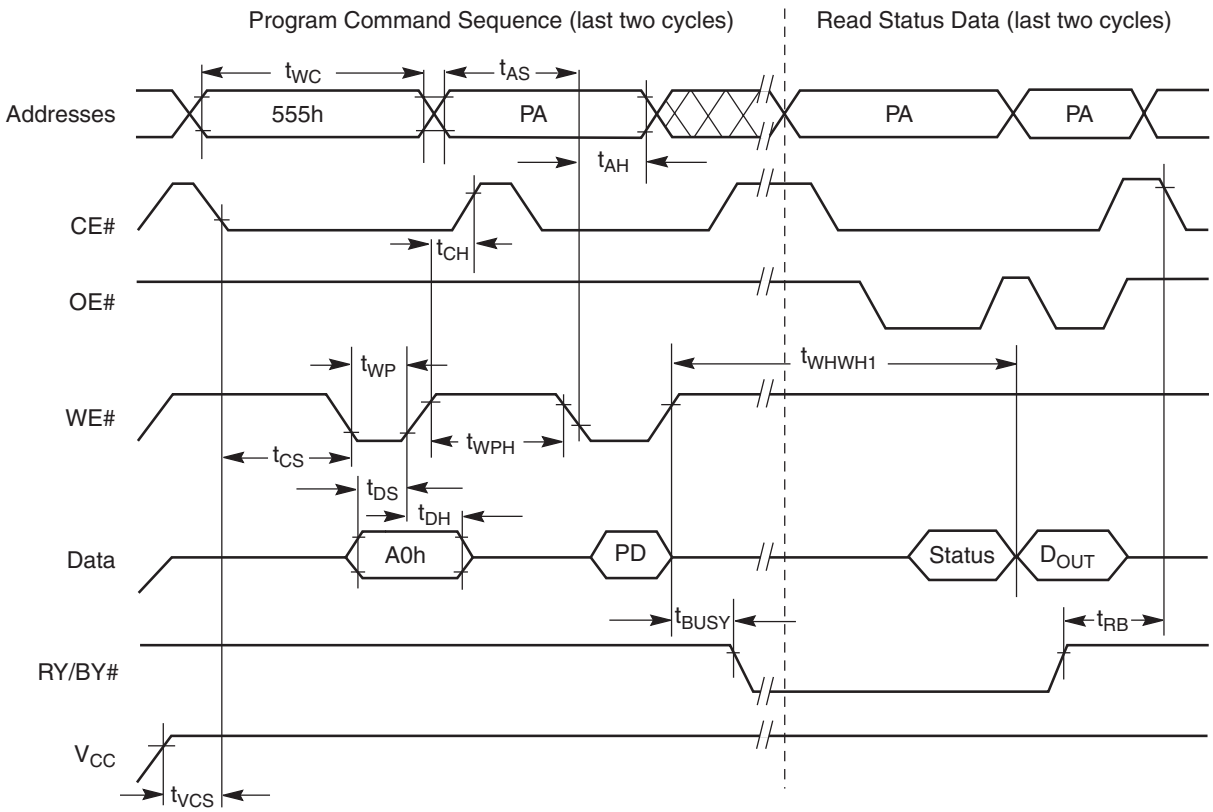
Erase and Program Operations–S29GLI28N, S29GL256N, S29GL5I2N

Parameter		Description			Speed Options				Unit
JEDEC	Std.				90	100	110	110	
t_{AVAV}	t_{WC}	Write Cycle Time (Note 1)		Min	90	100	110	110	ns
t_{AVWL}	t_{AS}	Address Setup Time		Min	0				ns
	t_{ASO}	Address Setup Time to OE# low during toggle bit polling		Min	15				ns
t_{WLAX}	t_{AH}	Address Hold Time		Min	45				ns
	t_{AHT}	Address Hold Time From CE# or OE# high during toggle bit polling		Min	0				ns
t_{DVWH}	t_{DS}	Data Setup Time		Min	45				ns
t_{WHDX}	t_{DH}	Data Hold Time		Min	0				ns
	t_{CEPH}	CE# High during toggle bit polling		Min	20				
	t_{OEPH}	Output Enable High during toggle bit polling		Min	20				ns
t_{GHWL}	t_{GHWL}	Read Recovery Time Before Write (OE# High to WE# Low)		Min	0				ns
t_{ELWL}	t_{CS}	CE# Setup Time		Min	0				ns
t_{WHEH}	t_{CH}	CE# Hold Time		Min	0				ns
t_{WLWH}	t_{WP}	Write Pulse Width		Min	35				ns
t_{WHDL}	t_{WPH}	Write Pulse Width High		Min	30				ns
t_{WHWH1}	t_{WHWH1}	Write Buffer Program Operation (Notes 2, 3)		Typ	240				µs
		Effective Write Buffer Program Operation (Notes 2, 4)	Per Word	Typ	15				µs
		Accelerated Effective Write Buffer Program Operation (Notes 2, 4)	Per Word	Typ	13.5				µs
		Program Operation (Note 2)	Word	Typ	60				µs
		Accelerated Programming Operation (Note 2)	Word	Typ	54				µs
t_{WHWH2}	t_{WHWH2}	Sector Erase Operation (Note 2)		Typ	0.5				sec
	t_{VHH}	V_{HH} Rise and Fall Time (Note 1)		Min	250				ns
	t_{VCS}	V_{CC} Setup Time (Note 1)		Min	50				µs
	t_{BUSY}	Erase/Program Valid to RY/BY# Delay		Min	90				ns

Notes:

1. *Not 100% tested.*
2. *See the "Erase and Programming Performance" section for more information.*
3. *For 1–16 words/1–32 bytes programmed.*
4. *Effective write buffer specification is based upon a 16-word/32-byte write buffer operation.*
5. *Unless otherwise indicated, AC specifications for 90 ns, 100 ns, and 110 ns speed options are tested with $V_{IO} = V_{CC} = 3$ V. AC specifications for 110 ns speed options are tested with $V_{IO} = 1.8$ V and $V_{CC} = 3.0$ V.*

AC Characteristics



Notes:

1. *PA = program address, PD = program data, D_{OUT} is the true data at the program address.*
2. *Illustration shows device in word mode.*

Figure 14. Program Operation Timings

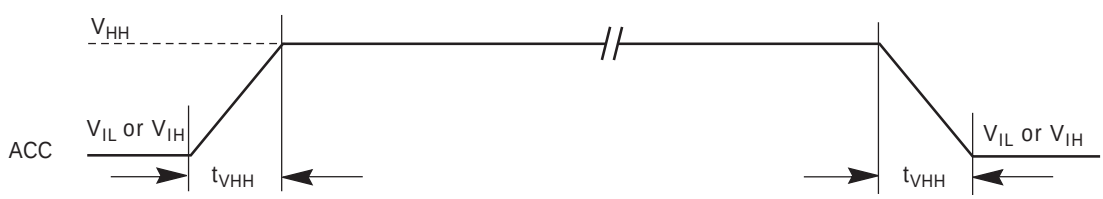
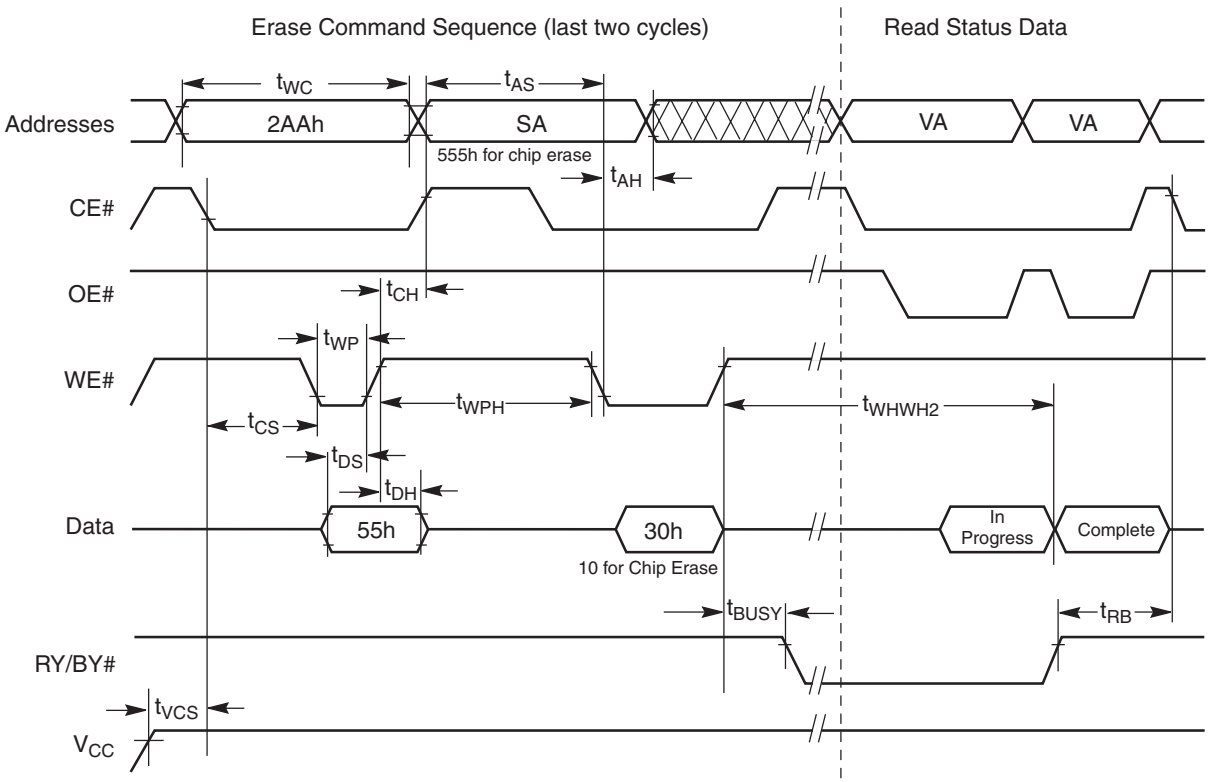


Figure 15. Accelerated Program Timing Diagram

Notes:

1. *Not 100% tested.*
2. *CE#, OE# = V_{IL}*
3. *OE# = V_{IL}*
4. *See Figure 9 and Table 14 for test specifications.*

AC Characteristics

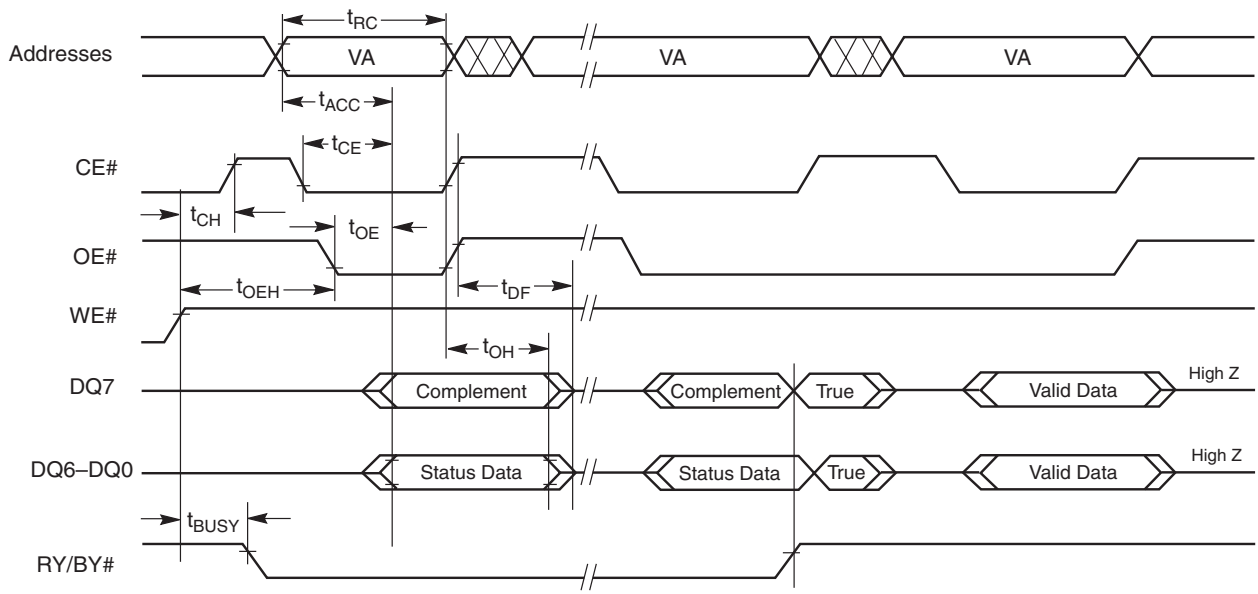


Notes:

1. *SA = sector address (for Sector Erase), VA = Valid Address for reading status data (.*
2. *These waveforms are for the word mode.*

Figure 16. Chip/Sector Erase Operation Timings

AC Characteristics

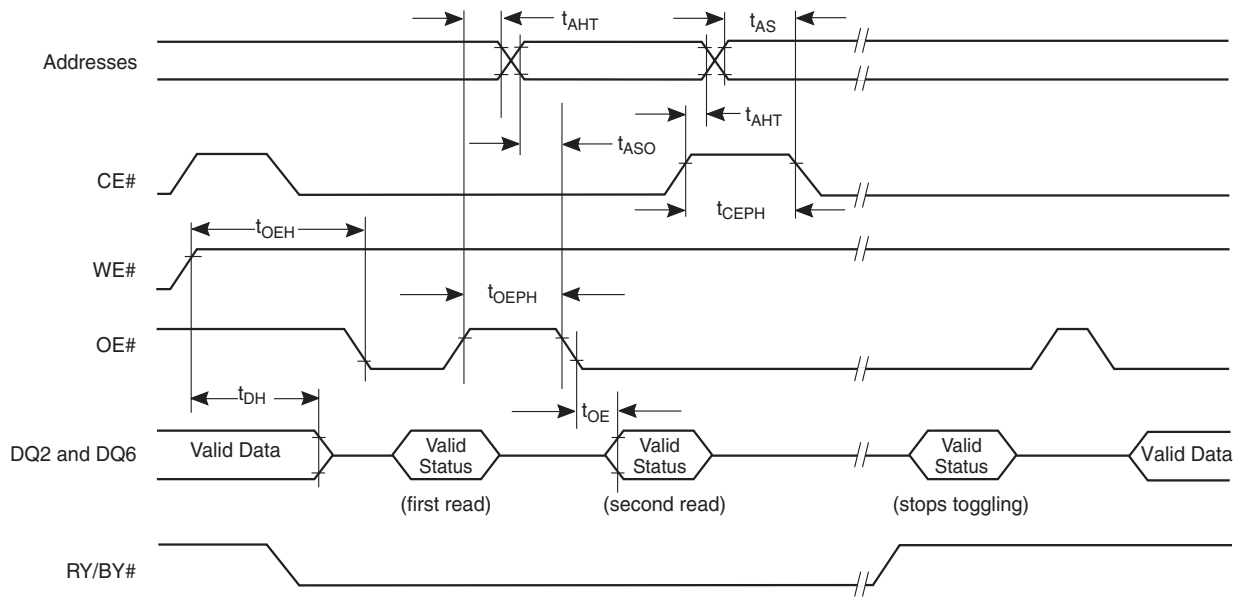


Note:

1. *VA = Valid address. Illustration shows first status cycle after command sequence, last status read cycle, and array data read cycle.*
2. *t_{OE} for data polling is 45 ns when V_{IO} = 1.65 to 2.7 V and is 35 ns when V_{IO} = 2.7 to 3.6 V*

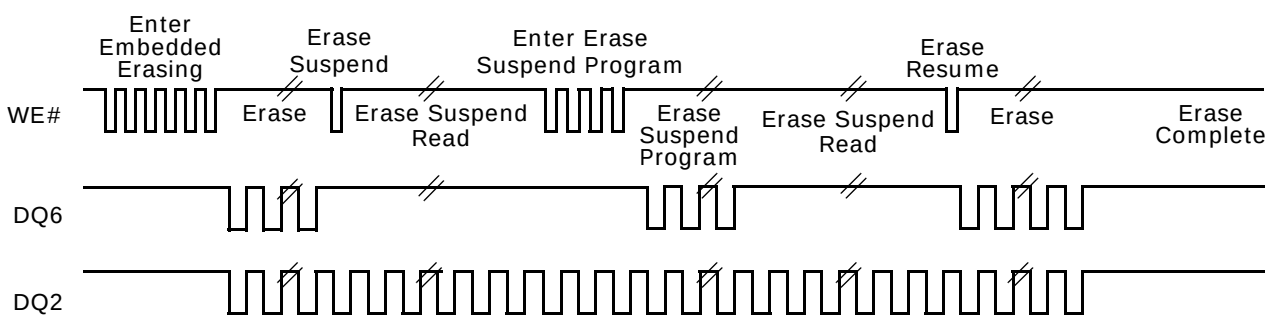
Figure 17. Data# Polling Timings (During Embedded Algorithms)

AC Characteristics



Note: *VA = Valid address; not required for DQ6. Illustration shows first two status cycle after command sequence, last status read cycle, and array data read cycle*

Figure 18. Toggle Bit Timings (During Embedded Algorithms)



Note: *DQ2 toggles only when read at an address within an erase-suspended sector. The system may use OE# or CE# to toggle DQ2 and DQ6.*

Figure 19. DQ2 vs. DQ6

AC Characteristics

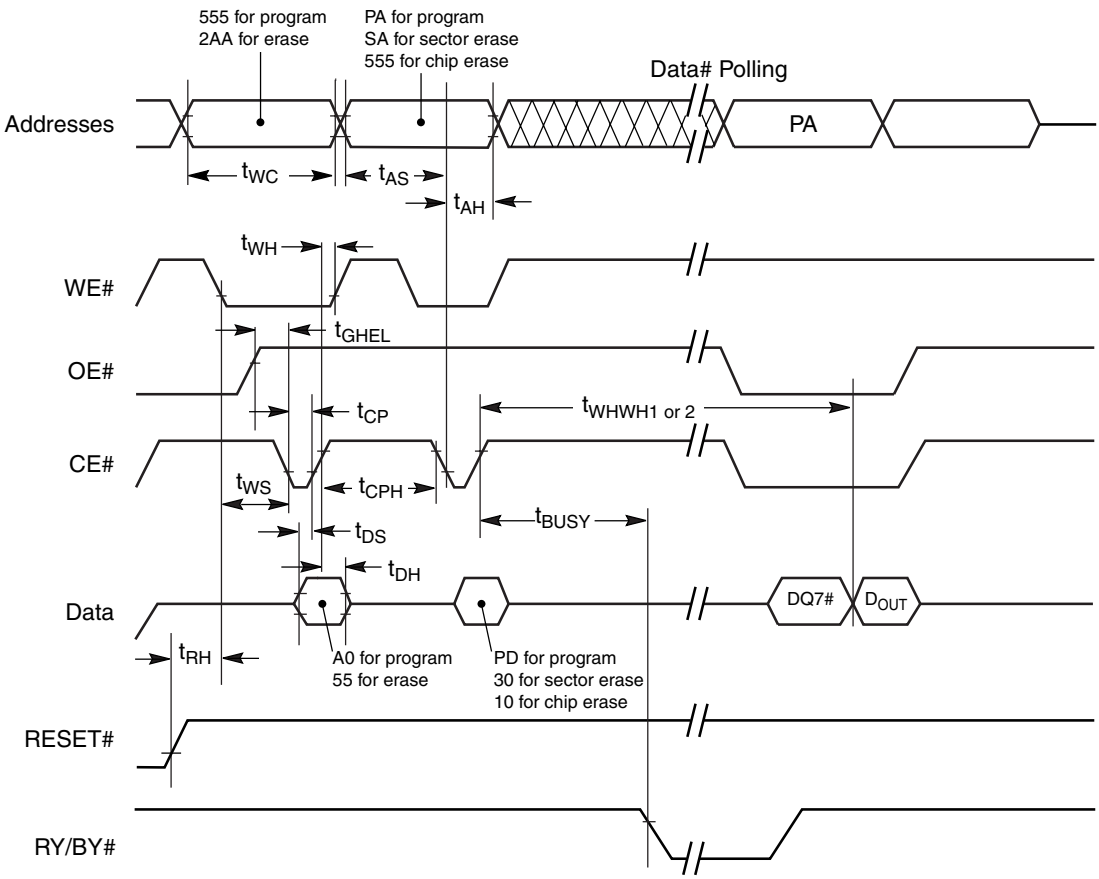
Alternate CE# Controlled Erase and Program Operations- S29GLI28N, S29GL256N, S29GL5I2N

Parameter		Description			Speed Options				Unit
JEDEC	Std.				90	100	110	110	
t_{AVAV}	t_{WC}	Write Cycle Time (Note 1)		Min	90	100	110	110	ns
t_{AVWL}	t_{AS}	Address Setup Time		Min	0				ns
	T_{ASO}	Address Setup Time to OE# low during toggle bit polling		Min	15				ns
t_{ELAX}	t_{AH}	Address Hold Time		Min	45				ns
	t_{AHT}	Address Hold Time From CE# or OE# high during toggle bit polling		Min	0				ns
t_{DVEH}	t_{DS}	Data Setup Time		Min	45				ns
t_{EHDX}	t_{DH}	Data Hold Time		Min	0				ns
	t_{CEPH}	CE# High during toggle bit polling		Min	20				ns
	t_{OEPH}	OE# High during toggle bit polling		Min	20				ns
t_{GHEL}	t_{GHEL}	Read Recovery Time Before Write (OE# High to WE# Low)		Min	0				ns
t_{WLEL}	t_{WS}	WE# Setup Time		Min	0				ns
t_{EHWH}	t_{WH}	WE# Hold Time		Min	0				ns
t_{ELEH}	t_{CP}	CE# Pulse Width		Min	35				ns
t_{EHEL}	t_{CPH}	CE# Pulse Width High		Min	30				ns
t_{WHWH1}	t_{WHWH1}	Write Buffer Program Operation (Notes 2, 3)		Typ	240				µs
		Effective Write Buffer Program Operation (Notes 2, 4)	Per Word	Typ	15				µs
		Effective Accelerated Write Buffer Program Operation (Notes 2, 4)	Per Word	Typ	13.5				µs
		Program Operation (Note 2)	Word	Typ	60				µs
		Accelerated Programming Operation (Note 2)	Word	Typ	54				µs
t_{WHWH2}	t_{WHWH2}	Sector Erase Operation (Note 2)		Typ	0.5				sec

Notes:

1. *Not 100% tested.*
2. *See the "AC Characteristics" section for more information.*
3. *For 1–16 words/1–32 bytes programmed.*
4. *Effective write buffer specification is based upon a 16-word/32-byte write buffer operation.*
5. *Unless otherwise indicated, AC specifications for 90 ns, 100ns, and 110 ns speed options are tested with $V_{IO} = V_{CC} = 3$ V. AC specifications for 110 ns speed options are tested with $V_{IO} = 1.8$ V and $V_{CC} = 3.0$ V.*

AC Characteristics



Notes:

1. *Figure indicates last two bus cycles of a program or erase operation.*
2. *PA = program address, SA = sector address, PD = program data.*
3. *DQ7# is the complement of the data written to the device. D_{OUT} is the data written to the device.*
4. *Waveforms are for the word mode.*

Figure 20. Alternate CE# Controlled Write (Erase/Program) Operation Timings

Erase And Programming Performance

Parameter		Typ (Note 1)	Max (Note 2)	Unit	Comments
Sector Erase Time		0.5	3.5	sec	Excludes 00h programming prior to erasure (Note 5)
Chip Erase Time	S29GL128N	64	256	sec	
	S29GL256N	128	512		
	S29GL512N	256	1024		
Total Write Buffer Programming Time (Note 3)		240		µs	Excludes system level overhead (Note 6)
Total Accelerated Effective Write Buffer Programming Time (Note 3)		200		µs	
Chip Program Time	S29GL128N	123		sec	
	S29GL256N	246			
	S29GL512N	492			

Notes:

1. *Typical program and erase times assume the following conditions: 25°C, 3.0 V V_{CC}, 10,000 cycles, checkerboard pattern.*
2. *Under worst case conditions of 90°C, V_{CC} = 3.0 V, 100,000 cycles.*
3. *Effective write buffer specification is based upon a 16-word write buffer operation.*
4. *The typical chip programming time is considerably less than the maximum chip programming time listed, since most words program faster than the maximum program times listed.*
5. *In the pre-programming step of the Embedded Erase algorithm, all bits are programmed to 00h before erasure.*
6. *System-level overhead is the time required to execute the two- or four-bus-cycle sequence for the program command. See Table 12 for further information on command definitions.*

TSOP Pin and BGA Package Capacitance

Parameter Symbol	Parameter Description	Test Setup		Typ	Max	Unit
C_{IN}	Input Capacitance	V_{IN} = 0	TSOP	6	7.5	pF
			BGA	4.2	5.0	pF
C_{OUT}	Output Capacitance	V_{OUT} = 0	TSOP	8.5	12	pF
			BGA	5.4	6.5	pF
C_{IN2}	Control Pin Capacitance	V_{IN} = 0	TSOP	7.5	9	pF
			BGA	3.9	4.7	pF

Notes:

1. *Sampled, not 100% tested.*
2. *Test conditions T_A = 25°C, f = 1.0 MHz.*

CellularRAM Type 2

I28/64/32 Megabit
Burst CellularRAM

Features

- **Single device supports asynchronous, page, and burst operations**
- **VCC Voltages**
  - 1.70V–1.95V V_{CC}
- **Random Access Time: 70ns**
- **Burst Mode Write Access**
  - Continuous burst
- **Burst Mode Read Access**
  - 4, 8, or 16 words, or continuous burst
- **Page Mode Read Access**
  - Sixteen-word page size
  - Interpage read access: 70ns
  - Intrapage read access: 20ns
- **Low Power Consumption**
  - Asynchronous READ < 25mA
  - Intrapage READ < 15mA
  - Initial access, burst READ < 35mA
  - Continuous burst READ < 11mA
  - Standby: 180µA
  - Deep power-down < 10µA
- **Low-Power Features**
  - Temperature Compensated Refresh (TCR) On-chip sensor control
  - Partial Array Refresh (PAR)
  - Deep Power-Down (DPD) Mode

General Description

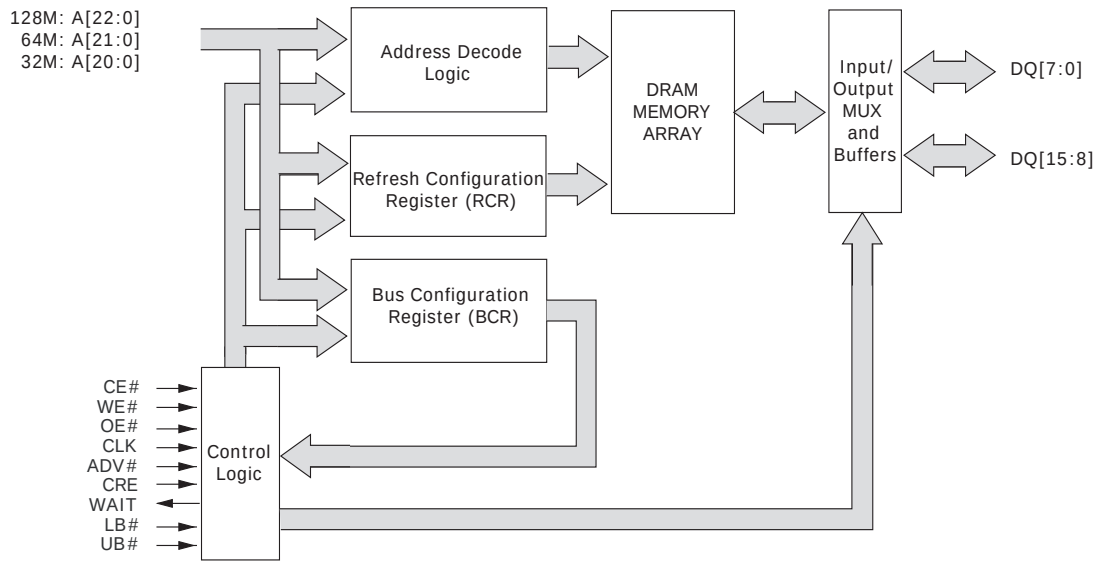
CellularRAM™ products are high-speed, CMOS dynamic random access memories developed for low-power, portable applications. These devices include an industry standard burst mode Flash interface that dramatically increases read/write bandwidth compared with other low-power SRAM or Pseudo SRAM offerings.

To operate smoothly on a burst Flash bus, CellularRAM products incorporate a transparent self-refresh mechanism. The hidden refresh requires no additional support from the system memory controller and has no significant impact on device read/write performance.

Two user-accessible control registers define device operation. The bus configuration register (BCR) defines how the CellularRAM device interacts with the system memory bus and is nearly identical to its counterpart on burst mode Flash devices. The refresh configuration register (RCR) is used to control how refresh is performed on the DRAM array. These registers are automatically loaded with default settings during power-up and can be updated anytime during normal operation.

Special attention has been focused on standby current consumption during self refresh. CellularRAM products include three mechanisms to minimize standby current. Partial array refresh (PAR) enables the system to limit refresh to only

that part of the DRAM array that contains essential data. Temperature compensated refresh (TCR) adjusts the refresh rate to match the device temperature—the refresh rate decreases at lower temperatures to minimize current consumption during standby. Deep power-down (DPD) enables the system to halt the refresh operation altogether when no vital information is stored in the device. The system-configurable refresh mechanisms are accessed through the RCR.



Note: *Functional block diagrams illustrate simplified device operation. See truth table, ball descriptions, and timing diagrams for detailed information.*

Figure 2I. Functional Block Diagram

Table 15. Signal Descriptions

Symbol	Type	Description
128M: A[22:0] 64M: A[21:0] 32M: A[20:0]	Input	Address Inputs: Inputs for addresses during READ and WRITE operations. Addresses are internally latched during READ and WRITE cycles. The address lines are also used to define the value to be loaded into the BCR or the RCR.
CLK	Input	Clock: Synchronizes the memory to the system operating frequency during synchronous operations. When configured for synchronous operation, the address is latched on the first rising CLK edge when ADV# is active. CLK is static (HIGH or LOW) during asynchronous access READ and WRITE operations and during PAGE READ ACCESS operations.
ADV#	Input	Address Valid: Indicates that a valid address is present on the address inputs. Addresses can be latched on the rising edge of ADV# during asynchronous READ and WRITE operations. ADV# can be held LOW during asynchronous READ and WRITE operations.
CRE	Input	Configuration Register Enable: When CRE is HIGH, WRITE operations load the RCR or BCR.
CE#	Input	Chip Enable: Activates the device when LOW. When CE# is HIGH, the device is disabled and goes into standby or deep power-down mode.
OE#	Input	Output Enable: Enables the output buffers when LOW. When OE# is HIGH, the output buffers are disabled.
WE#	Input	Write Enable: Determines if a given cycle is a WRITE cycle. If WE# is LOW, the cycle is a WRITE to either a configuration register or to the memory array.
LB#	Input	Lower Byte Enable. DQ[7:0]
UB#	Input	Upper Byte Enable. DQ[15:8]
DQ[15:0]	Input/ Output	Data Inputs/Outputs.
WAIT	Output	Wait: Provides data-valid feedback during burst READ and WRITE operations. The signal is gated by CE#. WAIT is used to arbitrate collisions between refresh and READ/WRITE operations. WAIT is asserted when a burst crosses a row boundary. WAIT is also used to mask the delay associated with opening a new internal page. WAIT is asserted and should be ignored during asynchronous and page mode operations. WAIT is High-Z when CE# is HIGH.
V_{CC}	Supply	Device Power Supply: (1.7V–1.95V) Power supply for device core operation.
$V_{CC}Q$	Supply	I/O Power Supply: (1.7V–1.95V) Power supply for input/output buffers.
V_{SS}	Supply	V_{SS} must be connected to ground.
$V_{SS}Q$	Supply	$V_{SS}Q$ must be connected to ground.

Note: *The CLK and ADV# inputs can be tied to V_{SS} if the device is always operating in asynchronous or page mode. WAIT will be asserted but should be ignored during asynchronous and page mode operations.*

Table 16. Bus Operations—Asynchronous Mode

MODE	POWER	CLK (Note 1)	ADV#	CE#	OE#	WE#	CRE	LB#/ UB#	WAIT (Note 2)	DQ[15:0] (Note 3)	NOTES
Read	Active	X	L	L	L	H	L	L	Low-Z	Data-Out	4
Write	Active	X	L	L	X	L	L	L	Low-Z	Data-In	4
Standby	Standby	X	X	H	X	X	L	X	High-Z	High-Z	5, 6
No Operation	Idle	X	X	L	X	X	L	X	Low-Z	X	4, 6
Configuration Register	Active	X	L	L	H	L	H	X	Low-Z	High-Z	
DPD	Deep Power-down	X	X	H	X	X	X	X	High-Z	High-Z	7

Notes:

1. *CLK may be HIGH or LOW, but must be static during synchronous read, synchronous write, burst suspend, and DPD modes; and to achieve standby power during standby and active modes.*
2. *The WAIT polarity is configured through the bus configuration register (BCR[10]).*
3. *When LB# and UB# are in select mode (LOW), DQ[15:0] are affected. When only LB# is in select mode, DQ[7:0] are affected. When only UB# is in the select mode, DQ[15:8] are affected.*
4. *The device will consume active power in this mode whenever addresses are changed.*
5. *When the device is in standby mode, address inputs and data inputs/outputs are internally isolated from any external influence.*
6. *V_{IN} = V_{CC}Q or 0V; all device balls must be static (unswitched) to achieve standby current.*
7. *DPD is maintained until RCR is reconfigured.*

Table 17. Bus Operations—Burst Mode

MODE	POWER	CLK (Note 1)	ADV#	CE#	OE#	WE#	CRE	LB#/ UB#	WAIT (Note 2)	DQ[15:0] (Note 3)	NOTES
Async Read	Active	X	L	L	L	H	L	L	Low-Z	Data-Out	4
Async Write	Active	X	L	L	X	L	L	L	Low-Z	Data-In	4
Standby	Standby	X	X	H	X	X	L	X	High-Z	High-Z	5, 6
No Operation	Idle	X	X	L	X	X	L	X	Low-Z	X	4, 6
Initial Burst Read	Active		L	L	X	H	L	L	Low-Z	Data-Out	4, 8
Initial Burst Write	Active		L	L	H	L	L	X	Low-Z	Data-In	4, 8
Burst Continue	Active		H	L	X	X	L	X	Low-Z	Data-In or Data-Out	4, 8
Burst Suspend	Active	X	X	L	H	X	L	X	Low-Z	High-Z	4, 8
Configuration Register	Active		L	L	H	L	H	X	Low-Z	High-Z	8
DPD	Deep Power-Down	X	X	H	X	X	X	X	High-Z	High-Z	7

Notes:

1. *CLK may be HIGH or LOW, but must be static during asynchronous read, synchronous write, burst suspend, and DPD modes; and to achieve standby power during standby and active modes.*
2. *The WAIT polarity is configured through the bus configuration register (BCR[10]).*
3. *When LB# and UB# are in select mode (LOW), DQ[15:0] are affected. When only LB# is in select mode, DQ[7:0] are affected. When only UB# is in the select mode, DQ[15:8] are affected.*
4. *The device will consume active power in this mode whenever addresses are changed.*
5. *When the device is in standby mode, address inputs and data inputs/outputs are internally isolated from any external influence.*
6. *V_{IN} = V_{CC}Q or 0V; all device balls must be static (unswitched) to achieve standby current.*
7. *DPD is maintained until RCR is reconfigured.*
8. *Burst mode operation is initialized through the bus configuration register (BCR[15]).*

Functional Description

The CellularRAM bus interface supports both asynchronous and burst mode transfers. Page mode accesses are also included as a bandwidth-enhancing extension to the asynchronous read protocol.

Power-Up Initialization

CellularRAM products include an on-chip voltage sensor used to launch the power-up initialization process. Initialization will configure the BCR and the RCR with their default settings (see Table 18 and Table 22). V_{CC} and V_{CC}Q must be applied simultaneously. When they reach a stable level at or above 1.7V, the device will require 150µs to complete its self-initialization process. During the initialization period, CE# should remain HIGH. When initialization is complete, the device is ready for normal operation.

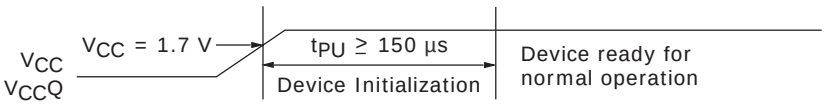


Figure 22. Power-Up Initialization Timing

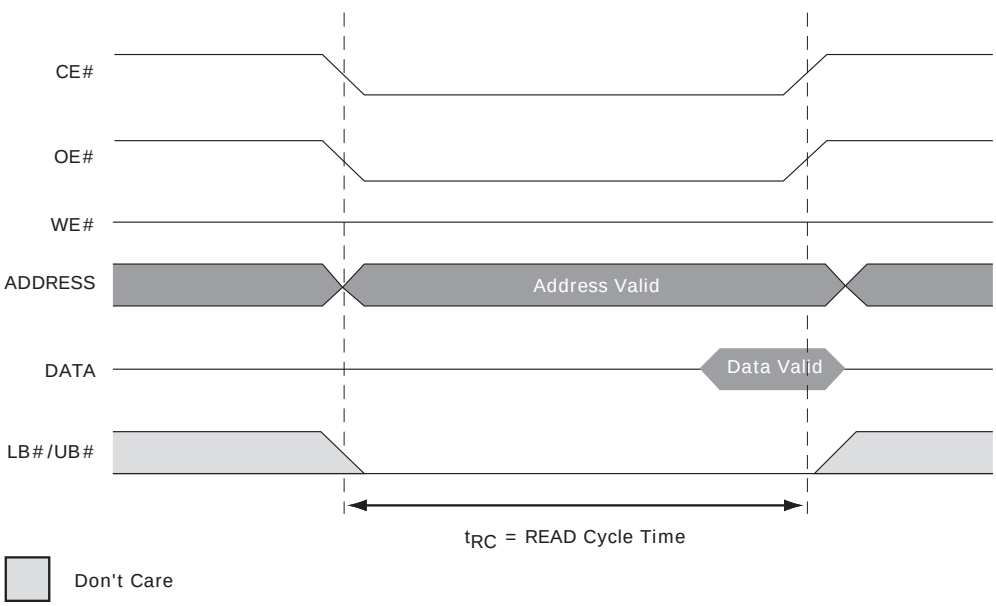
Bus Operating Modes

CellularRAM products incorporate a burst mode interface found on Flash products targeting low-power, wireless applications. This bus interface supports asynchronous, page mode, and burst mode read and write transfers. The specific interface supported is defined by the value loaded into the BCR. Page mode is controlled by the refresh configuration register (RCR[7]).

Asynchronous Mode

CellularRAM products power up in the asynchronous operating mode. This mode uses the industry standard SRAM control bus (CE#, OE#, WE#, LB#/ UB#). READ operations (Figure 23) are initiated by bringing CE#, OE#, and LB#/UB# LOW while keeping WE# HIGH. Valid data will be driven out of the I/Os after the specified access time has elapsed. WRITE operations (Figure 24) occur when CE#, WE#, and LB#/ UB# are driven LOW. During asynchronous WRITE operations, the OE# level is a “Don't Care,” and WE# will override OE#. The data to be written is latched on the rising edge of CE#, WE#, or LB#/UB# (whichever occurs first). Asynchronous operations (page mode disabled) can either use the ADV input to latch the address, or ADV can be driven LOW during the entire READ/ WRITE operation.

During asynchronous operation, the CLK input must be held static (HIGH or LOW, no transitions). WAIT will be driven while the device is enabled and its state should be ignored.



Note: *ADV must remain LOW for page mode operation.*

Figure 23. READ Operation (ADV# LOW)

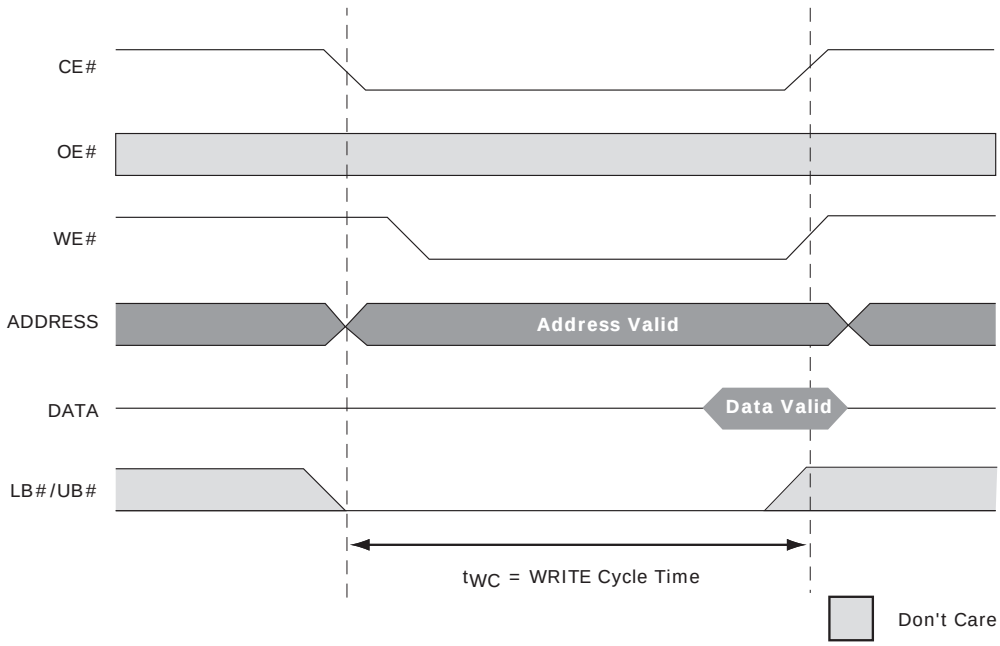


Figure 24. WRITE Operation (ADV# LOW)

Page Mode READ Operation

Page mode is a performance-enhancing extension to the legacy asynchronous READ operation. In page mode-capable products, an initial asynchronous read access is performed, then adjacent addresses can be read quickly by simply changing the low-order address. Addresses A[3:0] are used to determine the members of the 16-address CellularRAM page. Addresses A[4] and higher must remain fixed during the entire page mode access. Figure 25 shows the timing for a page mode access. Page mode takes advantage of the fact that adjacent addresses can be read in a shorter period of time than random addresses. WRITE operations do not include comparable page mode functionality.

During asynchronous page mode operation, the CLK input must be held LOW. CE# must be driven HIGH upon completion of a page mode access. WAIT will be driven while the device is enabled and its state should be ignored. Page mode is enabled by setting RCR[7] to HIGH. WRITE operations do not include comparable page mode functionality. ADV must be driven LOW during all page mode read accesses.

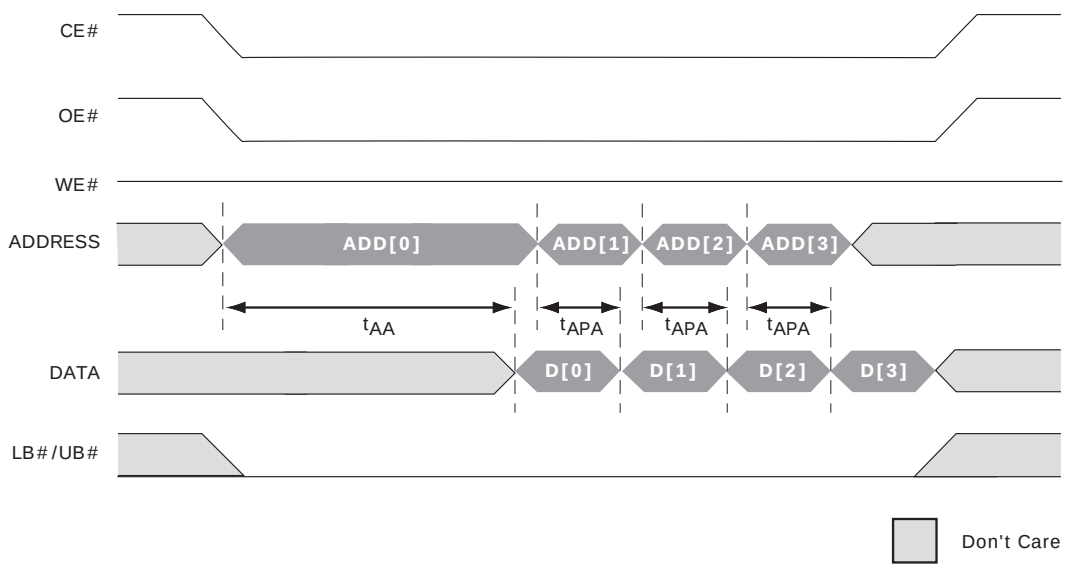


Figure 25. Page Mode READ Operation (ADV# LOW)

Burst Mode Operation

Burst mode operations enable high-speed synchronous READ and WRITE operations. Burst operations consist of a multi-clock sequence that must be performed in an ordered fashion. After CE# goes LOW, the address to access is latched on the rising edge of the next clock that ADV# is LOW. During this first clock rising edge, WE# indicates whether the operation is going to be a READ (WE# = HIGH, Figure 26) or WRITE (WE# = LOW, Figure 27).

The size of a burst can be specified in the BCR either as a fixed length or continuous. Fixed-length bursts consist of four, eight, or sixteen words. Continuous bursts have the ability to start at a specified address and burst through the entire memory.

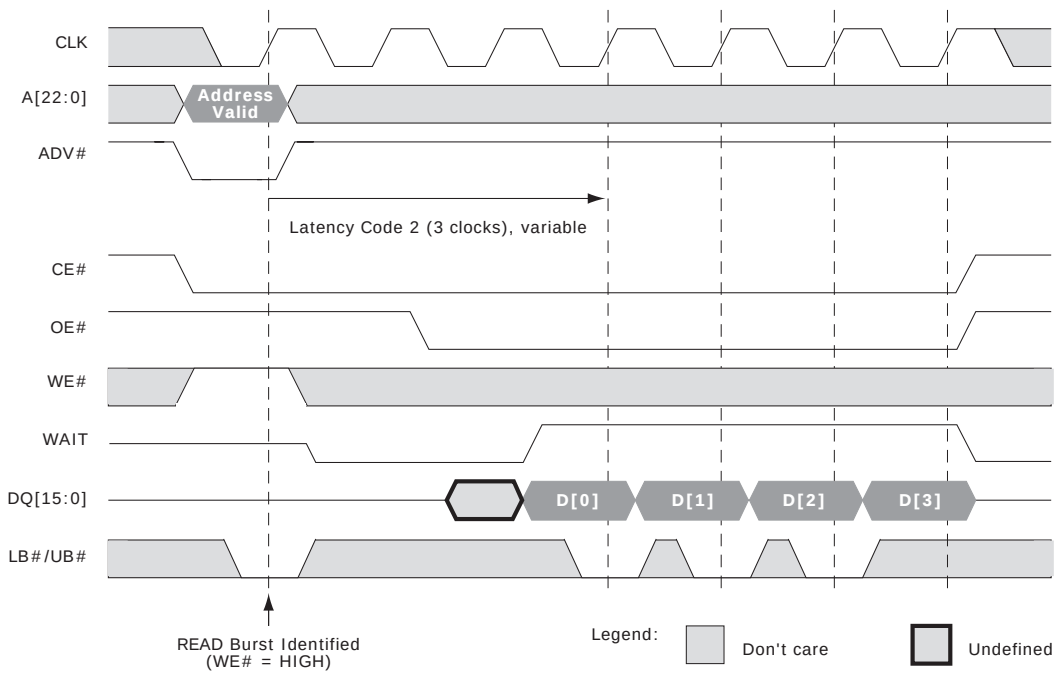
The latency count stored in the BCR defines the number of clock cycles that elapse before the initial data value is transferred between the processor and CellularRAM device.

The WAIT output asserts as soon as a burst is initiated, and de-asserts to indicate when data is to be transferred into (or out of) the memory. WAIT will again be asserted if the burst crosses a row boundary. Once the CellularRAM device has restored the previous row's data and accessed the next row, WAIT will be deasserted and the burst can continue (see Figure 47).

To access other devices on the same bus without the timing penalty of the initial latency for a new burst, burst mode can be suspended. Bursts are suspended by stopping CLK. CLK can be stopped HIGH or LOW. If another device will use the data bus while the burst is suspended, OE# should be taken HIGH to disable the CellularRAM outputs; otherwise, OE# can remain LOW. Note that the WAIT output will continue to be active, and as a result no other devices should directly share the WAIT connection to the controller. To continue the burst sequence, OE# is taken LOW, then CLK is restarted after valid data is available on the bus.

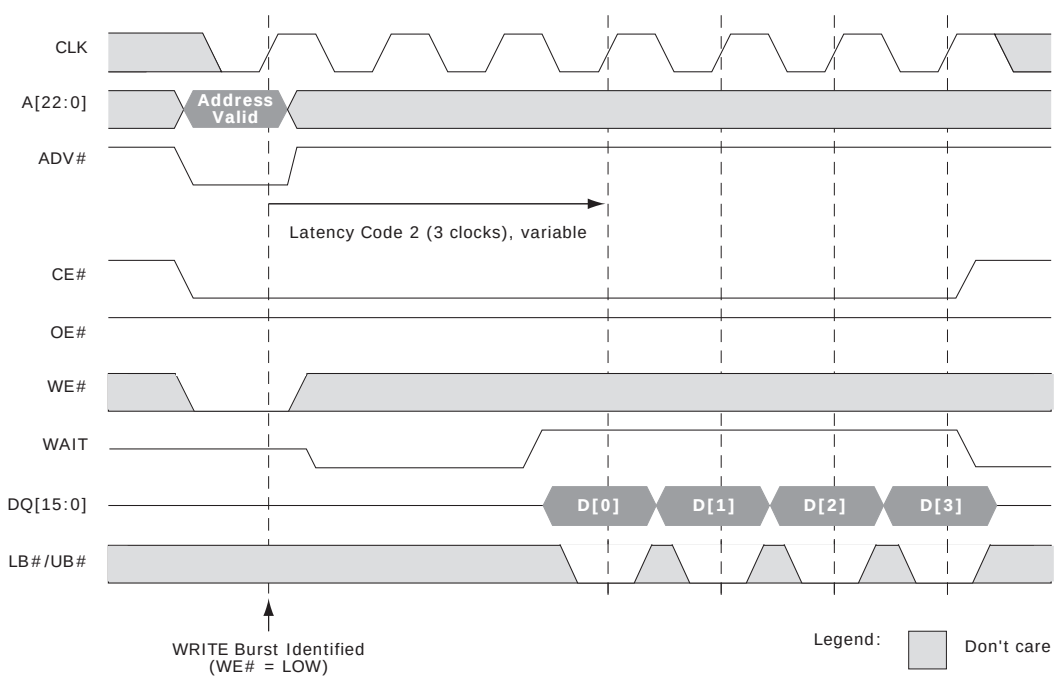
See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time during burst operations. If a burst suspension will

cause CE# to remain LOW for longer than t_{CEM}, CE# should be taken HIGH and the burst restarted with a new CE# LOW/ADV# LOW cycle.



Note: *Non-default BCR settings: Variable latency; latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*

Figure 26. Burst Mode READ (4-word burst)



Note: *Non-default BCR settings: Variable latency; latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*

Figure 27. Burst Mode WRITE (4-word burst)

Mixed-Mode Operation

The device can support a combination of synchronous READ and asynchronous WRITE operations when the BCR is configured for synchronous operation. The asynchronous WRITE operation requires that the clock (CLK) remain static (HIGH or LOW) during the entire sequence. The ADV# signal can be used to latch the target address, or it can remain LOW during the entire WRITE operation. CE# can remain LOW when transitioning between mixed-mode operations with fixed latency enabled. Note that the t_{CKA} period is the same as a READ or WRITE cycle. This time is required to ensure adequate refresh. Mixed-mode operation facilitates a seamless interface to legacy burst mode Flash memory controllers. See Figure 55 for the “Asynchronous WRITE Followed by Burst READ” timing diagram.

WAIT Operation

The WAIT output on a CellularRAM device is typically connected to a shared, system-level WAIT signal (see Figure 28 below). The shared WAIT signal is used by the processor to coordinate transactions with multiple memories on the synchronous bus.

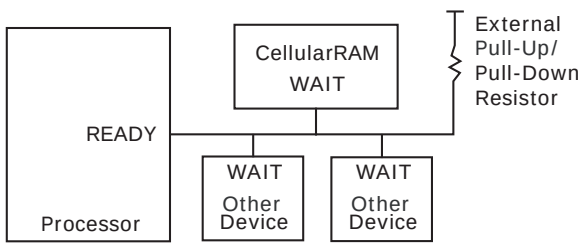


Figure 28. Wired or WAIT Configuration

Once a READ or WRITE operation has been initiated, WAIT goes active to indicate that the CellularRAM device requires additional time before data can be transferred. For READ operations, WAIT will remain active until valid data is output from the device. For WRITE operations, WAIT will indicate to the memory controller when data will be accepted into the CellularRAM device. When WAIT transitions to an inactive state, the data burst will progress on successive clock edges.

CE# must remain asserted during WAIT cycles (WAIT asserted and WAIT configuration BCR[8] = 1). Bringing CE# HIGH during WAIT cycles may cause data corruption. (Note that for BCR[8] = 0, the actual WAIT cycles end one cycle after WAIT de-asserts, and for row boundary crossings, start one cycle after the WAIT signal asserts.)

When using variable initial access latency (BCR[14] = 0), the WAIT output performs an arbitration role for READ or WRITE operations launched while an on-chip refresh is in progress. If a collision occurs, the WAIT pin is asserted for additional clock cycles until the refresh has completed (see Figure 29 and Figure 30). When the refresh operation has completed, the READ or WRITE operation will continue normally.

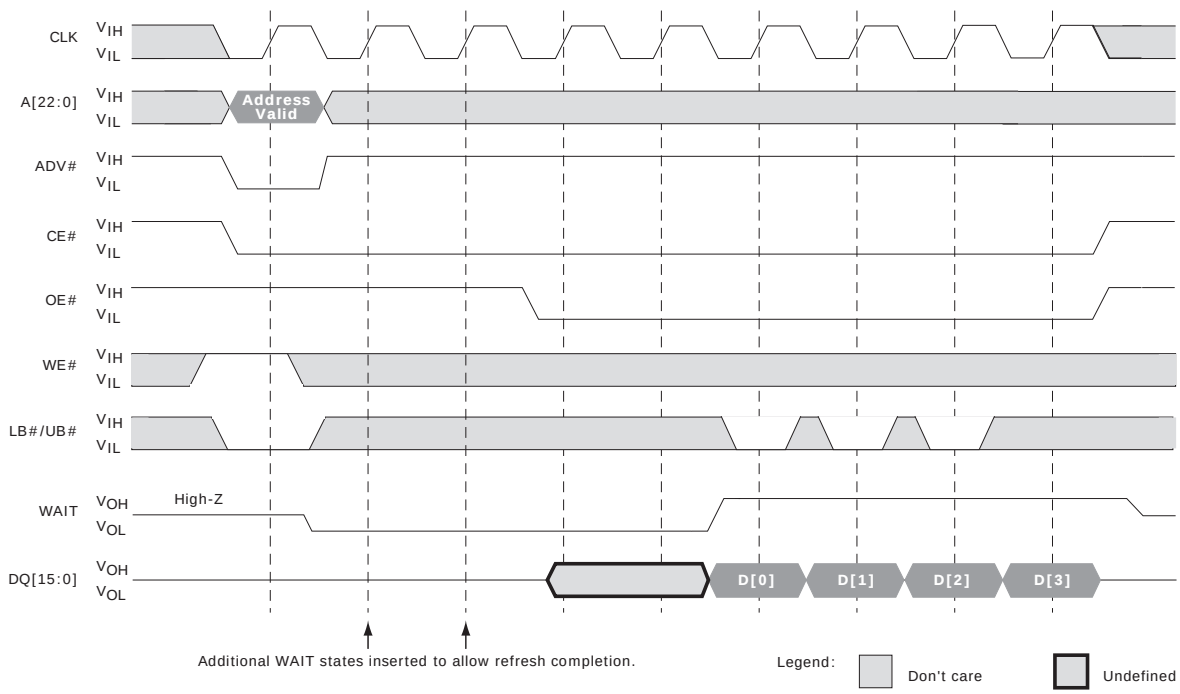
WAIT is also asserted when a continuous READ or WRITE burst crosses the boundary between 128-word rows. The WAIT assertion allows time for the new row to be accessed, and permits any pending refresh operations to be performed.

WAIT will be asserted but should be ignored during asynchronous READ and WRITE, and page READ operations.

LB#/UB# Operation

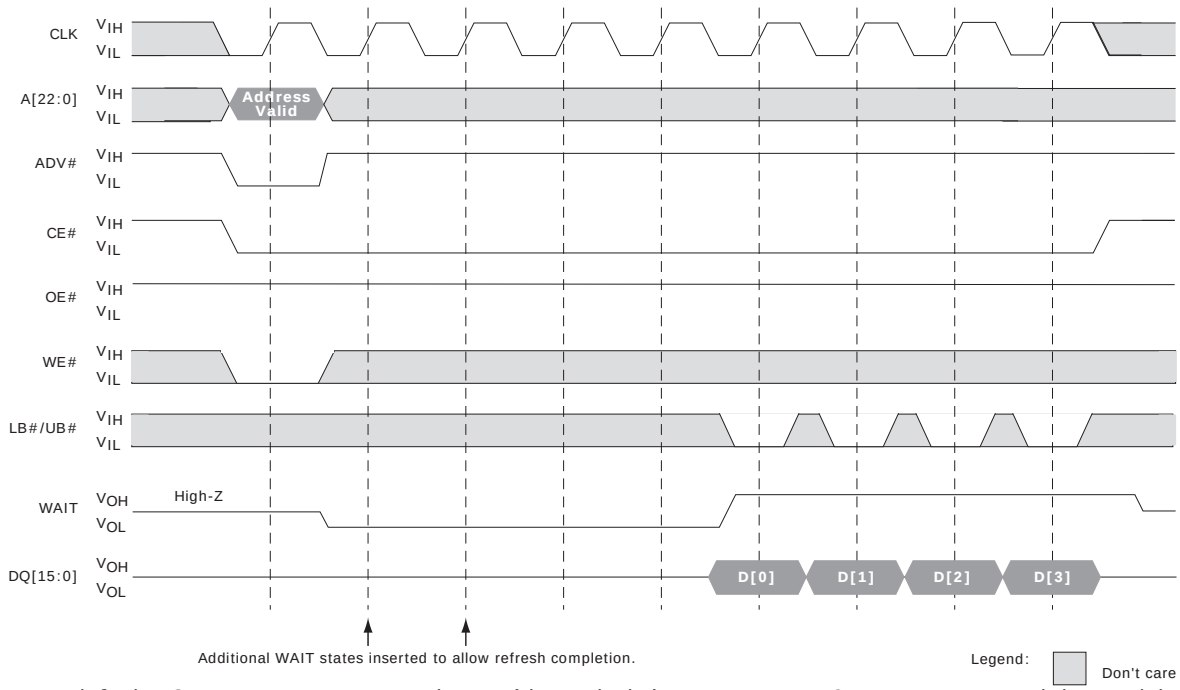
The LB# enable and UB# enable signals support byte-wide data transfers. During READ operations, the enabled byte(s) are driven onto the DQs. The DQs associated with a disabled byte are put into a High-Z state during a READ operation. During WRITE operations, any disabled bytes will not be transferred to the RAM array and the internal value will remain unchanged. During an asynchronous WRITE cycle, the data to be written is latched on the rising edge of CE#, WE#, LB#, or UB#, whichever occurs first.

When both the LB# and UB# are disabled (HIGH) during an operation, the device will disable the data bus from receiving or transmitting data. Although the device will seem to be deselected, it remains in an active mode as long as CE# remains LOW.



Note: *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*

Figure 29. Refresh Collision During READ Operation



Note: *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*

Figure 30. Refresh Collision During WRITE Operation

Low-Power Operation

Standby Mode Operation

During standby, the device current consumption is reduced to the level necessary to perform the DRAM refresh operation. Standby operation occurs when CE# is HIGH.

The device will enter a reduced power state upon completion of a READ or WRITE operation, or when the address and control inputs remain static for an extended period of time. This mode will continue until a change occurs to the address or control inputs.

Temperature Compensated Refresh

Temperature compensated refresh (TCR) is used to adjust the refresh rate depending on the device operating temperature. DRAM technology requires increasingly frequent refresh operation to maintain data integrity as temperatures increase. More frequent refresh is required due to increased leakage of the DRAM capacitive storage elements as temperatures rise. A decreased refresh rate at lower temperatures will facilitate a savings in standby current.

TCR allows for adequate refresh at four different temperature thresholds (+15°C, +45°C, +70°C, and +85°C). The setting selected must be for a temperature higher than the case temperature of the CellularRAM device. For example, if the case temperature is 50°C, the system can minimize self refresh current consumption by selecting the +7°0C setting. The +15°C and +45°C settings would result in inadequate refreshing and cause data corruption.

Partial Array Refresh

Partial array refresh (PAR) restricts refresh operation to a portion of the total memory array. This feature enables the device to reduce standby current by refreshing only that part of the memory array required by the host system. The refresh options are full array, one-half array, one-quarter array, three-quarter array, or none of the array. The mapping of these partitions can start at either the beginning or the end of the address map (see Table 23). READ and WRITE operations to address ranges receiving refresh will not be affected. Data stored in addresses not receiving refresh will become corrupted. When re-enabling additional portions of the array, the new portions are available immediately upon writing to the RCR.

Deep Power-Down Operation

Deep power-down (DPD) operation disables all refresh-related activity. This mode is used if the system does not require the storage provided by the CellularRAM device. Any stored data will become corrupted when DPD is enabled. When refresh activity has been re-enabled by rewriting the RCR, the CellularRAM device will require 150µs to perform an initialization procedure before normal operations can resume. During this 150µs period, the current consumption will be higher than the specified standby levels, but considerably lower than the active current specification.

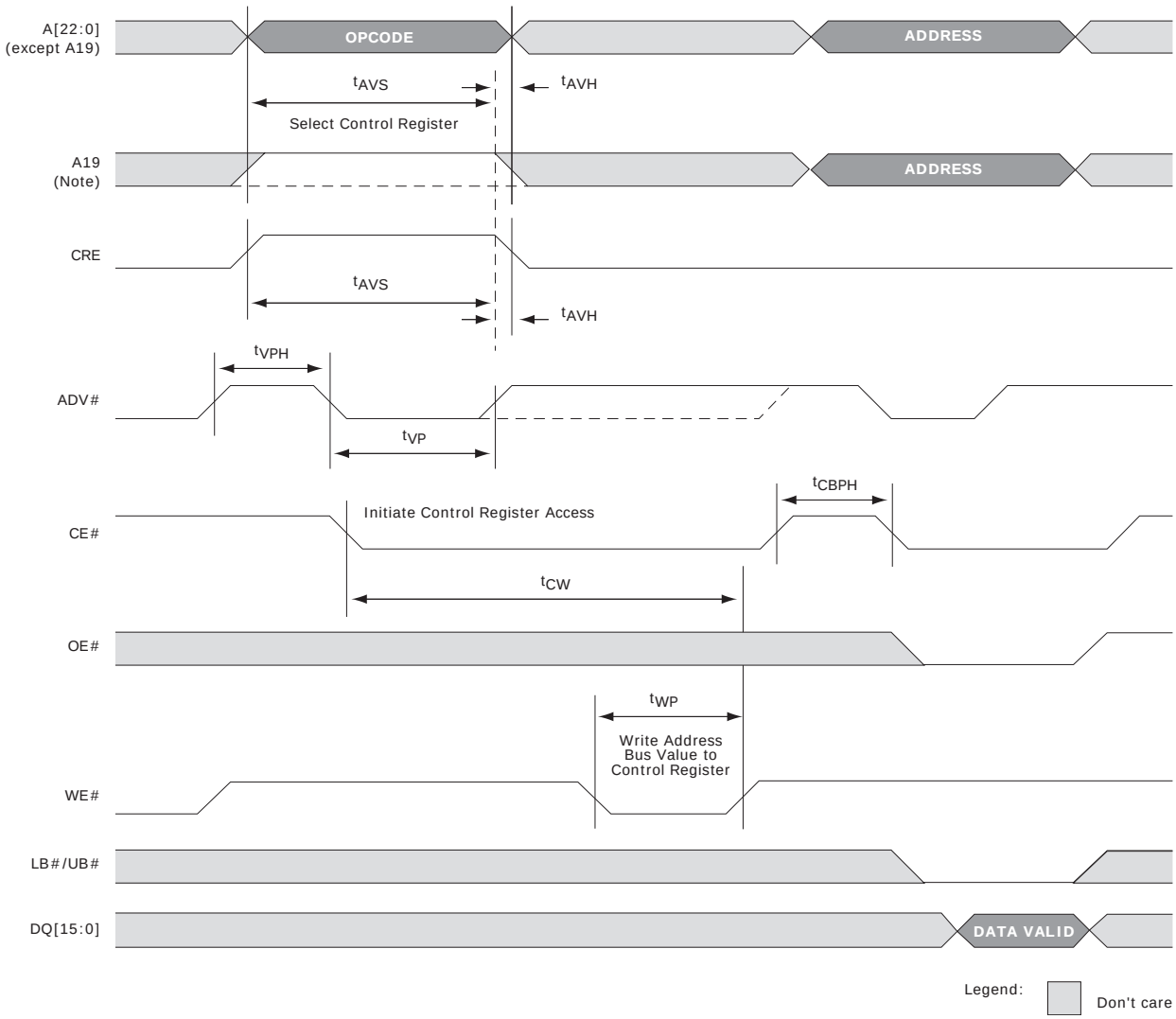
DPD cannot be enabled or disabled by writing to the RCR using the software access sequence; the RCR should be accessed using CRE instead.

Configuration Registers

Two user-accessible configuration registers define the device operation. The bus configuration register (BCR) defines how the CellularRAM interacts with the system memory bus and is nearly identical to its counterpart on burst mode Flash devices. The refresh configuration register (RCR) is used to control how refresh is performed on the DRAM array. These registers are automatically loaded with default settings during power-up, and can be updated any time the devices are operating in a standby state.

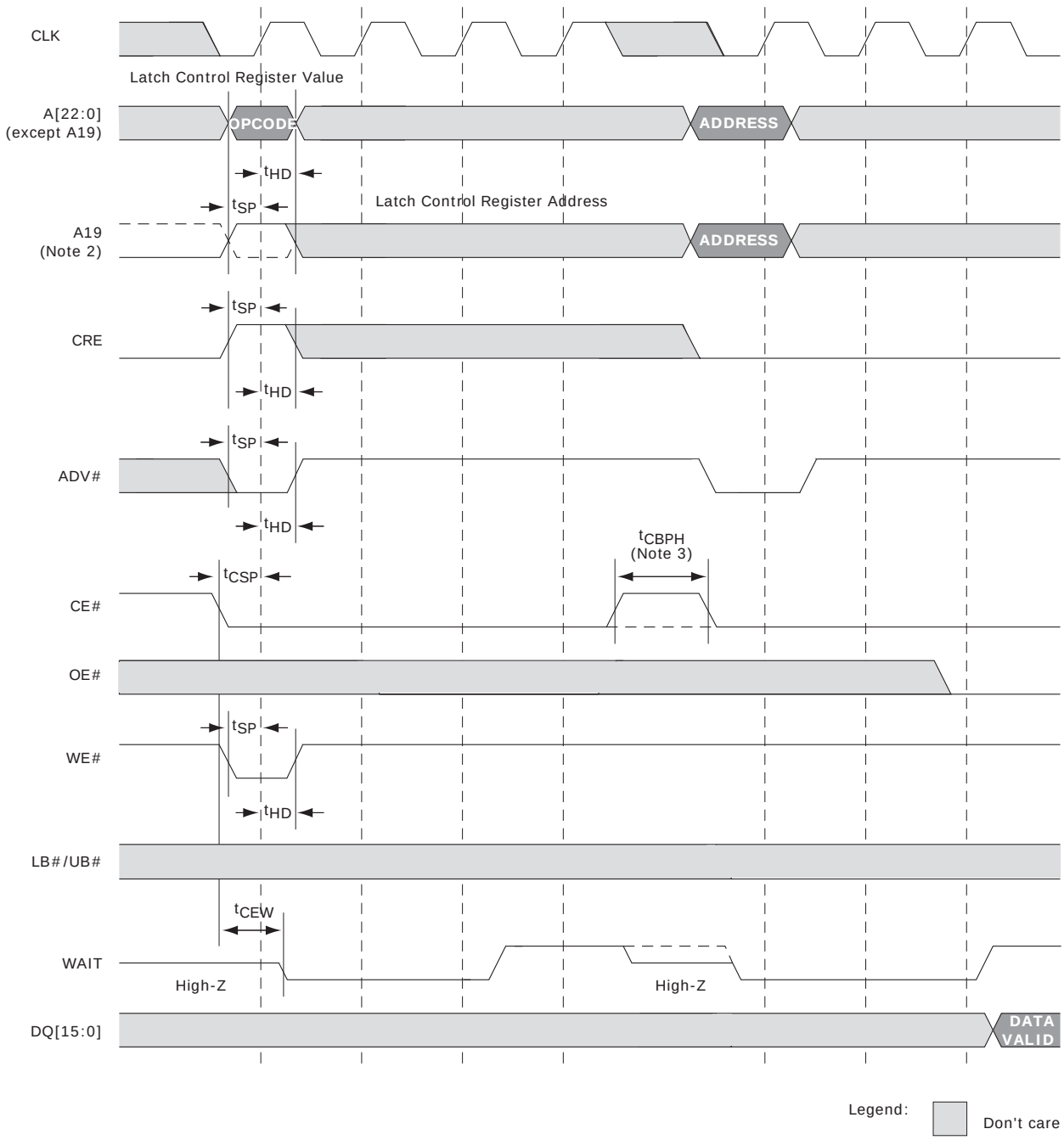
Access Using CRE

The configuration registers can be written to using either a synchronous or an asynchronous operation when the configuration register enable (CRE) input is HIGH (see Figure 31 and Figure 32). When CRE is LOW, a READ or WRITE operation will access the memory array. The register values are written via address pins A[21:0]. In an asynchronous WRITE, the values are latched into the configuration register on the rising edge of ADV#, CE#, or WE#, whichever occurs first; LB# and UB# are “Don’t Care.” The BCR is accessed when A[19] is HIGH; the RCR is accessed when A[19] is LOW. For reads, address inputs other than A[19] are “Don’t Care,” and register bits 15:0 are output on DQ[15:0].



Note: *A[19] = LOW to load RCR; A[19] = HIGH to load BCR.*

Figure 31. Configuration Register WRITE, Asynchronous Mode Followed by READ



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *A[19] = LOW to load RCR; A[19] = HIGH to load BCR.*
3. *CE# must remain LOW to complete a burst-of-one WRITE. WAIT must be monitored—additional WAIT cycles caused by refresh collisions require a corresponding number of additional CE# LOW cycles.*

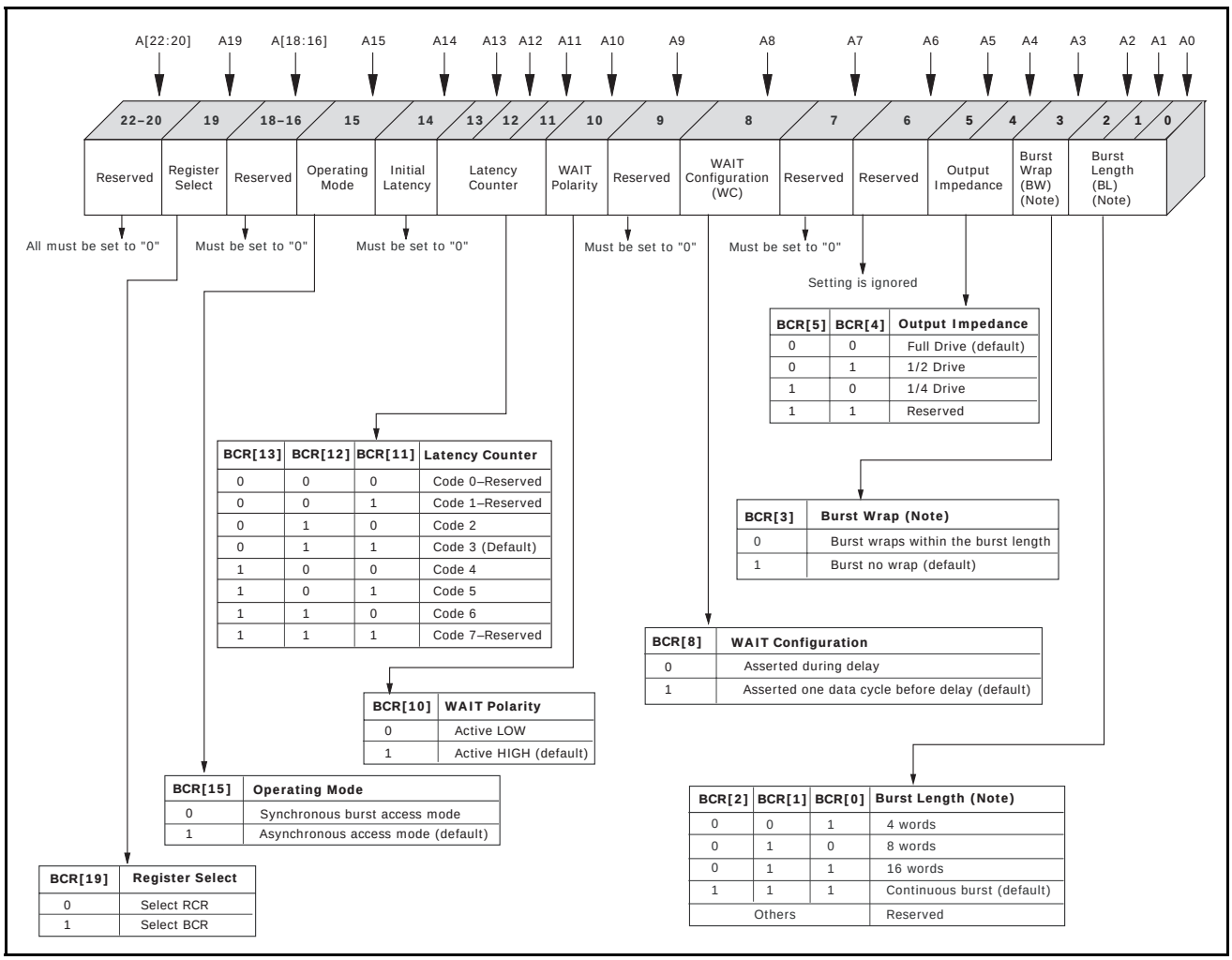
Figure 32. Configuration Register WRITE, Synchronous Mode Followed by READ0

Bus Configuration Register

The BCR defines how the CellularRAM device interacts with the system memory bus. Page mode operation is enabled by a bit contained in the RCR. Table 18 below describes the control bits in the BCR. At power up, the BCR is set to 9D4Fh.

The BCR is accessed using CRE and A[19] HIGH.

Table 18. Bus Configuration Register Definition



BCR[5]	BCR[4]	Output Impedance
0	0	Full Drive (default)
0	1	1/2 Drive
1	0	1/4 Drive
1	1	Reserved

BCR[13]	BCR[12]	BCR[11]	Latency Counter
0	0	0	Code 0–Reserved
0	0	1	Code 1–Reserved
0	1	0	Code 2
0	1	1	Code 3 (Default)
1	0	0	Code 4
1	0	1	Code 5
1	1	0	Code 6
1	1	1	Code 7–Reserved

BCR[3]	Burst Wrap (Note)
0	Burst wraps within the burst length
1	Burst no wrap (default)

BCR[8]	WAIT Configuration
0	Asserted during delay
1	Asserted one data cycle before delay (default)

BCR[10]	WAIT Polarity
0	Active LOW
1	Active HIGH (default)

BCR[15]	Operating Mode
0	Synchronous burst access mode
1	Asynchronous access mode (default)

BCR[19]	Register Select
0	Select RCR
1	Select BCR

BCR[2]	BCR[1]	BCR[0]	Burst Length (Note)
0	0	1	4 words
0	1	0	8 words
0	1	1	16 words
1	1	1	Continuous burst (default)
Others			Reserved

Note: *Burst wrap and length apply to READ operations only.*

Table 19. Sequence and Burst Length

BURST WRAP		STARTING ADDRESS	4-WORD BURST LENGTH	8-WORD BURST LENGTH	16-WORD BURST LENGTH	CONTINUOUS BURST
BCR[3]	WRAP	(DECIMAL)	LINEAR	LINEAR	LINEAR	LINEAR
0	Yes	0	0-1-2-3	0-1-2-3-4-5-6-7	0-1-2-3-4-5-6-7-8-9-10-11-12-13-14-15	0-1-2-3-4-5-6-…
		1	1-2-3-0	1-2-3-4-5-6-7-0	1-2-3-4-5-6-7-8-9-10-11-12-13-14-15-0	1-2-3-4-5-6-7-…
		2	2-3-0-1	2-3-4-5-6-7-0-1	2-3-4-5-6-7-8-9-10-11-12-13-14-15-0-1	2-3-4-5-6-7-8-…
		3	3-0-1-2	3-4-5-6-7-0-1-2	3-4-5-6-7-8-9-10-11-12-13-14-15-0-1-2	3-4-5-6-7-8-9-…
		4		4-5-6-7-0-1-2-3	4-5-6-7-8-9-10-11-12-13-14-15-0-1-2-3	4-5-6-7-8-9-10-…
		5		5-6-7-0-1-2-3-4	5-6-7-8-9-10-11-12-13-14-15-0-1-2-3-4	5-6-7-8-9-10-11-…
		6		6-7-0-1-2-3-4-5	6-7-8-9-10-11-12-13-14-15-0-1-2-3-4-5	6-7-8-9-10-11-12-…
		7		7-0-1-2-3-4-5-6	7-8-9-10-11-12-13-14-15-0-1-2-3-4-5-6	7-8-9-10-11-12-13-…
		…			…	…
		14			14-15-0-1-2-3-4-5-6-7-8-9-10-11-12-13	14-15-16-17-18-19-20-…
		15			15-0-1-2-3-4-5-6-7-8-9-10-11-12-13-14	15-16-17-18-19-20-21…
1	No	0	0-1-2-3	0-1-2-3-4-5-6-7	0-1-2-3-4-5-6-7-8-9-10-11-12-13-14-15	0-1-2-3-4-5-6-…
		1	1-2-3-4	1-2-3-4-5-6-7-8	1-2-3-4-5-6-7-8-9-10-11-12-13-14-15-16	1-2-3-4-5-6-7-…
		2	2-3-4-5	2-3-4-5-6-7-8-9	2-3-4-5-6-7-8-9-10-11-12-13-14-15-16-17	2-3-4-5-6-7-8-…
		3	3-4-5-6	3-4-5-6-7-8-9-10	3-4-5-6-7-8-9-10-11-12-13-14-15-16-17-18	3-4-5-6-7-8-9-…
		4		4-5-6-7-8-9-10-11	4-5-6-7-8-9-10-11-12-13-14-15-16-17-18-19	4-5-6-7-8-9-10-…
		5		5-6-7-8-9-10-11-12	5-6-7-8-9-10-11-12-13-…-15-16-17-18-19-20	5-6-7-8-9-10-11…
		6		6-7-8-9-10-11-12-13	6-7-8-9-10-11-12-13-14-…-16-17-18-19-20-21	6-7-8-9-10-11-12…
		7		7-8-9-10-11-12-13-14	7-8-9-10-11-12-13-14-…-17-18-19-20-21-22	7-8-9-10-11-12-13…
		…			…	…
		14			14-15-16-17-18-19-…-23-24-25-26-27-28-29	14-15-16-17-18-19-20-…
		15			5-16-17-18-19-20-…-24-25-26-27-28-29-30	15-16-17-18-19-20-21-…

Burst Length (BCR[2:0]): Default = Continuous Burst

Burst lengths define the number of words the device outputs during burst READ operations. The device supports a burst length of 4, 8, or 16 words. The device can also be set in continuous burst mode where data is accessed sequentially without regard to address boundaries. Enabling burst no-wrap with BCR[3] = 1 overrides the burst-length setting.

Burst Wrap (BCR[3]): Default = No Wrap

The burst-wrap option determines if a 4-, 8-, or 16-word READ burst wraps within the burst length or steps through sequential addresses. If the wrap option is not enabled, the device accesses data from sequential addresses without regard to burst boundaries. When continuous burst operation is selected, the internal address wraps to 000000h if the burst goes past the last address. Enabling burst nowrap (BCR[3] = 1) overrides the burst-length setting.

Output Impedance (BCR[5:4]): Default = Outputs Use Full Drive Strength

The output driver strength can be altered to full, one-half, or one-quarter strength to adjust for different data bus loading scenarios. The reduced-strength options are intended for stacked chip (Flash + CellularRAM) environments when there is a dedicated memory bus. The reduced-drive-strength option minimizes the noise generated on the data bus during READ operations. Normal output drive strength should be selected when using a discrete CellularRAM device in a more heavily loaded data bus environment. Outputs are configured at full drive strength during testing.

Table 20. Output Impedance

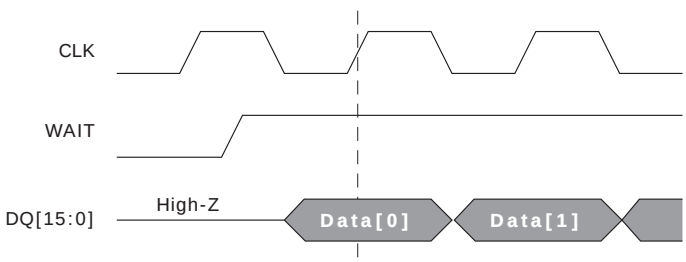
BCR[5]	BCR[4]	DRIVE STRENGTH
0	0	Full
0	1	1/2
1	0	1/4
1	1	Reserved

WAIT Configuration (BCR[8]): Default = WAIT Transitions One Clock Before Data Valid/Invalid

The WAIT configuration bit is used to determine when WAIT transitions between the asserted and the de-asserted state with respect to valid data presented on the data bus. The memory controller will use the WAIT signal to coordinate data transfer during synchronous READ and WRITE operations. When BCR[8] = 0, data will be valid or invalid on the clock edge immediately after WAIT transitions to the de-asserted or asserted state, respectively (Figure 33 and Figure 35). When A8 = 1, the WAIT signal transitions one clock period prior to the data bus going valid or invalid (Figure 34).

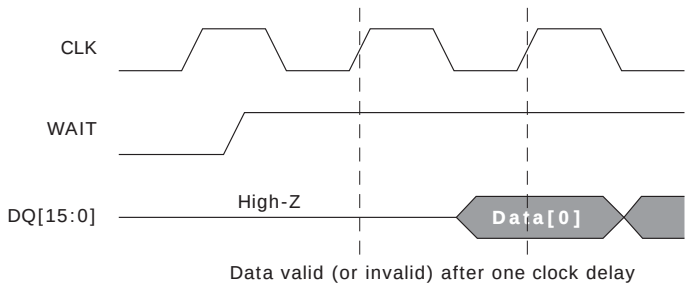
WAIT Polarity (BCR[10]): Default = WAIT Active HIGH

The WAIT polarity bit indicates whether an asserted WAIT output should be HIGH or LOW. This bit will determine whether the WAIT signal requires a pull-up or pull-down resistor to maintain the de-asserted state.



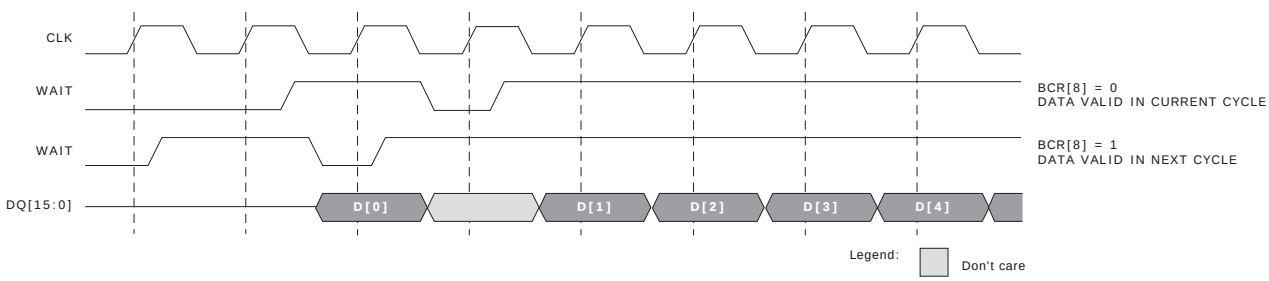
Note: *Data valid/invalid immediately after WAIT transitions (BCR[8] = 0). See Figure 35.*

Figure 33. WAIT Configuration (BCR[8] = 0)



Note: *Valid/invalid data delayed for one clock after WAIT transitions (BCR[8] = 1). See Figure 35.*

Figure 34. WAIT Configuration (BCR[8] = I)



Note: *Non-default BCR setting: WAIT active LOW.*

Figure 35. WAIT Configuration During Burst Operation

Latency Counter (BCR[13:11]): Default = Three-Clock Latency

The latency counter bits determine how many clocks occur between the beginning of a READ or WRITE operation and the first data value transferred. Latency codes from two (three clocks) to six (seven clocks) are allowed (see Table 21 and Figure 36 below).

Table 21. Variable Latency Configuration Codes

BCR[13:11]	LATENCY CONFIGURATION CODE	LATENCY (Note)		MAX INPUT CLK FREQUENCY (MHz)	
		NORMAL	REFRESH COLLISION	70ns/80 MHz	85ns/66 MHz
010	2 (3 clocks)	2	4	75 (13.0ns)	44 (22.7ns)
011	3 (4 clocks)—default	3	6	80 (12.5ns)	66 (15.2ns)
100	4 (5 clocks)	4	8		

Note: *Latency is the number of clock cycles from the initiation of a burst operation until data appears. Data is transferred on the next clock cycle.*

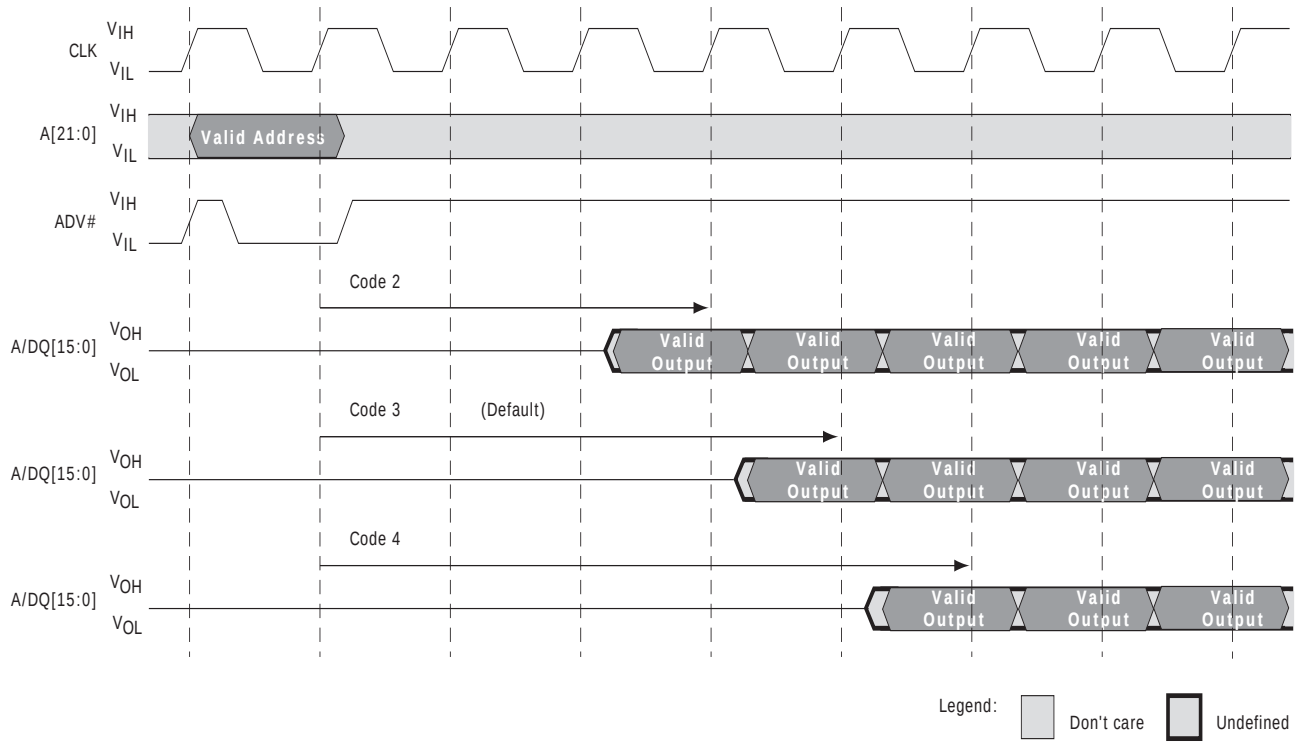


Figure 36. Latency Counter (Variable Initial Latency, No Refresh Collision)

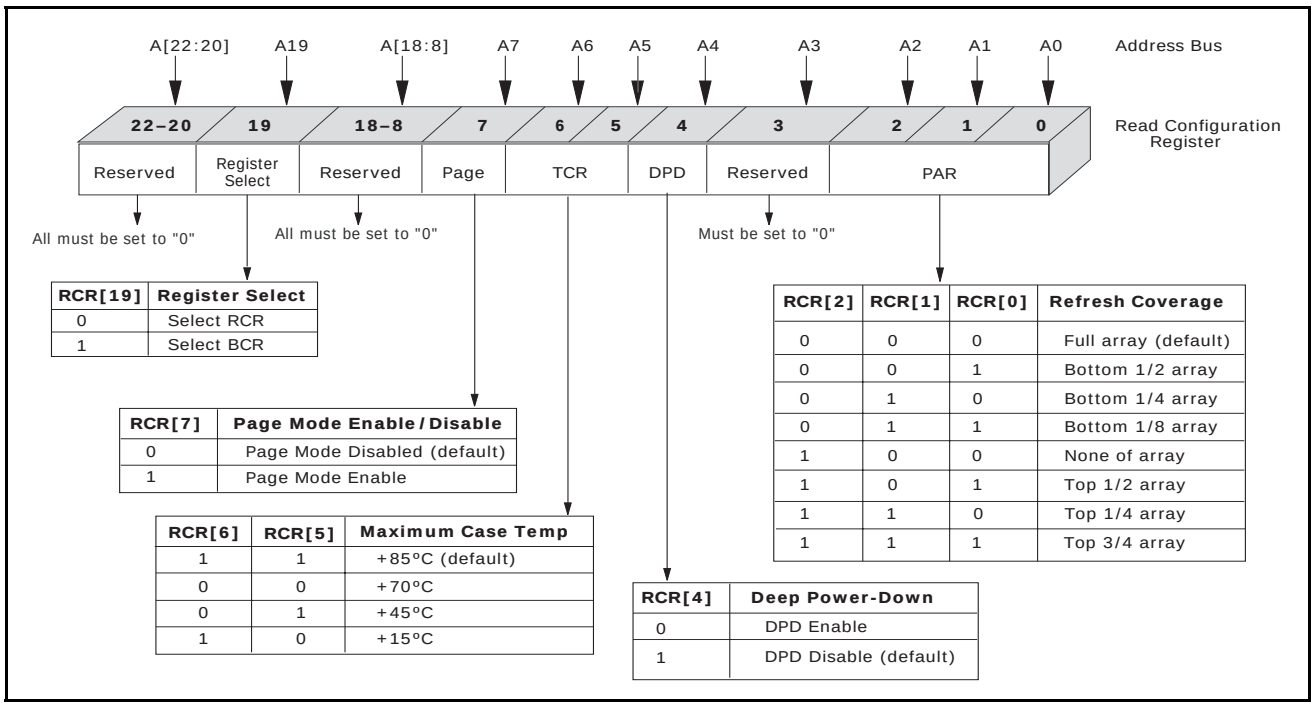
Operating Mode (BCR[15]): Default = Asynchronous Operation

The operating mode bit selects either synchronous burst operation or the default asynchronous mode of operation.

Refresh Configuration Register

The refresh configuration register (RCR) defines how the CellularRAM device performs its transparent self refresh. Altering the refresh parameters can dramatically reduce current consumption during standby mode. Page mode control is also embedded into the RCR. Table 22 below describes the control bits used in the RCR. At power-up, the RCR is set to 0070h. The RCR is accessed using CRE and A[19] LOW.

Table 22. Refresh Configuration Register Mapping



RCR[19]	Register Select
0	Select RCR
1	Select BCR

RCR[7]	Page Mode Enable / Disable
0	Page Mode Disabled (default)
1	Page Mode Enable

RCR[6]	RCR[5]	Maximum Case Temp
1	1	+85°C (default)
0	0	+70°C
0	1	+45°C
1	0	+15°C

RCR[4]	Deep Power-Down
0	DPD Enable
1	DPD Disable (default)

RCR[2]	RCR[1]	RCR[0]	Refresh Coverage
0	0	0	Full array (default)
0	0	1	Bottom 1/2 array
0	1	0	Bottom 1/4 array
0	1	1	Bottom 1/8 array
1	0	0	None of array
1	0	1	Top 1/2 array
1	1	0	Top 1/4 array
1	1	1	Top 3/4 array

Partial Array Refresh (RCR[2:0]): Default = Full Array Refresh

The PAR bits restrict refresh operation to a portion of the total memory array. This feature allows the device to reduce standby current by refreshing only that part of the memory array required by the host system. The refresh options are full array, one-half array, one-quarter array, three-quarters array, or none of the array. The mapping of these partitions can start at either the beginning or the end of the address map (see Table 23 through Table 25).

Table 23. 128Mb Address Patterns for PAR (RCR[4] = 1)

RCR[2]	RCR[1]	RCR[0]	ACTIVE SECTION	ADDRESS SPACE	SIZE	DENSITY
0	0	0	Full die	000000h–7FFFFFh	8 Meg x 16	128Mb
0	0	1	One-half of die	000000h–3FFFFFh	4 Meg x 16	64Mb
0	1	0	One-quarter of die	000000h–1FFFFFh	2 Meg x 16	32Mb
0	1	1	One-eighth of die	000000h–0FFFFFh	1 Meg x 16	16Mb
1	0	0	None of die	0	0 Meg x 16	0Mb
1	0	1	One-half of die	400000h–7FFFFFh	4 Meg x 16	64Mb
1	1	0	One-quarter of die	600000h–7FFFFFh	2 Meg x 16	32Mb
1	1	1	One-eighth of die	700000h–7FFFFFh	1 Meg x 16	16Mb

Table 24. 64Mb Address Patterns for PAR (RCR[4] = I)

RCR[2]	RCR[I]	RCR[0]	ACTIVE SECTION	ADDRESS SPACE	SIZE	DENSITY
0	0	0	Full die	000000h–3FFFFFh	4 Meg x 16	64Mb
0	0	1	One-half of die	000000h–2FFFFFh	3 Meg x 16	48Mb
0	1	0	One-quarter of die	000000h–1FFFFFh	2 Meg x 16	32Mb
0	1	1	One-eighth of die	000000h–0FFFFFh	1 Meg x 16	16Mb
1	0	0	None of die	0	0 Meg x 16	0Mb
1	0	1	One-half of die	100000h–3FFFFFh	3 Meg x 16	48Mb
1	1	0	One-quarter of die	200000h–3FFFFFh	2 Meg x 16	32Mb
1	1	1	One-eighth of die	300000h–3FFFFFh	1 Meg x 16	16Mb

Table 25. 32Mb Address Patterns for PAR (RCR[4] = I)

RCR[2]	RCR[I]	RCR[0]	ACTIVE SECTION	ADDRESS SPACE	SIZE	DENSITY
0	0	0	Full die	000000h–1FFFFFh	2 Meg x 16	32Mb
0	0	1	One-half of die	000000h–17FFFFh	1.5 Meg x 16	24Mb
0	1	0	One-quarter of die	000000h–0FFFFFh	1 Meg x 16	16Mb
0	1	1	One-eighth of die	000000h–07FFFFh	512K x 16	8Mb
1	0	0	None of die	0	0 Meg x 16	0Mb
1	0	1	One-half of die	080000h–1FFFFFh	1.5 Meg x 16	24Mb
1	1	0	One-quarter of die	100000h–1FFFFFh	1 Meg x 16	16Mb
1	1	1	One-eighth of die	180000h–1FFFFFh	512K x 16	8Mb

Deep Power-Down (RCR[4]): Default = DPD Disabled

The deep power-down bit enables and disables all refresh-related activity. This mode is used if the system does not require the storage provided by the CellularRAM device. Any stored data will become corrupted when DPD is enabled. When refresh activity has been re-enabled, the CellularRAM device will require 150µs to perform an initialization procedure before normal operations can resume.

Deep power-down is enabled when RCR[4] = 0, and remains enabled until RCR[4] is set to “1.”

Temperature Compensated Refresh (RCR[6:5]): Default = +85ºC Operation

The TCR bits allow for adequate refresh at four different temperature thresholds (+15ºC, +45ºC, +70ºC, and +85ºC). The setting selected must be for a temperature higher than the case temperature of the CellurlarRAM device. If the case temperature is +50ºC, the system can minimize self refresh current consumption by selecting the +70ºC setting. The +15ºC and +45ºC settings would result in inadequate refreshing and cause data corruption.

Page Mode Operation (RCR[7]): Default = Disabled

The page mode operation bit determines whether page mode is enabled for asynchronous READ operations. In the power-up default state, page mode is disabled.

Absolute Maximum Ratings

Voltage to Any Ball Except V_{CC}, $V_{CC}Q$
Relative to V_{SS} . . . . . -0.50V to (4.0V or $V_{CC}Q$ + 0.3V, whichever is less)

Voltage on V_{CC} Supply Relative to V_{SS} . . . . . -0.2V to +2.45V

Voltage on $V_{CC}Q$ Supply Relative to V_{SS} . . . . . -0.2V to +2.45V

Storage Temperature (plastic) . . . . . -55ºC to +150ºC

Operating Temperature (case)
Wireless. . . . . -25ºC to +85ºC

**Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.*

DC Characteristics

Table 26. Electrical Characteristics and Operating Conditions

Description	Conditions	Symbol		Min	Max	Units	Notes
Supply Voltage		V_{CC}		1.70	1.95	V	
I/O Supply Voltage		V_{CCQ}	W: 1.8V	1.70	1.95	V	
			J: 1.5V	1.35	1.65	V	
Input High Voltage		V_{IH}		V_{CCQ} - 0.4	V_{CCQ} + 0.2	V	2
Input Low Voltage		V_{IL}		-0.20	0.4	V	3
Output High Voltage	I_{OH} = -0.2mA	V_{OH}		0.80 V_{CCQ}		V	4
Output Low Voltage	I_{OL} = +0.2mA	V_{OL}			0.20 V_{CCQ}	V	4
Input Leakage Current	V_{IN} = 0 to V_{CCQ}	I_{LI}			1	µA	
Output Leakage Current	OE# = V_{IH} or Chip Disabled	I_{LO}			1	µA	
Operating Current							
Asynchronous Random READ	V_{IN} = V_{CCQ} or 0V Chip Enabled, IOUT = 0	$I_{CC}1$	-70		25	mA	5
			-85		20		
Asynchronous Page READ			-70		15		
			-85		12		
Initial Access, Burst READ	V_{IN} = V_{CCQ} or 0V Chip Enabled, IOUT = 0	$I_{CC}1$	80 MHz		35	mA	5
			66 MHz		30		
Continuous Burst READ			80 MHz		18		
			66 MHz		15		
WRITE Operating Current	V_{IN} = V_{CCQ} or 0V Chip Enabled	$I_{CC}2$	-70		25	mA	
			-85		20		
Standby Current	V_{IN} = V_{CCQ} or 0V CE# = V_{CCQ}	I_{SB}	128 M		180	µA	6
			64 M		120		
			32 M		110		

Notes:

1. *Wireless Temperature (-25ºC < TC < +85ºC); Industrial Temperature (-40ºC < TC < +85ºC).*
2. *Input signals may overshoot to $V_{CC}Q$ + 1.0V for periods less than 2ns during transitions.*
3. *Input signals may undershoot to V_{SS} - 1.0V for periods less than 2ns during transitions.*
4. *BCR[5:4] = 00b.*
5. *This parameter is specified with the outputs disabled to avoid external loading effects. The user must add the current required to drive output capacitance expected in the actual system.*
6. *ISB (MAX) values measured with PAR set to FULL ARRAY and TCR set to +85°C. To achieve low standby current, all inputs must be driven to either $V_{CC}Q$ or V_{SS}.*

Table 27. Temperature Compensated Refresh Specifications and Conditions

Description	Conditions	Symbol	Density	Max Case Temperature	Standard Power (No Desig.)	Units
Temperature Compensated Refresh Standby Current	V_{IN} = V_{CC}Q or 0V, CE# = V_{CC}Q	I_{TCR}	64 Mb	+85°C	120	µA
				+70°C	105	
				+45°C	85	
				+15°C	70	
			32 Mb	+85°C	110	
				+70°C	95	
				+45°C	80	
				+15°C	70	

Note: *I_{PAR} (MAX) values measured with TCR set to 85°C.*

Table 28. Partial Array Refresh Specifications and Conditions

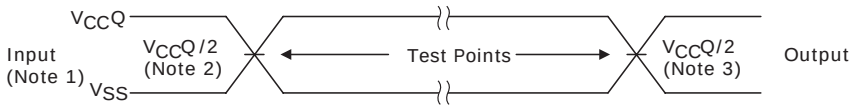
Description	Conditions	Symbol	Density	Array Partition	Standard Power (No Desig.)	Units
Partially Array Refresh Standby Current	V_{IN} = V_{CC}Q or 0V, CE# = V_{CC}Q	I_{PAR}	64 Mb	Full	120	µA
				1/2	115	
				1/4	110	
				1/8	105	
				0	70	
			32 Mb	Full	110	
				1/2	105	
				1/4	100	
				1/8	95	
				0	70	
			128 Mb	Full	180	
				0	50	

Note:I_{PAR} (MAX) values measured with TCR set to 85°C.

Table 29. Deep Power-Down Specifications

Description	Conditions	Symbol	Typ	Units
Deep Power-down	V_{IN} = V_{CC}Q or 0V; +25°C; V_{CC} = 1.8V	I_{ZZ}	10	µA

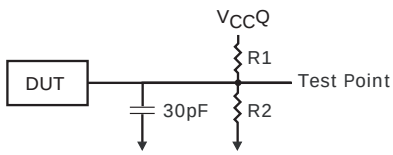
AC Characteristics



Notes:

1. *AC test inputs are driven at $V_{CC}Q$ for a logic 1 and V_{SS} for a logic 0. Input rise and fall times (10% to 90%) < 1.6ns.*
2. *Input timing begins at $V_{CC}Q/2$.*
3. *Output timing ends at $V_{CC}Q/2$.*

Figure 37. AC Input/Output Reference Waveform



Note: *All tests are performed with the outputs configured for full drive strength (BCR[5] = 0).*

Figure 38. Output Load Circuit

Table 30. Output Load Circuit

$V_{CC}Q$	RI/R2
1.8V	2.7K Ω

Table 31. Asynchronous READ Cycle Timing Requirements

Parameter	Symbol	85ns/66 MHz		70ns/80 MHz		Units	Notes
		Min	Max	Min	Max		
Address Access Time	t_{AA}		85		70	ns	
ADV# Access Time	t_{AADV}		85		70	ns	
Page Access Time	t_{APA}		25		20	ns	
Address Hold from ADV# HIGH	t_{AVH}	5		5		ns	
Address Setup to ADV# HIGH	t_{AVS}	10		10		ns	
LB#/UB# Access Time	t_{BA}		85		70	ns	
LB#/UB# Disable to DQ High-Z Output	t_{BHZ}		8		8	ns	4
LB#/UB# Enable to Low-Z Output	t_{BLZ}	10		10		ns	3
CE# HIGH between Subsequent Mixed-Mode Operations	t_{CBPH}	5		5		ns	
Maximum CE# Pulse Width	t_{CEM}		4		4	µs	2
CE# LOW to WAIT Valid	t_{CEW}	1	7.5	1	7.5	ns	
Chip Select Access Time	t_{CO}		85		70	ns	
CE# LOW to ADV# HIGH	t_{CVS}	10		10		ns	
Chip Disable to DQ and WAIT High-Z Output	t_{HZ}		8		8	ns	4
Chip Enable to Low-Z Output	t_{LZ}	10		10		ns	3
Output Enable to Valid Output	t_{OE}		20		20	ns	
Output Hold from Address Change	t_{OH}	5		5		ns	
Output Disable to DQ High-Z Output	t_{OHZ}		8		8	ns	4
Output Enable to Low-Z Output	t_{OLZ}	5		5		ns	3
Page Cycle Time	t_{PC}	25		20		ns	
READ Cycle Time	t_{RC}	85		70		ns	
ADV# Pulse Width LOW	t_{VP}	10		10		ns	
ADV# Pulse Width HIGH	t_{VPH}	10		10		ns	

Notes:

1. *All tests are performed with the outputs configured for full drive strength (BCR[5] = 0).*
2. *See "How Extended Timings Impact CellularRAM™ Operation" below.*
3. *High-Z to Low-Z timings are tested with the circuit shown in Figure 38. The Low-Z timings measure a*
4. *100mV transition away from the High-Z ($V_{CC}Q/2$) level toward either V_{OH} or V_{OL}.*
5. *Low-Z to High-Z timings are tested with the circuit shown in Figure 38. The High-Z timings measure a 100mV transition from either V_{OH} or V_{OL} toward $V_{CC}Q/2$.*

Table 32. Burst READ Cycle Timing Requirements

Parameter	Symbol	70ns/80 MHz		85ns/66 MHz		Units	Notes
		Min	Max	Min	Max		
Burst to READ Access Time (Variable Latency)	t_{ABA}		35		55	ns	
CLK to Output Delay	t_{ACLK}		9		11	ns	
Address Setup to ADV# HIGH	t_{AVS}	10		10		ns	
Burst OE# LOW to Output Delay	t_{BOE}		20		20	ns	
CE# HIGH between Subsequent Mixed-Mode Operations	t_{CBPH}	5		5		ns	
CE# LOW to WAIT Valid	t_{CEW}	1	7.5	1	7.5	ns	
CLK Period	t_{CLK}	12.5		15		ns	
CE# Setup Time to Active CLK Edge	t_{CSP}	4		5		ns	
Hold Time from Active CLK Edge	t_{HD}	2		2		ns	
Chip Disable to DQ and WAIT High-Z Output	t_{HZ}		8		8	ns	2
CLK Rise or Fall Time	t_{KHKL}		1.6		1.6	ns	
CLK to WAIT Valid	t_{KHTL}		9		11	ns	
CLK to DQ High-Z Output	t_{KHZ}	3	8	3	8	ns	
CLK to Low-Z Output	t_{KLZ}	2	5	2	5	ns	
Output HOLD from CLK	t_{KOH}	2		2		ns	
CLK HIGH or LOW Time	t_{KP}	3		3		ns	
Output Disable to DQ High-Z Output	t_{OHZ}		8		8	ns	2
Output Enable to Low-Z Output	t_{OLZ}	5		5		ns	3
Setup Time to Active CLK Edge	t_{SP}	3		3		ns	

Notes:

1. *All tests are performed with the outputs configured for full drive strength (BCR[5] = 0).*
2. *Low-Z to High-Z timings are tested with the circuit shown in Figure 38. The High-Z timings measure a 100mV transition from either V_{OH} or V_{OL} toward $V_{CC}Q/2$.*
3. *High-Z to Low-Z timings are tested with the circuit shown in Figure 38. The Low-Z timings measure a 100mV transition away from the High-Z ($V_{CC}Q/2$) level toward either V_{OH} or V_{OL}.*

Table 33. Asynchronous WRITE Cycle Timing Requirements

Parameter	Symbol	70ns/80 MHz		85ns/66 MHz		Units	Notes
		Min	Max	Min	Max		
Address and ADV# LOW Setup Time	t_{AS}	0		0		ns	
Address Hold from ADV# Going HIGH	t_{AVH}	5		5		ns	
Address Setup to ADV# Going HIGH	t_{AVS}	10		10	ns		
Address Valid to End of Write	t_{AW}	70		85		ns	
LB#/UB# Select to End of Write	t_{BW}	70		85		ns	
Maximum CE# Pulse Width	t_{CEM}		4		4	µs	1
CE# LOW to WAIT Valid	t_{CEW}	1	7.5	1	7.5	ns	
Async Address-to-Burst Transition Time	t_{CKA}	70		85		ns	
CE# Low to ADV# HIGH	t_{CVS}	10		10		ns	
Chip Enable to End of Write	t_{CW}	70		85		ns	
Data Hold from Write Time	t_{DH}	0		0		ns	
Data WRITE Setup Time	t_{DW}	23		23		ns	1
Chip Disable to WAIT High-Z Output	t_{HZ}		8		8	ns	
Chip Enable to Low-Z Output	t_{LZ}	10		10		ns	3
End WRITE to Low-Z Output	t_{OW}	5		5		ns	3
ADV# Pulse Width	t_{VP}	10		10		ns	
ADV# Pulse Width HIGH	t_{VPH}	10		10		ns	
ADV# Setup to End of WRITE	t_{VS}	70		85		ns	
WRITE Cycle Time	t_{WC}	70		85		ns	
WRITE to DQ High-Z Output	t_{WHZ}		8		8	ns	2
WRITE Pulse Width	t_{WP}	46		55		ns	1
WRITE Pulse Width HIGH	t_{WPH}	10		10		ns	
WRITE Recovery Time	t_{WR}	0		0		ns	

Notes:

1. *See "How Extended Timings Impact CellularRAM™ Operation" below.*
2. *Low-Z to High-Z timings are tested with the circuit shown in Figure 38. The High-Z timings measure a 100mV transition from either V_{OH} or V_{OL} toward $V_{CC}Q/2$.*
3. *High-Z to Low-Z timings are tested with the circuit shown in Figure 38. The Low-Z timings measure a 100mV transition away from the High-Z ($V_{CC}Q/2$) level toward either V_{OH} or V_{OL}.*

Table 34. Burst WRITE Cycle Timing Requirements

Parameter	Symbol	70ns/80 MHz		85ns/66 MHz		Units	Notes
		Min	Max	Min	Max		
CE# HIGH between Subsequent Mixed-Mode Operations	t_{CBPH}	5		5		ns	
CE# LOW to WAIT Valid	t_{CEW}	1	7.5	1	7.5	ns	

Table 34. Burst WRITE Cycle Timing Requirements (Continued)

Parameter	Symbol	70ns/80 MHz		85ns/66 MHz		Units	Notes
		Min	Max	Min	Max		
Clock Period	t_{CLK}	12.5		15		ns	
CE# Setup to CLK Active Edge	t_{CSP}	4		5		ns	
Hold Time from Active CLK Edge	t_{HD}	2		2		ns	
Chip Disable to WAIT High-Z Output	t_{HZ}		8		8	ns	
CLK Rise or Fall Time	t_{KHKL}		1.6		1.6	ns	
Clock to WAIT Valid	t_{KHTL}		9		11	ns	
CLK HIGH or LOW Time	t_{KP}	3		3		ns	
Setup Time to Activate CLK Edge	t_{SP}	3		3		ns	

Timing Diagrams

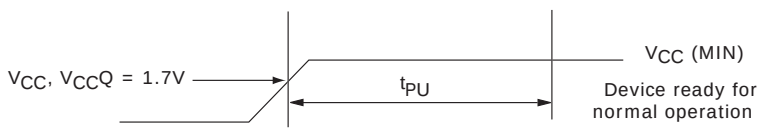


Figure 39. Initialization Period

Table 35. Initialization Timing Parameters

Parameter	Symbol	70ns/80 MHz		85ns/66 MHz		Units	Notes
		Min	Max	Min	Max		
Initialization Period (required before normal operations)	t_{PU}		150		150	µs	

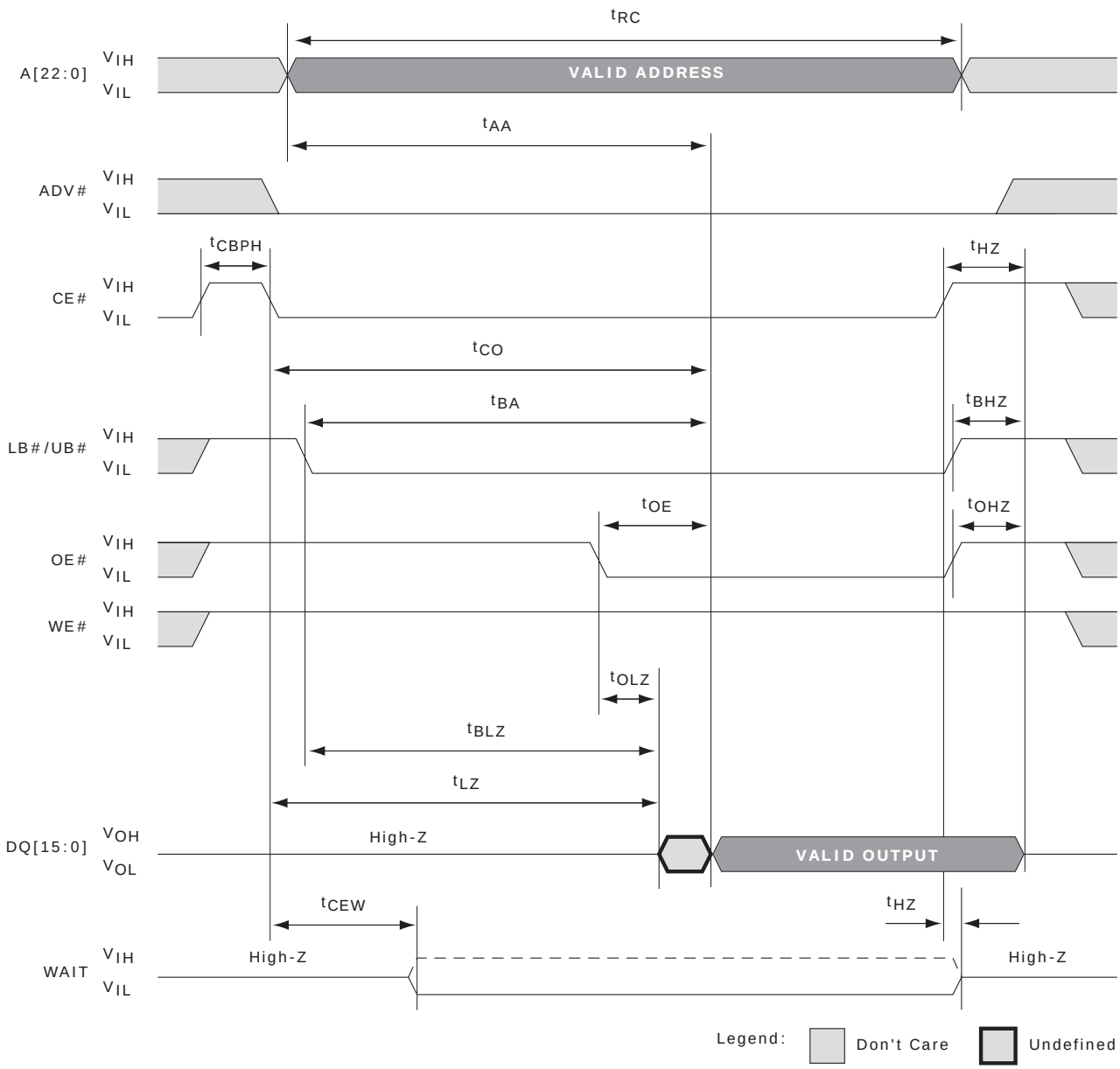


Figure 40. Asynchronous READ

Table 36. Asynchronous READ Timing Parameters

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AA}		70		85	ns
t_{BA}		70		85	ns
t_{BHZ}		8		8	ns
t_{BLZ}	10		10		ns
t_{CBPH}	5		5		ns

Table 36. Asynchronous READ Timing Parameters (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CEW}	1	7.5	1	7.5	ns
t_{CO}		70			ns
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{OE}		20		20	ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns
t_{RC}	70		85		ns

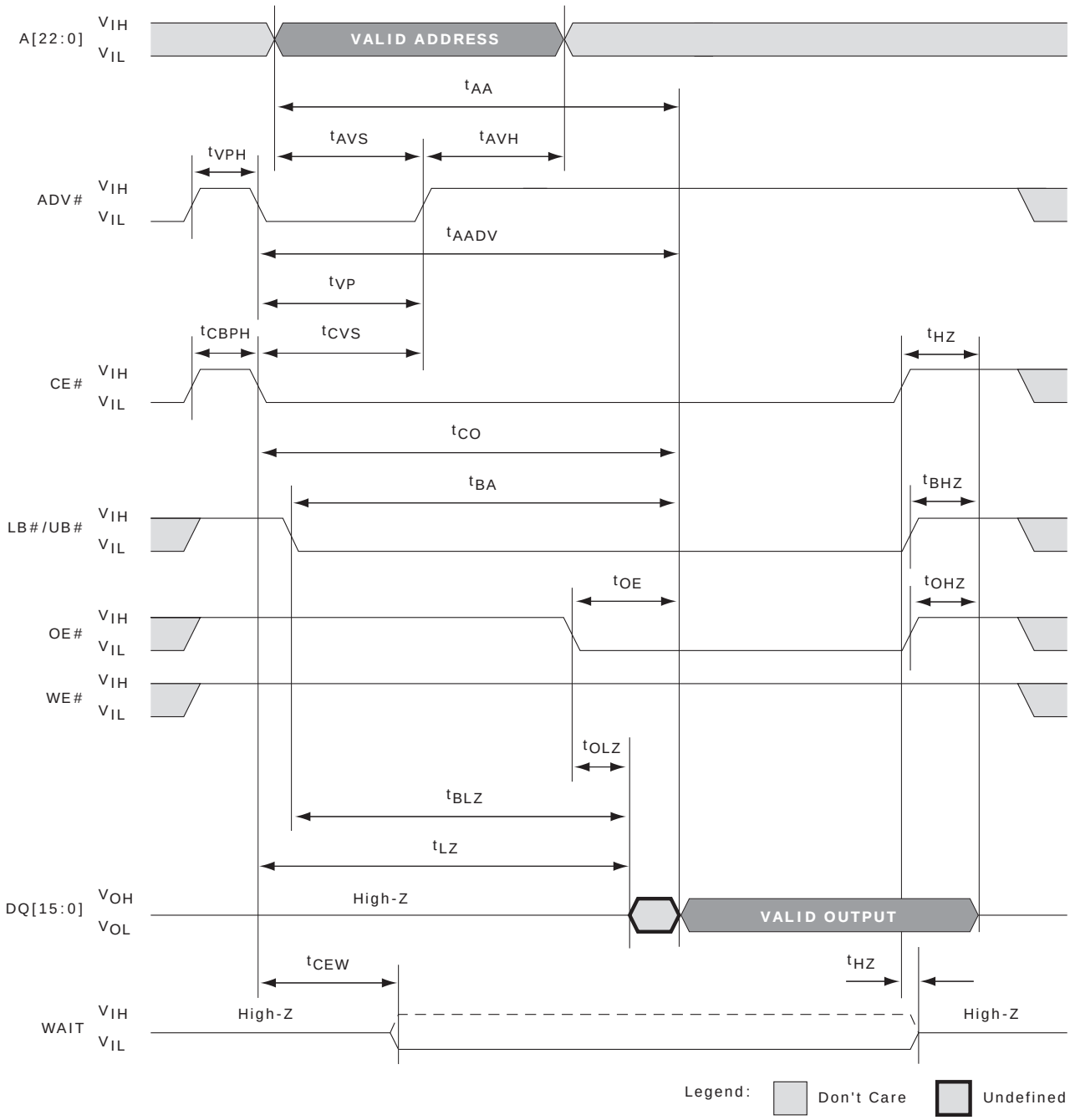


Figure 41. Asynchronous READ Using ADV#

Table 37. Asynchronous READ Timing Parameters Using ADV#

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AA}		70		85	ns
t_{AADV}		70		85	ns

Table 37. Asynchronous READ Timing Parameters Using ADV# (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CVS}	10		10		ns
t_{AVH}	5		5		ns
t_{AVS}	10		10		ns
t_{BA}		70		85	ns
t_{BHZ}		8		8	ns
t_{BLZ}	10		10		ns
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CO}		70		85	ns
t_{CVS}	10		10		ns
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{OE}		20		20	ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns
t_{VP}	10		10		ns
t_{VPH}	10		10		ns

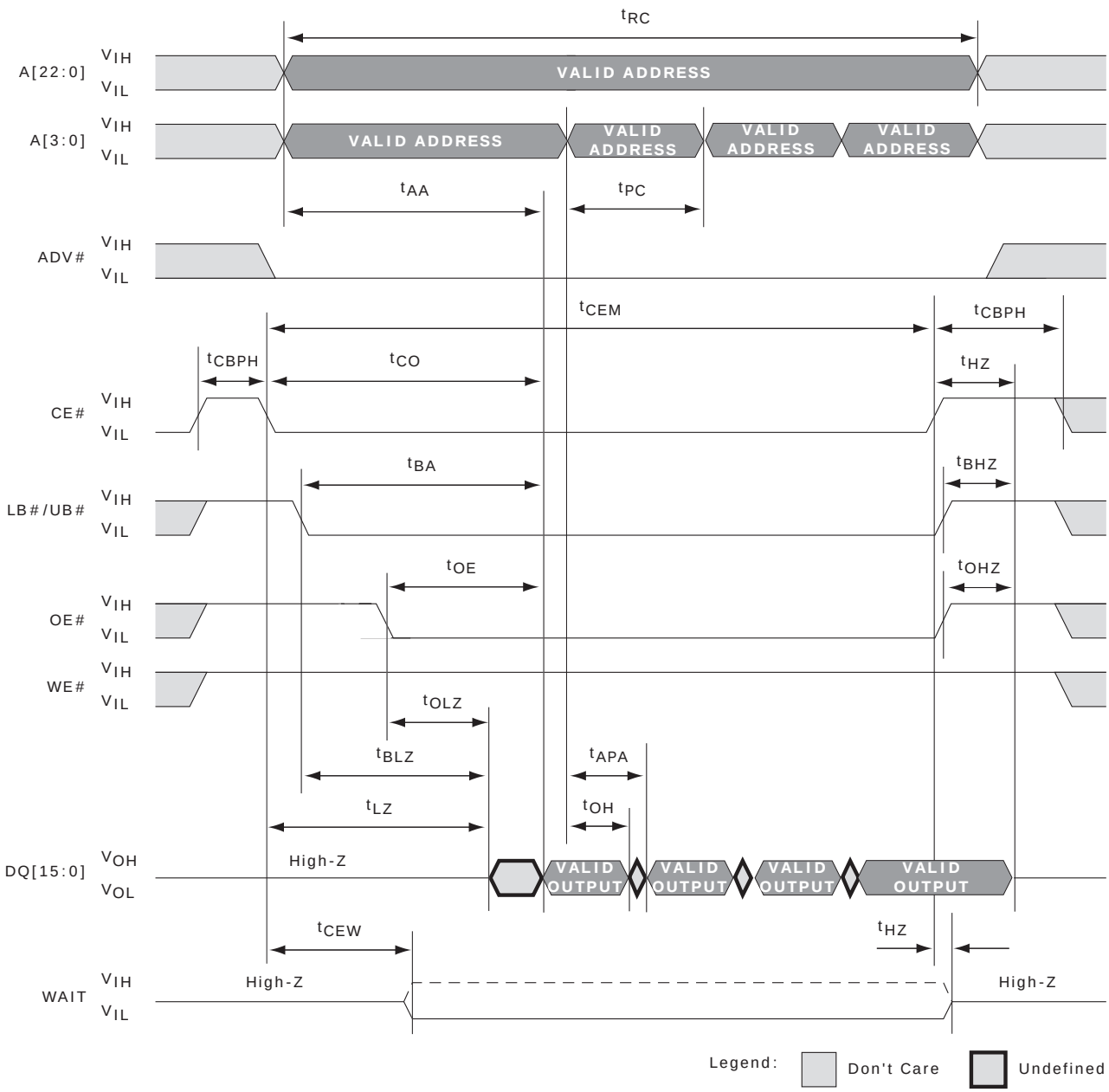


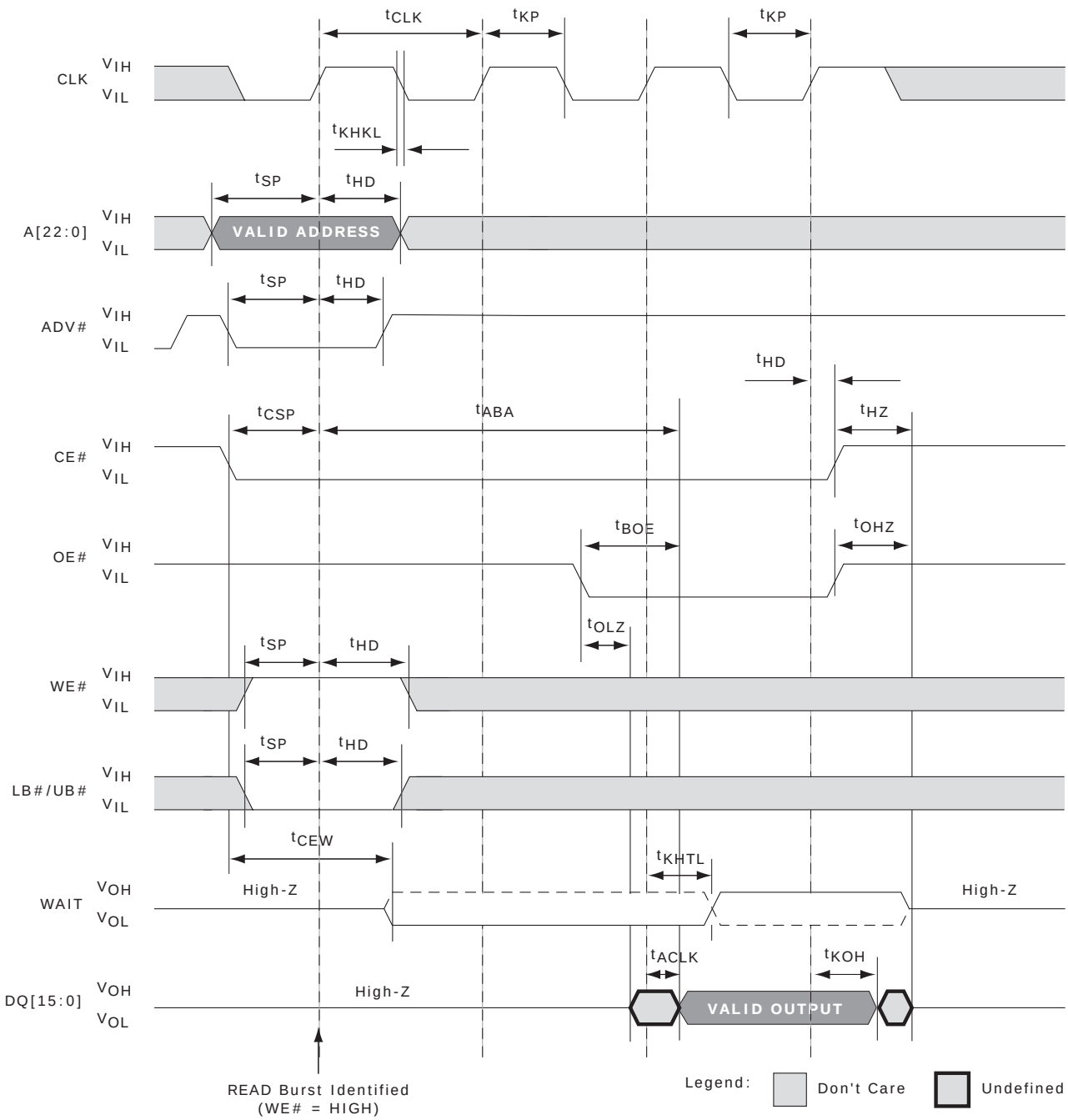
Figure 42. Page Mode READ

Table 38. Asynchronous READ Timing Parameters—Page Mode Operation

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AA}		70		85	ns
t_{APA}		20		25	ns
t_{BA}		70		85	ns
t_{BHZ}		8		8	ns

Table 38. Asynchronous READ Timing Parameters—Page Mode Operation (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{BLZ}	10		10		ns
t_{CBPH}	5		5		ns
t_{CEM}		4		4	µs
t_{CEW}	1	7.5	1	7.5	ns
t_{CO}		70		85	ns
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{OE}		20		20	ns
t_{OH}	5		5		ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns
t_{PC}	20		25		ns
t_{RC}	70		85		ns



Note: *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*

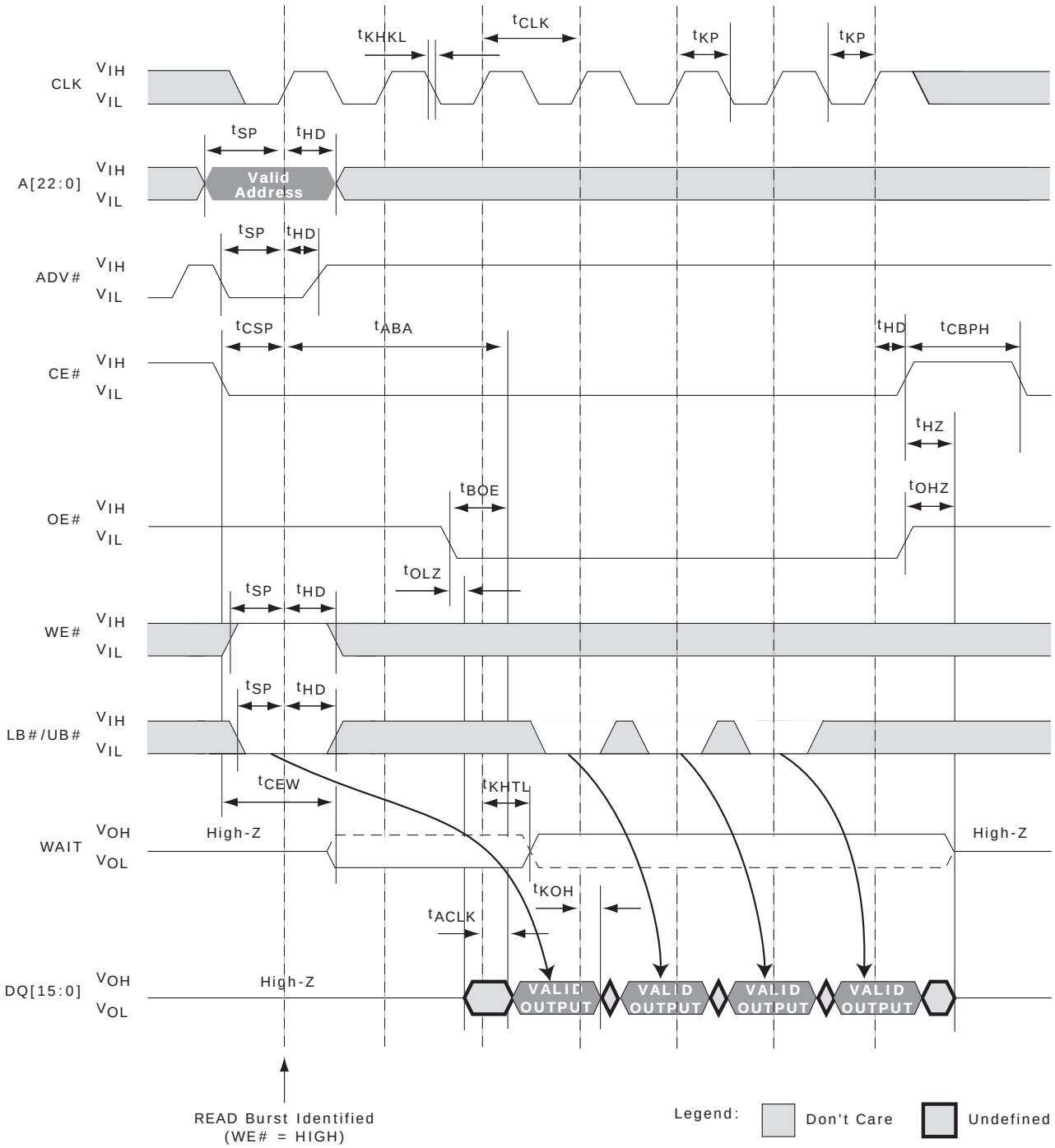
Figure 43. Single-Access Burst READ Operation—Variable Latency

Table 39. Burst READ Timing Parameters—Single Access, Variable Latency

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ABA}		35		55	ns
t_{ACLK}		9		11	ns

Table 39. Burst READ Timing Parameters—Single Access, Variable Latency (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{BOE}		20		20	ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{HZ}		8		8	ns
t_{KHKL}		1.6		1.6	ns
t_{KHTL}		9		11	ns
t_{KOH}	2		2		ns
t_{KP}	3		3		ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns
t_{SP}	3		3		ns

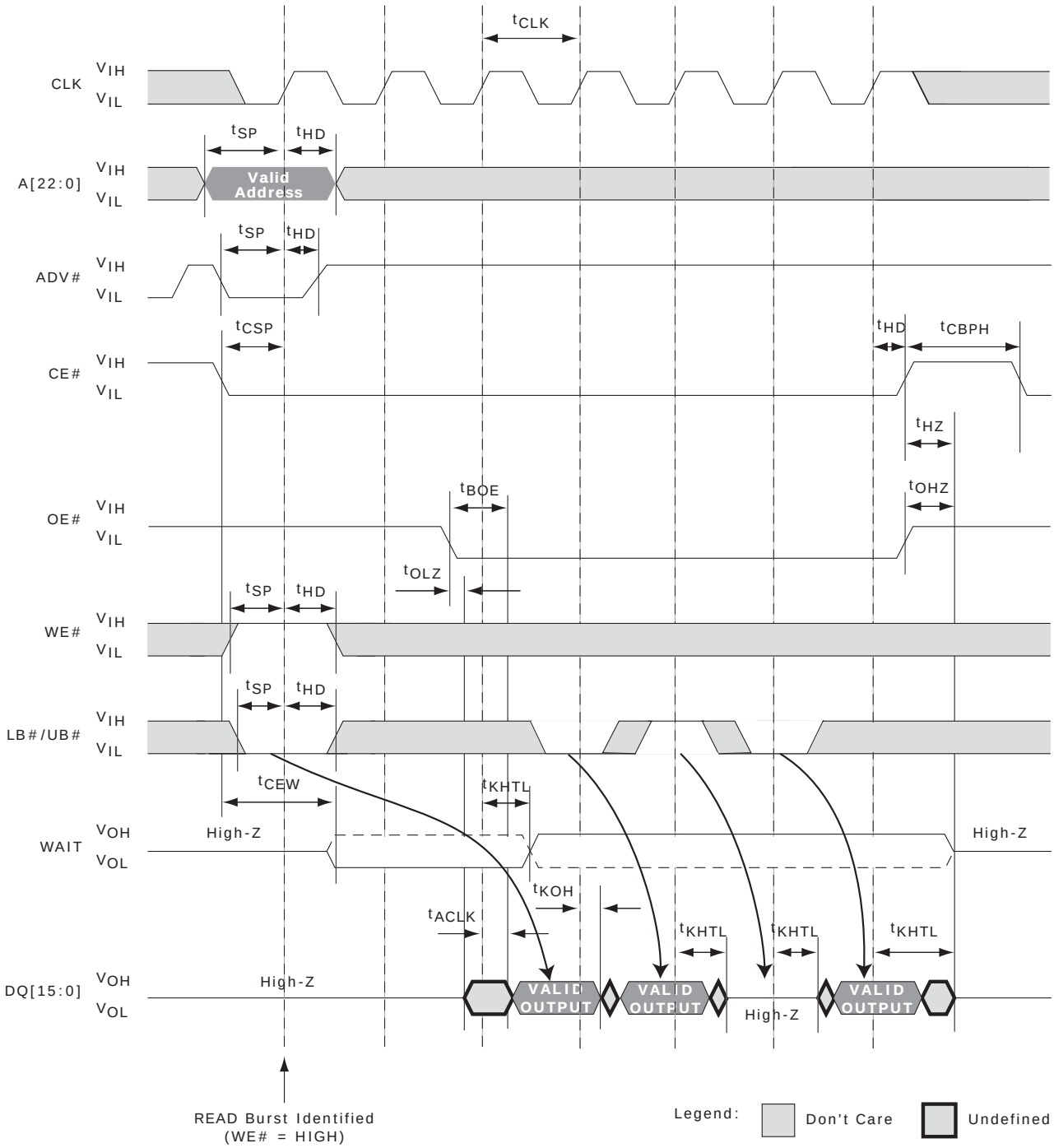


Note: *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*

Figure 44. Four-word Burst READ Operation—Variable Latency

Table 40. Burst READ Timing Parameters—4-word Burst

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ABA}		35		55	ns
t_{ACLK}		9		11	ns
t_{BOE}		20		20	ns
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{HZ}		8		8	ns
t_{KHKL}		1.6		1.6	ns
t_{KHTL}		9		11	ns
t_{KOH}	2		2		ns
t_{KP}	3		3		ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns
t_{SP}	3		3		ns

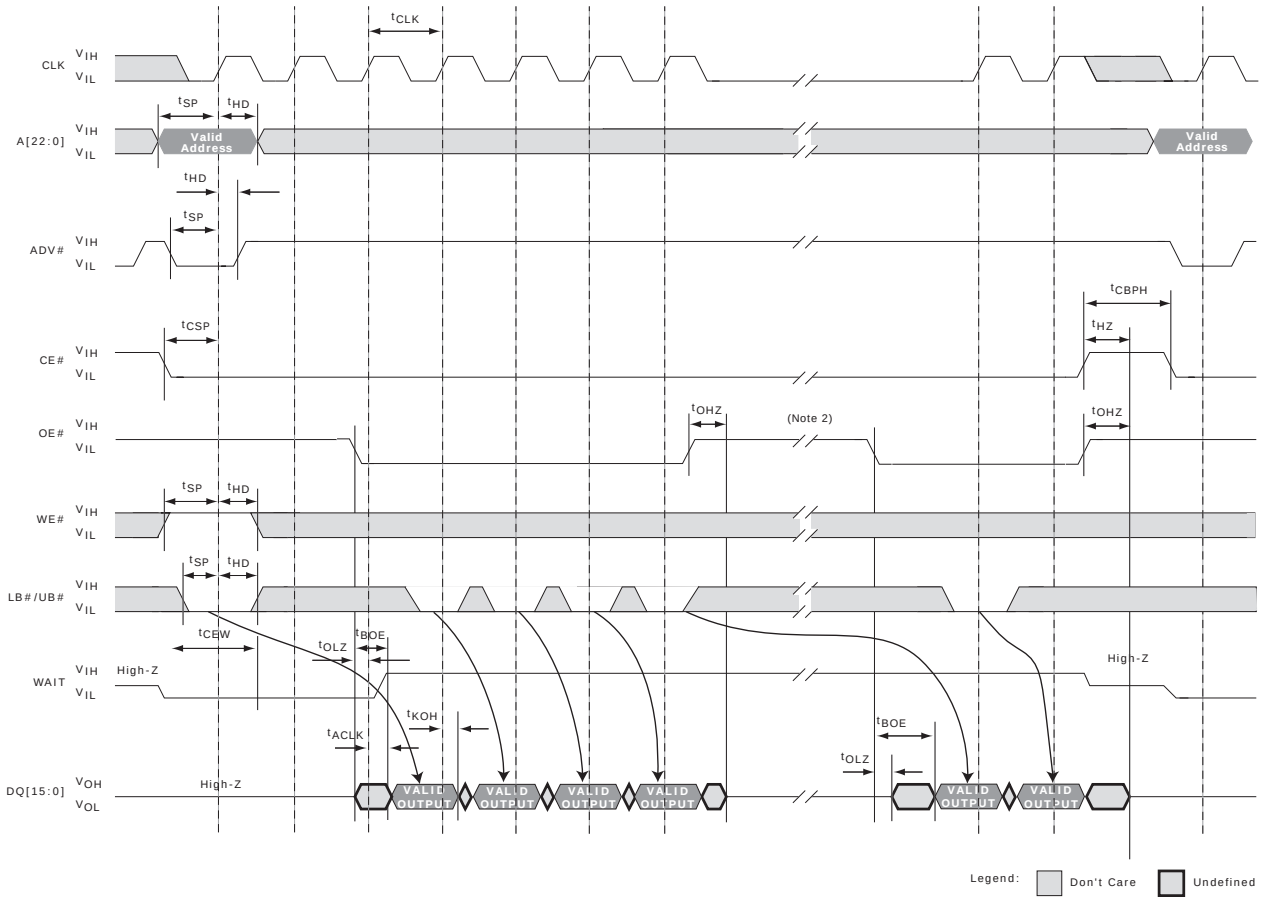


Note: *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*

Figure 45. Four-word Burst READ Operation (with LB#/UB#)

Table 41. Burst READ Timing Parameters—4-word Burst with LB#/UB#

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}		9		11	ns
t_{BOE}		20		20	ns
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{HZ}		8		8	ns
t_{KHTL}		9		11	ns
t_{KHZ}	3	8	3	8	ns
t_{KLZ}	2	5	2	5	ns
t_{KOH}	2		2		ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns
t_{SP}	3		3		ns



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *OE# can stay LOW during burst suspend. If OE# is LOW, DQ[15:0] will continue to output valid data.*

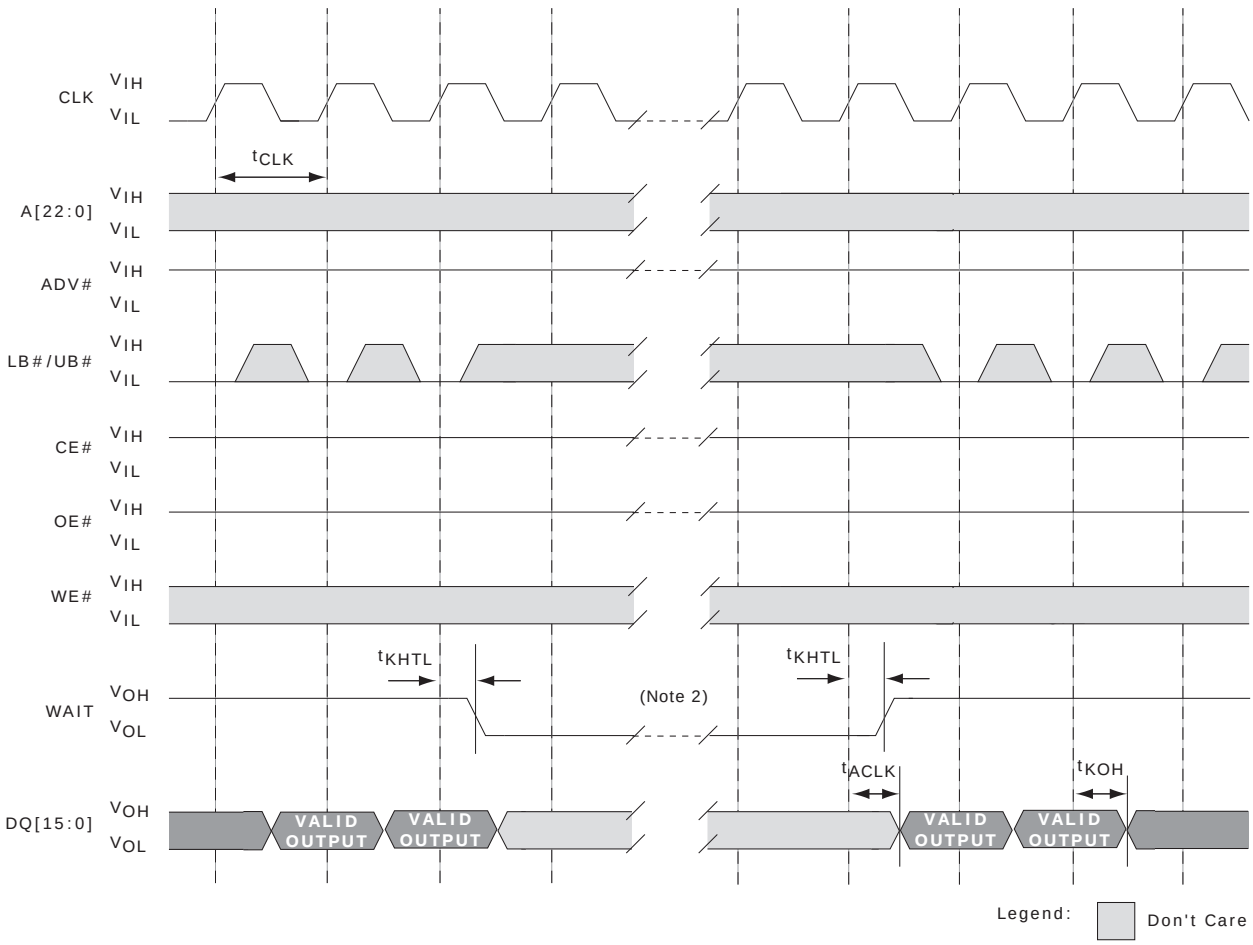
Figure 46. READ Burst Suspend

Table 42. Burst READ Timing Parameters—Burst Suspend

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}		9		11	ns
t_{BOE}		20		20	ns
t_{CBPH}	5		5		ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{HZ}		8		8	ns
t_{KOH}	2		2		ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns

Table 42. Burst READ Timing Parameters—Burst Suspend (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{SP}	3		3		ns



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *WAIT will assert LC + 1 or 2LC + 1 cycles for variable latency (depending upon refresh status).*

Figure 47. Continuous Burst READ Showing an Output Delay with BCR[8] = 0 for End-of-Row Condition

Table 43. Burst READ Timing Parameters—BCR[8] = 0

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}		9		11	ns
t_{CLK}	12.5		15		ns
t_{KHTL}		9		11	ns
t_{KOH}	2		2		ns

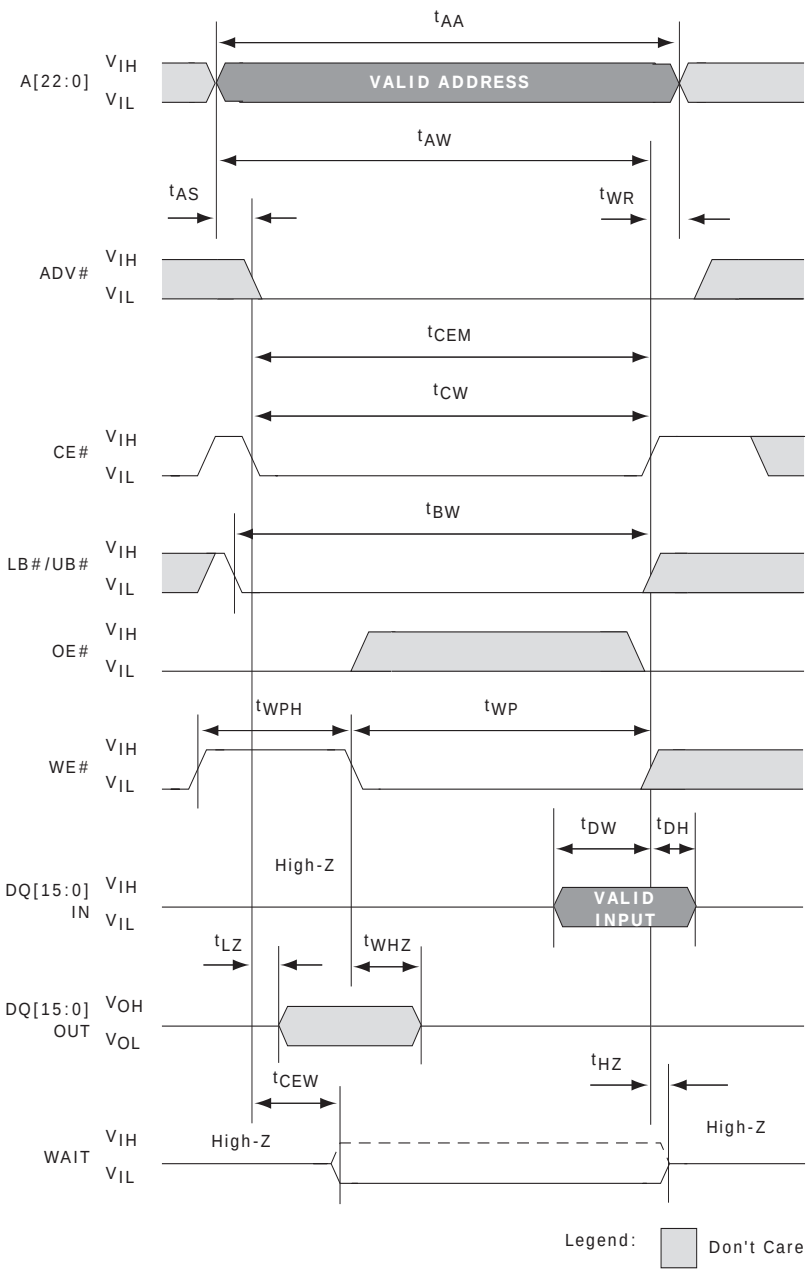


Figure 48. CE#-Controlled Asynchronous WRITE

Table 44. Asynchronous WRITE Timing Parameters—CE#-Controlled

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0		0		ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CEM}		4		4	µs

Table 44. Asynchronous WRITE Timing Parameters—CE#-Controlled (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CEW}	1	7.5	1	7.5	ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{WC}	70		85		ns
t_{WHZ}		8		8	ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns

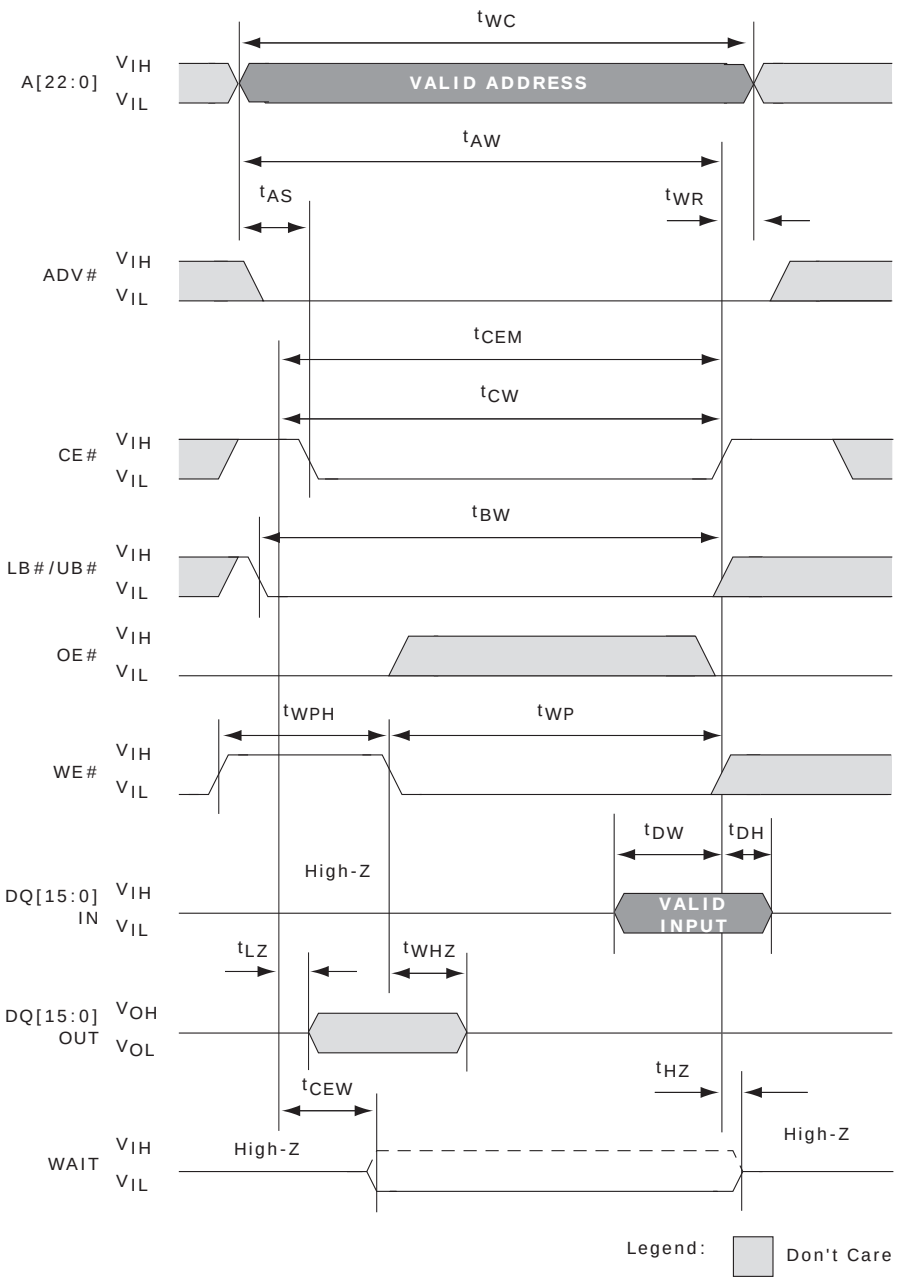


Figure 49. LB#/UB#-Controlled Asynchronous WRITE

Table 45. Asynchronous WRITE Timing Parameters—LB#/UB#-Controlled

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0		0		ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns

Table 45. Asynchronous WRITE Timing Parameters—LB#/UB#-Controlled (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CEM}		4		4	µs
t_{CEW}	1	7.5	1	7.5	ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{WC}	70		85		ns
t_{WHZ}		8		8	ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns

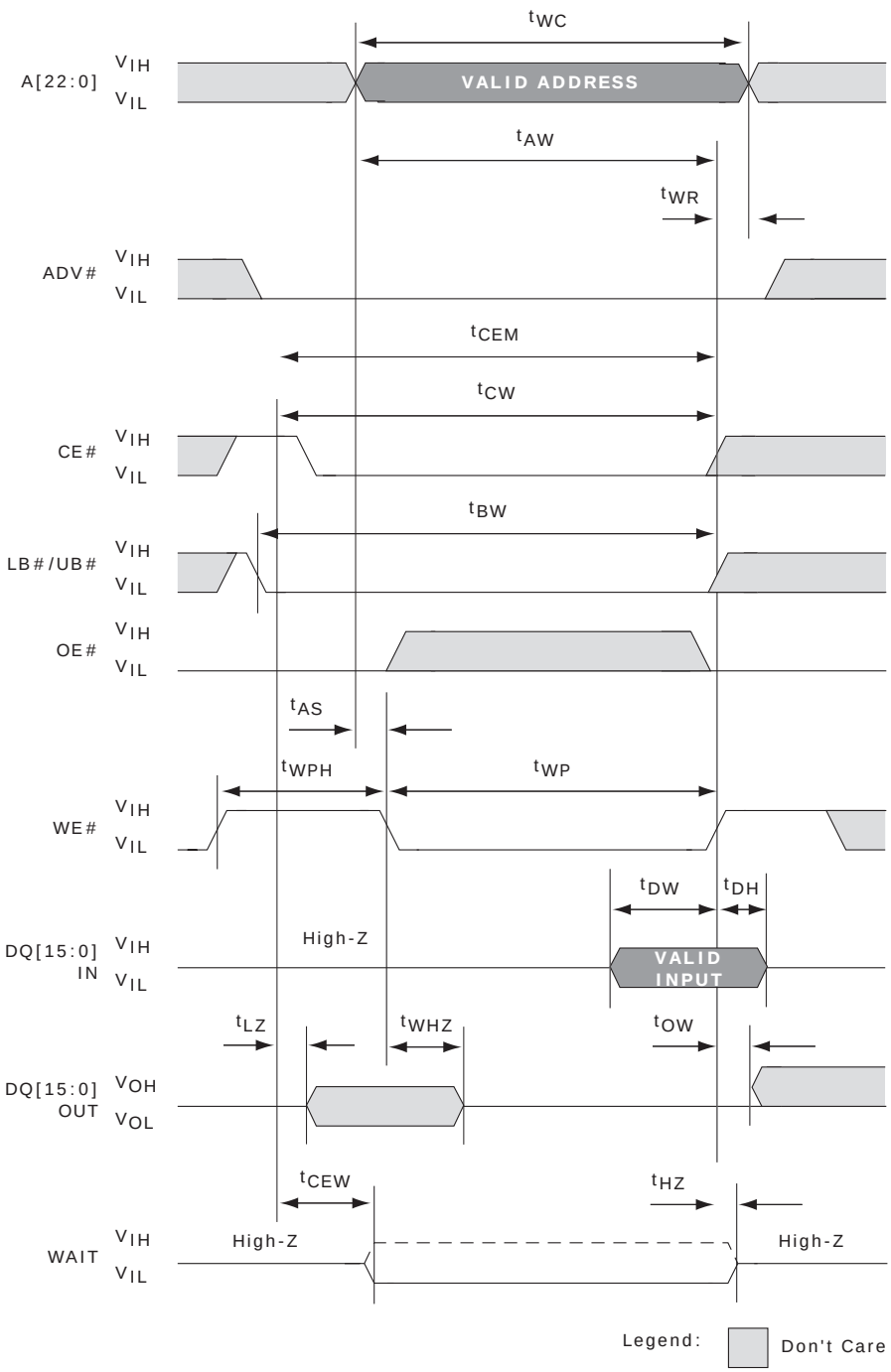


Figure 50. WE#-Controlled Asynchronous WRITE

Table 46. Asynchronous WRITE Timing Parameters—WE#-Controlled

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0		0		ns

Table 46. Asynchronous WRITE Timing Parameters—WE#-Controlled (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CEM}		4		4	µs
t_{CEW}	1	7.5	1	7.5	ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{OW}	5		5		ns
t_{WC}	70		85		ns
t_{WHZ}		8		8	ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns

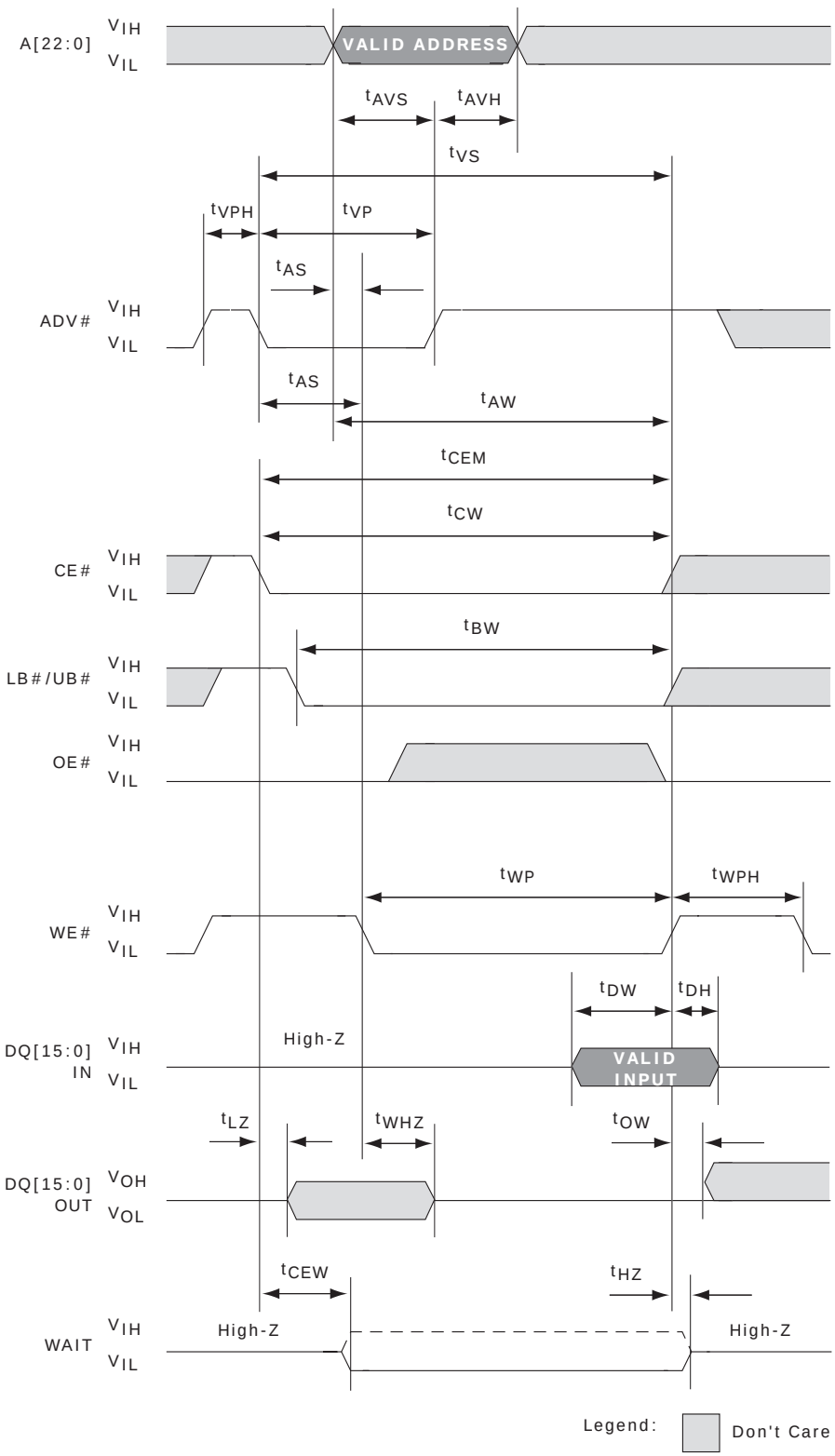
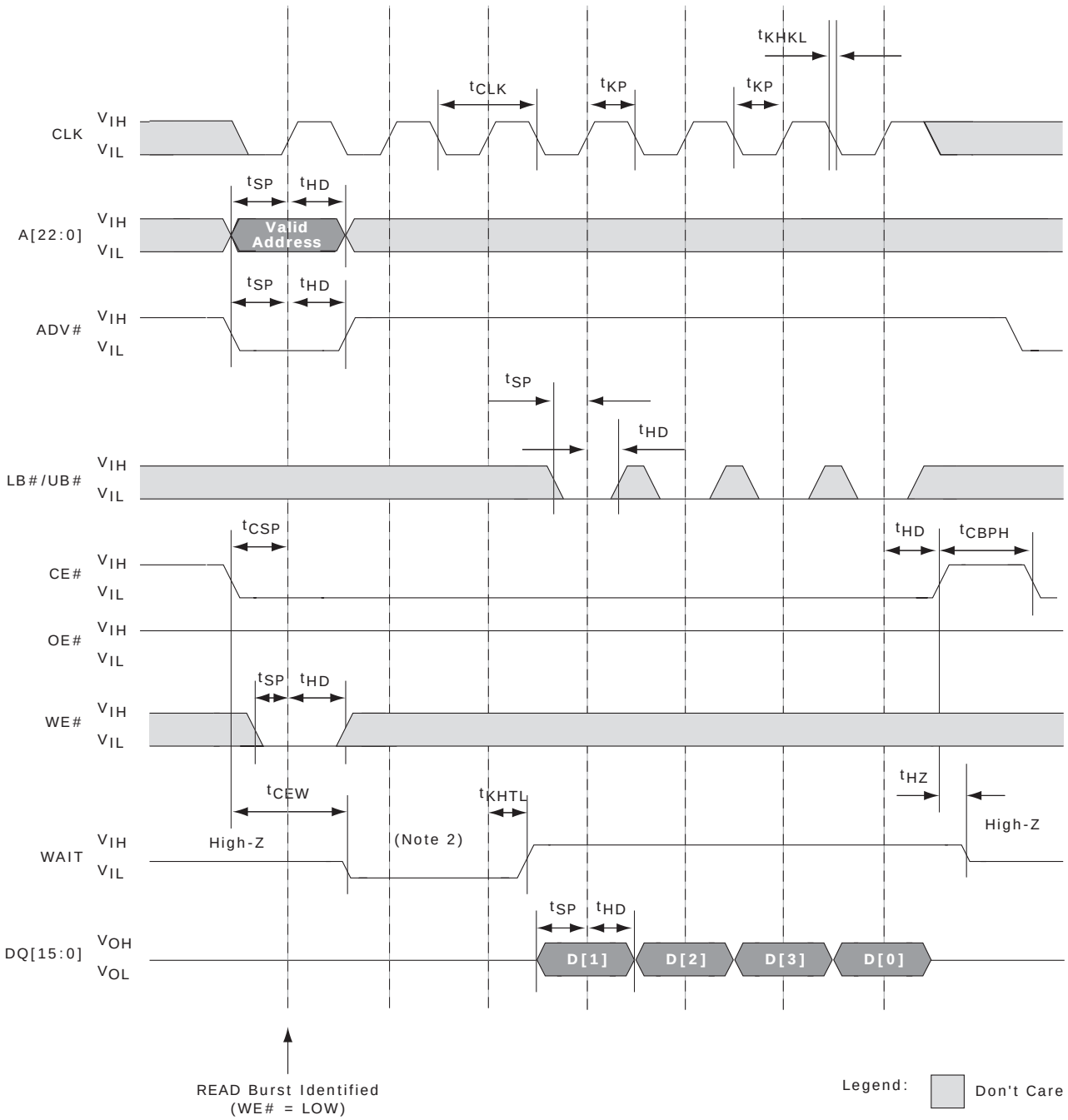


Figure 51. Asynchronous WRITE Using ADV#

Table 47. Asynchronous WRITE Timing Parameters Using ADV#

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0		0		ns
t_{AVH}	5		5		ns
t_{AVS}	10		10		ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CEM}		4		4	µs
t_{CEW}	1	7.5	1	7.5	ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{OW}	5		5		ns
t_{AS}	0		0		ns
t_{VP}	10		10		ns
t_{VPH}	10		10		ns
t_{VS}	70		85		ns
t_{WHZ}		8		8	ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns



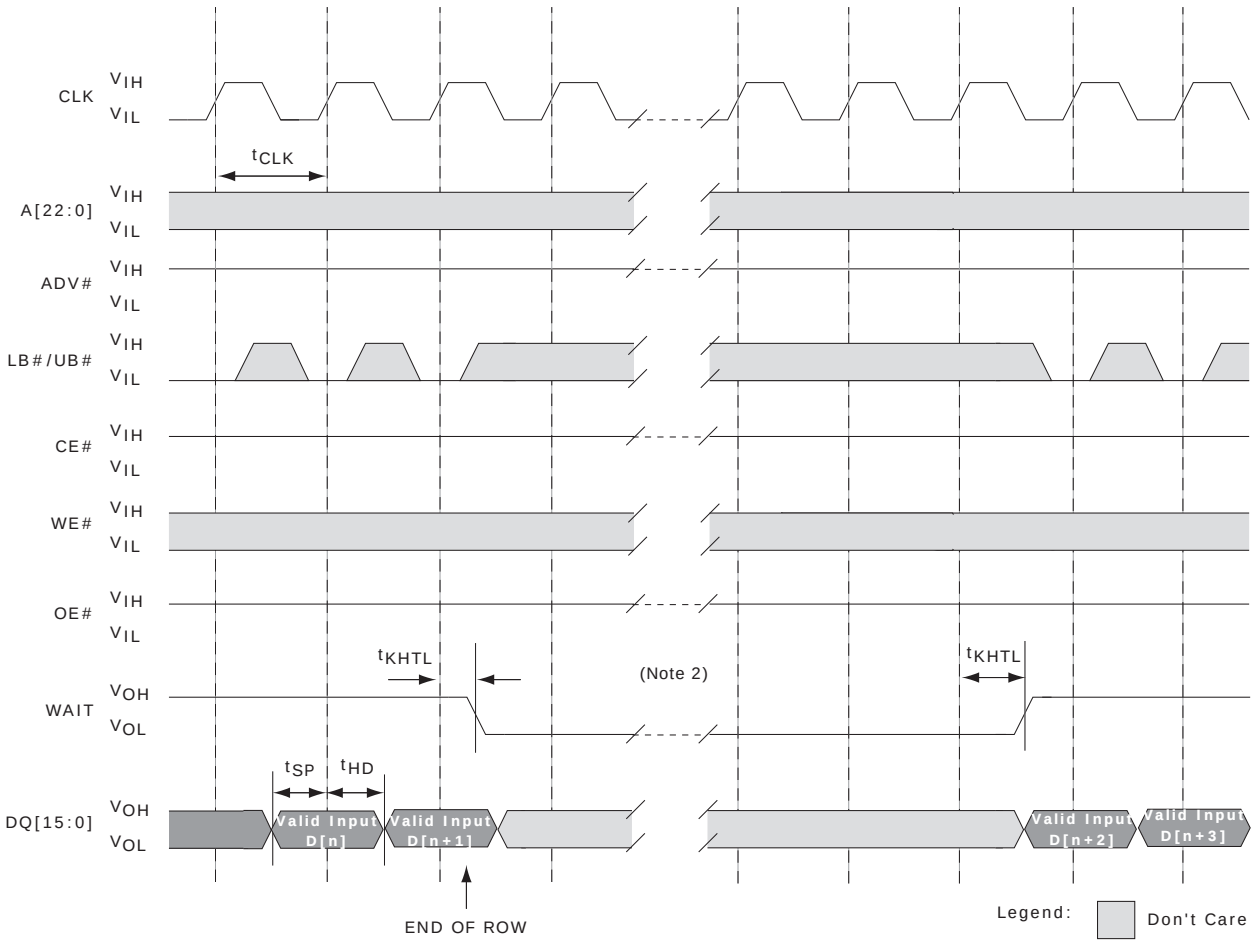
Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay; burst length four; burst wrap enabled.*

Figure 52. Burst WRITE Operation

Table 48. Burst WRITE Timing Parameters

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{HZ}		8		8	ns
t_{KHKL}		1.6		1.6	ns
t_{KHTL}		9		11	ns
t_{KP}	3		3		ns
t_{SP}	3		3		ns



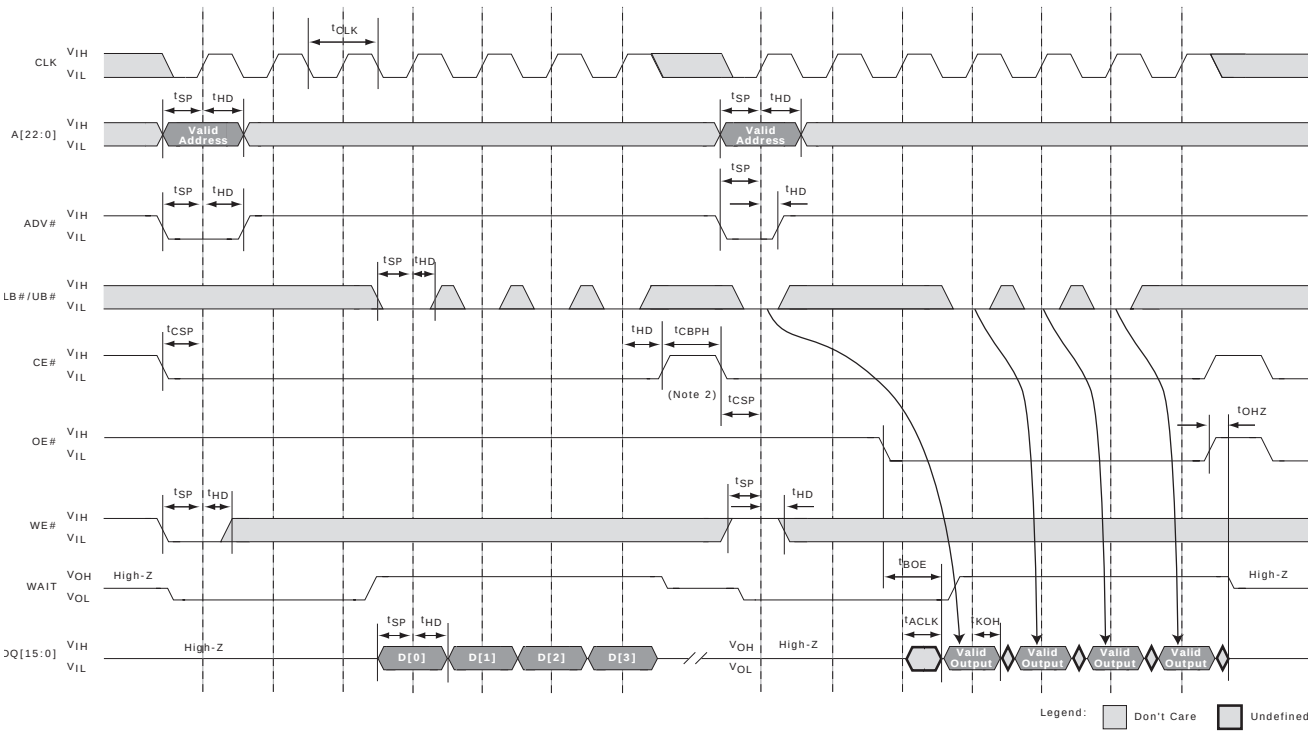
Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *WAIT will assert LC + 1 or 2LC + 1 cycles for variable latency (depending upon refresh status).*

Figure 53. Continuous Burst WRITE Showing an Output Delay with BCR[8] = 0 for End-of-Row Condition

Table 49. Burst WRITE Timing Parameters—BCR[8] = 0

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CLK}	12.5		15		ns
t_{HD}	2		2		ns
t_{KHTL}		8		11	ns
t_{SP}		3		3	ns



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *To allow self-refresh operations to occur between transactions, CE# must remain HIGH for at least 5ns (t_{CBPH}) to schedule the appropriate internal refresh operation. CE# can stay LOW between burst READ and burst WRITE operations. See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time (t_{CEM}).*

Figure 54. Burst WRITE Followed by Burst READ

Table 50. WRITE Timing Parameters—Burst WRITE Followed by Burst READ

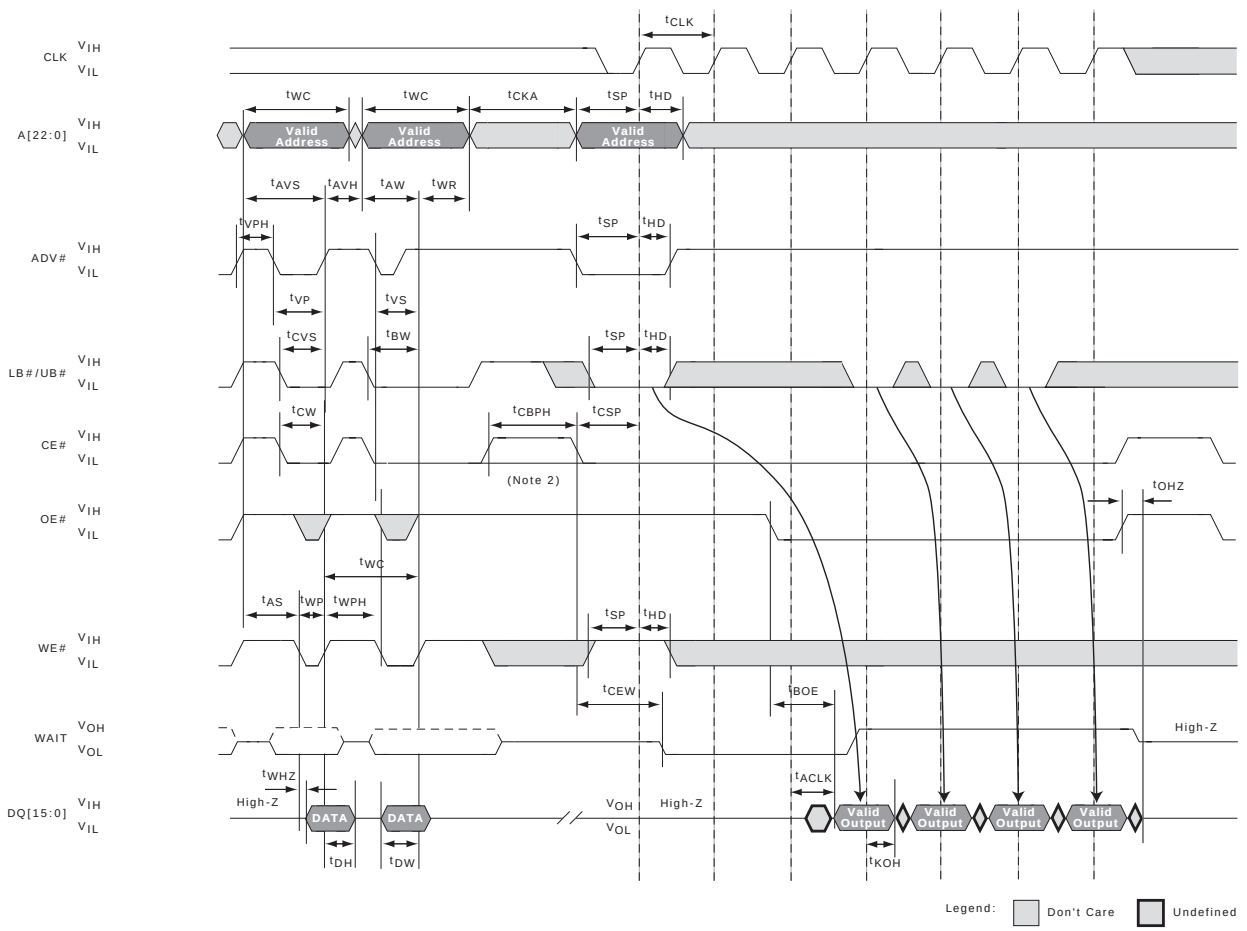
Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CBPH}	5		5		ns
t_{CLK}	12.5	20	15	20	ns
t_{CSP}	4	20	5	20	ns
t_{HD}	2		2		ns
t_{SP}	3		3		ns

Table 51. READ Timing Parameters—Burst WRITE Followed by Burst READ

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}	9		11	ns	
t_{BOE}		20		20	ns
t_{CLK}	12.5		15		ns

Table 51. READ Timing Parameters—Burst WRITE Followed by Burst READ (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{KOH}	2		2		ns
t_{OHZ}		8		8	ns
t_{SP}	3		3		ns



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *When transitioning between asynchronous and variable-latency burst operations, CE# must go HIGH. If CE# goes HIGH, it must remain HIGH for at least 5ns (t_{CBPH}) to schedule the appropriate internal refresh operation. See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time (t_{CEM}).*

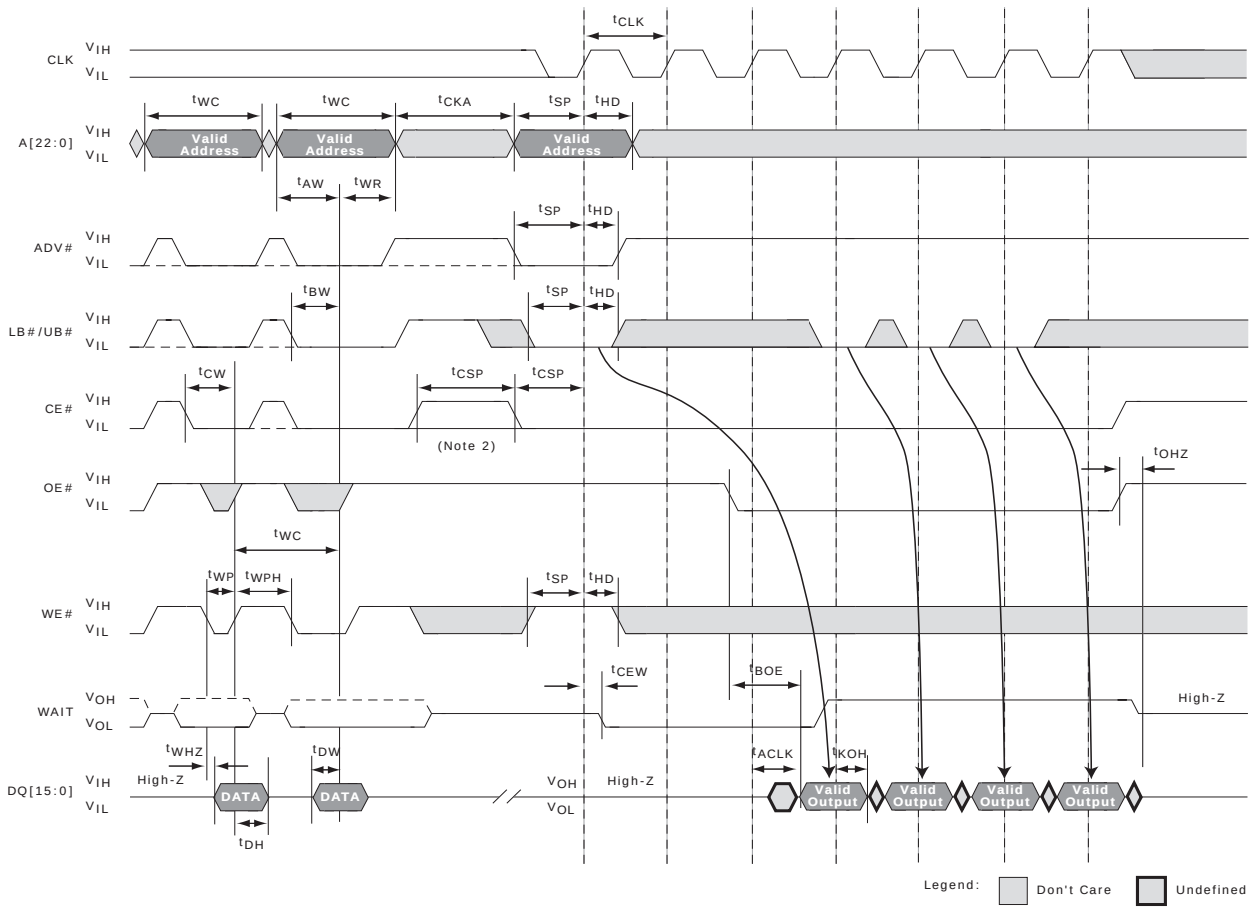
Figure 55. Asynchronous WRITE Followed by Burst READ

Table 52. WRITE Timing Parameters—Asynchronous WRITE Followed by Burst READ

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AVH}	5		5		ns
t_{AS}	0		0		ns
t_{AVS}	10		10		ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CKA}	70		85		ns
t_{CVS}	10		10		ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	20		23		ns
t_{VP}	10		10		ns
t_{VPH}	10		10		ns
t_{VS}	70		85		ns
t_{WC}	70		85		ns
t_{WHZ}		8		8	ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns

Table 53. READ Timing Parameters—Asynchronous WRITE Followed by Burst READ

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}		9		11	ns
t_{BOE}		20		20	ns
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{KOH}	2		2		ns
t_{OHZ}		8		8	ns
t_{SP}	3		3		ns



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *When transitioning between asynchronous and variable-latency burst operations, CE# must go HIGH. If CE# goes HIGH, it must remain HIGH for at least 5ns (t_{CBPH}) to schedule the appropriate internal refresh operation. See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time (t_{CEM}).*

Figure 56. Asynchronous WRITE (ADV# LOW) Followed By Burst READ

Table 54. Asynchronous WRITE Timing Parameters—ADV# LOW

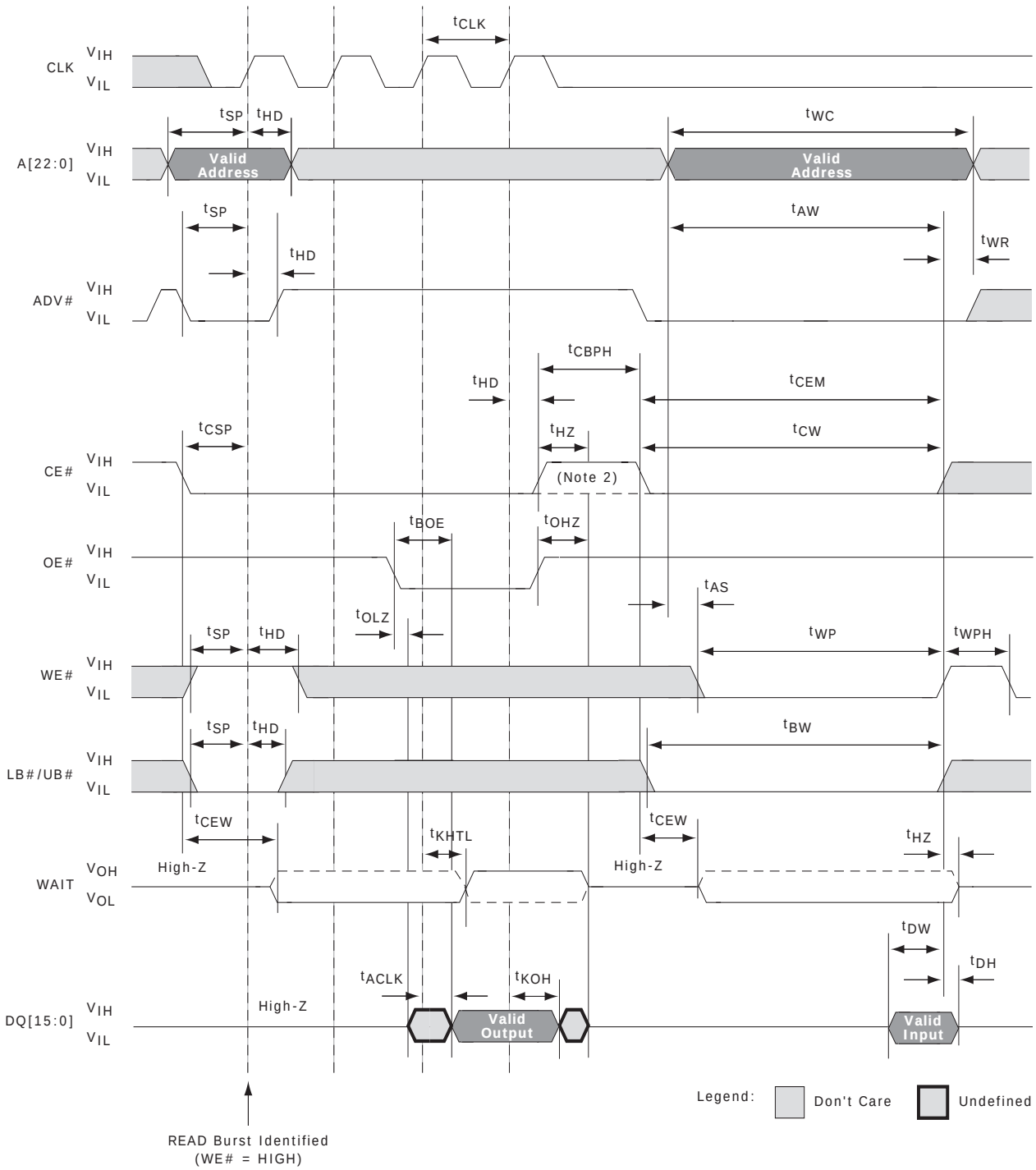
Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CKA}	70		85		ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{WC}	70		85		ns
t_{WHZ}		8		8	ns

Table 54. Asynchronous WRITE Timing Parameters—ADV# LOW (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns

Table 55. Burst READ Timing Parameters

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}		9		11	ns
t_{BOE}		20		20	ns
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{KOH}	2		2		ns
t_{OHZ}		8		8	ns
t_{SP}	3		3		ns



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *When transitioning between asynchronous and variable-latency burst operations, CE# must go HIGH. If CE# goes HIGH, it must remain HIGH for at least 5ns (t_{CBPH}) to schedule the appropriate internal refresh operation. See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time (t_{CEM}).*

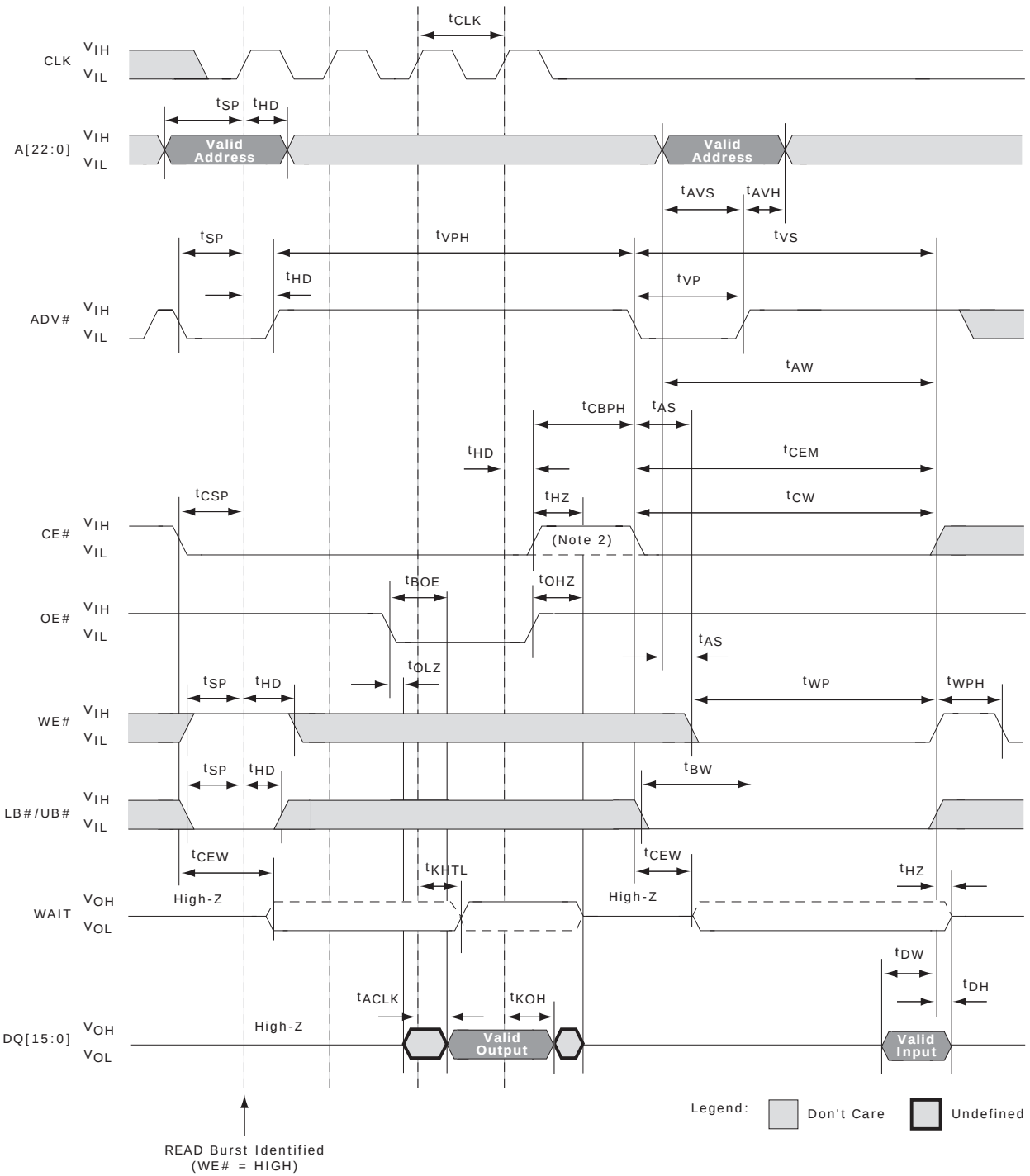
Figure 57. Burst READ Followed by Asynchronous WRITE (WE#-Controlled)

Table 56. Burst READ Timing Parameters

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}		9		11	ns
t_{BOE}		20		20	ns
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{HZ}		8		8	ns
t_{KHKL}		1.6		1.6	ns
t_{KHTL}		9		11	ns
t_{KOH}	2		2		ns
t_{KP}	3		3		ns
t_{OHZ}		8		8	ns

Table 57. Asynchronous WRITE Timing Parameters—WE# Controlled

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0			0	ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CEM}		4		4	µs
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{HZ}		8		8	ns
t_{WC}	70		85		ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns



Notes:

1. *Non-default BCR settings: Latency code two (three clocks); WAIT active LOW; WAIT asserted during delay.*
2. *When transitioning between asynchronous and variable-latency burst operations, CE# must go HIGH. If CE# goes HIGH, it must remain HIGH for at least 5ns (t_{CBPH}) to schedule the appropriate internal refresh operation. See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time (t_{CEM}).*

Figure 58. Burst READ Followed by Asynchronous WRITE Using ADV#

Table 58. Burst READ Timing Parameters

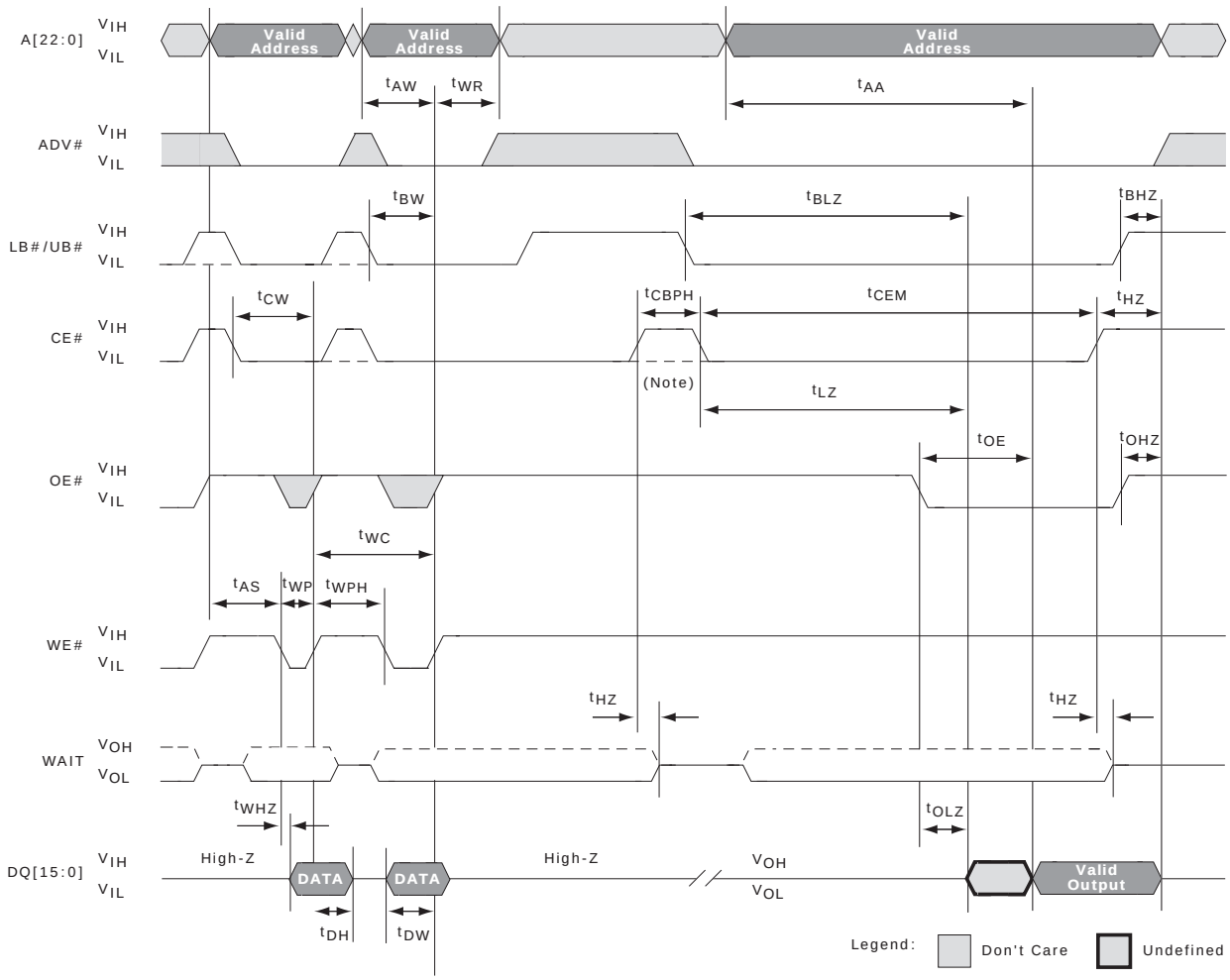
Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{ACLK}		9		11	ns
t_{BOE}		20		20	ns
t_{CBPH}	5		5		ns
t_{CEW}	1	7.5	1	7.5	ns
t_{CLK}	12.5		15		ns
t_{CSP}	4		5		ns
t_{HD}	2		2		ns
t_{HZ}		8		8	ns
t_{KHKL}		1.6		1.6	ns
t_{KHTL}		9		11	ns
t_{KOH}	2		2		ns
t_{KP}	3		3		ns
t_{OHZ}		8		8	ns

Table 59. Asynchronous WRITE Timing Parameters Using ADV#

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0		0		ns
t_{AVH}	5		5		ns
t_{AVS}	10		10		ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CEM}		4		4	µs
t_{CEW}	1	7.5	1	7.5	ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{HZ}		8		8	ns
t_{VP}	10		10		ns
t_{VPH}	10		10		ns
t_{VS}	70		85		ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns

Table 59. Asynchronous WRITE Timing Parameters Using ADV# (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{WR}	0		0		ns



Note: *CE# can stay LOW when transitioning between asynchronous operations. If CE# goes HIGH, it must remain HIGH for at least 5ns (t_{CBPH}) to schedule the appropriate internal refresh operation. See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time (t_{CEM}).*

Figure 59. Asynchronous WRITE Followed by Asynchronous READ—ADV# LOW

Table 60. WRITE Timing Parameters—ADV# LOW

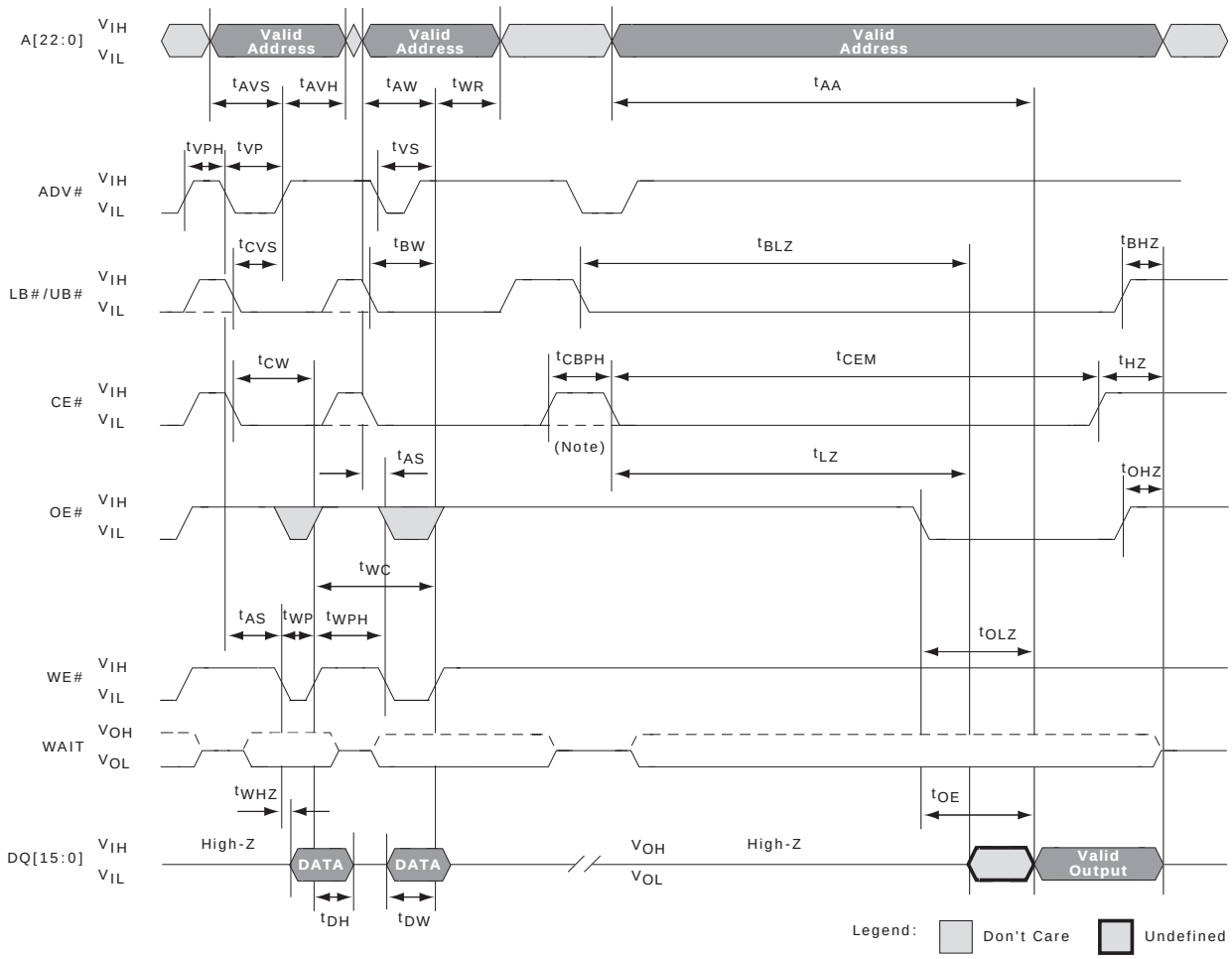
Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0		0		ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CW}	70		85		ns

Table 60. WRITE Timing Parameters—ADV# LOW (Continued)

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{DH}	0		0		ns
t_{DW}	23		23		ns
t_{HZ}		8		8	ns
t_{WC}	70		85		ns
t_{WHZ}		8		8	ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns

Table 61. READ Timing Parameters—ADV# LOW

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AA}		70		85	ns
t_{BHZ}		8		8	ns
t_{BLZ}	10		10		ns
t_{CBPH}	5		5		ns
t_{CEM}		4		4	µs
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{OE}		20		20	ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns



Note: *CE# can stay LOW when transitioning between asynchronous operations. If CE# goes HIGH, it must remain HIGH for at least 5ns (t_{CBPH}) to schedule the appropriate internal refresh operation. See "How Extended Timings Impact CellularRAM™ Operation" for restrictions on the maximum CE# LOW time (t_{CEM}).*

Figure 60. Asynchronous WRITE Followed by Asynchronous READ

Table 62. WRITE Timing Parameters—Asynchronous WRITE Followed by Asynchronous READ

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AS}	0		0		ns
t_{AVH}	5		5		ns
t_{AVS}	10		10		ns
t_{AW}	70		85		ns
t_{BW}	70		85		ns
t_{CVS}	10		10		ns
t_{CW}	70		85		ns
t_{DH}	0		0		ns
t_{DW}	23		23		ns

Table 62. WRITE Timing Parameters—Asynchronous WRITE Followed by Asynchronous READ

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{VP}	10		10		ns
t_{VPH}	10		10		ns
t_{VS}	70		85		ns
t_{WC}	70		85		ns
t_{WHZ}		8		8	ns
t_{WP}	46		55		ns
t_{WPH}	10		10		ns
t_{WR}	0		0		ns

Table 63. READ Timing Parameters—Asynchronous WRITE Followed by Asynchronous READ

Symbol	70ns/80 MHz		85ns/66 MHz		Units
	Min	Max	Min	Max	
t_{AA}		70		85	ns
t_{BHZ}		8		8	ns
t_{BLZ}	10		10		ns
t_{CBPH}	5		5		ns
t_{CEM}		4		4	µs
t_{HZ}		8		8	ns
t_{LZ}	10		10		ns
t_{OE}		20		20	ns
t_{OHZ}		8		8	ns
t_{OLZ}	5		5		ns

How Extended Timings Impact CellularRAM™ Operation

Introduction

This section describes CellularRAM™ timing requirements in systems that perform extended operations.

CellularRAM products use a DRAM technology that periodically requires refresh to ensure against data corruption. CellularRAM devices include on-chip circuitry that performs the required refresh in a manner that is completely transparent in systems with normal bus timings. The refresh circuitry imposes constraints on timings in systems that take longer than 4µs to complete an operation. WRITE operations are affected if the device is configured for asynchronous operation. Both READ and WRITE operations are affected if the device is configured for page or burst-mode operation.

Asynchronous WRITE Operation

The timing parameters provided in Figure 33 require that all WRITE operations must be completed within 4µs. After completing a WRITE operation, the device must either enter standby (by transitioning CE# HIGH), or else perform a second operation (READ or WRITE) using a new address. Figure 61 and Figure 62 demonstrate these constraints as they apply during an asynchronous (page-mode-disabled) operation. Either the CE# active period (t_{CEM} in Figure 61) or the address valid period (t_{TM} in Figure 62) must be less than 4µs during any WRITE operation, otherwise, the extended WRITE timings must be used.

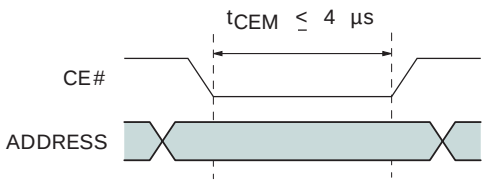


Figure 61. Extended Timing for t_{CEM}

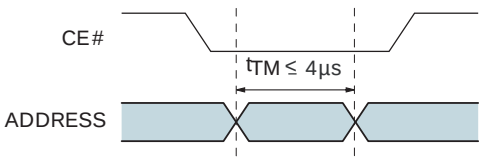


Figure 62. Extended Timing for t_{TM}

Table 64. Extended Cycle Impact on READ and WRITE Cycles

Page Mode	Timing Constraint	Read Cycle	Write Cycle
Asynchronous Page Mode Disabled	t_{CEM} and t_{TM} > 4µs (See Figure 61 and Figure 62.)	No impact.	Must use extended WRITE timing. (See Figure 62)
Asynchronous Page Mode Enabled	t_{CEM} > 4µs (See Figure 61.)	All following intrapage READ access times are t_{AA} (not t_{APA}).	Must use extended WRITE timing. (See Figure 63)
Burst	t_{CEM} > 4µs (See Figure 61.)	Burst must cross a row boundary within 4µs.	

Extended WRITE Timing— Asynchronous WRITE Operation

Modified timings are required during extended WRITE operations (see Figure 63). An extended WRITE operation requires that both the write pulse width (t_{WP}) and the data valid period (t_{DW}) be lengthened to at least the minimum WRITE cycle time (t_{WC} [MIN]). These increased timings ensure that time is available for both a refresh operation and a successful completion of the WRITE operation.

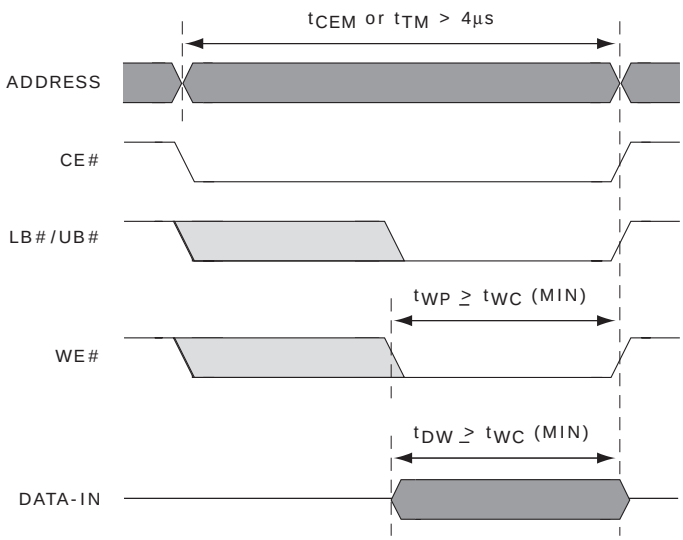


Figure 63. Extended WRITE Operation

Page Mode READ Operation

When a CellularRAM device is configured for page mode operation, the address inputs are used to accelerate read accesses and cannot be used by the on-chip circuitry to schedule refresh. If CE# is LOW longer than the t_{CEM} maximum time of 4µs during a READ operation, the system must allow t_{AA} (not t_{APA}, as would otherwise be expected) for all subsequent intrapage accesses until CE# goes HIGH.

Burst-Mode Operation

When configured for burst-mode operation, it is necessary to allow the device to perform a refresh within any 4µs window. One of two conditions will enable the device to schedule a refresh within 4µs. The first condition is when all burst operations complete within 4µs. A burst completes when the CE# signal is registered HIGH on a rising clock edge. The second condition that allows a refresh is when a burst access crosses a row boundary. The row-boundary crossing causes WAIT to be asserted while the next row is accessed and enables the scheduling of refresh.

Summary

CellularRAM products are designed to ensure that any possible asynchronous timings do not cause data corruption due to lack of refresh. Slow bus timings on asynchronous WRITE operations require that t_{WP} and t_{DW} be lengthened. Slow bus timings during asynchronous page READ operations cause the next intrapage READ data to be delayed to t_{AA}.

Burst mode timings must allow the device to perform a refresh within any 4µs period. A burst operation must either complete (CE# registered HIGH) or cross a row boundary within 4µs to ensure successful refresh scheduling. These timing requirements are likely to have little or no impact when interfacing a CellularRAM device with a low-speed memory bus.

CellularRAM-2A

64 Megabit
Asynchronous CellularRAM

Features

- **Asynchronous and Page Mode interface**
- **Random Access Time: 70 ns**
- **Page Mode Read Access**
  - Sixteen-word page size
  - Interpage read access: 70 ns
  - Intrapage read access: 20 ns
- **V_{CC}, V_{CCQ} Voltages**
  - 1.70 V to 1.95 V V_{CC}
  - 1.70 V to 2.25 V V_{CCQ}
- **Low Power Consumption**
  - Asynchronous READ < 25 mA
  - Intrapage READ < 15 mA
  - Standby: 100 µA
  - Deep power-down < 10 µA
- **Low-Power Features**
  - Temperature Compensated Refresh (TCR)
  - Partial Array Refresh (PAR)
  - Deep Power-Down (DPD) Mode

General Description

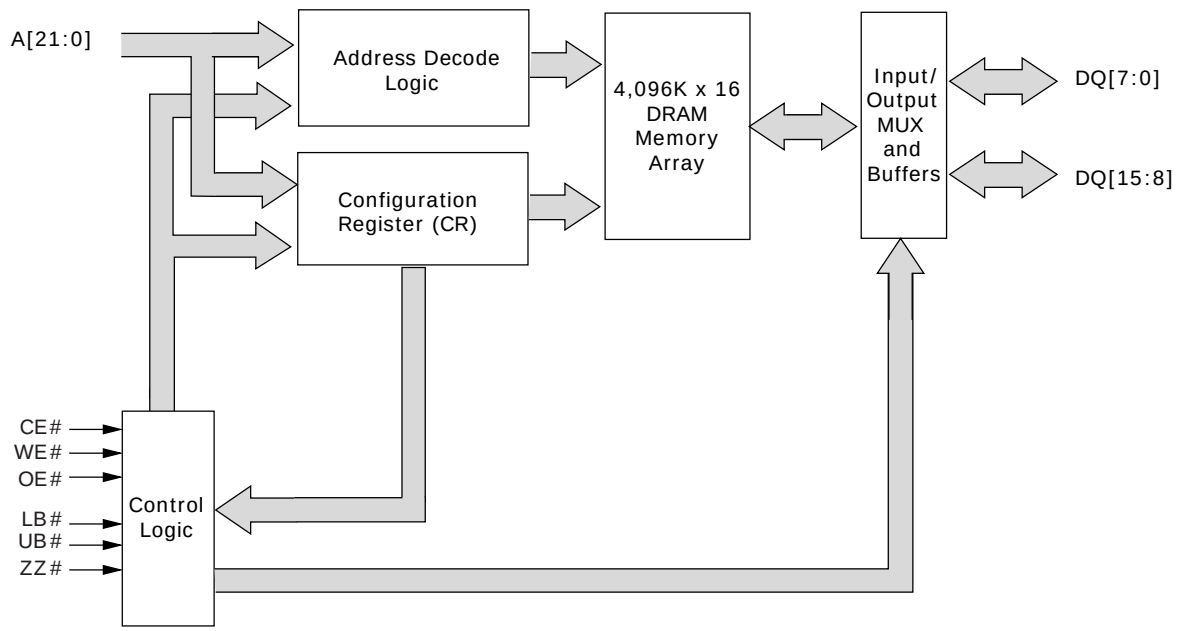
CellularRAM™ products are high-speed, CMOS dynamic random access memories that have been developed for low-power portable applications. The 64Mb device is organized as 4 Meg x 16 bits. These devices include the industry-standard, asynchronous memory interface found on other low-power SRAM or Pseudo SRAM offerings.

A user-accessible configuration register (CR) has been included to define device operation. The CR defines how the CellularRAM device performs on-chip refresh and whether page mode read accesses are permitted. This register is automatically loaded with a default setting during power-up and can be updated at any time during normal operation.

To operate smoothly on an asynchronous memory bus, CellularRAM products have incorporated a transparent self refresh mechanism. The hidden refresh requires no additional support from the system memory controller and has no significant impact on device read/write performance.

Special attention has been focused on current consumption during self refresh. CellularRAM products include three system-accessible mechanisms used to minimize refresh current. Temperature compensated refresh (TCR) is used to adjust the refresh rate according to the case temperature. The refresh rate can be decreased at lower temperatures to minimize current consumption during standby. Setting the sleep enable pin ZZ# to LOW enables one of two low-power modes: partial array refresh (PAR); or deep power-down (DPD). PAR limits refresh to only that part of the DRAM array that contains essential data. DPD halts refresh oper-

ation altogether and is used when no vital information is stored in the device. These three refresh mechanisms are accessed through the CR.



Note: *Functional block diagrams illustrate simplified device operation. See truth table, pin descriptions, and timing diagrams for detailed information.*

Figure 64. Functional Block Diagram

Table 65. Pin Descriptions

Symbol	Type	Description
A[21:0]	Input	Address Inputs: Inputs for the address accessed during READ or WRITE operations. The address lines are also used to define the value to be loaded into the configuration register.
ZZ#	Input	Sleep Enable: When ZZ# is LOW, the configuration register can be loaded or the device can enter one of two low-power modes (DPD or PAR).
CE#	Input	Chip Enable: Activates the device when LOW. When CE# is HIGH, the device is disabled and goes into standby power mode.
OE#	Input	Output Enable: Enables the output buffers when LOW. When OE# is HIGH, the output buffers are disabled.
WE#	Input	Write Enable: Enables WRITE operations when LOW.
LB#	Input	Lower Byte Enable. DQ[7:0]
UB#	Input	Upper Byte Enable. DQ[15:8]
DQ[15:0]	Input/ Output	Data Inputs/Outputs.
V_{CC}	Supply	Device Power Supply: (1.7 V–1.95 V) Power supply for device core operation.
$V_{CC}Q$	Supply	I/O Power Supply: (1.8 V) Power supply for input/output buffers.
V_{SS}	Supply	V_{SS} must be connected to ground.

Table 65. Pin Descriptions (Continued)

Symbol	Type	Description
$V_{SS}Q$	Supply	$V_{SS}Q$ must be connected to ground.

Table 66. Bus Operations—Asynchronous Mode

Mode	Power	CE#	WE#	OE#	LB#/UB#	ZZ#	DQ[15:0] (Note 1)	Notes
Standby	Standby	H	X	X	X	H	High-Z	2, 5
Read	Active > Standby	L	H	L	L	H	Data-Out	1, 4
Write	Active > Standby	L	L	X	L	H	Data-In	1, 3, 4
Active	Standby	L	H	H	L	H	High-Z	4, 5
PAR	Partial Array Refresh	H	X	X	X	L	High-Z	6
DPD	Deep Power-down	H	X	X	X	L	High-Z	6
Load Configuration Register	Active	L	L	X	X	L	High-Z	

Notes:

1. *When LB# and UB# are in select mode (LOW), DQ[15:0] are affected. When LB# only is in select mode, only DQ[7:0] are affected. When UB# only is in the select mode, DQ[15:8] are affected.*
2. *When the device is in standby mode, control inputs (WE#, OE#), address inputs, and data inputs/outputs are internally isolated from any external influence.*
3. *When WE# is invoked, the OE# input is internally disabled and has no effect on the I/Os.*
4. *The device consumes active power in this mode whenever addresses are changed.*
5. *V_{IN} = V_{CC} or 0V; all device balls must be static (unswitched) in order to achieve minimum standby current.*
6. *DPD is enabled when configuration register bit CR[4] is "0"; otherwise, PAR is enabled.*

Functional Description

The 64Mb async/page CellularRAM device is a high-density alternative to SRAM and Pseudo SRAM products, popular in low-power, portable applications. The device contains 67,108,864 bits organized as 4,194,304 addresses by 16 bits. It includes the industry-standard, asynchronous memory interface found on other low-power SRAM or Pseudo SRAM offerings. Page mode accesses are also included as a bandwidth-enhancing extension to the asynchronous read protocol.

Power-Up Initialization

CellularRAM products include an on-chip voltage sensor that is used to launch the power-up initialization process. Initialization will load the CR with its default settings. V_{CC} and V_{CCQ} must be applied simultaneously, and when they reach a stable level above 1.70 V, the device requires 150 µs to complete its self initialization process (see Figure 2). During the initialization period, CE# should remain HIGH. When initialization is complete, the device is ready for normal operation. At power-up, the CR is set to 0070h.

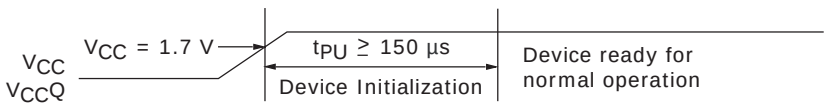


Figure 65. Power-Up Initialization Timing

Bus Operating Modes

CellularRAM products incorporate the industry-standard, asynchronous interface found on other low-power SRAM or Pseudo SRAM offerings. This bus interface supports asynchronous READ and WRITE operations as well as the bandwidth-enhancing page mode READ operation. The specific interface that is supported is defined by the value loaded into the CR.

Asynchronous Mode

CellularRAM products power up in the asynchronous operating mode. This mode uses the industry standard SRAM control interface (CE#, OE#, WE#, LB#/ UB#). READ operations (Figure 66) are initiated by bringing CE#, OE#, and LB#/UB# LOW while keeping WE# HIGH. Valid data will be driven out of the I/Os after the specified access time has elapsed. WRITE operations (Figure 67) occur when CE#, WE#, and LB#/ UB# are driven LOW. During WRITE operations, the level of OE# is a “Don't Care”; WE# will override OE#. The data to be written will be latched on the rising edge of CE#, WE#, or LB#/UB# (whichever occurs first).

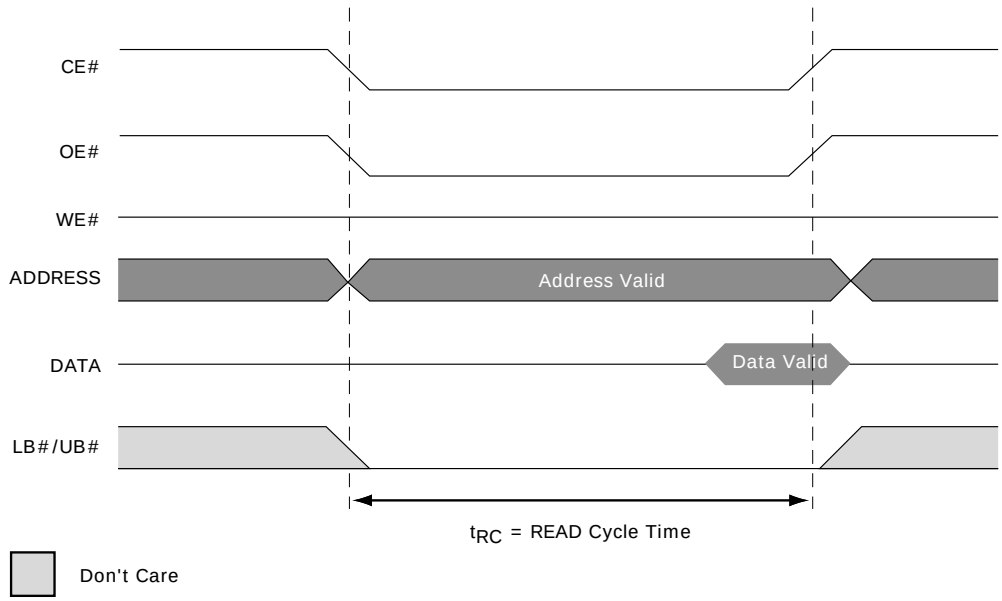


Figure 66. READ Operation

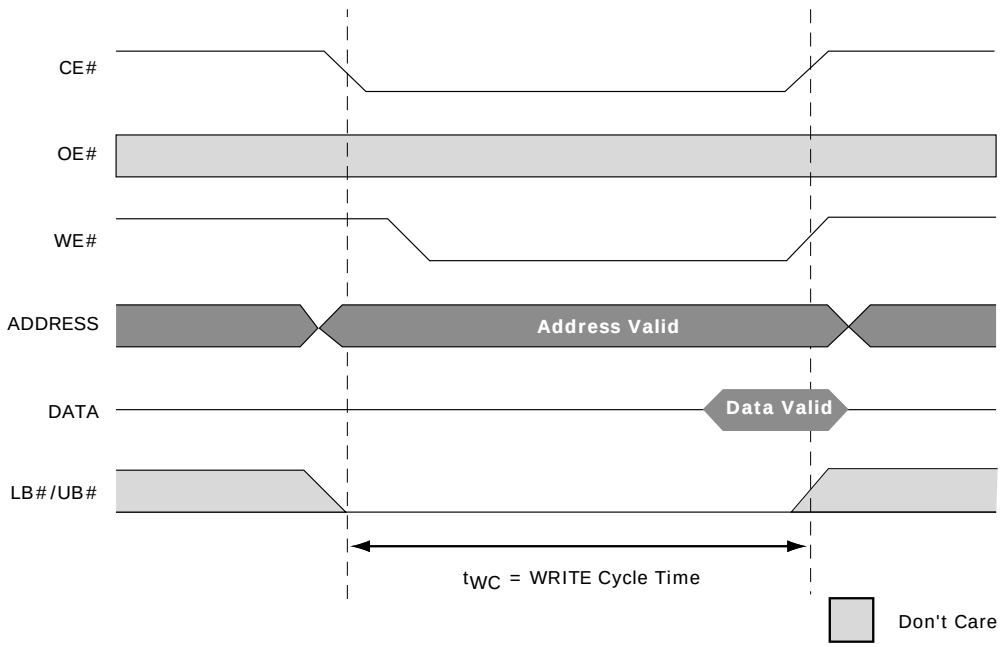


Figure 67. WRITE Operation

Page Mode READ Operation

Page mode is a performance-enhancing extension to the legacy asynchronous READ operation. In page mode-capable products, an initial asynchronous read access is performed, then adjacent addresses can be quickly read by simply changing the low-order address. Addresses A[3:0] are used to determine the members of the 16-address CellularRAM page. Addresses A[4] and higher must remain fixed during the entire page mode access. Figure 68 shows the timing diagram for a page mode access.

Page mode takes advantage of the fact that adjacent addresses can be read in a shorter period of time than random addresses. WRITE operations do not include comparable page mode functionality.

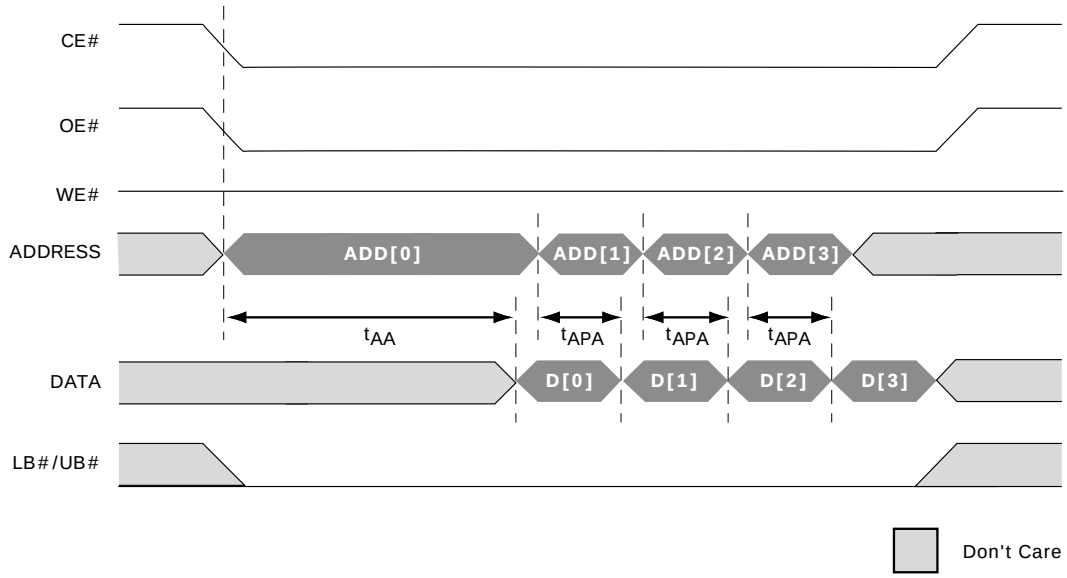


Figure 68. Page Mode READ Operation

LB# / UB# Operation

The lower byte (LB#) enable and upper byte (UB#) enable signals allow for byte-wide data transfers. During READ operations, enabled bytes are driven onto the DQs. The DQs associated with a disabled byte are put into a High-Z state during a READ operation. During WRITE operations, any disabled bytes will not be transferred to the memory array and the internal value will remain unchanged. During a WRITE cycle, the data to be written is latched on the rising edge of CE#, WE#, LB#, or UB#, whichever occurs first.

When both the LB# and UB# are disabled (HIGH) during an operation, the device will disable the data bus from receiving or transmitting data. Although the device will seem to be deselected, the device remains in an active mode as long as CE# remains LOW.

Low Power Operation

Standby Mode Operation

During standby, the device current consumption is reduced to the level necessary to perform the DRAM refresh operation on the full array. Standby operation occurs when CE# and ZZ# are HIGH and there are no transactions in progress.

The device will enter standby operation during READ and WRITE operations where the address and control inputs remain static for an extended period of time. This “active” standby mode will continue until a change occurs to the address or control inputs.

Temperature Compensated Refresh

Temperature compensated refresh (TCR) is used to adjust the refresh rate depending on the device operating temperature. DRAM technology requires more

frequent refresh operations to maintain data integrity as temperatures increase. More frequent refresh is required due to the increased leakage of the DRAM's capacitive storage elements as temperatures rise. A decreased refresh rate at lower temperatures will facilitate a savings in standby current.

TCR allows for adequate refresh at four different temperature thresholds: +15°C, +45°C, +70°C, and +85°C. The setting selected must be for a temperature higher than the case temperature of the CellularRAM device. If the case temperature is +50°C, the system can minimize self refresh current consumption by selecting the +70°C setting. The +15°C and +45°C settings would result in inadequate refreshing and cause data corruption.

Partial Array Refresh

Partial array refresh (PAR) restricts refresh operation to a portion of the total memory array. This feature enables the system to reduce refresh current by only refreshing that part of the memory array that is absolutely necessary. The refresh options are full array, three-quarters array, one-half array, one-quarter array, or none of the array. Data stored in addresses not receiving refresh will become corrupted. The mapping of these partitions can start at either the beginning or the end of the address map (Tables 5 and 6). READ and WRITE operations are ignored during PAR operation.

The device can only enter PAR mode if the SLEEP bit in the configuration register has been set HIGH (CR[4] = 1). PAR is initiated by bring the ZZ# pin to the LOW state for longer than 10µs. Returning ZZ# to HIGH will cause an exit from PAR and the entire array will be immediately available for READ and WRITE operations.

Deep Power-Down Operation

Deep power-down (DPD) operation disables all refresh-related activity. This mode is used when the system does not require the storage provided by the CellularRAM device. Any stored data will become corrupted when DPD is entered. When refresh activity has been re-enabled, the CellularRAM device will require 150µs to perform an initialization procedure before normal operations can resume. READ and WRITE operations are ignored during DPD operation.

The device can only enter DPD if the SLEEP bit in the CR has been set LOW (CR[4] = 0). DPD is initiated by bringing the ZZ# pin to the LOW state for longer than 10µs. Returning ZZ# to HIGH will cause the device to exit DPD and begin a 150µs initialization process. During this 150µs period, the current consumption will be higher than the specified standby levels but considerably lower than the active current specification.

Driving the ZZ# pin LOW will place the device in the PAR mode if the SLEEP bit in the CR has been set HIGH (CR[4] = 1).

Configuration Register Operation

The configuration register (CR) defines how the CellularRAM device performs its transparent self refresh. This register is automatically loaded with default settings during power-up and can be updated anytime while the device is operating in a standby state.

The CR is loaded using a WRITE operation immediately after ZZ# makes a HIGH-to-LOW transition (Figure 69). The values placed on addresses A[21:0] are latched into the CR on the rising edge of CE# or WE#, whichever occurs first. Al-

tering the refresh parameters can dramatically reduce current consumption during standby mode. Page mode control is also embedded into the configuration register. Table 67 describes the control bits used in the CR. At power up, the CR is set to 0070h.

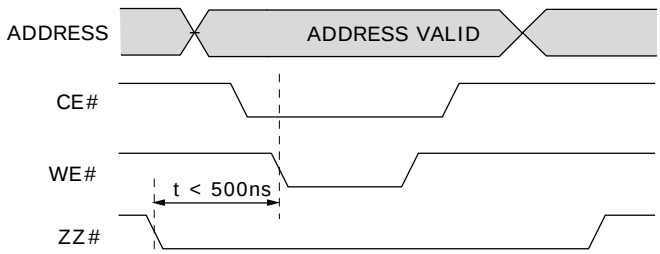


Figure 69. Load Configuration Register Operation

Partial Array Refresh (CR[2:0]) Default = Full Array Refresh

The PAR bits restrict refresh operation to a portion of the total memory array. This feature allows the system to reduce current by only refreshing that part of the memory array required by the host system. The refresh options are full array, three-quarters array, one-half array, one-quarter array, or none of the array. The mapping of these partitions can start at either the beginning or the end of the address map (see Table 68 on page 181).

Sleep Mode (CR[4]) Default = PAR Enabled, DPD Disabled

The sleep mode bit determines which low-power mode is to be entered when ZZ# is driven LOW. If CR[4] = 1, PAR operation is enabled. If CR[4] = 0, DPD operation is enabled.

DPD operation disables all refresh-related activity. This mode will be used when the system does not require the storage provided by the CellularRAM device. Any stored data will become corrupted when DPD is enabled. When refresh activity has been re-enabled, the CellularRAM device will require 150µs to perform an initialization procedure before normal operation can resume.

Temperature Compensated Refresh (CR[6:5]) Default = +85°C Operation

The TCR bits allow for adequate refresh at four different temperature thresholds: +15°C, +45°C, +70°C, and +85°C. The setting selected must be for a temperature higher than the case temperature of the CellularRAM device. If the case temperature is +50°C, the system can minimize self refresh current consumption by selecting the +70°C setting. The +15°C and +45°C settings would result in inadequate refreshing and cause data corruption.

Page Mode READ Operation (CR[7]) Default = Disabled

The page mode operation bit determines whether page mode READ operations are enabled. In the power-up default state, page mode is disabled.

Table 67. Configuration Register Bit Mapping

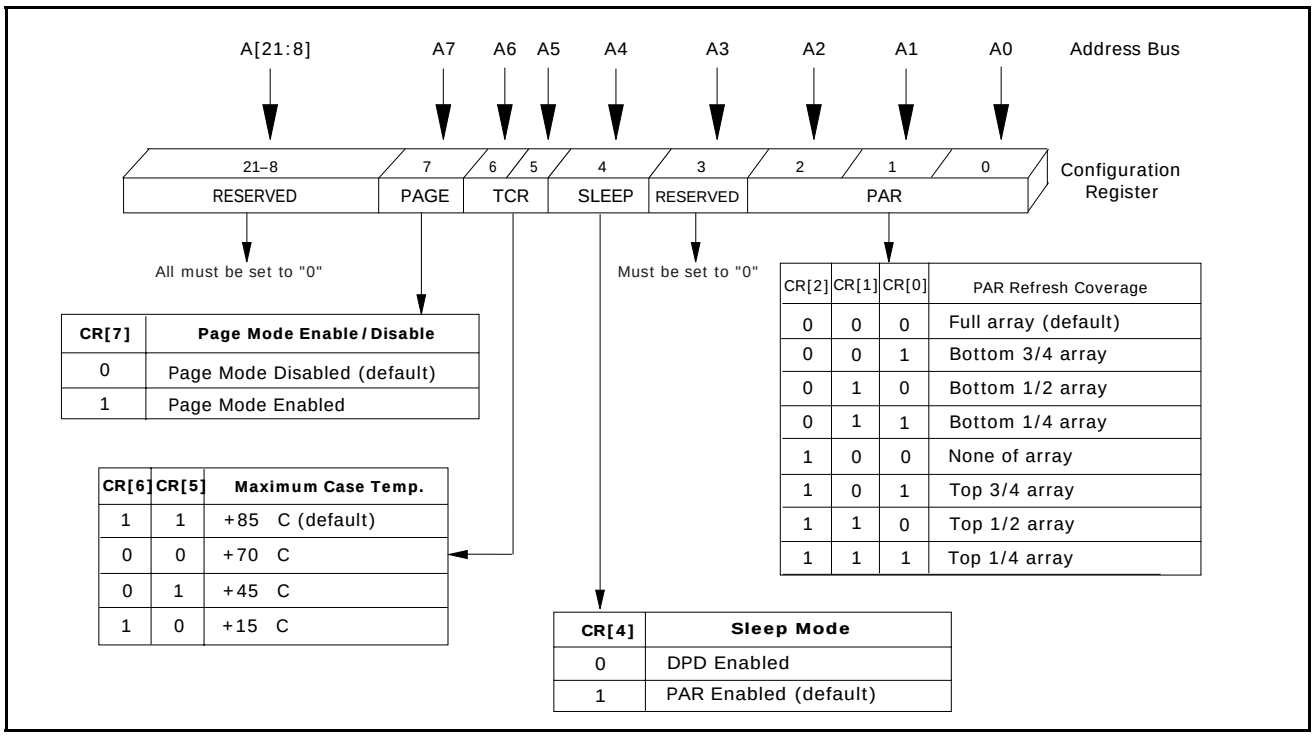


Table 68. 64Mb Address Patterns for PAR (CR[4] = 1)

CR[2]	CR[1]	CR[0]	Active Section	Address Space	Size	Density
0	0	0	Full die	000000h–3FFFFFh	4 Meg x 16	64Mb
0	0	1	Three-quarters of die	000000h–2FFFFFh	3 Meg x 16	48Mb
0	1	0	One-half of die	000000h–1FFFFFh	2 Meg x 16	32Mb
0	1	1	One-quarter of die	000000h–0FFFFFh	1 Meg x 16	16Mb
1	0	0	None of die	0	0 Meg x 16	0Mb
1	0	1	Three-quarters of die	100000h–3FFFFFh	3 Meg x 16	48Mb
1	1	0	One-half of die	200000h–3FFFFFh	2 Meg x 16	32Mb
1	1	1	One-quarter of die	300000h–3FFFFFh	1 Meg x 16	16Mb

Absolute Maximum Ratings

Voltage to Any Ball Except V_{CC}, $V_{CC}Q$
Relative to V_{SS} . . . -0.50 V to (4.0 V or $V_{CC}Q$ + 0.3 V, whichever is less)

Voltage on V_{CC} Supply Relative to V_{SS} . . . . . -0.20 V to +2.45 V

Voltage on $V_{CC}Q$ Supply Relative to V_{SS} . . . . . -0.20 V to +4.0 V

Storage Temperature . . . . . -55ºC to +150ºC

Operating Temperature (case)

Wireless. . . . . -25ºC to +85ºC

Industrial . . . . . -40ºC to +85ºC

Soldering Temperature and Time

10s (lead only) 260ºC

**Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.*

DC Characteristics

Wireless Temperature ($-25°C \le T_C \le +85°C$)

Industrial Temperature ($-40°C < T_C < +85°C$)

Table 69. Electrical Characteristics and Operating Conditions

Description	Conditions	Symbol	Min	Max	Units	Notes
Supply Voltage		V_{CC}	1.70	1.95	V	
I/O Supply Voltage	1.8 V	V_{CCQ}	1.70	2.25	V	
Input High Voltage		V_{IH}	1.4	$V_{CC}Q$ + 0.2	V	
Input Low Voltage		V_{IL}	-0.20	0.4	V	
Output High Voltage	I_{OH} = -0.2mA	V_{OH}	0.80 V_{CCQ}		V	
Output Low Voltage	I_{OL} = +0.2mA	V_{OL}		0.20 V_{CCQ}	V	
Input Leakage Current	V_{IN} = 0 to V_{CCQ}	I_{LI}		1	µA	
Output Leakage Current	OE# = V_{IH} or Chip Disabled	I_{LO}		1	µA	2
Read Operating Current	V_{IN} = V_{CCQ} or 0V Chip Enabled, I_{OUT} = 0	I_{CC1}		25	mA	1, 2
Write Operating Current	V_{IN} = V_{CCQ} or 0V Chip Enabled	I_{CC2}		25	mA	1, 2
MAX Standby Current	V_{IN} = V_{CCQ} or 0V Chip Disabled	I_{SB}		100	µA	2, 3

Notes:

1. *This parameter is specified with the outputs disabled to avoid external loading effects. The user must add current required to drive output capacitance expected in the actual system.*
2. *This device assumes a standby mode if the chip is disabled (CE# HIGH). It will also automatically go into a standby mode whenever all input signals are quiescent (not toggling), regardless of the state of CE#, LB#, and UB#. In order to achieve low standby current, all inputs must be either VCCQ or VSS.*
3. *ISB (MAX) values measured with PAR set to FULL ARRAY and TCR set to +85°C.*

Table 70. Temperature Compensated Refresh Specifications and Conditions

Description	Conditions	Symbol	Density	Max Case Temperature	Typ	Max	Units
Temperature Compensated Refresh Standby Current	V_{IN} = $V_{CC}Q$ or 0V, Chip Disabled	I_{TCR}	64 Mb	+85°C		100	µA
				+70°C		TBD	
				+45°C		TBD	
				+15°C		50	

Notes:

1. *ITCR (MAX) values measured with FULL ARRAY refresh.*
2. *This device assumes a standby mode if the chip is disabled (CE# HIGH). It will also automatically go into a standby mode whenever all input signals are quiescent (not toggling), regardless of the state of CE#, LB#, and UB#. In order to achieve low standby current, all inputs must be either VCCQ or VSS.*

Table 71. Partial Array Refresh Specifications and Conditions

Description	Conditions	Symbol	Density	Array Partition	Typ	Max	Units
Partially Array Refresh Current	V_{IN} = V_{CC}Q or 0V, ZZ# = Low CR[4] = 1	I_{PAR}	64 Mb	Full		100	µA
				3/4		TBD	
				1/2		TBD	
				1/4		TBD	
				0		50	

Note: I_{PAR} (MAX) values measured with TCR set to 85°C.

Table 72. Deep Power-Down Specifications

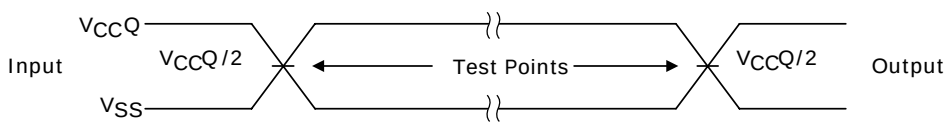
Description	Conditions	Symbol	Typ	Max	Units
Deep Power-down	V_{IN} = V_{CC}Q or 0V; +25°C; ZZ# = LOW CR[4] = 0	I_{ZZ}		10	µA

Table 73. Capacitance Specifications and Conditions

Description	Conditions	Symbol	Min	Max	Units	Notes
Input Capacitance	T_C = +25ºC; f = 1 MHz; V_{IN} = 0V	C_{IN}	-	6	pF	1
Input/Output Capacitance (DQ)		C_{IO}	-	6	pF	1

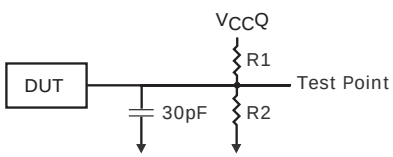
Notes:
1. *These parameters are verified in device characterization and are not 100% tested.*

AC Characteristics



Notes:
1. *AC test inputs are driven at VCCQ for a logic 1 and VSS for a logic 0. Input timing begins at VCCQ/2, and output timing ends at VCCQ/2. Input rise and fall times (10% to 90%) < 1.6ns.*

Figure 70. AC Input/Output Reference Waveform



Note: *All tests are performed with the outputs configured for full drive strength (BCR[5] = 0).*

Figure 71. Output Load Circuit

Table 74. Output Load Circuit

V_{CC}Q	RI/R2
1.8 V	2.7 KΩ

Table 75. READ Cycle Timing Requirements

Parameter	Symbol	Min	Max	Units	Notes
Address Access Time	t_{AA}		70	ns	
Page Access Time	t_{APA}		20	ns	
LB#/UB# Access Time	t_{BA}		70	ns	
LB#/UB# Disable to High-Z Output	t_{BHZ}	0	8	ns	2
LB#/UB# Enable to Low-Z Output	t_{BLZ}	10		ns	1
Chip Select Access Time	t_{CO}		70	ns	
Chip Disable to High-Z Output	t_{HZ}	0	8	ns	2
Chip Enable to Low-Z Output	t_{LZ}	10		ns	1
Output Enable to Valid Output	t_{OE}		20	ns	
Output Hold from Address Change	t_{OH}	5		ns	
Output Disable to High-Z Output	t_{OHZ}	0	8	ns	2
Output Enable to Low-Z Output	t_{OLZ}	5		ns	1
Page Cycle Time	t_{PC}	20		ns	
READ Cycle Time	t_{RC}	70		ns	

Notes:

1. *High-Z to Low-Z timings are tested with the circuit shown in Figure 71 on page 184. The Low-Z timings measure a 100mV transition away from the High-Z ($V_{CCQ}/2$) level toward either V_{OH} or V_{OL}.*
2. *Low-Z to High-Z timings are tested with the circuit shown in Figure 71 on page 184. The High-Z timings measure a 100mV transition from either V_{OH} or V_{OL} toward $V_{CCQ}/2$.*

Table 76. WRITE Cycle Timing Requirements

Parameter	Symbol	Min	Max	Units	Notes
Address Setup Time	t_{AS}	0		ns	
Address Valid to End of Write	t_{AW}	70		ns	
Byte Select to End of Write	t_{BW}	70		ns	
CE# HIGH Time During Write	t_{CEH}	5		ns	
Maximum CE# Pulse Width	t_{CEM}		10	µs	
Chip Enable to End of Write	t_{CW}	70		ns	
Data Hold from Write Time	t_{DH}	0		ns	
Data WRITE Setup Time	t_{DW}	23		ns	
Chip Enable to Low-Z Output	t_{LZ}	10		ns	1
End WRITE to Low-Z Output	t_{OW}	5		ns	
Write Cycle Time	t_{WC}	70		ns	
Write to High-Z Output	t_{WHZ}	0	8	ns	2
Write Pulse Width	t_{WP}	46			
Write Recovery Time	t_{WR}	0		ns	

Notes:

1. *High-Z to Low-Z timings are tested with the circuit shown in Figure 71 on page 184. The Low-Z timings measure a 100mV transition away from the High-Z ($V_{CCQ}/2$) level toward either V_{OH} or V_{OL}.*
2. *Low-Z to High-Z timings are tested with the circuit shown in Figure 71 on page 184. The High-Z timings measure a 100mV transition from either V_{OH} or V_{OL} toward $V_{CCQ}/2$.*

Table 77. Load Configuration Register Timing Requirements

Parameter	Symbol	Min	Max	Units	Notes
Address Setup Time	t_{AS}	0		ns	
Address Valid to End of Write	t_{AW}	70		ns	
Chip Deselect to ZZ# LOW	t_{CDZZ}	5		ns	
Chip Enable to End of Write	t_{CW}	70		ns	
Write Cycle Time	t_{WC}	70		ns	
Write Pulse Width	t_{WP}	40		ns	
Write Recovery Time	t_{WR}	0		ns	
ZZ# LOW to WE# LOW	t_{ZZWE}	10		ns	

Table 78. Deep Power Down Timing Requirements

Parameter	Symbol	Min	Max	Units	Notes
Chip Deselect to ZZ# LOW	t_{CDZZ}	5		ns	
Deep Power-Down Recovery	t_R	150		µs	
Minimum ZZ# Pulse Width	t_{ZZMIN}	10		µs	

Table 79. Power-up Initialization Timing Parameters

Parameter	Symbol	Min	Max	Units	Notes
Initialization Period (required before normal operations)	t_{PU}	150		µs	

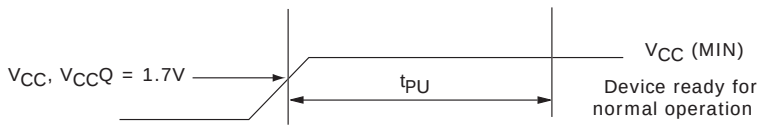


Figure 72. Power-up Initialization Period

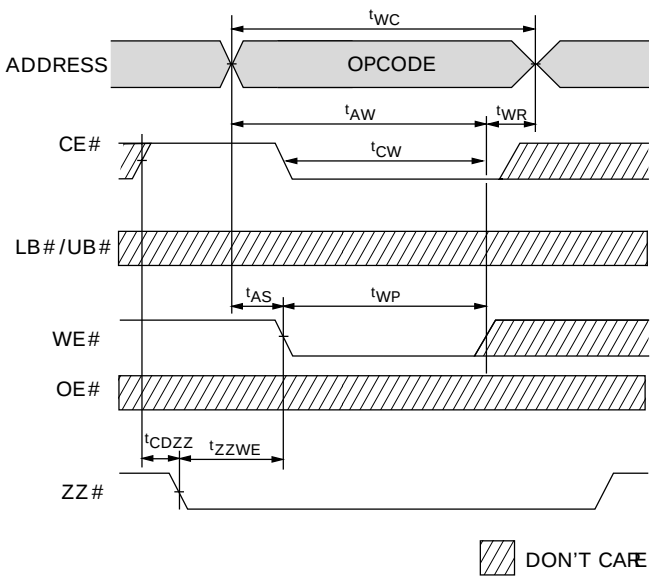


Figure 73. Load Configuration Register Timing

Table 80. Load Configuration Register Timing Requirements

Symbol	Min	Max	Units		Symbol	Min	Max	Units
t_{AS}	0		ns		t_{WC}	70		ns
t_{AW}	70				t_{WP}	40		
t_{CDZZ}	5				t_{WR}	0		
t_{CW}	70				t_{ZZWE}	10	500	

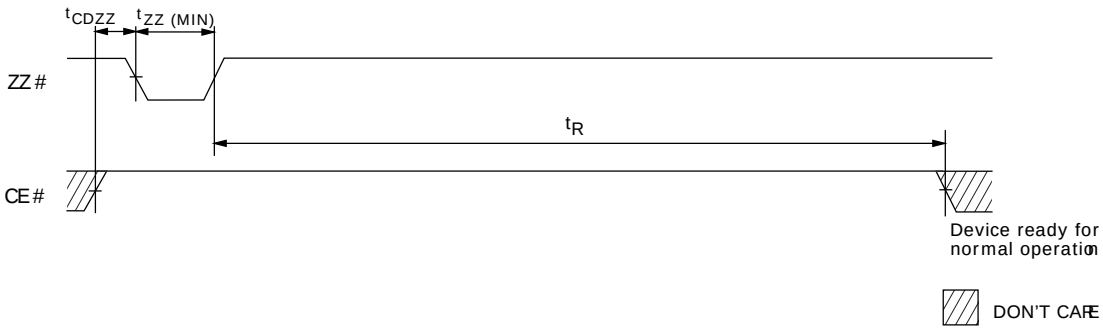


Figure 74. Deep Power Down Entry/Exit TIming

Table 81. Load Configuration Register Timing Requirements

Symbol	Min	Max	Units
t_{CDZZ}	5		ns
t_R	150		µs
$t_{ZZ(MIN)}$	10		µs

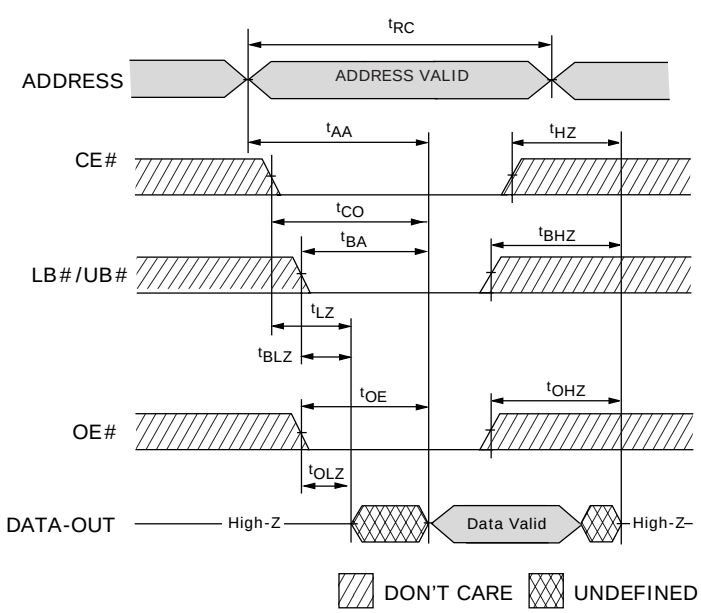


Figure 75. Single READ Operation (WE# = V_{IH})

Table 82. READ Timing Parameters

Symbol	Min	Max	Units		Symbol	Min	Max	Units
t_{AA}		70	ns		t_{LZ}	10		ns
t_{BA}		70			t_{OE}		20	
t_{BHZ}	0	8			t_{OHZ}	0	8	
t_{BLZ}	10				t_{OLZ}	5		
t_{CO}		70			t_{RC}	70		
t_{HZ}	0	8						

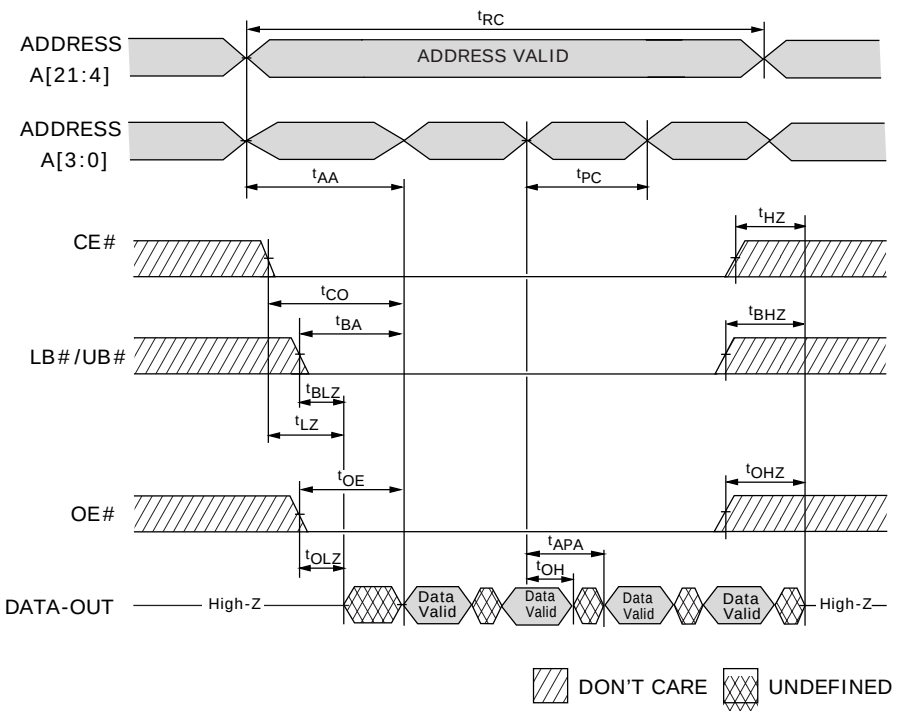


Figure 76. Page Mode Read Operation (WE# = V_{IH})

Table 83. Page Mode READ Timing Parameters

Symbol	Min	Max	Units		Symbol	Min	Max	Units
t_{AA}		70	ns		t_{LZ}	10		ns
t_{APA}		20			t_{OE}		20	
t_{BA}		70			t_{OH}	5		
t_{BHZ}	0	8			t_{OHZ}	0	8	
t_{BLZ}	10				t_{OLZ}	5		
t_{CO}		70			t_{PC}	20		
t_{HZ}	0	8			t_{RC}	70		

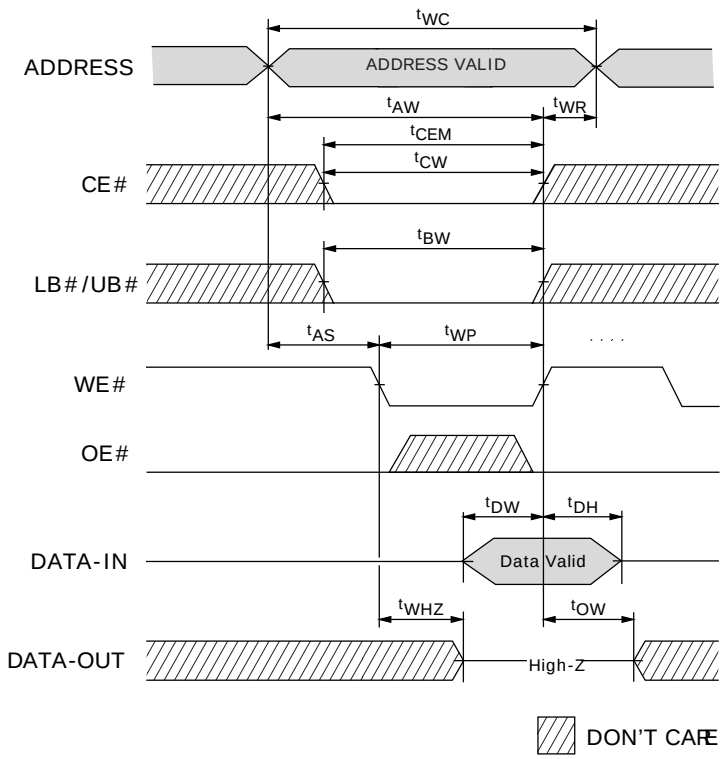


Figure 77. WRITE Cycle (WE# Control)

Table 84. Write Timing Parameters

Symbol	Min	Max	Units	Symbol	Min	Max	Units
t_{AS}	0		ns	t_{DW}	23		ns
t_{AW}	70			t_{OW}	5		
t_{BW}	70			t_{WC}	70		
t_{CEM}		10	µs	t_{WHZ}	0	8	
t_{CW}	70		ns	t_{WP}	46		
t_{DH}	0			t_{WR}	0		

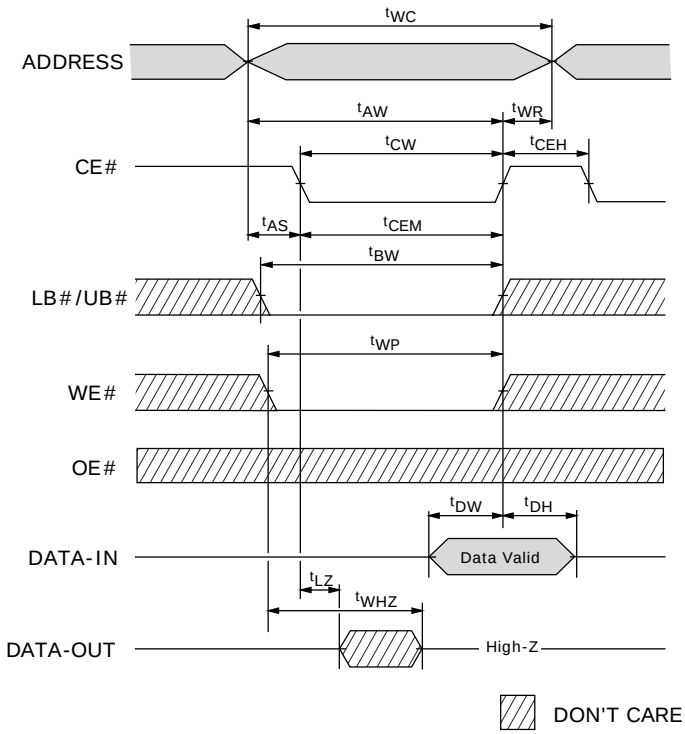


Figure 78. Write Timing Parameters (CE# Control)

Table 85. Write Timing Parameters (CE# Control)

Symbol	Min	Max	Units	Symbol	Min	Max	Units
t_{AS}	0		ns	t_{DW}	23		ns
t_{AW}	70			t_{LZ}	10		
t_{BW}	70			t_{WC}	70		
t_{CEH}	5			t_{WHZ}	0	8	
t_{CEM}		10	µs	t_{WP}	46		
t_{CW}	70		ns	t_{WR}	0		
t_{DH}	0						

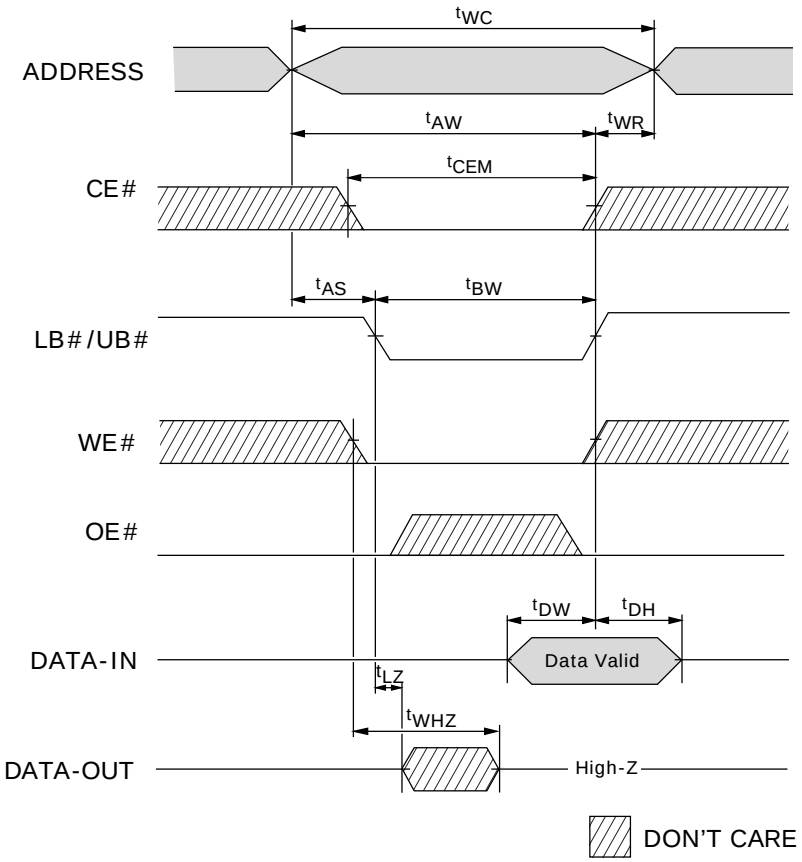


Figure 79. WRITE Cycle (LB# / UB# Control)

Table 86. Write Timing Parameters (LB# / UB# Control)

Symbol	Min	Max	Units		Symbol	Min	Max	Units
t_{AS}	0		ns		t_{DW}	23		ns
t_{AW}	70				t_{LZ}	10		
t_{BW}	70				t_{WC}	70		
t_{CEM}		10	µs		t_{WHZ}	0	8	
t_{DH}	0		ns		t_{WR}	0		

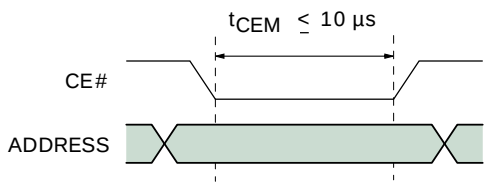
How Extended Timings Impact CellularRAM™ Operation

Introduction

CellularRAM products use a DRAM technology that periodically requires refresh to ensure against data corruption. CellularRAM devices include on-chip circuitry that performs the required refresh in a manner that is completely transparent in systems with normal bus timings. The refresh circuitry does impose constraints on timings in systems that take longer than 10µs to complete WRITE operations. This section describes CellularRAM timing requirements in systems that perform extended operations.

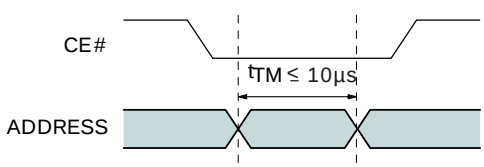
Operation When Page Mode is Disabled

CellularRAM products require that all WRITE operations must be completed within 10µs. After completing an operation, the device must either enter standby (by transitioning CE# HIGH), or else perform a second operation using a new address. Figures 80 and 81 demonstrate these constraints as they apply during an asynchronous (page-mode-disabled) operation. Either the CE# active period (t_{CEM} in Figure 80) or the address valid period (t_{TM} in Figure 81) must be less than 10 µs during any operation to accommodate orderly scheduling of refresh.



Note:Timing constraints when page mode is enabled.

Figure 80. Extended Timing for t_{CEM}

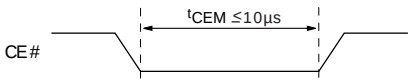


Note:Timing constraints when page mode is enabled.

Figure 81. Extended Timing for t_{TM}

Operation When Page Mode is Enabled

When a CellularRAM device is configured for page mode operation, the address inputs are used to accelerate read accesses and cannot be used by the on-chip circuitry to schedule refresh. CE# must return HIGH upon completion of all WRITE operations when page mode is enabled (Figure 82). The total time taken for a WRITE operation should not exceed 10 µs to accommodate orderly scheduling of refresh.



Note:Timing constraints when page mode is enabled.

Figure 82. Extended Timing for t_{CEM} (2)

Impact on Extended WRITE Operations

Modified timings are only required during extended WRITE operations (see Figure 83 below). An extended WRITE operation requires that both the write pulse width (t_{WP}) and the data valid period (t_{DW}) will need to be lengthened to at least the minimum WRITE cycle time ($t_{WC[MIN]}$). These increased timings ensure that time is available for both a refresh operation and successful completion of the WRITE operation.

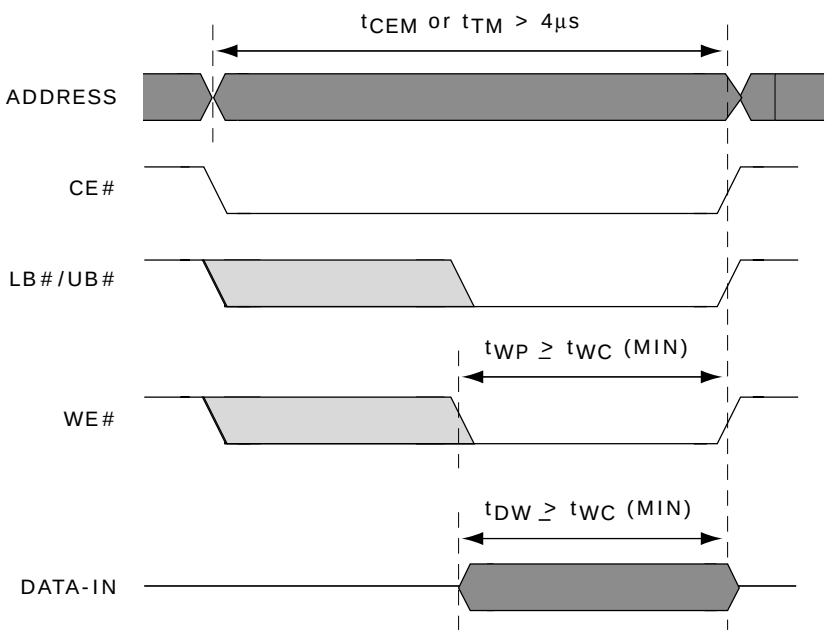


Figure 83. Extended WRITE Operation

Summary

CellularRAM products are designed to ensure that any possible bus timings do not cause corruption of array data due to lack of refresh. The on-chip refresh circuitry will only affect the required timings for WRITE operations (READs are unaffected) performed in a system with a slow memory interface. The impact for WRITE operations is that some of the timing parameters (t_{WP}, t_{DW}) are lengthened. The modified timings are likely to have little or no impact when interfacing a CellularRAM device with a low-speed memory bus.

Revision Summary

Revision A0 (December 17, 2004)

Initial release.

Colophon

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